# Section 1

**SIGMA 5 - 9
DIAGNOSTIC PROGRAM
MAGNETIC TAPE LIBRARY
CONTROL PROGRAM**

**PROGRAM NO. 705691**

Section 1

CONTENTS

Chapter I

INTRODUCTION

**1-1  GENERAL**

This document covers the operating procedure, updating procedures, copy procedure and the various messages associated with the magnetic tape library. All procedures, with the exception of the operation procedure, are tutorial.

**1-2  OPERATING PROCEDURE**

**1-3  TO LOAD PROGRAMS FROM MAGNETIC TAPE**

a. Remove write ring from tape reel and mount to tape unit 0.

b. If the systems configuration prohibits the contents of the upper core from being destroyed (for example, shared memory system), set sense switch 1 and reset sense switches 2, 3, and 4. Otherwise, reset all sense switches.

c. Execute a LOAD from the processor control panel (PCP). If sense switch 1 is set, the program will come to WAIT. Enter the maximum memory address to general register 1, reset sense switch 1 and clear the WAIT condition. If sense switch 1 is reset, the program will not come to a WAIT.

d. A message giving the magnetic tape library title will be typed to the operator keyboard, KSR, and control will be given to the KSR for input.

e. Type in the program name, followed by a NL (New Line-EBCDIC 15) character. The program will be loaded, the tape rewound and control transferred to the program.

f. Refer to individual program write-ups for each program.

Further explanations assume that the program has been loaded and is ready to receive data from the operator.

**1-4  INPUT PROCEDURE**

a. Valid inputs to the KSR can be a program name, a simple NL (New Line - EBCDIC 15) character, or a utility request for UPDATE.

b. All valid KSR input will be terminated with termination character, NL (New Line - EBCDIC 15).

c. Input errors to the KSR can be cleared by the EOM (End of Message - EBCDIC 08) character if the EOM character is input before the termination character (NL).

**1-5  PROGRAM NAME LISTING PROCEDURE**

a. A message giving the magnetic tape library title will be typed to the operator keyboard, KSR, and control will be given to the KSR for input.

b. Type in a NL (New Line - EBCDIC 15) character.

c. Program name, revision level, loader type, if the program is interfaced to the diagnostic program monitor, and the starting address of the program will be printed.

The program name will be listed in the following format:

XXXX. . . XXX  A  B  C  YYYYY

| | |
|---|---|
| XXXX. . X | Program name. This is the name used in calling the program from the magnetic tape library. |
| A | Program revision level. This should always correspond to the latest revision level. The revision level is not required as a part of the name to call a program. |
| B | Loader Type. If this field is blank, it means that the program uses the Relocatable Diagnostic (Sigma 5 and 7 Program No. 704356, Sigma 2 and 3 Program No. 705299) Loader Program. If this field prints letter L, it means that the program uses the CPU Loader. |
| C | Diagnostic Program Monitor. If this field is blank, it means that the program is a stand-alone program and does not interface to the diagnostic program monitor. (Refer to Sigma 5 and 7 Program No. 705682, Sigma 2 and 3 Program No. 705681). If this field prints letter M, it means that the program uses the diagnostic program monitor. |
| YYYYY | The starting address of the program in hexadecimal. |

1-6  **PROCEDURE TO FOLLOW WHEN OPERATOR DOES
NOT KNOW OR CANNOT REMEMBER PROGRAM
NAME**

a.  List program names as described in paragraph 1-5.

b.  Find the appropriate name.  Input the name to
the KSR, followed by a NL (New Line) character.  The
program will be loaded, the tape rewound, and control
transferred to the program.

1-7  **PROCEDURE TO FOLLOW WHEN OPERATOR
REMEMBERS PARTIAL PROGRAM NAME**

a.  Type in the partial program name followed by a
NL (New Line) character.

b.  All program names with a matching partial
program name will be listed on the operator keyboard,
KSR.  Then the partial name will be typed on the KSR.
The user will complete the program name and terminate
input with the NL (New Line) character.  The program
will be loaded, the tape rewound, and control transferred
to the program.

1-8  **OTHER OPERATING FEATURES**

All message outputs can be terminated by the user by
depressing the BREAK key.

Chapter II

OPERATING PROCEDURE

## 2-1  GENERAL

The magnetic tape library updating function requires a minimum of two tape drives. The availability of a third drive can reduce all operator interventions. The updating function covers the program adding feature, the program deleting feature, and the program replacing feature, all of which are very similar operations.

## 2-2  UPDATING PROGRAMS TO THE MAGNETIC TAPE LIBRARY

a. The master tape is assumed to be mounted to tape unit 0 with the write enable ring removed. Insert write ring to scratch tape and mount to unit 1. If a third drive is available, insert a write ring to the tape that the new magnetic tape library is to go on and mount to unit 2.

b. Place an update control card in front of each object deck and place an update termination card at the bottom of the deck. See paragraph 3-1 for control card format and description. The deck must be sequenced in the same order that the program names exist on the library tape.

c. Stack the card deck in the card reader and set card reader ready.

d. Type in UPDATE followed by a NL (New Line) character.

e. The cards will be read, and the updating will start. Users with only two tape drives will be alerted to leave the scratch tape on unit 1 and mount a scratch tape (the tape that is to be designated as the new master) on unit 2. To do this, the master must be removed from unit 0. Users with three tape drives will ignore this message.

f. The completion of the updating of programs is indicated by a message informing the operator that the copy portion of update is completed on unit 2.

g. The operator now has the option of verifying the new master tape or of taking the new master without verification. Users wishing to verify the new tape should refer to paragraph 2-7.

## 2-3  ADDING PROGRAMS TO THE MAGNETIC TAPE LIBRARY

a. To add programs to the magnetic tape library, the operator must make certain that the first 38 characters of

the program name being assigned to the program, in the program name field on the control card, are unique. The operator should then follow the instructions in paragraph 2-2 to perform the update. See Sigma 2 for deck set-up.

b. If the operator has any doubts about the name, check all program names by listing them as described in paragraph 1-5.

## 2-4  REPLACING PROGRAMS ON THE MAGNETIC TAPE LIBRARY

a. To replace programs on the magnetic tape library, the operator must make certain that the first 38 characters of the program name, in the program name field of the control card, correspond to the existing name of the program to be replaced. The new revision level letters should reflect a difference of one level. Refer to paragraph 3-5 for a graphic depiction of deck set-up.

b. When the program names have been checked, follow the instructions in paragraph 2-2 to perform the update.

c. If the operator has any doubts about the name, list the program name as described in paragraph 1-5.

## 2-5  DELETING PROGRAMS FROM THE MAGNETIC TAPE LIBRARY

a. Deleting programs from the magnetic tape library does not require object decks behind the control cards as described in step (b) of paragraph 2-2.

b. To delete programs from the magnetic tape library, the operator must make certain that the first 38 characters of the program name, in the program name field of the control card, correspond to the name of the program to be deleted. Refer to paragraph 3-5 for an illustration of deck set-up.

c. Stack the delete control cards, place a termination card at the bottom of the deck and follow the instructions of paragraph 2-2 to perform the update.

d. If the operator has any doubts about the name, list the program name as described in paragraph 1-5.

## 2-6  COPYING THE MAGNETIC TAPE LIBRARY

a. Copying the magnetic tape library is accomplished through the update mechanism and only

⬤quires a termination card to be put in the card reader. Refer to paragraph 3-7 for an illustration of deck set-up.

   b. Follow instructions in paragraph 2-2 to perform the copy.

2-7  VERIFYING THE UPDATED MAGNETIC TAPE
      LIBRARY

   a. After the magnetic tape library addition, deletion and/or copying function is completed, the operator may verify his new master tape.

   b. To verify the updated magnetic tape, leave the new master tape on unit 2. If the user is only using two tape drives, mount the old master tape on unit 0. If three tape drives are available, leave the tapes in the original updating configuration and restack the cards in the hopper.

   c. When the verification is completed, the operator will be notified by a message informing him that update is complete and that he should remove the write ring from the tape on unit 2.

*Copy Tape to Tape !COPY*

Chapter III

CONTROL CARD FORMATS

## 3-1 CARD FORMATS

There are two types of card formats, the updating card
format and the termination card format. Column 1 is the up-
dating control character field. Columns 2 through 39 are the
program name field. Columns 40 through 59 are the revision
letter and date field. Columns 60 is the loader type field.
Column 65 is the diagnostic program monitor field. Columns
70 through 74 are the starting address field.

## 3-2 ADDING AND/OR REPLACING PROGRAM
CONTROL CARD

    a. Column 1 must contain a + (plus).

    b. Columns 2 through 39 must contain the program
name. When adding programs to the magnetic tape library,
the name in this field must be unique from any name cur-
rently on the magnetic tape library. When replacing or
deleting programs on the magnetic tape library, the name
in this field must be identical to an existing name on the
magnetic tape library.

Columns 40 through 59 should contain the letters represent-
ing the program revision level and a date, if desired.

    c. Column 60 must be left blank if the program uses
the meta-symbol loader (Program No. 704356). Column
60 must contain an L if the program uses the CPU format
loader. (Program No. 704029).

    d. Column 65 must be left blank if the program is not
interfaced to the Diagnostic Program Monitor (Program No.
705682). Column 65 must contain an M if the program is
interfaced to Diagnostic Program Monitor.

    e. Columns 70 through 74 must contain the starting
address of the program in hexadecimal.

## 3-3 DELETE PROGRAM CONTROL CARD

    a. Column 1 must contain a - (minus).

    b. Other fields are identical to the description in
paragraph 3-2.

## 3-4 END CARD

    a. All END cards have the same format.

    b. Column 1 must contain an ! (exclamation).

    c. Columns 2 through 39 must contain the magnetic
tape library title.

    d. Columns 40 through 59 must contain the magnetic
tape library revision level and creation date.

This information will become the new title which is printed
on the operator keyboard, KSR, when the magnetic tape
library is loaded.

## 3-5 DECK SET-UP ADDING AND/OR REPLACING
PROGRAMS



## 3-6 DECK SET-UP DELETING PROGRAMS

3-7   DECK SET-UP COPYING PROGRAMS

```
  /! END MTL REV  1/1/70|
  |                      |
  |                      |
  |_____|
```

3-8   MESSAGES

Most messages are self-explanatory. Those messages
which require operator intervention will continue to
print in 30-second intervals until the operator intervenes.
In the cases of card reader errors, the updating can pro-
ceed by taking the card which causes the error and re-
stacking it in the card reader.

# Section 2

# SIGMA 5 - 9
# RELOCATABLE
# DIAGNOSTIC PROGRAM LOADER

## PROGRAM NO. 704356

**Section 2**

## CONTENTS

2

The loader is designed to use a minimum instruction repertoire

Chapter I
PROGRAM OBJECTIVES

## PROGRAM OBJECTIVES

The Sigma 5 through 9 Relocatable Diagnostic Program Loader is designed to use a minimum instruction repertoire and to provide adequate flexibility to the user. The program provides the capability to detect sequence errors, checksum errors, and many input device errors. In addition, the loader protects itself from self destruction. The loader may be used as a subroutine to load additional programs. This is described in the usage section.

### OPERATING REQUIREMENTS AND SPECIFICATIONS

#### Required Equipment

Sigma 5 through 9 with minimum 4K memory. ASR/KSR for message input/output if relocation is desired. Paper tape reader, card reader, or magnetic tape for program input.

#### Loading Procedure

1. Set compute switch to idle.

2. Clear memory by simultaneously pressing CPU/CLEAR and CPU/RESET switches for Sigma 5/6/7 or by pressing the memory clear switch for Sigma 8/9.

3. Set the unit address switches to the address of the desired input peripheral device.

4. Set the watchdog timer switch to halt.

5. Set the interleave switch to the desired position, interleave or diagnostic mode.

6. Set the parity error mode switch to continue.

7. Set clock mode switch to continue.

8. Set the address stop switch to the off position.

9. For Sigma 9 press not normal switch and check for normal indication.

10. Set sense switches for desired options (see program options).

11. Press I/O reset and then load switch.

12. Move compute switch from idle to run.

At this point the program will be loaded according to the sense switch settings.

#### Program Options

Sense Switch 1:
OFF    Loading will complete without waits.

ON    Loading will halt after the loader has been stored in lower core. At this time a prompt message will be output to the ASR/KSR. The prompt messages are:

Message:

Relocation bias for resident loader in hex

Response:

1. (Hex value) N/L – This value will be the starting location of the loader.

2. A N/L with no preceding characters tells the loader to place itself at the top of memory.

3. An EOM specifies that the preceding input should be disregarded.

Message:

Relocation bias for diagnostic program in hex

Response:

1. (Hex value) N/L – This value will be the starting location of the program to be loaded.

2. A N/L with no preceding characters tells the loader to use the bias where the program has assembled.

3. Same as 3. above.

Message:

Alternate input device address

Response:

1. (Hex value) N/L – This is the address that the diagnostic program will be loaded from.

2. A N/L with no preceding characters tells the loader to use the address indicated by the unit address switches.

3. Same as 3. above.

Sense Switch 2:
OFF    Loading will complete without waits.

ON    After loading is complete and just before the loader transfers control to the loaded program, SS2 is checked and the loader comes to a wait with the contents of register 12 pointing to the starting address. Indicated on the end card. Clearing the wait executes a branch indirect on register 12.

## PROGRAM WAITS AND LOOPS

When a wait occurs at location 000F0 or 00149, the ASR/KSR did not respond to device address 1. Store correct address into register 2 and clear wait.

## USAGE

Use as a subroutine to load additional object modules. Register 1 contains the starting location of the loader. This must be saved to communicate with the loader. The contents of the location pointed to by register 1 is the address of table. The contents of table are as follows:

| | | |
|---|---|---|
| Table | 0 | These locations are for |
| Table+1 | 0 | future expansion. |
| Table+2 | Loader Address | These are the values that |
| Table+3 | BA of Loader | are used to protect the loader from self destruction. |
| | | These values may be altered to protect additional memory locations. |
| Table+4 | Teletype Address | The device address used to notify the operator of errors that occur during the load operation. |
| Table+5 | LIA Address | This address is where processing starts. |
| Table+6 | LIC Address | This address contains a NOP and could be used to insert a branch instruction for user interpretation of buffer data, input by the loader. |
| Table+7 | Expr Address | Address of an useful subroutine. |
| Table+8 | FOB Address | Address of an useful subroutine. |
| Table+9 | ENDPROGRAM | First location above loader (Table +2)+(Table +9)=First unused location. (Table+2) +478=Last unused location. |

Other useful locations are:

| | | |
|---|---|---|
| SCNT | Table Address | SCNT is the label that is attached to location indicated by register 1. |
| SCNT+1 | I/O Return Address | When input is done by the user, this is where sequence and checksum checking starts. |
| SCNT+2 | IOCD | IOCD used by the loader SIO. |
| SCNT+3 | * | |

| | |
|---|---|
| SCNT+4 | Address of the loader SIO |
| SCNT+5 | Input Device Address |
| SCNT+6 | Last Memory Address |
| SCNT+7 | Buffer Address used by the loader for input. |

When using the loader as a subroutine, register 11 should contain the address that the loader returns to. If register 11 contains a zero, the loader goes to the address indicated on the end card of the object deck. Register 0 must contain the amount of relocation bias to be added to the object module to be loaded. This value can not be negative. An example would be:

| | | |
|---|---|---|
| LI,0 | RELOCATIONBIAS | |
| LI,1 | LOADERADDRESS | |
| BAL,11 | 8,1 | |
| GO | | The loader will return here. |

Section 3

SIGMA 5 - 9
DIAGNOSTIC PROGRAM
MONITOR (DPM)

PROGRAM NO. 705682

**Section 3**

**CONTENTS**

**SUBJECT MODEL** -- This program is used as the operating monitor program for DPM peripheral test programs. Refer to the individual test programs for further information.

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Input; Output Device: Keyboard Printer or Line Printer. The remote facility is available in systems with more than 16K of memory.

## PROGRAM LOADING INSTRUCTIONS

### From Magnetic Tape Library

- Mount tape on unit 0 (without write-ring) and set its address on the control panel
- Reset all sense switches
  Exception: Set sense switch 1 if the upper core protection is desired
- Execute a LOAD from the control panel:
  1. If sense switch 1 is reset, the loader is loaded to the upper end of memory.
  2. If sense switch 1 is set, the following occurs:
     a. If the keyboard printer is not on IOP 0, device address 1, the program will come to a wait. Enter the correct address into register 2 and clear the wait.
     b. If the keyboard printer is at the standard address or the correct address has been entered, the following three messages will be printed: (Reset sense switch 1 once printing has begun)
        - RELOCATION BIAS FOR RESIDENT LOADER IN HEX; Type in the hexadecimal memory address of the first location the resident loader is to occupy in memory followed by a carriage return. Minimum address is 400 and the maximum address is 1FE00 or maximum memory size less 200.
        - RELOCATION BIAS FOR DIAGNOSTIC PROGRAM IN HEX; DPM programs may not be relocated, therefore type in only a carriage return.
        - ALTERNATE INPUT DEVICE ADDRESS; To continue loading, type in only a carriage return.
        - Loading will continue following the third entry

  A message giving the tape library title and revision letter should be typed out from the keyboard

- Type in the program name desired and a N/L
  1. If a listing of all programs on tape is desired, type: !LIST, ADR, N/L N/L where ADR = output device address in hex. Default is to the keyboard printer.
  2. If the full name cannot be remembered, type in the partial name and a N/L. Complete the partial name by selecting the desired name from the suggested names typed out by program.
- To make a copy of the MTL, mount MTL on unit 0 and execute a LOAD. Mount scratch tape on unit 1 and make ready. Type: !COPY. The MTL tape will be copied to the scratch tape and verified.

### From Card Deck (same for Paper Tape)

- Place card deck in Card Reader and set its address on the control panel
- Reset all sense switches
  Exceptions: Set sense switch 1 if the upper core protection is desired or sense switch 2 if register control

is desired by the keyboard printer (ASR DPM) test, program no. 705651

- Execute a LOAD from the control panel:
  1. If sense switch 1 is reset, no wait will occur unless sense switch 2 is set (see 3.)
  2. If sense switch 1 is set, the following occurs:
     a. If the keyboard printer is not on IOP 0, device address 1, the program will come to a wait. Enter the correct address into register 2 and clear the wait.
     b. If the keyboard printer is at the standard address or the correct address has been entered, the following three messages will be printed: (Reset sense switch 1 once printing has begun)
        - RELOCATION BIAS FOR RESIDENT LOADER IN HEX; Type in the hexadecimal memory address of the first location the resident loader is to occupy in memory, followed by a carriage return. Minimum address is 400 and the maximum address is 1FE00 or maximum memory size less 200.
        - RELOCATION BIAS FOR DIAGNOSTIC PROGRAM IN HEX; DPM programs may not be relocated, therefore type in only a carriage return.
        - ALTERNATE INPUT DEVICE ADDRESS; To continue loading, type in only a carriage return.
        - Loading will continue following the third entry

  3. If sense switch 2 is set, the program comes to a wait:
  - Clear the wait, the program will come to a second wait
  - Enter X'FFFFFFFF' into register 0
  - Reset sense switch 2
  - Clear the wait
  - The test program is automatically loaded (without requiring a "LOAD" directive) and comes to a wait.

  - The KSR/ASR program will operate in register control mode.

  Exceptions: Sense switch 2 option was used or the keyboard is not on IOP 0, device address 001.

     1. If sense switch 2 option was used, "LOAD" directive will automatically be performed
     2. If keyboard is not address 001, the program will come to a wait:
        - Enter IOP and device address of the keyboard into register 2, i.e. X'105'
        - Clear the wait
        - "!" should be typed on keyboard
  - Type in "LOAD" and a "Space Character" if sense switch 2 option was not used. A message giving the program name and revision letter should be typed out

**DIRECTIVES** –directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| *Monitor Directives* | | | | | |
| Message Output Device | MOD, A, IXX | A<br><br>I<br>XX | Device type<br><br>IOP number<br>Device controller address | TY (KSR/ASR)<br>LP (Line Printer)<br>0 ~ IF<br>00 ~ 7F | TY<br><br>0<br>01 |
| Message Input Device | MID, A, IXX | A<br><br><br>I<br>XX | Device type<br><br><br>IOP number<br>Device controller address | TY (KSR/ASR)<br>CR (Card Reader)<br>PR (Paper Tape Reader)<br>0 ~ IF<br>00 ~ 7F | TY<br><br><br>0<br>01 |
| Dump Memory | DMP, H1, H2 [ ,C ] | H1<br>H2<br>C | Starting address<br>Ending address<br>Relative address flag (displacement from the starting address) | 0 ~ FFFFF<br>0 ~ FFFFF<br>C ≠ 0 | <br><br>0 |
| Dump Memory on ASR/KSR | TDMP, H1, H2 [ ,C ] | H1<br>H2<br>C | Starting address<br>Ending address<br>Relative address flag (displacement from the starting address) | 0 ~ FFFFF<br>0 ~ FFFFF<br>C ≠ 0 | <br><br>0 |
| Alter Memory | ALT, H1, X1 [ ,...,XN] | H1<br>X1<br>·<br>·<br>·<br>XN | Memory address<br><br>Values to be inserted into memory starting from H1 | 0 ~ FFFFF<br><br><br><br><br>N ≤ 254 | |
| Load Program (from object deck) | LOAD, [H1] | H1 | Load device address | 0 ~ IFFF | Initial loading device |
| *Program Directives – Environmental Directives* | | | | | |
| System Environment | SYST, D1, D2, H3, H4,...,HN | D1<br>D2<br><br>H3<br>H4<br>·<br>·<br>·<br>HN | Device or controller model number | The 'SYST directive interpretation and value ranges are supplied by the program loaded by the 'LOAD' directive. Refer to the applicable diagnostic program reference manual. Also, the diagnostic program will generally print its 'SYST' format following the 'LOAD' operation. | |
| *Program Directives – Testing Directives* | | | | | |
| Test Directives (used to test a device or to modify test data) | Determined by Diagnostic Program | | Supplied by the Diagnostic Program. Refer to the applicable Diagnostic Program Reference Manual. | | |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal.

(Continued)

**DIRECTIVES** (Continued)

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Monitor Directives (Available Only If Memory Size > 16K). | | | | | |
| These directives simulate PCP control and provide remote troubleshooting facilities. | | | | | |
| Turn On Pseudo Sense Switches | SON [ ,D1, D2, D3, D4] | D1<br>D2<br>D3<br>D4 | Sense switch number<br>Sense switch number<br>Sense switch number<br>Sense switch number | 1 ~ 4<br>1 ~ 4<br>1 ~ 4<br>1 ~ 4 | D1 thru D4<br>=0, display<br>pseudo sense<br>switches |
| Turn Off Pseudo Sense Switches | SOFF [ ,D1, D2, D3, D4] | D1<br>D2<br>D3<br>D4 | Sense switch number<br>Sense switch number<br>Sense switch number<br>Sense switch number | 1 ~ 4<br>1 ~ 4<br>1 ~ 4<br>1 ~ 4 | D1 thru D4<br>=0, display<br>pseudo sense<br>switches |
| Use Real Sense Switches | SSWC | | | | |
| Simulate PCP Reset | RES | | | | |
| Set Address Stop | STOP [ ,H1] | H1 | Stop address | 0 ~ FFFFF | D1 = 0;<br>Remove<br>address stop |
| Continue with next instruction after program wait or address stop (from stop directive) | GO<br>(continue with next location after wait)<br><br>GO1<br>(continue with next location +1 after wait) | | | | |
| Start Program at Location n. | BR, H1 | H1 | Branch address | 0 ~ FFFFF | Note: Registers or flags may not be set up correctly. |
| Allow Remote User to Log On | LOG, A, H2, H3 | A<br><br>H2<br>H3 | 4-character password<br><br>COC address<br>DIO address of COC | Alpha/num characters<br>0 ~ 1F7F<br>0 ~ F | <br><br><br>0 |
| Swap Control Between Controller and Observer | SWAP | | | | |
| Disconnect Remote Users | ROFF | | | | |
| Load Another Program from MTL | BOOT [ ,H1] | H1 | Load device address | 0 ~ 1FFF | Initial loading device |

## LOADER ERROR MESSAGES

| Error Message | Description of Error |
|---|---|
| Sequence Error Job Aborted | The last record read was out of sequence (if reading cards, the deck may be missing a card) and loading has been aborted |
| Checksum Error Job Aborted | The last record read had a checksum error (the input media may be damaged) and loading has been aborted |
| Dev Not Redy | The input device failed to come 'READY' following the last read operation and loading has been aborted |
| Illegal Load ITM | The last record read contained an illegal load item type and loading has been aborted |

1. If any loader error message is printed, loading has been aborted
2. Retry entire loading procedure:
    a. If identical error occurs, obtain a new copy of the program
    b. If loading still fails, check input device for correct operation

## MONITOR ERROR MESSAGES

All monitor error messages are output to the keyboard, KSR, and have the following format:

MONITOR ERROR XXXX  where XXXX is a four-digit
number.

The four-digit error numbers have the following interpretation:

| ERROR NO. | DESCRIPTION OF ERROR |
|---|---|
| 0700 | Illegal address (ALT directive, DMP directive, message print routine) |
| 1000 | Illegal device mnemonic, parameter A1, MOD directive |
| 1100 | Illegal device mnemonic, parameter A1, MID directive |
| 1200 | Illegal character in a hexadecimal parameter |
| 1201 | Illegal character in a decimal parameter |
| 1202 | No termination or continuation character in first 72 characters of a record containing a directive input from a device other than the keyboard/printer |
| 1203 | First character of a continuation line is not an exclamation |
| 1301 | First character of a record is not an exclamation |
| 1302 | Illegal directive |
| 1303 | More parameters indicated for a directive than authorized |
| 1800 | No parameters with SYST directive |

| | |
|---|---|
| 1801 | Diagnostic program does not show the model number specified in a SYST directive that is executed while diagnostic program is loaded |
| 1802 | Context data block in diagnostic program is not long enough |
| 1804 | Context data table in diagnostic program shows zero model numbers to which a context data block applies |
| 2201 | SIO yielded IOP halt |
| 2202 | SIO yielded incorrect length indication |
| 2203 | SIO yielded IOP memory error indication |
| 2204 | SIO yielded memory address error indication |
| 2205 | SIO yielded transmission memory error indication |
| 2206 | SIO yielded transmission data error |
| 2301 | SIO not accepted after maximum delay |
| 2302 | I/O address not recognized |
| 2303 | I/O interrupt fails to reset |
| 2304 | Device not operational |
| 2305 | Controller not operational |
| 2306 | SIO rejected after operational status byte obtained |
| 2307 | Manual mode |

## START PROCEDURE

1. Sense Switch Options

| Sense Switch | Position | Function |
|---|---|---|
| 1 | Reset | Continuous operation, no looping |
| 1 | Set | Loop on failing test or selected test if SSW3 is set |
| 2 | – | Not used * |
| 3 | Reset | Wait on error or successful completion of tests. (Clearing the wait causes looping on the error or selected test. PCP instruction address increment before clearing the wait continues the program without looping.) |
| 3 | Set | No wait after error or successful completion of test. See SSW1 for looping |
| 4 | Reset | Print all message(s) |
| 4 | Set | No message printout except from the monitor |

*Note: Sense switch 2 may be used during the loading of the Diagnostic Program Monitor, see Program Loading Instructions.
2. Monitor Directive Options – Desired Monitor Directive(s) entered
3. Environmental Directives – SYST directive is entered for test environment (Diagnostic Program Dependent)
4. Test Strategy Selection (Diagnostic Program Dependent)
5. Repeat 1, 2 and 4 when the program terminates. Repeat 3 only if system environment is to be changed

## TERMINATION INDICATION

1. Completion of a directive – Control returns to the message input device or loops on an instruction sequence
2. Error indication – Error message printout or looping on an instruction sequence
3. PCP interrupt – Control returns to the message input device and the current operation is aborted
4. Watchdog timer trap – WAIT without message (if no jumper for I/O reset)
   – Looping with message (if no jumper is connected, Sigma 5: 4C17 to 6C15, Sigma 7: 27G21 to Ground)
5. Other traps or interrupts – The following type-out will occur:

    TRAP/INTER = XX    TCC = YYYY    REGSAVE = AAAAAAAA
    PSW1 = TTTTTTTT    PSW2 = RRRRRRRR

    where:  XX          Denotes the trap or interrupt location
           YYYY       Denotes the trap condition codes
           AAAAAAAA   Denotes the location in memory where the register contents at the time of the trap or interrupt are stored
        TTTTTTTT and RRRRRRRR are the contents of the Program Status Doubleword saved by the LPSD instruction executed as a result of the Trap or Interrupt

    a. Memory Fault Trap or Interrupt only – The program will
       Type-Out: (Sigma 8 and 9 only)
         MSW0 = WWWWWW   MSW1 = EEEEEE   MSW2 = RRRRRR
       Giving the status of the faulted memory
    b. Processor Fault Interrupt only – The program will type-out:(Sigma 8 and 9 only)
       PROC. NO.   SS   F/STAT = C
       Giving the faulted processor address and the fault status

## RESTART PROCEDURE

1. Perform applicable steps under Start Procedure
2. Depress System or CPU reset switches and return the system to a RUN condition. Control returns to the message input device and the current operation (if any) is aborted
3. PCP Interrupt – Control returns to the message input device and the current operation (if any) is aborted
4. If program fails to restart correctly, reload the program

## REMOTE FACILITY

### Control

To allow a remote user to log on, the controller must use the directive !LOG. The parameters contain the password, the COC address, and the DIO Address (0 – F) e.g., !LOG, DIAG, 5, 1

Upon receipt of this directive, the COC will be activated and all lines scanned for input. If (and when) a connect signal is received, a log in message is sent to that line. The valid reply to the log in message is password. If the password is received, that teletype becomes the observer and all other lines are ignored. The controller is informed when the user has logged on.

To transfer control from the controller to the observer, the controller must use the directive !SWAP. There are no parameters for the directive.

To disconnect the COC and the remote user, the local user when he is the controller can issue the directive !ROFF. No parameters are required.

If the program detects that the remote user is "lost" due to some malfunction, the program continues with the local user as the controller even if the remote user was controller; and the COC is set up ready to reconnect the remote user equivalent to its state following a !LOG directive.

If the local ASR/KSR is "lost" due to a malfunction, the program will "WAIT".

### Directive Mode

In directive mode the controller is issuing a directive to the system. The observer obtains a copy of the directive but cannot communicate with the system or the controller.

The system is in directive mode when:

    a.    The DPM has typed out a ! and is awaiting input.
    b.    The system was running and the controller types in a !.
    c.    The local user, if controller, stops output with break key.
    d.    The remote user, if controller, stops output with the ! or escape key.

The system is not running when in directive mode.

If the local user is the controller, the local ASR/KSR is in input mode and characters input are passed to the system for use as the directive and any associated parameters. The input is copied to the remote user. Input from the remote user is ignored except as outlined under Message Mode.

If the remote user is the controller, characters from this device are used as the directive and its associated parameters. All characters input are echoed to the device and copied to the local ASR/KSR. Input from the remote user is ignored except as outlined under Message Mode.

Directives are terminated by any character other than:
                 A – Z 0 – 9, ; – ( )!

### Message Mode

In message mode, the two users can communicate with each other via their respective teletype devices. The characters are passed from one to the other and do not effect the system operation.

The system is in message mode when:

    a.    The program is running.
    b.    The system entered directive mode and the controller has not input any characters.
    c.    The system was in directive mode and the controller types in a (. This condition continues until the controller types in a ) or a !.

Characters from the remote user are echoed to the device and copied to the local ASR/KSR.

Input from the local ASR/KSR is copied to the remote user. The local ASR/KSR is input mode at all times unless chracters need to be output to it.

If the local user is the controller and the device is not in input mode because of output the user can obtain control by the procedure described under System Output.

### System Output

System output is sent to both the local ASR/KSR and the remote user.

Input other than a !, escape, or NUL character from the remote user is ignored.

Output can be stopped by the controller in two different ways.

    a.    Output of a single message line can be terminated by the controller hitting the NUL key if he is the remote user or depressing the break key from .1 to .9 seconds if he is the local user.
    b.    Output can be terminated and the DPM forced into directive mode by the controller hitting the ! or escape key if he is the remote user or depressing the break key for more than 1 second if he is the local user.

## PCP FACILITY

### Sense Switches

Real sense switches – these are the hardware sense switches on the PCP which are switched manually and their position can be found by a read direct instruction.

Pseudo sense switches – these are four positions in a defined memory location. If the bit is a one, the switch is on. Directives are available to change the settings.

After loading, if no information is received from the magnetic tape library control program about pseudo sense switches, and until (if ever) a directive is used to adjust the pseudo sense switches, the real sense switches control the program.

Following a directive to set/reset one or more of the pseudo sense switches, the pseudo sense switches control the program. A directive allows the system to switch back to using the real sense switches.

If the magnetic tape library control program informs the DPM that the pseudo sense switches are in use, then the settings will be used as received and pseudo switches will control the program until the !SSWC (see below) directive is used.

The pseudo sense switch directives are:

> For turning switches on:
>    !SON, $n_1, n_2, n_3, n_4$
>
> For turning switches off:
>    !SOFF, $n_1, n_2, n_3, n_4$

Any number of parameters up to a maximum of four can be used and the values must be in the range 1 to 4.

> e.g.,     !SON,3          Turns on pseudo sense switch 3
>           !SOFF,4,1       Turns off pseudo sense switch 4 and 1.

If the first pseudo sense switch directive used following the use of the real sense switches does not change all four switches, the state of the others are copied from the corresponding real switches.

Following a pseudo sense switch directive the state of all the switches are shown, e.g., assume that real switches are 0101, and this is the first pseudo sense switch directive.

>        !SON,1
>        !!SW1234
>        !!  1101

If no parameters are given, no switches are set or reset but a printout of the current positions occurs.

A type-in of either:
>                !SON or !SOFF
results in a type-out of:
>        !!SW1234
>        !!  0101

To revert to the use of real sense switches the directive !SSWC is used, no parameters are required.

### WAIT Instructions

Because WAIT instructions cannot be observed or cleared from a remote location they will be eliminated as far as possible from the system.

A WAIT instruction in the last program is replaced by a call to a subroutine in the DPM. The routine will type a message and then give the user control, e.g.,

|        |       |                        |
|--------|-------|------------------------|
| BAL,15 | :WAIT | (address via MLT+43)   |
| DATA   | MESS1 | ADDRESS OF MESSAGE     |

The controller can use the !ALT directive to adjust any locations required and use the !GO or !GO1 directives described below to continue the program.

The only situations which still require PCP control are:

1. If after loading, an ASR/KSR cannot be found  –  a WAIT is performed and the user puts a valid ASR/KSR address in register 2.
2. If I/O to the ASR/KSR cannot be performed the program will WAIT.
3. If a manual reset is required after a trap  -  the program hangs.
4. If the local user depressed control panel interrupt switch to gain control of the program.

### PCP FACILITY (Continued)

#### Address Stop Function

A directive is implemented to simulate the address stop feature of the PCP.

To set an address stop the controller uses the !STOP directive. The parameter is the address at which the program should stop, e.g.,

!STOP,2FE.

This directive will cause an XPSD to be placed into the address specified. If the XPSD is executed, a type out of the saved PSW1, PSW2 and the address of a stack containing the saved PSW1, PSW2 and all the registers (0-15) will occur and the user obtains control. The PCP will not reflect the saved machine state.

The user may change the saved PSW1, PSW2 and registers by use of the !ALT directive. The layout of the stack will be:

|  |  |
|---|---|
| ADDRESS PRINTED | REGISTER 0 |
|  | REGISTER 1 |
|  | . |
|  | . |
|  | . |
|  | REGISTER 15 |
|  | PSW1 |
|  | PSW2 |

and the address of register zero will be on a 16 word boundary.

The controller can continue the program with the replaced instruction, or with the new environment if he has changed any of the saved values, by using the !GO directive.

A second !STOP directive with a new address causes the initial instruction to be replaced at its correct address and the XPSD to replace the instruction at the address specified.

A !STOP directive without an address causes the XPSD to be removed and the location replaced with its valid instruction; i.e., the address stop is removed.

#### Reset Function

A directive is implemented to simulate a reset from the PCP. A reset from PCP is performed by:

    a.    Hitting the interrupt button.
    b.    Putting the CPU into IDLE, hitting reset, and putting CPU to RUN.

This function can be simulated by the controller using the !RES directive. No parameters are required.

A reset does not disconnect the remote user. In all cases the DPM will remember if there was a remote user. Control after a reset will revert to the controller.

#### Continue Function

Two directives are implemented to work in conjunction with the !STOP directive, the programmed WAIT instruction and to simulate the RUN/IDLE switch on the PCP. When the program has stopped running because:

    a.    It arrived at the simulated stop address.
    b.    It arrived at the :WAIT subroutine.
    c.    The controller typed in an ! character or stopped output via break key.

The program can be continued correctly at the next "logical" instruction by using the !GO directive. No parameters are required. The next "logical" instruction is defined in the three cases above as:

    a.    The instruction which was replaced by the XPSD, or the new environment if the user altered PSW1, PSW2 and/or any of the saved registers.

    b.    The instruction which presently follows the WAIT instruction.

    c.    The next instruction in the main line code which would have been executed if the system had not switched to directive mode. There will be a loss of output if break key stopped output. A continuation of the test (with GO directive) may lead to error printouts.

At present following a WAIT associated with the sense switch routine the user either clears the WAIT and continues at the next instruction, or he increases the Instruction Register by 1 and then continues. The !GO directive simulates the former action and another new directive !GO1 will simulate the latter action.

**PCP FACILITY** (Continued)

Between the time the program stops running and the issuance of the !GO or !GO1 directives the user may issue any of the following directives:

    !LOG, !SON, !SOFF, !SSWC, !STOP, !MID, !MOD, !DMP, !ALT, !TDMP

If any other directives are issued the DPM will "forget" the "place to go", e.g.,

        SYSTEM RUNNING
        !DMP        (DPM remembers next logical instruction)
        !ALT
        !SON
        !GO
        System restart at next logical instruction
        SYSTEM RUNNING
        !SON        (DPM remembers next logical instruction)
        !TST1
        System restarts with Test 1 and forgets the logical instruction address.

Branch Function

A new directive is implemented to allow the controller to branch to any location he requires. The directive requires one parameter:

    !BR,2FE.

The directive is intended to allow the user to depart from the normal diagnostic program procedure. Having taken the branch there is no guarantee that the program will perform according to the specification. The directive must be used with caution.
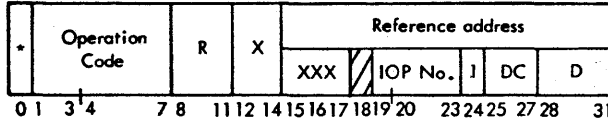
## COMMAND DOUBLEWORD FORMAT

## INPUT/OUTPUT INSTRUCTIONS

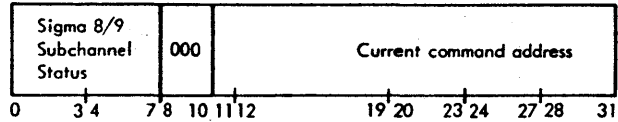### I/O ADDRESS                                    I/O STATUS RESPONSE

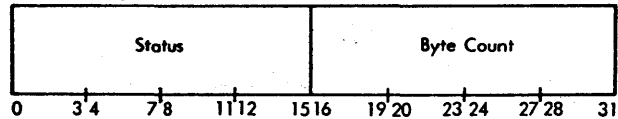SIO, HIO, TIO, AND TDV

Multiunit device controllers (bit 24 is 1)

| * | Operation Code | R | X | Reference address | | | | | |
|---|---|---|---|---|---|---|---|---|---|
| | | | | XXX | IOP No. | J | DC | D |

0 1    3 4    7 8    11 12  14 15 16 17 18 19 20    23 24 25  27 28    31

Sigma 8/9 systems only
000 = HIO
001 = RIO
010 = POLP
011 = POLR

Word into register R

| Sigma 8/9 Subchannel Status | 000 | Current command address |
|---|---|---|

0    3 4    7 8  10 11 12    19 20    23 24    27 28    31

Word into register Ru1

| Status | Byte Count |
|---|---|

0    3 4    7 8    11 12    15 16    19 20    23 24    27 28    31

AIO

| * | 6E | R | X | Reference address | | |
|---|---|---|---|---|---|---|
| | | | | ///// | 0  0000 | ///// |

0 1    3 4    7 8    11 12  14 15 16    18 19 20    23 24    27 28    31

| Status | 000 | I/O address |
|---|---|---|

0    3 4    7 8    11 12    15 16 18 19 20    23 24    27 28    31

## GENERAL CONDITION CODES

Note: These condition codes apply to most devices but they may differ. Refer to the individual device reference manual for correct condition code.

The condition code settings are:

**1  2  3* 4   Result of SIO**

0  0  –  –   I/O address recognized and SIO accepted

0  1  –  –   I/O address recognized but SIO not accepted

1  0  –  –   device controller is attached to a "busy" selector IOP or Sigma 8/9 MIOP operating in Burst Mode

1  1  –  –   I/O address not recognized

**1  2  3* 4   Result of TIO**

0  0  –  –   I/O address recognized and acceptable SIO is currently possible

0  1  –  –   I/O address recognized but acceptable SIO is not currently possible

1  0  –  –   device controller is attached to "busy" selector IOP or Sigma 8/9 MIOP operating in Burst Mode

1  1  –  –   I/O address not recognized

**1  2  3* 4   Result of HIO**

0  0  –  –   I/O address recognized and device controller is not "busy"

0  1  –  –   I/O address recognized but device controller was "busy" at the time of the halt

1  1  –  –   I/O address not recognized

**1  2  3  4   Result of RIO (Sigma 8/9 only)**

0  0  –  –   I/O address recognized

1  1  –  –   I/O address not recognized

**1  2  3  4   Result of POLP or POLR (Sigma 8/9 only)**

0  0  –  –   processor fault interrupt not pending

0  1  –  –   processor fault interrupt pending

1  1  –  –   processor address not recognized

**1  2  3* 4   Result of TDV**

0  0  –  –   I/O address recognized

0  1  –  –   I/O address recognized and device-dependent condition is present

1  0  –  –   device controller is attached to "busy" selector IOP or Sigma 8/9 MIOP operating in Burst Mode

1  1  –  –   I/O address not recognized

**1  2  3* 4   Result of AIO**

0  0  –  –   normal interrupt recognition

0  1  –  –   previous operations ended with unusual end or transmission error

1  0  –  –   AIO is accepted

1  1  –  –   no interrupt recognition

*On Sigma 8/9 systems only
CC 3 = 0  Status information in general registers is correct
CC 3 = 1  Status information in general registers is incorrect

## STATUS BITS FOR I/O INSTRUCTIONS

### Position and State in Register Ru1

| Device Status Byte | | Operational Status Byte * | | Significance for SIO, HIO, and TIO | Significance for TDV |
|---|---|---|---|---|---|
| 0 1 2 3 | 4 5 6 7 | 8 9 10 11 | 12 13 14 15 | | |
| 1 - - - | - - - - | - - - - | - - - - | Dev Interrupt Pending | * |
| - 0 0 - | - - - - | - - - - | - - - - | Dev Ready | * |
| - 0 1 - | - - - - | - - - - | - - - - | Dev Not Oper | * |
| - 1 0 - | - - - - | - - - - | - - - - | Dev Unavailable | * |
| - 1 1 - | - - - - | - - - - | - - - - | Dev Busy | * |
| - - - 0 | - - - - | - - - - | - - - - | Dev Manual | Unique |
| - - - 1 | - - - - | - - - - | - - - - | Dev Automatic | to the device |
| - - - - | 1 - - - | - - - - | - - - - | Dev Unusual End | and the |
| - - - - | - 0 0 - | - - - - | - - - - | Dev Cntr Ready | device |
| - - - - | - 0 1 - | - - - - | - - - - | Dev Cntr Not Oper | cntr |
| - - - - | - 1 0 - | - - - - | - - - - | Dev Cntr Unavail | * |
| - - - - | - 1 1 - | - - - - | - - - - | Dev Cntr Busy | * |
| - - - - | - - - 0 | - - - - | - - - - | Unassigned | * |
| - - - - | - - - - | 1 - - - | - - - - | Incorrect Length | * |
| - - - - | - - - - | - 1 - - | - - - - | Trans Data Error | * |
| - - - - | - - - - | - - 1 - | - - - - | Trans Mem Error | Same |
| - - - - | - - - - | - - - 1 | - - - - | Mem Addr Error | as for SIO, |
| - - - - | - - - - | - - - - | 1 - - - | IOP Mem Error | HIO, |
| - - - - | - - - - | - - - - | - 1 - - | IOP Contl Error | TIO |
| - - - - | - - - - | - - - - | - - 1 - | IOP Halt | * |
| - - - - | - - - - | - - - - | - - - 1 | Selector IOP Busy | * |

### Position and State in Register R

| Device Status Byte | | Operational Status Byte * | | Significance for AIO |
|---|---|---|---|---|
| 0 1 2 3 | 4 5 6 7 | 8 9 10 11 | 12 13 14 15 | |
| 1 - - - | - - - - | - - - - | - - - - | * |
| - 1 - - | - - - - | - - - - | - - - - | * |
| - - 1 - | - - - - | - - - - | - - - - | * |
| - - - 1 | - - - - | - - - - | - - - - | * |
| - - - - | - - - - | - - - - | - - - - | Unique to the device and device controller |
| - - - - | 1 - - - | - - - - | - - - - | * |
| - - - - | - 1 - - | - - - - | - - - - | * |
| - - - - | - - 1 - | - - - - | - - - - | * |
| - - - - | - - - 1 | - - - - | - - - - | * |
| - - - - | - - - - | 1 - - - | - - - - | Incorrect Length |
| - - - - | - - - - | - 1 - - | - - - - | Trans Data Error |
| - - - - | - - - - | - - 1 - | - - - - | Zero BC Interrupt |
| - - - - | - - - - | - - - 1 | - - - - | Channel End Intrpt |
| - - - - | - - - - | - - - - | 1 - - - | Unusual End Intrpt |
| - - - - | - - - - | - - - - | - 0 - - | Unassigned |
| - - - - | - - - - | - - - - | - - 0 - | Unassigned |
| - - - - | - - - - | - - - - | - - - 0 | Unassigned |

### MONITOR LINK TABLE (MLT)

The MLT table allows the interfaced diagnostic program access to subroutines with the DPM and allows for data/information exchange between the DPM and the interfaced program.

| Name | Definition | Program Location | Core Location |
|---|---|---|---|
| MLT | Absolute program recovery address | MLT+0 | X'200' |
| MLT01 | Parameter 1 | MLT+1 | X'201' |
| MLT02 | Parameter 2 | MLT+2 | X'202' |
| MLT03 | Parameter 3 | MLT+3 | X'203' |
| MLT04 | Parameter 4 | MLT+4 | X'204' |
| MLT05 | Unassigned | MLT+5 | X'205' |
| . | | . | . |
| MLT12 | | MLT+12 | X'20C' |
| MLT13 | Temporary ASR mode flag | MLT+13 | X'20D' |
| MLT14 | Unassigned | MLT+14 | X'20E' |
| MLT15 | 'DMP' directive routine call location for interfaced programs | MLT+15 | X'20F' |
| MLT16 | DPM Reentry | MLT+16 | X'210' |
| MLT17 | Parameter status word | MLT+17 | X'211' |
| MLT18 | Unassigned | MLT+18 | X'212' |
| MLT19 | Binary coded decimal (BCD) to binary, conversion subroutine interface location | MLT+19 | X'213' |
| MLT20 | Directive return address — returns control to the DPM | MLT+20 | X'214' |
| MLT21 | Unassigned | MLT+21 | X'215' |
| MLT22 | Binary to EBCDIC conversion subroutine interface location | MLT+22 | X'216' |
| MLT23 | Decimal to EBCDIC conversion subroutine interface location | MLT+23 | X'217' |
| MLT24 | Hexadecimal to EBCDIC conversion subroutine interface location | MLT+24 | X'218' |
| MLT25 | One-byte input subroutine interface location | MLT+25 | X'219' |
| MLT26 | Current character counter for one-byte input routine | MLT+26 | X'21A' |
| MLT27 | Error report subroutine interface location | MLT+27 | X'21B' |
| MLT28 | Message print subroutine interface location | MLT+28 | X'21C' |
| MLT29 | Sense switch check subroutine interface location | MLT+29 | X'21D' |
| MLT30 | 'WAIT' instruction, after I/O failure of 'MOD/MID' device | MLT+30 | X'21E' |
| MLT31 | Branch instruction — retry after I/O failure | MLT+31 | X'21F' |
| MLT32 | I/O address of current 'MOD' device (branch instruction) | MLT+32 | X'220' |
| MLT33 | I/O address of current 'MID' device | MLT+33 | X'221' |
| MLT34 | I/O address of initial loading device | MLT+34 | X'222' |
| MLT35 | Teletype print routine location | MLT+35 | X'223' |
| MLT36 | I/O address of default 'MOD/MID' device | MLT+36 | X'224' |
| MLT37 | Computer type code storage, 0 = Sigma 5/7, 9 = Sigma 8/9 | MLT+37 | X'225' |
| MLT38 | Relocation bias of DPM program | MLT+38 | X'226' |
| MLT39 | Resident loader base address | MLT+39 | X'227' |

(Continued)

## MONITOR LINK TABLE (MLT) (Continued)

| Name | Definition | Memory Location | |
|------|------------|-----------------|---|
| | | Program Location | Core Location |
| MLT40 | Unassigned | MLT+40 | X'228' |
| MLT41 | Parameter error report subroutine interface location | MLT+41 | X'229' |
| MLT42 | Quick sense routine address | MLT+42 | X'22A' |
| MLT43 | Wait routine address | MLT+43 | X'22B' |
| MLT44 | DPM directive dictionary base address | MLT+44 | X'22C' |
| MLT45 | Length of DPM directive dictionary | MLT+45 | X'22D' |
| MLT46 | Address of last memory location | MLT+46 | X'22E' |
| MLT47 | Address of last memory location interfaced program may use | MLT+47 | X'22F' |
| MLT48 | Base address of 120 byte input buffer | MLT+48 | X'230' |
| MLT49 | Base address of 40 word parameter input buffer | MLT+49 | X'231' |
| MLT50 | 'LOAD' directive memory location | MLT+50 | X'232' |
| MLT51 | Input routine address | MLT+51 | X'233' |
| MLT52 | Output routine address | MLT+52 | X'234' |
| MLT53 | Error routine address for DPM IO errors | MLT+53 | X'235' |
| MLT54 | Directive preprocessor | MLT+54 | X'236' |
| MLT55 . . . MLT63 | Unassigned | MLT+55 . . . MLT+63 | X'237' . . . X'23F' |

## PROGRAM INTERFACE TABLE (PIT)

The PIT table is established by the user program at 'LOAD' time and provides the DPM with information describing the user diagnostic program.

| Name | Definition | Program Location | Core Location |
|---|---|---|---|
| PIT | Unassigned | PIT+0 | X'300' |
| PIT01 | Address of the user program's title message | PIT+1 | X'301' |
| PIT02 | Address of the user program's directive dictionary | PIT+2 | X'302' |
| PIT03 | The count of the number of words in the user program's directive dictionary | PIT+3 | X'303' |
| PIT04 | Address of the user program's absolute recovery routine | PIT+4 | X'304' |
| PIT05 | Address of the user program's context description table | PIT+5 | X'305' |
| PIT06 | The count of the number of words in the user program's context description table | PIT+6 | X'306' |
| PIT07 | Unassigned | PIT+7 | X'307' |
| PIT08 | Address of the user program's initializer routine | PIT+8 | X'308' |
| PIT09 | Contains the last device model number input via 'SYST' directive transferred to a context data block | PIT+9 | X'309' |
| PIT10 | Specifies the number of the faulty parameter in a parameter error message | PIT+10 | X'30A' |
| PIT11 | The DPM stores a zero in PIT11 prior to branching to the user program's initialization routine. If this location is non zero upon returning to the DPM, the contents are assumed to be a message address and the message is printed | PIT+11 | X'30B' |
| PIT12 | The user program's RUN switch. This location must be non zero to execute a user directive. If zero when a user directive is called, the error mesage: 'ENTER SYST DIRECTIVE' is printed | PIT+12 | X'30C' |
| PIT13 PIT14 | Unassigned | PIT+13 PIT+14 | X'30D' X'30E' |
| PIT15 | Address of the user program's trap and fault interrupt handling routine | PIT+15 | X'30F' |
| PIT16 . . . PIT31 | Unassigned | PIT+16 . . . PIT+31 | X'310' . . . X'31F' |

# Section 4

# SIGMA 5 - 9
# KEYBOARD PRINTER (ASR/KSR)

## PROGRAM NO. 705651

**Section 4**

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**SUBJECT MODEL** -- KSR, Model number 7012, ASR, Model number 7020

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 8K: Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit: Output Device: Keyboard Printer or Line Printer

## PROGRAM PREREQUISITES

If the keyboard printer is inoperative, register mode of operation must be selected at program load time.

The ASR punch tests require blank paper tape and the reader tests require prepunched paper tape from the corresponding punch test.

## GENERAL OPERATING PROCEDURES

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

The following additional operating procedures are unique to this program.  See also START PROCEDURE.

### Program Loading Instructions

If the message input/message output device is the device to be tested, the method of loading is determined by the operational state of the KSR/ASR.

### KSR/ASR Operational

The test program can be loaded either from cards or MTL using normal loading procedures.  (Sense switch 2 must be OFF if loaded from cards.)
Program/User communication is via the message input/message output device (operation mode 1).

### KSR/ASR Not Operational

The test program can be loaded only from cards.  Since the KSR/ASR is not available for program/user communication, a procedure is established to automatically load the test program and to control the program via registers.

- Set sense switch 2 to ON position.
- Boot in loader.  The deck consists of:

        Loader
        Relocation Card
        DPM
        ASR/KSR test program
- Clear first wait.
- On second wait enter a  -1 in register 0 and clear wait.
- The DPM and the ASR/KSR test program are loaded.
- Test program defaults to register communication mode (operation mode 0).

### Operation Modes

#### Mode 0

In mode 0 operation, all program-operator communication is accomplished using the PCP general registers for directive input and message output. This mode is normally used when the ASR (or KSR) under diagnosis is the only message device available in the system and the device cannot be relied upon for error-free communication with the program.  Test directives 'TST0', 'TST1' and 'TST2' can be invoked in the operating mode. Messages and error number messages appear in a general register.

#### Mode 1

In mode 1 operation, program-operator communication is accomplished using the input/output device(s) specified by the operator (refer to DPM directives 'MID' and 'MOD').  Also, pertinent status and data information is available in the general registers (this is due to the duality of the program).

#### Changing of Operation Modes:

If the program operation mode is to be changed from mode 0 to mode 1, press PCP reset switch and go to RUN.  The program will type a 1.

To change from mode 1 to mode 0, enter SYST directive with parameter 4 = 0.

**DIRECTIVES** – directives are entered after a " ! " is typed out when operating in mode 1.

See START PROCEDURE for entering directives via general registers when operating in mode 0.

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives | | | | | |
| System Environment | SYST, D1, H2, H3, H4 | D1<br><br>H2<br>H3<br>H4 | Device model number<br><br>Revision number<br>IOP and device address<br>Operation mode | 7012 KSR<br>7020 ASR<br><br>0 – 1FFF<br>0 = Mode 0 register communication<br>1 = Mode 1 MID/MOD communication | |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (all functional tests 1 – 13, and random tests 1 – 2) | TST0 | | | | |
| Functional Test | TST1 | D1<br>D2 | First subtest to be executed<br>Last subtest to be executed<br>D1, D2 = 0<br>0 < D1 ≤ D2 ≤ 13 | 1 – 13<br>1 – 13<br><br>all subtests | 0<br>0 |
| Random Exerciser Test | TST2 | D1<br>D2 | First test to be executed<br>Last test to be executed<br>0 < D1 ≤ D2 ≤ 2 | 1 – 2<br>1 – 2 | 0<br>0 |
| Utility Test | TST3, D1, D2 | D1<br>D2<br>D1=1<br><br>D1=2<br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br>D1=3 | Utility test selection<br>Function selection<br>Printer character spacing<br>D2 – not used<br>Paper tape punch/read/verify<br>D2 = 1 Punch a preselected pattern with 20 byte leader<br>D2 = 2 Punch a preselected pattern without leader<br>D2 = 3 Read paper tape ignoring leader<br>D2 = 4 Read paper tape immediate<br>D2 = 5 Read paper tape (ignoring leader) and verify with preselected pattern.<br>D2 = 6 Read paper tape (immediate) and verify with preselected pattern<br>Mechanical print check test<br>D2 – not used | | |

**DIRECTIVES** (Continued)

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Optional Directives |
| Pattern Selection (for Utility Test TST3,2) | DATA, D1, H2, H3 | D1<br><br><br><br>H2<br>H3 | = 0, Fixed pattern<br>= 1, Incremental pattern<br>= 2, Random pattern<br>= 4, Paper tape pattern<br>Pattern seed (for D1 = 0, 1, 2)<br>Incrementing constant (for D = 1) | 0 – 4<br><br><br><br>00000000<br>FFFFFFFF | |
| Length of Record Selection (for Utility Test TST3,2) | LEN, D1 | D1 | Length of record in bytes (Must be a multiple of 4) | Min. = 4<br>Max. = 1600 | |
| Pass Control and Pass Count Printout for TST0,2,3 | LIMT, D1, D2, D3 | D1<br>D2<br><br>D3 | = 2 Effect pass control only<br>Number of passes after which pass count is to be printed out.<br>Total number of passes to be completed. | 2<br>D2 ≥ 0<br><br>D3 ≥ 0 | |

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Test Printer, Paper Tape Reader/Punch |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT | LIMT | LIMT | LIMT, DATA, LEN |
| Subtests | All functional subtests (1–13) and random exerciser tests | 13 subtests (see error messages for the test types) | Print; punch and read paper tape | Print; punch and read paper tape |
| Error Message Format (from MOD or general register) | 1. ERROR NO. DDDD LOC XXXX<br>2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

3. Start/Restart Procedures (unique to this program)

   **START:**

   Mode 0 – After the program is successfully loaded, the program comes to a wait condition with message #1 in general register 1 (X'80000001'). The user may then input into register 0 the desired test directive in the following format:

   > Byte 0  –  Test number
   >              0 = TST0
   >              1 = TST1
   >              2 = TST2
   > Byte 1  –  Must be 0
   > Byte 2  –  Starting subtest number (in hex)
   > Byte 3  –  Ending subtest number (in hex)

   Clearing the wait causes the test to begin.

   Mode 1 – After the program is successfully loaded and the program identification is printed, the operator may specify any test directive(s) (using the message input device).

   Unless a 'SYST' directive is entered, the program assumes (by default) model 7012 (KSR), device address X'01' and mode 0 operation.

   **RESTART :**

   Mode 0 – The PCP interrupt switch, when depressed, causes the program to request a directive be entered into register 0. The PCP system reset switch, when depressed, causes the program to re-initialize and request a directive input from the last declared message input device. In this manner, the conversion from mode 0 to mode 1 may be accomplished, as the operator may then enter a 'SYST' directive specifying mode 1 operation.

   Mode 1 – Both the PCP interrupt and system reset switch, when depressed, causes the program to re-initialize and request a directive input from the last declared message input device.

   **TERMINATION PROCEDURE:**

   The completion of a test or subtest is indicated by the directive input request message #1 (mode 0) or by the message input device's request for a directive.

   **SUCCESS-FAILURE INDICATIONS:**

   **WAITS:**

   The program comes to a wait condition:

   1. During an error message report (SSW3=0).
   2. After a test completion (SSW3=0).
   3. During a message requesting future operator intervention.
   4. If the device address was not recognized, the wrong address will be found in register 2. To continue, enter the new device address in register 2 and clear the wait.

   **LOOPS:**

   The program loops on an instruction sequence producing an error or loops on a test or subtest (SSW1=1 or SSW3=0).

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the ASR/KSR test program.

TST0

The directive selects the comprehensive test consisting of the functional tests (subtests 1-13) and the random exerciser (subtests 1-2).

TST1

The test descriptions of each functional test are included at the beginning of each subtest error number in the Functional Subtest and Related Error Message section.

TST2

The random exerciser operates the device in a random manner in order to detect intermittent logic failures.  The random exerciser consists of 2 subtests, each subtest independently selectable.  Punching and reading portions of the random exerciser test are automatically bipassed if the KSR is under test.

Subtest 1  -  Print ripple pattern,punch random paper tape.
Subtest 2  -  Read and verify the random paper tape.

TST3

This directive selects one of the following utility tests.

TST3,1      Character spacing adjustment and ribbon shift option test
            A set of 12 pre-determined characters is printed to aid in keyboard printer character spacing adjustments.  The ribbon shift option
            is checked by sending shift-out and printing the first 6 character lines in red then sending shift-in and printing the second 6
            character lines in black.

TST3,2      Paper tape punch/reader tests
            The DATA and LEN directives are available to specify the pattern and record length respectively.

TST3,2,1    Paper tape punch with leader
            A paper tape is punched with a 20-byte leader.  The punched pattern is selected by the 'DATA' directive.
            The punched pattern length is selected by the 'LEN' directive.

TST3,2,2    Paper tape punch
            A paper tape is punched (without leader).  The pattern and length are selected by the 'DATA' and 'LEN' directives, respectively.

TST3,2,3    Paper tape read ignoring leader
            A paper tape is read (ignoring leader).  The length is selected by the 'LEN' directive.

TST3,2,4    Paper tape read immediate
            A paper tape is read (immediate).  The length is selected by the 'LEN' directive.

TST3,2,5    Paper tape read and verify
            A paper tape is read (ignoring leader) and verified.  The length is selected by the 'LEN' directive and the pattern used for
            verification is selected by the 'DATA' directive.

TST3,2,6    Paper tape read immediate and verify
            A paper tape is read (immediate) and verified.  The length is selected by the 'LEN' directive and the pattern used for verification
            is selected by the 'DATA' directive.

TST3,3      Mechanical print check test
            A 40 line pattern is printed to verify the mechanical alignment of the printer.

## ORDER CODES

| | | Applicable Devices | |
|---|---|---|---|
| | | KSR | ASR |
| X'00' | Stop | - | 1 |
| X'01' | Punch | - | 1 |
| X'02' | Read | - | 1 |
| X'05' | Type | 1 | 1 |
| X'06' | Read keyboard continuously until EOM character is typed or "count done" signal | 1 | 1 |
| X'82' | Read immediate | - | 1 |
| X'86' | Read keyboard until control character [codes 05 (HT), 08 (EOM), or 15 (NL)] is typed or "count done" signal | 1 | 1 |

**TDV STATUS**

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7012 | ←———————————————— NOT USED ————————————————→ | | | | | | | |
| 7020 | ←——— NOT USED ———→ | | | Read Manual | Unit Off–Line | ←——— NOT USED ———→ | | |

**AIO STATUS**

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7012 | ←———————————————— NOT USED ————————————————→ | | | | | | | |
| 7020 | ←———————————————— NOT USED ————————————————→ | | | | | | | |

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES

### MESSAGE PRINTOUT

Mode 0   During mode 0 operation, program messages have the follow-
ing format in register 0:
    (REG 0) = X'800000DD' where DD = message number
                 defined under register operation messages.

The error messages have the following format in register 0:
    (REG 0) = X'C000DDDD' where DDDD = error number
                 defined in the fault index.

Mode 1   During mode 1 operation, the standard error messages have
the following format:
    ERR NO.DDDD LOC.XXXX where DDDD=error message
         number defined in the fault dictionary and XXXX is
         the listing location where the error was detected.

### REGISTER OPERATION (MODE 0) MESSAGES

Register Operation Messages:

| | |
|---|---|
| 0001 | Enter a test directive into register 0. Clear wait. |
| 0003 | Enter one or two failing characters (in EBCDIC) into Reg 0 (bytes 2 and 3) and clear wait. If no failing character(s), depress the PCP instr addr increment switch and clear wait. |
| 0004 | Echo test 1 is to begin. Clear wait. |
| 0005 | Echo test 2 is to begin. Clear wait. |
| 0006 | Echo test 3 is to begin. Clear wait. |
| 0007 | Insert punched paper tape into reader. |

### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest
and a list of associated error numbers with a brief description of each
error. The subtests and error numbers are arranged in ascending
sequence. The description of subtest NN is numbered NN00. The
first two digits of the error number correspond to the associated subtest;
the last two numbers correspond to the individual errors within the
subtest.

NN = 0 indicates a general error message.

Functional Test Error Messages:

| | |
|---|---|
| 0001 | Test directive parameter P1 invalid. Input correct directive. |
| 0002 | Test directive parameter P2 invalid. Input correct directive. |
| 0003 | Test directive parameter P3 invalid. Input correct directive. |
| 0004 | Test directive invalid. Input correct directive. |
| 0005 | Watchdog timer trap has occurred indicating an IO instruction hang-up. (Reg 1) = address of trapped IO instruction. |
| 0006 | Trap has occurred.(Reg 1) = address of trapped instruction. |
| 0007 | Spurious interrupt received from a disarmed interrupt location. |
| 0008 | AIO instruction condition codes 1,2 indicate device address not recognized. Previous SIO received address recognition. |
| 0009 | AIO instruction results in invalid condition codes 1,2 = 10. |
| 0010 | AIO instruction results in unusual interrupt recognition condition codes 1,2 = 01.(Reg 2) = status, device address. |
| 0011 | AIO instruction status bit(s) set indicating failure in status line(s). (Reg 2) = status, device address. |
| 0012 | AIO instruction returned device address unequal to specified device address. (Reg 2) = status, device address. |
| 0013 | SYST directive parameter invalid. Program will return to monitor for error message printout attempt. |

Subtest Description:

   TST1,1    Tests the HIO, TDV and TIO instructions.

| | |
|---|---|
| 0101 | HIO instruction results in invalid condition codes 1,2 = 10. (DOR(TTSH)) |
| 0102 | HIO instruction condition codes 1,2 indicate address not recognized. (DOR(TTSH)) |
| 0103 | HIO instruction status indicates both device, controller not operative. (REG2, REG3) = STATUS DW. (UNEN/DCB) (STATUS(TSH)1,2) |

| | |
|---|---|
| 0104 | HIO instruction device status bits 1,2 unequal to controller status bits 5,6. (REG2, REG3) = STATUS DW. (STATUS(TSH)6) |
| 0105 | HIO instruction device status bit 3 reset to indicate device is manual. (REG2, REG3) = STATUS DW. (RAUT:R) (STATUS(TSH)3) |
| 0106 | HIO instruction device status indicates device not available. (REG2, REG3) = STATUS DW. (STATUS(TSH)1) (RAUT:R) |
| 0107 | HIO instruction device and controller status bits 1,5 unequal. (REG2, REG3) = STATUS DW. (STATUS(TSH)1,5) |
| 0108 | HIO instruction condition codes 1,2 = 01 indicating previous HIO failed to clear busy condition. (REG2, REG3) = STATUS DW. (SUBCONTROLLER PBLM) (IOR(HIO)) (DCBUSY) |
| 0109 | HIO instruction condition codes 1,2 = 00 while device status indicates device busy. (REG2, REG3)=STATUS DW. (DCBUSY) |
| 0110 | HIO instruction condition codes 1,2 = 00, device not busy while controller status indicates controller busy. (REG2, REG3)=STATUS. (STATUS(TSH)5,6) |
| 0111 | HIO instruction interrupt pending status bit set. (REG2,3) STATUS DW. (CIL) (STATUS(TST)0) |
| 0112 | HIO instruction unusual end status bit set. (REG2,3)=STATUS DW. (UNE) (STATUS(TST)4) |
| 0113 | HIO instruction status bit 7 set. (REG2,3)=STATUS DW. (STATUS(TSH)7) |
| 0121 | TDV instruction condition codes 1,2 indicate device address not recognized after previous HIO received address recognition. (SUBCONTROLLER PROBLEM) |
| 0122 | TDV instruction condition codes 1,2=01 indicating subcontroller in test mode. (REG2,3)=STATUS DW. (IOR(TDV)) (TEST) |
| 0123 | TDV instruction condition codes 1,2=10 indicating busy selector IOP. (REG2,3)=STATUS DW. (SUBCONTROLLER PBLM) |
| 0124 | TDV instruction status bit(s) 0 thru 2 or 5 thru 7 set. (REG2,3)=STATUS DW. (STATUS(TSH)0,1,2,5,6,7) |
| 0125 | TDV instruction status bit 4 set indicating device off-line. (REG2,3)=STATUS DW. (NONLINE) (STATUS(TDV)4) |
| 0126 | TDV instruction status bit 3 set indicating device reader manual. (REG2,3)=STATUS DW. (NRAUT:R) (STATUS(TDV)3) |
| 0131 | TIO instruction condition codes 1,2 indicate no address recognition. Previous HIO and TDV received address recognition. (SUBCONTROLLER PBLM) |
| 0132 | TIO instruction condition codes 1,2=10 indicating busy selector IOP. Previous HIO, TDV condition codes 1,2=00. (REG2,3)=STATUS. (SUBCONTROLLER PBLM) |
| 0133 | TIO instruction condition codes 1,2=01 indicating SIO not possible. Previous HIO condition codes 1,2 and status correct. (REG2,3)=STATUS DW. (NDCBUSY) (CIL) (OPER/SI) (SUBCONTROLLER PBLM) |
| 0134 | TIO instruction status error after successful HIO. (REG2,3)= STATUS DW. (SUBCONTROLLER PBLM) |

   TST1,2    Tests the SIO instructions associated with the printing
            operation. Tests TIO busy indications. Tests the SIO
            instructions associated with the input operation
            function.

| | |
|---|---|
| 0201 | SIO instruction condition codes 1,2 indicate device address not recognized. (SUBCONTROLLER PBLM) |
| 0202 | SIO instruction condition codes 1,2=10 indicating busy selector IOP. (REG2,3)=STATUS DW. (SUBCONTROLLER PROBLEM) |
| 0203 | SIO instruction condition codes 1,2=01 indicating SIO not accepted. (SUBCONTROLLER PBLM) |
| 0204 | SIO instruction device and/or controller status error. (REG 2,3)=STATUS DW. |
| 0205 | TIO instruction condition codes 1,2=11 during SIO execution. (REG2,3)=STATUS DW. |
| 0206 | TIO instruction condition codes 1,2=10 during SIO execution. (REG2,3)=STATUS DW. |
| 0207 | TIO instruction condition codes 1,2=01 while status indicates not busy during SIO execution. (REG 2,3)=STATUS DW. (STATUS(TSH)1,2) (DCBUSY) (UNEN/DCB) |
| 0208 | TIO instruction status indicates device not operational after SIO accepted. (REG2,3)=STATUS DW. |
| 0209 | TIO instruction status indicates device not available after SIO accepted. (REG 2,3)=STATUS DW. |

TST1, 2 (Continued)

0210    TIO instruction condition codes 1,2 and status indicate device not busy 50 msec after SIO (print) accepted. (REG 2,3)–STATUS DW. (NCDN/S1EN)

0211    TIO instruction condition codes 1,2–00 while status indicates device busy 50 msec after SIO (print) accepted. (DCBUSY)

0212    TIO instruction device status indicates busy while controller status does not. Condition exists 50 msec after SIO (print) accepted. (REG 2,3)–STATUS DW. (STATUS(TSH)5,6)

0213    TIO instruction status indicates operational error during SIO (print). (REG 2,3)=STATUS DW.

0214    TIO instruction status interrupt pending bit set during SIO (print) but no interrupt requested. (REG 2,3)–STATUS DW. (CIL) (CIL/S1)

0215    TIO instruction condition codes 1,2 and status indicate device busy after SIO (print) accepted but status unusual end bit set. (REG 2,3)=STATUS DW. (DOP:R) (ORDENABLE)

0216    TIO instruction condition codes 1,2–00 indicates SIO (print 2 characters) terminated prematurely after 175 msec. (REG 2,3)=STATUS DW.

0217    TIO instruction condition codes 1,2=01 indicating SIO (print 2 characters) not terminated after 275 msec. (REG 2,3)=STATUS DW. (PROUT) (CTR/C)

0218    TIO instruction status error after SIO (print) execution. (REG 2,3)=STATUS DW.

0219    SIO instruction (read) not accepted. Previous SIO (print) accepted and completed. (SUBCONTROLLER PBLM)

0220    SIO instruction status error after previous SIO status correct. (REG 2,3)=STATUS DW.

0221    TIO instruction condition codes 1,2=00 after SIO (read) accepted. (REG 2,3)=STATUS DW. (KBINP) (INSR)

0222    TIO instruction byte count reduced from 2 during SIO (read) with no input expected. (REG 2,3)=STATUS DW. (INSR)

0223    TIO instruction status indicates device not busy during SIO (read). (REG 2,3)=STATUS DW.

0224    TIO instruction status indicates controller not busy during SIO (read) execution. (REG 2,3)=STATUS DW.

0225    HIO instruction condition codes 1,2=00 during SIO (read) execution. (REG 2,3)=STATUS DW.

0226    TIO instruction condition codes 1,2 indicate HIO instruction did not terminate SIO (read) execution. (REG 2,3)=STATUS DW. (HIOU) (PHSL.T100)

0227    TIO instruction byte count not equal to 1 at 50 msec after SIO (print 2 characters) accepted. (REG 2,3)=STATUS DW. (KA/C) (CNTR/C) (CSL/S1)

0228    TIO instruction byte count not reduced to 0 at 175 msec after SIO (print 2 characters) accepted. (REG 2,3)=STATUS DW.

TST1,3    Tests the AIO instruction, the channel end and the zero byte count interrupts, and the HIO instruction interrupt – clearing.

0301    SIO instruction condition codes indicate no address recognition.

0302    No channel end interrupt received after SIO (print 2 characters) terminated. TIO instruction indicates device not busy, and no interrupt pending status. (REG 2,3)=STATUS DW. (SUBCONTROLLER PBLM)

0303    No channel end interrupt received after SIO (print 2 characters) terminated. TIO instruction indicates device not busy but status interrupt pending bit set. (REG 2,3)=STATUS DW. (IO INTERRUPT PBLM)

0304    TIO instruction condition codes 1,2 indicate SIO (print 2 characters with interrupt) not terminated after 225 msec. (REG 2,3)=STATUS DW.

0305    TIO instruction condition codes 1,2 indicate SIO (print 2 characters with interrupt) not terminated after 225 msec but status interrupt pending bit set and no interrupt received. (REG 2,3)=STATUS DW.

0306    AIO instruction status bit(s) 1 thru 7 set. (REG 2)–STATUS.

0307    AIO instruction status bit 0 set after SIO (print 2 characters with interrupt) indicating data overrun. (REG 2)–STATUS.

0308    AIO instruction operational status after SIO (print 2 characters with interrupt) indicates operational error. (REG 2)–STATUS.

0309    AIO instruction operational status channel end interrupt bit not set after SIO (print with channel end interrupt). Interrupt was received. (REG 2)=STATUS.

0310    TIO instruction indicates AIO did not clear interrupt pending. (REG 2,3)–STATUS DW. (SUBCONTROLLER PBLM)

0311    TIO instruction indicates device not ready after SIO (print 2 characters with interrupt) terminated. Interrupt was received and cleared. (REG 2,3)–STATUS DW

0312    TIO instruction indicates channel end interrupt pending status not cleared. (REG 2,3)–STATUS DW.

0313    No zero byte count interrupt received after SIO (print 2 characters with ZBC) accepted.

0314    AIO instruction status indicates error. (REG 2)–STATUS.

0315    AIO instruction operational status zero byte count interrupt bit not set after SIO (print 2 characters with ZBC) terminated and interrupt received. (REG 2)–STATUS.

0316    Disabled interrupt received after SIO (print 2 characters) terminated. (REG 2)–AIO STATUS. (IO INTERRUPT PBLM)

0317    TIO instruction condition codes 1,2 indicate SIO possible after SIO (print 2 characters with interrupt) terminated and no AIO issued to clear interrupt. (REG 2,3)–STATUS DW.

0318    TIO instruction condition codes 1,2–01 after SIO (print 2 characters with interrupt) but status interrupt pending bit not set. No AIO issued to clear IP. (REG 2,3)=STATUS DW.

0319    HIO instruction condition codes 1,2 not 00 when instruction issued to clear interrupt pending. (REG 2,3)=STATUS DW.

0320    TIO instruction indicates device not ready after HIO. (REG 2,3)=STATUS DW.

0321    TIO instruction indicates HIO did not clear interrupt pending. Device not ready. (REG 2,3)=STATUS DW.

0322    TIO instruction indicates HIO did not reset interrupt pending status bit. (REG 2,3)–STATUS DW.

TST1,4    Tests the printing of all alpha and numeric characters. Subtest prints failing character input by the operator.

Operation Intervention:

Operator visually verifies the alpha and numeric characters. Operator may enter one or two characters into Reg 0 (bytes 2,3) for continuous printing (SSW1=1).

0401    HIO instruction condition codes 1,2 or status error after previous HIO. (REG 2,3)=STATUS DW.

0402    SIO instruction not accepted after previous HIO successful. (REG 2,3)=STATUS DW.

0403    TIO instruction indicates previously accepted SIO (new line carriage movement) was not terminated after 500 msec. (REG 2,3)=STATUS DW.

0404    TIO instruction indicates a status error after SIO (new line carriage movement) terminated. (REG 2,3)=STATUS DW.

0405    SIO instruction not accepted after previously successful TIO. (REG 2,3)=STATUS DW.

0406    TIO instruction indicates a status error or failure to complete SIO (print 1 character) after 110 msec. (REG 2,3)=STATUS DW.

TST1,5    Tests the printing using variable length records.

0501    SIO instruction status error after HIO. (REG 2,3)–STATUS DW.

0502    TIO instruction indicates an SIO (print new line carriage movement) status error. (REG 2,3)–STATUS DW.

0503    TIO instruction indicates status or operational status error after SIO terminated. (REG 2,3)–STATUS DW.

TST1,6    Tests the data chaining function.

0601    SIO instruction (print with data chaining) not accepted or status error. (REG 2,3)–STATUS DW.

0602    TIO instruction indicates accepted SIO (print with data chaining) terminated prematurely at 400 msec. (REG 2,3)–STATUS DW.

0603    TIO instruction indicates the SIO command address not changed from first IOCD address to second IOCD address. (REG 2,3)–STATUS DW.

0604    TIO instruction indicates SIO not terminated. (REG 2,3)=STATUS DW.

TST1,7    Tests the command chaining function.

0701    SIO instruction not accepted/status error after HIO. (REG 2,3)=STATUS DW.

0702    TIO instruction indicates SIO terminated prematurely. (REG 2,3)=STATUS DW.

0703    TIO instruction indicates an unexpected command address during SIO. (REG 2,3)= STATUS DW.

0704    TIO instruction indicates device terminated after first operation of the SIO (command chaining). (REG 2,3)=STATUS DW.

0705    TIO instruction indicates the second command address not present during second operation of SIO (command chaining). (REG 2,3)= STATUS DW.

0706    TIO instruction indicates a status error at SIO (command chaining) termination. (REG 2,3)=STATUS DW.

TST1,8    Echo test 1. Test the input SIO instruction and function by printing each received character input by the operator.

      Operator intervention:

      Operator inputs characters 'HT'=(horizontal tab), then "NL'=(new line) then any characters. Each character is echoed back. Termination character is 'EOM'.

      After the EOM char is detected, up to 80 chars/line are printed 10 times.

0801    SIO instruction not accepted or status error after HIO. (REG 2,3)=STATUS DW.

0802    No channel interrupt received within 15 seconds indicating either operator had not entered character or logic failure has occurred. (KBINP) (KSRDI) (KAO/SEN)

0803    TIO instruction indicates a status error after SIO (input 1 character) channel end received. (REG 2,3)=STATUS DW.

0804    Character received during SIO (input) not 'HT' (X'5') character. (REG 2)=CHARACTERS RECEIVED. (DL0 thru DL7)

0805    First character received during SIO (input) not 'HT' (X'5'). Second character is 'HT' indicating operator error (first character required to be 'HT'). (REG 2)=CHARACTERS RECEIVED.

0806    TIO instruction indicates 'HT' character did not terminate SIO (input 2 characters, order code X'86') operation. Byte count not 1 as expected. (REG 2,3)=STATUS DW. (KBEDM/DET) (KBLA:D)

0807    Character received during SIO (input) not 'NL' (X'15') character. (REG 2)=CHARACTERS RECEIVED. (DL0 thru DL7)

0808    First character received during SIO (input) not 'NL' (X'15'). Second character received is 'NL' indicating operator error (first character required to be 'NL'). (REG 2)=CHARACTERS RECEIVED.

0809    TIO instruction indicates 'NL' character did not terminate SIO (input 2 characters, order code X'86') operation. Byte count not 1 as expected. (REG 2,3)=STATUS DW.

0810    TIO instruction indicates a status error after SIO (input 1 character, order X'06') terminates. (REG 2,3)=STATUS DW.

0811    TIO instruction byte count not reduced to zero after SIO (input 1 character, order X'06') terminates. (REG 2,3)=STATUS DW.

0812    TIO instruction indicates status error after SIO (input 2 characters, order X'86') terminated by 'NL' character. (REG 2,3)=STATUS DW.

TST1,9    Echo test 2. Test IO lines by printing of 16 characters and requiring the operator to input each character as it is printed.

      Operator intervention:

      Operator inputs each character as it is received.

0901    SIO instruction not accepted or status error after HIO. (REG 2,3)=STATUS DW.

0902    TIO instruction status error after SIO (print new line character) terminated. (REG 2,3)=STATUS DW.

0903    SIO instruction not accepted or status error. (REG 2,3)= STATUS DW.

0904    Character received not equal to previously printed character. (REG 1)=PRINTED BYTE. (REG 2)=OBSERVED BYTE. (DL0 thru DL7) (KA0/S1 thru KA7/S1)

TST1,10    Echo test 3. Test IO lines and multiple character input by printing 8 characters and requiring the operator to input the characters after the printout is complete.

      Operator intervention:

      Operator inputs character string identical to that received.

1001    SIO instruction not accepted or status error after HIO. (REG 2,3)=STATUS DW.

1003    Character string received not equal to previously printed character string. (REG 1)=PRINTED 4 BYTES. (REG 2)=OBSERVED 4 BYTES.

TST1,11    Tests the SIO instruction and paper tape punching function. Automatic bipassing of test if KSR unit under test.

      Operator intervention:

      Operator insures blank paper tape is in punch station.

1101    SIO instruction not accepted or status error after HIO. (REG 2,3)=STATUS DW.

1102    TIO instruction indicates device busy after maximum allowable time (2.4 sec) of SIO (punch leader) operation. (REG 2,3)=STATUS DW.

1103    TIO instruction indicates device not busy but SIO (punch leader) byte count not reduced to 0. (REG 2,3)=STATUS DW.

1104    TIO instruction indicates status error after SIO (punch leader) terminated. (REG 2,7)=STATUS DW.

1105    TIO instruction indicates status error after SIO (punch pattern) terminated. (REG 2,3)=STATUS DW. (OUT:D)

1106    Error detected during punching of 80 byte trailer (blanks).

TST1,12    Tests the SIO instruction, paper tape read function. Automatic bipassing of test if KSR unit under test.

      Operator intervention:

      Operator visually verifies first portion of paper tape and inserts tape into read station:

| BYTES | | PUNCH |
|---|---|---|
| 0–15 | | Blank |
| 16–19 | | X'FF' |
| 20–23 | | Blanks |
| 24–31 | | X'01' |
| 32–39 | | X'02' |
| 40–47 | | X'04' |
| | (etc) | |
| 80–87 | | X'80' |
| 88–95 | | Alt. X'00'–X'FF' |
| 96–103 | | Alt. X'55'–X'AA' |
| 104–307 | | Random numbers |
| 308–388 | | Blank |

1201    SIO instruction not accepted or status error. (REG 2,3)= STATUS DW.

1202    TIO instruction indicates SIO (read ignoring leader) not terminated within 15 sec. (REG 2,3)=STATUS DW.

1203    TIO instruction indicates status error after SIO (read ignoring leader) terminated. (REG 2,3)=STATUS DW.

TST1, 12 (Continued)

1204     TIO instruction indicates SIO (read ignoring leader) byte count not equal to 0. (REG 2,3)=STATUS DW.

1205     First four bytes read not equal to X'FF'. (REG 1)=EXPECTED 4 CHARACTERS. (REG 2)=RECEIVED 4 CHARACTERS. (DL0:R thru DL7:R) (ASR(X)KA/S)

1206     SIO instruction not accepted or status error. (REG 2,3)= STATUS DW.

1207     TIO instruction indicates SIO (read immediate) accepted but device not busy. (REG 2,3)=STATUS DW.

1208     TIO instruction indicates SIO (read immediate) accepted, device busy, but byte count not being reduced. (REG 2,3)= STATUS DW.

1209     TIO instruction indicates SIO (read immediate) terminated but byte count not reduced to 0. (REG 2,3)=STATUS DW.

1210     Character received not equal to character expected. (REG 1) =EXPECTED CHARACTER. (REG 2)=CHARACTER RECEIVED. (ASR(X)KA/S) (DL0:R thru DL7:R) (DA0 thru DA7)

TST1,13     Checks for channel end and unusual end interrupt when break key is depressed.

Operator intervention:

Before entering subtest 13 insure that mode 1 is in effect with a SYST directive. This test will not run in mode 0. Operator presses break key when message from KSR says 'PRESS BREAK KEY'. Break key should not be held down for more than 1 sec any one time.

1300     SIO not accepted or device not recognized. Status, byte count in register 5.

1301     Expected channel end, unusual end interrupts did not come.

1302     AIO instruction issued, expected CEI, UEI, bits not set. Status may be found in reg. 2.

1303     TIO instruction issued, expected conditions: device ready, controller ready and/or device unusual end bit not set. Status may be found in register 2.

1304     AIO issued, condition code did not signal an expected unusual interrupt recognition. CC1,2. EXPECTED CC1,2=01

# Section 5

## SIGMA 5 - 9
## COMPREHENSIVE CARD
## EQUIPMENT (TEST)

### PROGRAM NO. 706169

**Section 5**

## CONTENTS

5

**SUBJECT MODEL** -- Card Readers Model Numbers 7120, 7121, 7122, 7140 and/or Card Punches Model Numbers 7160-1, 7160-2, 7165.

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer.

## PROGRAM PREREQUISITES

Test Deck:  For card reader only systems, a test deck may be obtained from the Xerox software library.  The test deck
(706169-74A) consists of the following cards:

   a.    Checkerboard deck – used for TST1, 41

   b.    50 card test deck – used for TST1, 49

   c.    Invalid EBCDIC – coded card – used for TST1, 50

   d.    Mode switching card – used for TST1, 51

   e.    500 random data cards – used for TST2

   f.    Blank cards required for TST1 are not included

## GENERAL OPERATING PROCEDURES

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

*SYST, 7120, 0, 003*

**DIRECTIVES** – directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives | | | | | |
| System Environment (Normally two SYST directives would be entered for a system, one specifying a card reader and one a card punch. Only the device selected by the last SYST directive will be used during the functional testing). | SYST, D1, H2, H3 | D1 | Device model number | 7120, 7121, 7122 7140 card readers<br><br>7160, 7165 card punches | 003<br><br>004 |
| | | H2 | Revision number of controller | 0 for card readers<br><br>0 for 7160–1 or 7165 card punches<br><br>2 for 7160–2 card punch | |
| | | H3 | IOP and device address<br><br>Note: A SYST directive with a device address of 'FFFFFFFF' will insure that no test will be attempted for that device. (To be used for systems without either a card reader or card punch). | 0 ~ 1FFF | |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 52, and random exerciser test) The functional tests will be run on the device specified in the most recent 'SYST' directive only. The random exerciser will process 750 cards. This test expects to punch and read verify cards. Note: See Program Test Description for detailed procedures. | TST0 | | | | |
| Functional Test (Punch device specified in most recent 'SYST' directive only) | TST1 [,D1 [,D2]] | D1<br><br>D2 | The first subtest to be executed<br><br>Last subtest to be executed | 0 (all subtests) 1~52 0 First subtest | 0 |
| Random Exerciser Test (This test expects to punch and read verify cards). Note: See Program Test Description for detailed procedures. | TST2, D1, D2 | D1<br>D2 | Number of cards to be punched<br>Number of punch retries | D1 > 0<br>D2 ≥ 0 | |

**DIRECTIVES** (Continued)

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Testing Directives (continued) | | | | | |
| Utility Test | TST3, D1, H2, H3, H4 | D1 | Utility test selected<br>· 0 Punch/Read EBCDIC cards<br>H2  1 Punch<br>   2 Reader | | |
| | | | 1 Punch/Read binary cards<br>H2  1 Punch<br>   2 Reader | | |
| | | | 2 Punch/Read cards<br>H2 = 1 Punch<br>  = 2 Reader<br>H3 Valid Punch/Read order | | |
| | | | = 3 Punch card matrix<br>H2 X coordinate (row)<br><br><br>H3 Y coordinate (column) | 1 – 12 is row<br>  10 is invalid<br>  13 is all rows<br><br>0 Punch all columns<br>1 – 80 is single column | |
| | | | = 4 Punch/Reader speed test<br>H2 = 1 Punch<br>  = 2 Reader | | |
| | | | = 5 Punch/Read then delay<br>H2 = 1 Punch<br>  = 2 Reader<br>H3 Number of cards<br>H4 Delay in milliseconds | | |
| | | | = 6 Punch/Read functional test deck<br>H2 = 1 Punch<br>  = 2 Reader<br>H3 = 0 All Decks<br>  = 40 Checkerboard deck<br>  = 48 50-Card test deck<br>  = 50 Invalid EBCDIC coded card<br>  = 51 Mode switching card | | |
| | | | = 7 Punch/Read shifting pattern<br>H2 = 1 Punch<br>  = 2 Reader<br>H3  12 Bit pattern to be shifted<br>   throughout the card<br>   (Punch Only) | | |
| Program Directives – Optional Directives | | | | | |
| Pattern Selection (for Utility Tests TST3, 0 and TST3, 1 Only) | DATA, D1, H2, H3 | D1<br><br><br>H2<br>H3 | = 0, Fixed pattern (2 columns)<br>= 1, Incremental pattern (1 column)<br>= 2, Random Pattern<br>Pattern seed<br>Incrementing constant (for D1=1) | 0 – 2<br><br><br>00000000 –<br>FFFFFFFF | |
| Set Testing Limits | LIMT, D1, D2, D3 | D1 | = 1 Limit compare error printouts<br>D2 = Maximum number of printouts | | |
| | | | = 2 TST2 Random delay limits<br>D2 = Lower delay limit in<br>   milliseconds<br>D3 = High limit of delay in<br>   milliseconds | | |

Note: Parameter of any directive beginning with a D means decimal; with an H means hexadecimal

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives — Refer to DPM section of this manual.
2. Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Punch/Read Tests |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT, D1 = 1,2 | LIMT, D1 = 1 | LIMT, D1 = 1, 2 | LIMT, D1 = 1 |
| Subtests | All functional subtests (1 — 52) and random exerciser test | 52 subtests (see error messages for the test types) | Punch and Read binary and EBCDIC cards with random patterns | Punch or Read an operator selected pattern |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX 2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

3. System reset should normally be used in order to insure the resetting of controller test mode logic.

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the Comprehensive Card Equipment test program.

TST0
The directive selects the comprehensive test consisting of the functional tests (subtests 1-52) and the random exerciser test.

Parameters: None

Test Variations:
1.  The functional test will be run on the device specified in the most recent 'SYST' directive (in sequence, subtest 1 thru 52).
2.  The random exercisor will attempt to simultaneously punch and read cards. The card count and retry on error parameters are initialized to 750 and 2 respectively. If a failure is encountered an error message is printed and the exercising continues.
3.  To avoid exercising a card punch or reader, enter a SYST directive for a punch or reader with an address of 'FFFFFFFF'.

Example:   SYST, 7121, 0, FFFFFFFF
           SYST, 7165, 0, 4
           TST0

1.  The functional test will be run on the Model 7165 card punch at address 4 (in sequence, subtest 1 thru 52).
2.  The random exercisor will be run only on the Model 7165 card punch. 750 cards will be punched with an error retry count of 2.

Note:  If only a card reader is being tested (card punch inhibited), the reader must be preloaded with a functional test deck and a 750 card random exerciser test deck prior to running.

TST1
The directive selects the entire functional test (no parameters entered) or selects one or more contiguous functional subtests. This test will be run only on the device specified in the most recent SYST directive.

Parameters:  D1 – First Functional Subtest
             D2 – Last Functional Subtest

             Where $0 < D1 \leq D2 \leq 52$

             TST1, D1, D2

Example:   SYST, 7122, 0, 3
           TST1

           Run all functional subtests that apply to a Model 7122 card reader on the device at address '3'.

Example:   SYST, 7122, 0, 3
           SYST, 7165, 0, 5
           TST1, 40, 40

           Execute functional subtest 40 on the Model 7165 card punch at device address '5'.

Example:   TST1, 46, 46

           Execute functional subtest 46 on the device specified in the most recent SYST directive. Since subtest 46 applies only to a Model 7165 card punch, the most recent SYST directive should have been for that model card punch.

Note:  The functional test card requirements are listed immediately following the error message listing.

TST2
This directive selects the random exerciser test, which exercises either or both the punch and reader devices specified in the most recent SYST directives. Binary and EBCDIC cards with random patterns are randomly intermixed when punching. These same cards can be read in any order. Exercising for any device can be terminated by placing that device in 'Manual' mode.

Parameters:   D1–Number of cards to be punched
                  $(0 \leq D1 < 32,768)$
              D2–Number of punch retries
                  $(0 \leq D2 \leq 99)$

              TST2, D1, D2

Test Variations:
              LIMT: The limit directive limits the range of the random delays introduced between successive card operations.
              SYST: A SYST directive for a card punch or reader with a device address of 'FFFFFFFF' will exclude that device from this test.

Example:      TST2, 2000, 1

              The random exerciser will punch 2000 cards and/or read and verify all cards in the card reader.

This test punches valid binary (punches in rows 1 and 2 of column 1) and EBCDIC cards in random sequence using a regenerative pattern. All reading takes place in the automatic mode, therefore binary cards are read in binary mode and EBCDIC cards are read in EBCDIC mode. These cards have no special sequence.

Cards in the punch error stacker should be read varified seperately to determine punch errors/check read errors.

TST3
This directive selects one of the following utility tests:

TST3, 0    Punch or Read EBCDIC Cards
           (Pattern punched and verified is that specified by the most recent data directive).
TST3, 1    Punch or Read Binary Cards
           (Pattern punched and verified is that specified by the most recent data directive).
TST3, 2    Using a valid device order specified by the operator, punch or read cards.
TST3, 3    Punch Card Matrix. Cards are punched with the punched positions selected by specifying the row number and column. A row number of 13 will cause the punching of all rows; a column entry of 0 will cause punching of all columns.

TST3, 4    Punch/Reader Speed Test. The speed of the punch or reader is determined by punching or reading 31 cards and averaging the speed over 1 minute.
TST3, 5    Punch/Read then Delay. Binary cards with random patterns are punched; no verification is performed on a read operation. The number of cards punched/read, and the following delay are specified by the operator.
TST3, 6    Punch/Read Functional Subtest Decks . All or individual functional subtest decks can be punched and verified.

## PROGRAM TEST DESCRIPTION (Continued)

TST3, 7 Punch/Read Shifting Pattern.
When punching, a 12-bit operator specified pattern for column 1 is circularly shifted throughout the binary card. Read verification of these cards is provided.

Test Variations:
SYST: The utility tests assume that SYST directives for the devices to be exercised have previously been entered by the operator.
Sense Switches: The following sense switch options apply to all TST3 tests.
  SSW3 Reset – Wait at end of test
  SSW1 Set – Loop on test
  SSW1 Reset – End Testing

Parameters: D1–Utility Test Selection
H2=1, Punch; H2=2, Read
H3–Defined by the utility test selected
H4–Defined by the utility test selected

Examples: TST3, 0, 1
Punch EBCDIC cards using the pattern specified by the most recent 'DATA' directive.

TST3, 2, 1, 4D
If the card punch last specified in a SYST directive was a model 7165, punch an EBCDIC card with the pattern specified by the most recent data directive.

TST3, 3, 1, 52
Punch cards with a single punch in row 1 of column 52.

TST3, 3, 13, 5
Punch Cards with punches in all rows of column 5.

TST3, 4, 2
Perform a speed test on the last card reader specified in a SYST directive

TST3, 5, 1, 10, 10000
Punch 10 cards then delay 10 seconds. Repeat if SSW1 set

TST3, 6, 1, 0
Punch all functional subtest decks

TST3, 6, 2, 48
Read and verify the 50-card test deck

TST3, 7, 1, 001
Punch a binary card where the bit pattern of column 1 (X'001') is shifted by 1 throughout successive columns of the card (Col. 2 = X'002', Col. 3 = X'004',..)

## ORDER CODES

### Card Punch Orders:

#### Model 7160 (EBCDIC)

| | |
|---|---|
| X'05' | Stack card in normal stacker. |
| X'0D' | If no error, stack card in normal stacker – on error, stack card in alternate stacker. |
| X'15' | Stack card in alternate stacker. |
| X'1D' | Stack card in alternate stacker. |

#### Model 7160 (Binary)

| | |
|---|---|
| X'01' | Stack card in normal stacker. |
| X'09' | If no error, stack card in normal stacker – on error, stack card in alternate stacker. |
| X'11' | Stack card in alternate stacker. |
| X'19' | Stack card in alternate stacker. |

#### Model 7165 (EBCDIC)

| | |
|---|---|
| X'05' | Stack card normally. |
| X'45' | Stack card normally and interrupt at data transmission complete. |
| X'0D' | Offset stack on error. |
| X'4D' | Offset stack on error and interrupt at data transmission complete. |
| X'15' | Offset stack. |
| X'1D' | Offset stack. |
| X'55' | Offset stack and interrupt at data transmission complete. |
| X'5D' | Offset stack and interrupt at data transmission complete. |

#### Model 7165 (Binary)

| | |
|---|---|
| X'01' | Stack card normally. |
| X'41' | Stack card normally and interrupt at data transmission complete. |
| X'09' | Offset stack on error. |
| X'49' | Offset stack on error and interrupt at data transmission complete. |
| X'11' | Offset stack. |
| X'19' | Offset stack. |
| X'51' | Offset stack and interrupt at data transmission complete. |
| X'59' | Offset stack and interrupt at data transmission complete. |

### Card Reader Orders:

#### Model 7120 (EBCDIC)

| | |
|---|---|
| X'06' | Stack card in normal stacker. |
| X'16' | Stack card in alternate stacker 1. |
| X'36' | Stack card in alternate stacker 2. |
| X'0E' | If no validity error or data overrun occurs, stack card in normal stacker; if validity error or data overrun occurs, stack card in alternate stacker 2. |
| X'1E' | If no validity error or data overrun occurs, stack card in alternate stacker 1; if validity error or data overrun occurs, stack card in alternate stacker 2. |
| X'3E' | Stack card in alternate stacker 2. |

#### Model 7120 (Binary)

| | |
|---|---|
| X'02' | Stack card in normal stacker. |
| X'12' | Stack card in alternate stacker 1. |
| X'32' | Stack card in alternate stacker 2. |
| X'0A' | If no data overrun occurs, stack card in normal stacker; if data overrun occurs, stack card in alternate stacker 2. |
| X'1A' | If no data overrun occurs, stack card in alternate stacker 1; if data overrun occurs, stack card in alternate stacker 2. |
| X'3A' | Stack card in alternate stacker 2. |

#### Model 7140 (EBCDIC)

| | |
|---|---|
| X'06' | Stack card in normal stacker. |
| X'16' | Stack card in alternate stacker. |
| X'36' | Stack card in normal stacker. |
| X'0E' | If no validity error or data overrun occurs, stack card in normal stacker; if validity error or data overrun occurs, stack card in alternate stacker. |
| X'1E' | If no validity error or data overrun occurs, stack card in normal stacker; if validity error or data overrun occurs, stack card in alternate stacker. |
| X'3E' | Stack card in normal stacker. |

#### Model 7140 (Binary)

| | |
|---|---|
| X'02' | Stack card in normal stacker. |
| X'12' | Stack card in alternate stacker. |
| X'32' | Stack card in alternate stacker. |
| X'0A' | If no data overrun occurs, stack card in normal stacker; if data overrun occurs, stack card in alternate stacker. |
| X'1A' | If no data overrun occurs, stack card in normal stacker; if data overrun occurs, stack card in alternate stacker. |
| X'3A' | Stack card in normal stacker. |

Note: Model's 7121 and 7122 accept all the above card reader orders, but offer no alternate stacking.

5-7

## NORMAL TDV STATUS

TDV SET 1

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7160-1/2 | Data Overrun | Not Used | Read Check | Parity Error | Row 15 time | Test Switch | ◄── Not Used ──► | |
| 7165 | Data Overrun | Not Used | Punch Error | ◄── | | Not Used | | ──► |
| CARD READERS | Data Overrun | ◄── | | | Not Used | | | ──► |

## TEST MODE TDV STATUS

| MODEL/SET | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7160-2 PUNCH/READ/VERIFY SET 2 | Punch Register PRO1 | Read Register PRO1 | Read Verify Bug RVCB4 | RVCB3 | RVCB2 | RVCB1 | Motor Speed | Chaining Mode |
| 7160-2 ROW, SKIP, DECODE SET 3 | Row Counter RCTD(MSB) | RCTC | TCTB | TCTA (LSB) | Skip Counter SCTA | SCTB | Binary Decode DATAB | EBCDIC Decode DATAE |
| 7160-2 DATA BUFFER SET 4 | Data Buffer DBO(MSB) | DB1 | DB2 | DB3 | DB4 | DB5 | DB6 | DB7(LSB) |

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7160 | Data Overrun | Not Used | Read Check (7160-2 Only) | ◄── | | Not Used | | ──► | Stop Order Interrupt |
| 7165 | Data Overrun | Not Used | Punch Error | ◄── | | Not Used | | ──► |
| CARD READERS | Data Overrun | ◄── | | | Not Used | | | ──► |

# FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES

## FAULT INDEX DESCRIPTION – FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

TST1, 1 HIO, TIO, TDV and AIO Instr. Recog. HIO, TIO, TDV and AIO instructions are issued and condition codes, status tested.

0101   HIO instr. cond. codes or status error.
0102   TIO instr. cond. codes or status error.
0103   TDV instr. cond. codes or status error.
0104   AIO instr. cond. code error. Expected no interrupt recognition.

TST1, 2 SIO invalid order test. An SIO is issued with an invalid order and the controller is tested for UE status.

0201   SIO condition codes indicate SIO not accepted. Card punch (Order = X'02').
0202   SIO status error for invalid order. Card punch (Order = X'02').
0203   TIO status indicates contr. remains busy after invalid order. Card punch (Order = X'02').
0204   TIO status error after invalid order. Expected UE status and contr. ready. Card punch (Order = X'02').
0205   Terminal byte count not the same as starting byte count for invalid order. Expected term. BC = 120. Card punch (Order = X'02').
0211   SIO condition codes indicate SIO not accepted. Card reader (Order = X'01').
0212   SIO status error for invalid order. Card reader (Order = X'01').
0213   TIO status indicates contr. remains busy after invalid order. Card reader (Order = X'01').
0214   TIO status error after invalid order. Expected UE status and contr. ready. Card reader (Order = X'01').
0215   Terminal byte count not the same as starting byte count for invalid order. Expected term. BC = 120. Card reader (Order = X'01').
0221   SIO condition codes indicate SIO not accepted. Card reader (Order = X'03').
0222   SIO status error for invloid order. Card reader (Order = X'03').
0223   TIO status indicates contr. remains busy after invalid order. Card reader (Order = X'03').
0224   TIO status error after invalid order. Expected UE status and contr. ready. Card reader (Order = X'03').
0225   Terminal byte count not the same as starting byte count for invalid order. Expected term. BC = 120. Card reader (Order = X'03').
0231   SIO condition codes indicate SIO not accepted. Card reader (Order = X'42').
0232   SIO status error for invalid order. Card reader (Order = X'42').
0233   TIO status indicates contr. remains busy after invalid order. Card reader (Order = X'42').
0234   TIO status error after invalid order. Expected UE status and contr. ready. Card reader (Order = X'42').
0235   Terminal byte count not the same as starting byte count for invalid order. Expected term. BC = 120. Card reader (Order = X'42').
0241   SIO condition codes indicate SIO not accepted. Card reader (Order = X'86').
0242   SIO status error for invalid order. Card reader = X'86').
0243   TIO status indicates contr. remains busy after invalid order. Card reader (Order = X'86').
0244   TIO status error after invalid order. Expected UE status and contr. ready. Card reader (Order = X'86').
0245   Terminal byte count not the same as starting byte count for invalid order. Expected term. BC = 120. Card reader (Order = X'86').
0250   Read check verification. The read check flag should be set by the invalid order (Models 7160-1 and 7160-2).

TST1,3 Test mode selection. SIO issued to select and reset controller test mode. TDV is used to verify test mode. (CC2 = 1 – Test mode).

0301   SIO instr. cond. code or status error.
0302   TIO instr. indicates contr. busy beyond normal termination time for select test mode order (X'13').
0303   TIO indicates UE for select test mode order.
0304   TIO indicates status error for select test mode order.
0305   Test mode byte not taken by contr.
0306   Contr. performed data in instead of data out for test mode order.
0307   TDV cond. codes 1, 2 not equal 01 following test mode order.
0308   SIO cond. code or status error while contr. in test mode.
0309   TIO indicates cond. code or status error following test mode order to reset test mode.
0310   TDV cond. code or status error following test mode order to reset test mode.

TST1, 4 interrupt generation test. The following orders are issued for a 7160-2 controller: X'13' (Data byte = 00), and X'02' in order to test the ICE, IZC, and IUE interrupt generation. AIO and HIO instr's are used to test the interrupt clearing.

0401   TIO indicates IP status not present after X'13' order with ICE flag set in the IOCD.
0402   TIO indicates cond. code or status error after X'13' order with ICE flag set.
0403   AIO instr. cond. code, status or device address error following X'13' order raising IP.
0404   HIO instr. did not reset IP in controller.
0405   TIO indicates IP not set by X'13' order with IZC flag set in the IOCD.
0406   TIO indicates cond. code or status error after X'13' order with IZC flag set in the IOCD.
0407   AIO instr. cond. code, status or device address error after X'13' order with IZC flag set in the IOCD.
0408   AIO or HIO instr. did not reset IP in controller.
0409   TIO indicates invalid order with IUE flag did not set IP in the controller.
0410   TIO indicates cond. code or status error after invalid order with IUE flag set in IOCD. Expected UE and IP.
0411   AIO instr. cond. code, status or device error after invalid order with IUE flag set in the IOCD.
0412   TIO indicates status error after AIO or HIO instruction to clear IP.
0413   TIO indicates HIO or AIO instr. did not reset IP in contr.
0414   AIO instr. did not reset IP in the controller.
0420   'Interrupt pending' not reported by the Model 7160-1 punch.
0421   AIO status error detected (7160-1). Expecting 'interrupt pending' and 'unusual end' indications. Refer to printout for observed status.
0422   TIO status error detected (7160-1). AIO did not reset 'interrupt pending' in the controller.
0430   'Interrupt pending' not reported by the Model 7165 punch.
0431   AIO status error detected (7165). Expecting 'interrupt pending' and 'unusual end' indications. Refer to printout for observed status.
0432   TIO status error detected (reader). AIO did not reset 'interrupt pending' in the controller.
0440   'Interrupt pending' not reported by card reader.
0441   AIO status error detected (reader). Expecting 'interrupt pending' and 'unusual end' indications. Refer to printout for observed status.

TST1, 4 (Continued)

0442 TIO status error detected (7165). AIO did not reset 'interrupt pending' in the controller.

TST1, 5 IO interrupt generation. Using an invalid order, verify that the punch/reader can generate 'channel end' and 'unusual end' interrupts.

0501 Interrupt not received by the CPU

0502 TIO status error after CPU received an interrupt from contr.

0503 AIO cond. code, status or device address error after ICE interrupt received by the CPU.

0504 TIO indicates HIO did not reset IP in the controller.

0505 AIO cond. code, status or device address error after IZC interrupt received by the CPU.

0506 TIO indicates HIO did not reset IP in the contr.

0507 AIO cond. code, status or device address error after IUE interrupt received by the CPU.

0508 TIO indicates HIO did not reset IP in the contr.

0510 Timeout occurred – No interrupt received.

0511 Status error detected after interrupt received. Refer to printout for expected and observed status.

TST1, 6 command chaining. Two test mode orders are command chained and chaining verified. Invalid order command chained to test mode order is tested for command chain termination after invalid order.

0601 TIO indicates contr. busy beyond normal termination time for command chain operation.

0602 TIO indicates status error during command chaining.

0603 TIO indicates operational status error during command chaining.

0604 Byte count not 0 following command chaining.

0605 TIO indicates command chaining did not terminate with the second IOCD.

0606 Contr. busy with invalid order.

0607 TIO indicates UE not generated by contr. for invalid order.

0608 TIO indicates status error for invalid order command chained to test mode order.

0609 Terminal byte count not 1 for invalid order command chained to test mode order.

0610 Command chaining not terminated by UE of invalid order.

TST1, 9 motor speed (test mode). A binary order is issued in test mode and TDV status tested to insure punch motor speed indicator is set.

0901 Test mode selection error. Expected TDV CC1, 2 = 01.

0902 SIO status error for binary order.

0903 TIO indicates contr. busy with binary order beyond normal termination time. Motor speed indicator is set.

0904 TIO indicates status error for binary order.

0905 TDV set 3 indicates motor speed indicator not set following a binary order.

0906 TDV set 3 indicates motor speed indicator not set during a binary order.

TST1, 10 stop and interr. A stop and interr. (X'80') order is issued and interrupt generation is verified.

1001 Interrupt not generated by contr. for stop and interrupt order.

1003 TIO cond. code or status error after interrupt received.

1004 AIO cond. code, status or device address error for interrupt of the stop and interrupt order.

1005 TIO indicates status error after AIO cleared the interrupt.

TST1, 11 valid orders (test mode). The following valid orders are issued in test mode with a byte count of one: X'00', X'01', X'15', X'0D', X'11', X'15', X'19', X'1D'. Correct termination of each order is verified.

1101 Test mode selection error. Expected TDV CC1, 2 = 01.

1102 SIO status error for valid order.

1103 TIO indicates status error after valid order.

1104 TIO indicates contr. busy with valid order beyond normal termination time.

TST1, 12 one-byte data buffer (test mode). A binary order is issued in test mode to transfer one byte (X'00' thru X'FF') to the contr. one-byte buffer. TDV set 4 is used to verify the buffer contents.

1201 Test mode selection error. Expected TDV CC1, 2 = 01.

1202 TIO indicates contr. busy with binary order beyond normal termination time.

1203 TIO indicates UE for binary order.

1204 TIO indicates status error for binary order.

1205 TIO indicates operational status error for binary order.

1207 Terminal byte count incorrect. Expected 0, received 1.

1208 Data buffer contents not correct for binary order. See printout.

TST1, 13 punch order completion/chaining mode. (test mode). A binary order is issued in test mode with byte count = 120. Test is made that all bytes are transferred and the chaining modifier set.

1301 Test mode selection error. Expected TDV CC1, 2 = 01.

1305 TIO indicates contr. busy beyond normal termination time for a binary order with byte count of 120.

1306 TIO indicates UE for binary order with byte count of 120.

1307 TIO indicates status error for binary order.

1308 Terminal byte count not 0 for binary order with starting byte count of 120.

1309 Operational status error for a binary order.

1311 Chaining modifier not set.

TST1, 14 row counter (test mode). A binary order is issued in test mode and TDV set 2 is used to verify the row counter increments from card row 1 (X'0') to card row 15 (X'E').

1401 Test mode selection error. Expected TDV CC1, 2 = 01.

1402 TDV set 2 indicates row counter did not reset to row 1 (X'0') after the binary order. See printout.

1403 TDV set 2 indicates row counter did not increment correctly. See printout.

1404 TIO indicates status error for binary order.

TST1, 15 skip counter (test mode). Binary orders are issued to test the binary skip counter. TDV set 2 is used to verify that the 2-bit skip counter assumes the following states in sequence: binary 10, 11 and 00.

1501 Test mode selection error. Expected TDV CC1, 2 = 01.

1502 TDV set 2 indicates the skip counter did not increment correctly (10 to 11 to 00 to etc.) after the binary order.

1503 TIO indicates status error for binary order with byte count = 1.

TST1, 18 binary decode (test mode). A series of binary orders are issued with data bytes of X'00', X'01', X'02', D'04'... and TDV set 2 is used to verify the binary decode output (DATAB) for each row time.

1801 Test mode selection error. Expected TDV CC1, 2 = 01.

1802 SIO status error for binary order.

1803 TIO indicates contr. busy beyond normal time for one row.

1804 TDV set 2 indicates row counter did not increment correctly.

1805 TDV set 2 indicates row counter did not increment correctly.

1806 TDV set 2 indicates binary decode output (DATAB) incorrect.

TST1, 19 EBCDIC decode (test mode). A series of EBCDIC orders are issued with all EBCDIC bytes. TDV set 2 is used to determine the EBCDIC decode output for each character and row. EBCDIC decode is accumulated and verified at the conclusion.

1901 Test mode selection error. Expected TDV CC1, 2 = 01.

1902 SIO status error for EBCDIC order with byte count = 80.

TST1, 19 (Continued)

1903    TIO indicates contr. busy beyond normal termination time for EBCDIC order with byte count = 80.
1905    TDV set 2 indicates row counter incremented incorrectly.
1906    EBCDIC decode error. See printout.

TST1, 22 punch register/read register – shifting (test mode). An EBCDIC order is issued with X'40' bytes and TDV set 3 is used to verify that the EBCDIC decode output (0 for X'40') is shifted through the punch register and through the read register. The test is repeated with X'00' bytes (row punches T0981) to verify that a 1 bit is shifted to the read register.

2201    Test mode selection error. Expected TDV CC1, 2 = 01.
2202    Channel end interrupt not received for the EBCDIC order with byte count = 80.
2203    Status error for EBCDIC order. See printout.
2204    TDV set 3 indicates the 1 bit was not shifted thru to the read register column 1 position.
2205    TDV set 3 indicates the 0 bit was not shifted thru to the read register column 1 position.

TST1, 23 incorrect length (test mode). Binary orders with byte counts of 119 and 121 and EBCDIC orders with byte counts of 79 and 81 are issued to verify the incorrect length reporting.

2301    Test mode selection error. Expected TDV CC1, 2 = 01.
2302    Channel end interrupt not received.
2303    Status error after EBCDIC or binary order.
2304    IL status not reported.

TST1, 24 sense order (test mode). Sense orders are issued with byte counts of 1 to 80 in order to verify the contr. ability to transfer the 80-bit read register data to the CPU.

2401    Test mode selection error. Expected TDV CC1, 2 = 01.
2402    SIO status error for sense (X'04') order.
2403    TIO indicates contr. busy after normal termination time for sense order.
2404    Status error for sense order.

TST1, 27 punch register/read register – 0's and 1's (test mode). A series of EBCDIC orders are issued with X'40' bytes and sense orders used to verify that all 0's are transferred to the read register for all row times. The test is repeated to verify all 1's are transferred for all row times.

2701    Test mode selection error. Expected TDV CC1, 2 = 01.
2702    TIO status error for EBCDIC order.
2703    TIO status error for sense order.
2704    Read register not all 0's for EBCDIC order with X'40' bytes. See printout.
2705    Read register not all 1's for EBCDIC order. See printout.

TST1, 28 punch register/read register–random bits (test mode). A series of binary orders are issued to transfer alternating 1's and 0's and random bits to the punch and read registers. Sense orders are used to verify the read register contents.

2801    Test mode selection error. Expected TDV CC1, 2 = 01.
2802    SIO status error for binary order.
2803    TIO status error for binary order.
2804    TIO status error for sense order.
2805    Read register contents incorrect. See printout.

TST1, 29 punch register/read register – random bits (test mode). A series of EBCDIC orders are issued to transfer random bits to the punch and read registers. Sense orders are used to verify the read register contents.

2901    Test mode selection error. Expect TDV CC1, 2 = 01.
2902    SIO status error for EBCDIC order.
2903    TIO indicates status error for EBCDIC order.
2904    TIO indicates status error for sense order.
2905    Read register contents incorrect. See printout.

TST1, 33 read verification registers A, B-incrementing test mode. An EBCDIC order is issued to transfer X'40' bytes. TDV set 3 is used to verify that 'read verify reg. B' contains all 1's. (The 1's complement of 'read verif. reg. A' after it has received no EBCDIC decode 1 bits.) The test is repeated using data bytes producing 'read verif. reg. B' outputs of X'E' thru X'0'.

3301    Test mode selection error. Expected TDV CC1, 2 = 01.
3302    TIO indicates status error for EBCDIC order.
3303    TDV set 3 indicates read verification register B contents incorrect. See printout.

TST1, 34 read verification (test mode). EBCDIC orders are issued with varying patterns producing EBCDIC decode outputs of 0 thru 15. TDV set 3 and 1 are used to verify the read verif. reg B contents and the read verification indicator.

3401    Test mode selection error. Expected TDV CC1, 2 = 01.
3402    TIO indicates status error for EBCDIC order.
3403    TIO indicates status error for 2nd EBCDIC order.
3404    TDV set 3 indicates read verif. reg. B not X'F' after being decremented during 2nd EBCDIC order.
3405    TDV set 1 indicates read verification error indicator set.

TST1, 36 card feed test #1. Verify that the device can correctly feed a blank card.

3601    Unsuccessful attempt to read an EBCDIC blank card. See printout for expected and observed status.
3602    Nonzero information was received from the card. Information should have been all blanks (X'40').
3603    Unsuccessful attempt to punch an EBCDIC blank card. See printout for expected and observed status.
3605    Unsuccessful attempt to read a blank binary card. See printout for expected and observed status.
3606    Nonzero information was received from the card. Information should have been all blanks (X'40').
3607    Unsuccessful attempt to punch a binary blank card. See printout for expected and observed status.

TST1, 37 incorrect length. Verifies that the device can correctly respond to punch/read orders with the following byte counts: 79, 81, 119, 121.

3701    Timeout on punch/read operation. TIO indicated that SIO still not currently possible. Byte count = 79.
3702    Status error detected on punch/read operation. Refer to printout for expected and observed status. Byte count = 79.
3703    Timeout on punch/read operation. TIO indicated that SIO still not currently possible. Byte count = 81.
3704    Status error detected on punch/read operation. Refer to printout for expected and observed status. Byte count = 81.
3705    Timeout on punch/read operation. TIO indicated that SIO still not currently possible. Byte count = 119.
3706    Status error detected on punch/read operation. Refer to printout for expected and observed status. Byte count = 119.
3707    Timeout on punch/read operation. TIO indicated that SIO still not currently possible. Byte count = 121.
3708    Status error detected on punch/read operation. Refer to printout for expected and observed status. Byte count = 121.

TST1, 38 punch blank cards. A series of 10 binary orders are issued to punch 10 blank cards, or a series of 12 binary orders are issued to read 12 cards.

3801    Status error detected on punch/read operation. Refer to printout for expected and observed status.

TST1, 38 (Continued)
3802    AIO status error on punch/read operation. Refer to printout for expected and observed status.
3803    TIO status error. Controller remained busy after operation.


TST1, 40 checkerboard pattern. A series of 10 cards are punched with a double checkerboard pattern. Visual verification is optional.

4001    IO interrupt not received for binary order.
4002    Punch status error for binary order punching checkerboard pattern.


TST1, 41 verify double checkerboard pattern. Read/verify double checkerboard pattern (deck of 10 cards).

4101    Timeout on read operation. Refer to printout for expected and observed status.
4102    Incorrect data entered by card reader. Refer to printout for failing columns.


TST1, 43 read brushes – column punching. A series of 80 cards are punched with each column read brush tested by moving the column being punched from col 1 to col 80. All rows are punched. Visual verification is optional.

4301    SIO status error for binary order.
4302    TIO indicates status or terminal byte count error.
4303    TDV indicates read check error for indicated column. See printout.


TST1, 44 read brushes – row punching. A series of 12 cards are punched with each column read brush tested by moving the rows being punched from row 9 thru row 12. Visual verification is optional.

4401    SIO status error for binary order.
4402    TIO status or terminal byte count error for binary order.
4403    TDV indicates read check error.


TST1, 45 read check – EBCDIC punching. A series of 10 EBCDIC cards are punched with random patterns. Read check is verified.

4501    Status error detected after binary punch operation. Refer to printout for expected and observed status.


TST1, 46 interrupt at data transmission complete. Verify that for a model 7165 card punch, the following orders generate an interrupt at data transmission complete: (X'45', X'4D', X'55', X'5D', X'41', X'49', X'51', X'59').

4601    Timeout occurred – No interrupt received (Order = X'45').
4602    AIO/TIO status error detected (Order = X'45'). Refer to printout for expected and observed status.
4603    Timeout occurred – No interrupt received (Order = X'4D').
4604    AIO/TIO status error detected (Order = X'4D'). Refer to printout for expected and observed status.
4605    Timeout occurred – No interrupt received (Order = X'55').

4606    AIO/TIO status error detected (Order = X'55'). Refer to printout for expected and observed status.
4607    Timeout occurred – No interrupt received (Order = X'5D').
4608    AIO/TIO status error detected (Order = X'5D'). Refer to printout for expected and observed status.
4609    Timeout occurred – No interrupt received (Order = X'41').
4610    AIO/TIO status error detected (Order = X'41'). Refer to printout for expected and observed status.
4611    Timeout occurred – No interrupt received (Order = X'49').
4612    AIO/TIO status error detected (Order = X'49'). Refer to printout for expected and observed status.
4613    Timeout occurred – No interrupt received (Order = X'51').
4614    AIO/TIO status error detected (Order = X'51'). Refer to printout for expected and observed status.
4615    Timeout occurred – No interrupt received (Order = X'59').
4616    AIO/TIO status error detected (Order = X'59'). Refer to printout for expected and observed status.


TST1, 48 punch 50-card deck. 25 binary cards followed by 25 EBCDIC cards are punched with pattern which allow for visual verification.

4801    Punch status error.


TST1, 49 read 50-card deck. The 50-card deck punched by TST1, 48 is verified.

4901    Read status error and/or pattern error detected on punched card. See printout.


TST1, 50 trans. error test (reader). A prepunched invalid-coded EBCDIC card is used to test the invalid EBCDIC code logic of the card reader.

5001    Unsuccessful attempt to read the card. Interrupt not received from the device.
5002    Read status error detected. Refer to printout for expected and observed status.
5003    Nonzero data was entered into the input buffer. All data read from the card should have been zero.


TST1, 51 automatic mode switch test (reader). A prepunched mode-switching card is used to test the ability of the card reader to automatically switch from automatic to binary mode when rows 1 and 2 of column 1 contain holes.

5101    Timeout. TIO cond. codes indicate that the device did not return to the 'ready' state after feeding a card.
5102    TIO status error detected. Refer to printout for expected and observed status.
5103    Error detected in observed data. Refer to printout for failing columns.


TST1, 52 transmission error test (punch). Any prepunched card is used to test the ability of the punch to detect extraneous punches.

5201    Unsuccessful attempt to punch the card. Interrupt not received from the device.
5202    Punch status error detected. Refer to the printout for expected and observed status.

FUNCTIONAL TEST (TST1) (SS1 = 0, SS3 = 1)
INITIALIZING CONDITIONS AND EXPECTED RESULTS

1. Initializing Conditions:
   Card Reader Test: (All Models)
   The following subtests will expect the following number of cards
   with their respective patterns to be in the card reader before each
   subtest

| Subtest | Number of cards | Pattern of Each Card |
|---------|-----------------|----------------------|
| 36 | 2 | Blank |
| 37 | 4 | Blank |
| 38 | 12 | Blank (Command Chained) |
| 41 | 10 | Double Checkerboard |
| 49 | 50 | 50-Card Test Deck |
| 50 | 1 | Invalid-Coded EBCDIC Card |
| 51 | 1 | Mode Switching Card |

2. Expected Results:
   Card Punch Test:
   Expected Results of each Subtest.

| | Subtest | Number of Cards | Pattern of Each Card |
|---|---------|-----------------|----------------------|
| Model 7160 | 36 | 2 | Blank |
| | 38 | 10 | Random (Command Chained) |
| | 40 | 10 | Double Checkerboard |
| | 43 | 80 | All Rows of a Column |
| | 44 | 12 | All Columns of a Row |
| | 45 | 10 | Random |
| | 48 | 50 | Standard Test Deck |
| | 52 | 2 | Operator Loads a Prepunched Deck into the Punch |
| Model 7165 | 36 | 2 | Blank |
| | 37 | 4 | Blank |
| | 38 | 10 | Blank (Command Chained) |
| | 40 | 10 | Double Checkerboard |
| | 43 | 80 | All Rows of a Column |
| | 44 | 12 | All Columns of a Row |
| | 45 | 10 | Random |
| | 46 | 8 | Random (4 Offset Stacked) |
| | 48 | 50 | Standard Test Deck |

TEST/DEVICE REFERENCE TABLE

| Test | Device Model Numbers | | | | | | | Not Used |
|------|--------|--------|------|------|------|------|------|------|
|      | 7160-1 | 7160-2 | 7165 | 7120 | 7121 | 7122 | 7140 |      |
| TST0 | X | X | X | X | X | X | X |   |
| **TST1** |   |   |   |   |   |   |   |   |
| 1  | X | X | X | X | X | X | X |   |
| 2  | X | X | X | X | X | X | X |   |
| 3  |   | X |   |   |   |   |   |   |
| 4  | X | X | X | X | X | X | X |   |
| 5  | X | X | X | X | X | X | X |   |
| 6  |   | X |   |   |   |   |   |   |
| 7  |   |   |   |   |   |   |   | X |
| 8  |   |   |   |   |   |   |   | X |
| 9  |   | X |   |   |   |   |   |   |
| 10 | X | X |   |   |   |   |   |   |
| 11 |   | X |   |   |   |   |   |   |
| 12 |   | X |   |   |   |   |   |   |
| 13 |   | X |   |   |   |   |   |   |
| 14 |   | X |   |   |   |   |   |   |
| 15 |   | X |   |   |   |   |   |   |
| 16 |   |   |   |   |   |   |   | X |
| 17 |   |   |   |   |   |   |   | X |
| 18 |   | X |   |   |   |   |   |   |
| 19 |   | X |   |   |   |   |   |   |
| 20 |   |   |   |   |   |   |   | X |
| 21 |   |   |   |   |   |   |   | X |
| 22 |   | X |   |   |   |   |   |   |
| 23 |   | X |   |   |   |   |   |   |
| 24 |   | X |   |   |   |   |   |   |
| 25 |   |   |   |   |   |   |   | X |
| 26 |   |   |   |   |   |   |   | X |
| 27 |   | X |   |   |   |   |   |   |
| 28 |   | X |   |   |   |   |   |   |
| 29 |   | X |   |   |   |   |   |   |
| 30 |   |   |   |   |   |   |   | X |
| 31 |   |   |   |   |   |   |   | X |
| 32 |   |   |   |   |   |   |   | X |
| 33 |   | X |   |   |   |   |   |   |
| 34 |   | X |   |   |   |   |   |   |
| 35 |   |   |   |   |   |   |   | X |
| 36 | X | X | X | X | X | X | X |   |
| 37 |   |   | X | X | X | X | X |   |
| 38 | X | X | X | X | X | X | X |   |
| 39 |   |   |   |   |   |   |   | X |
| 40 | X | X | X |   |   |   |   |   |
| 41 |   |   |   | X | X | X | X |   |
| 42 |   |   |   |   |   |   |   | X |
| 43 | X | X | X |   |   |   |   |   |
| 44 | X | X | X |   |   |   |   |   |
| 45 | X | X | X |   |   |   |   |   |
| 46 |   |   | X |   |   |   |   |   |
| 47 |   |   |   |   |   |   |   | X |
| 48 | X | X | X |   |   |   |   |   |
| 49 |   |   |   | X | X | X | X |   |
| 50 |   |   |   | X | X | X | X |   |
| 51 |   |   |   | X | X | X | X |   |
| 52 | X | X |   |   |   |   |   |   |
| TST2 | X | X | X | X | X | X | X |   |
| **TST3** |   |   |   |   |   |   |   |   |
| 0 | X | X | X | X | X | X | X |   |
| 1 | X | X | X | X | X | X | X |   |
| 2 | X | X | X | X | X | X |   |   |
| 3 | X | X | X |   |   |   |   |   |
| 4 | X | X | X | X | X | X | X |   |
| 5 | X | X | X | X | X | X | X |   |
| 6 | X | X | X | X | X | X | X |   |
| 7 | X | X | X | X | X | X | X |   |

**CARD SAMPLES (TST1)**
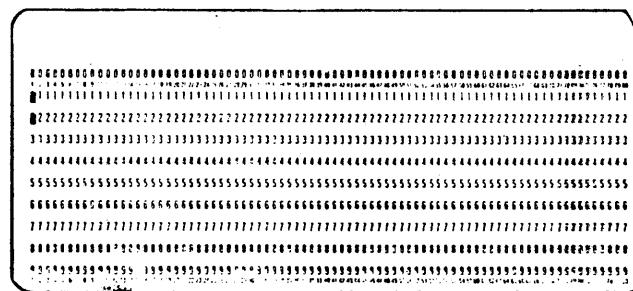


Double Checkerboard Pattern, 10 Identical Cards (TST1, 40 and 41)
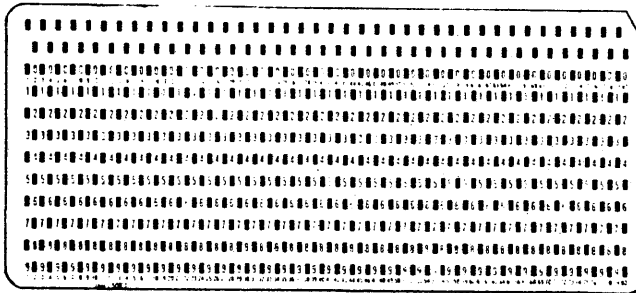


Transmission Error Test Card (TST1, 50)
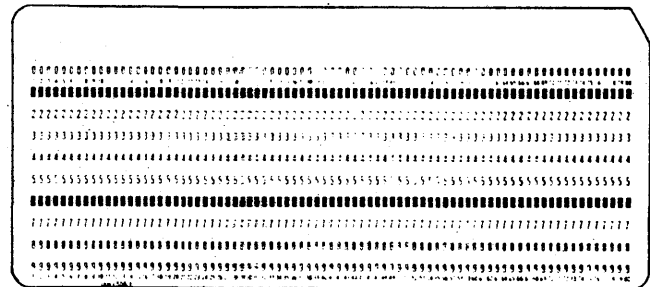


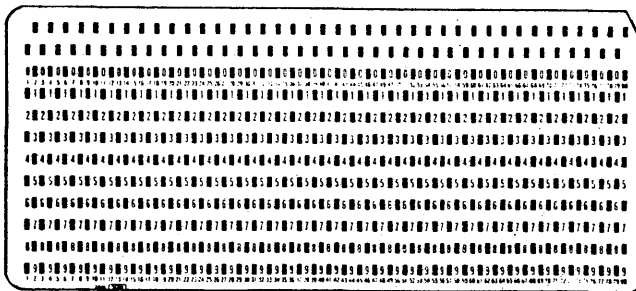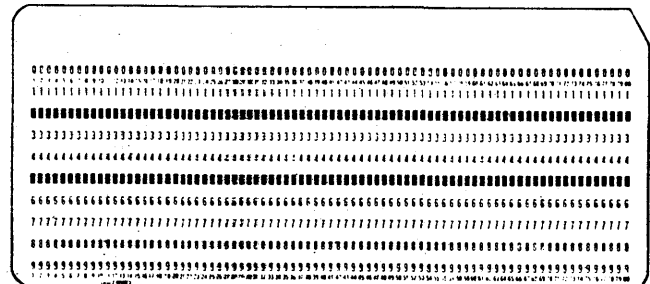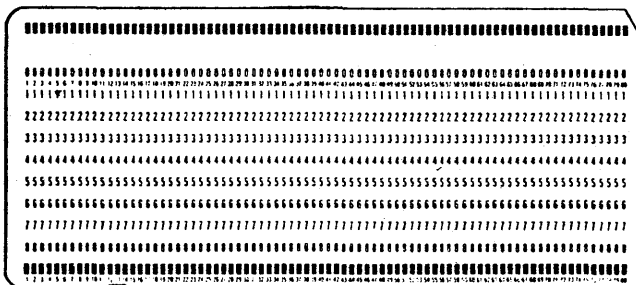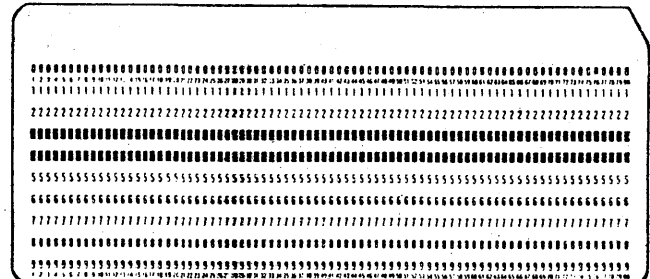Automatic Mode Switching Card (TST1, 51)
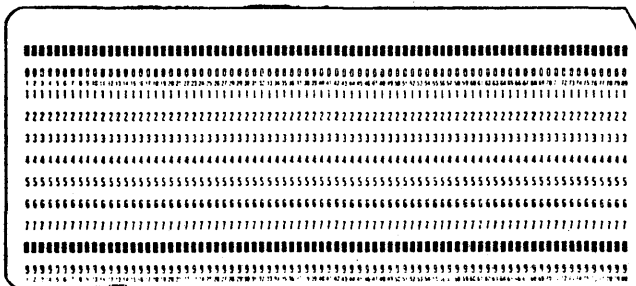
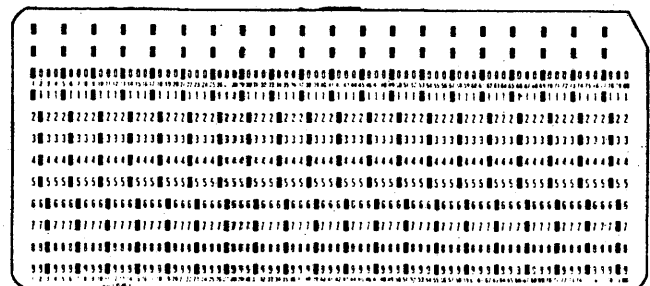## 50 CARD TEST DECK (TST1, 48 AND 49)
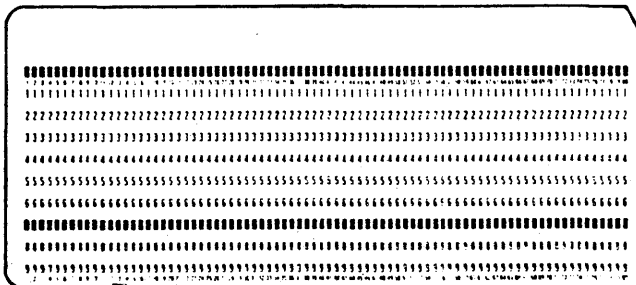


Card 1



Card 6



Card 2



Card 7



Card 3



Card 8



Card 4



Card 9



Card 5



Card 10

Card 11


Card 12


Card 13


Card 14


Card 15


Card 16


Card 17


Card 18


Card 19


Card 20

Card 21

Card 22

Card 23

Card 24

Card 25

Card 26

Card 27

Card 28

Card 29

Card 30

Card 31

Card 32

Card 33

Card 34

Card 35

Card 36

Card 37

Card 38

Card 39

Card 40

Card 41

Card 42

Card 43

Card 44

Card 45

Card 46

Card 47

Card 48

Card 49

Card 50

# Section 6

# SIGMA 5 - 9
# COMPREHENSIVE RAD/CARTRIDGE DISK
# TEST (COMPR RAD)

## PROGRAM NO. 705730

6

## Section 6

## CONTENTS

**SUBJECT MODEL**-- RAD Controllers, Model numbers 7201, 7211, 7231, New Extended Interface Controllers, Model numbers 7201-3, 7231-3, Cartridge Disk (CD) Controller 7250, RAD Storage Units, Model numbers 7202, 7203, 7204, 7212, 7232, Cartridge Disk (CD) Drives 7251, 7252

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer

## PROGRAM PREREQUISITES
None

## GENERAL OPERATING PROCEDURES
General operating procedures of the Sigma 5 through 9 Diagnostic Program Monitor (DPM), apply to this program.

**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| **Program Directives – Environmental Directives** | | | | | |
| System Environment | SYST, D1, D2, H3, H4, D5, H6, [, H7, D8, H9 ..., H25, D26, H27] | D1<br>H2 | Controller model number<br>IOP Type and Revision number | 7201, 7211, 7231, 7250<br>H2 = 000000XX; MIOP<br>H2 = 000001XX; SIOP<br>H2 = 00000X03;<br>(7201-3, 7231-3)<br>H2 = 00000X00;<br>(all other RADs) | |
| | | H3 | Valid IOP and Controller but invalid Storage Unit address | 80 – 1FFF (If blank, or 0, or 8 units are specified, TST1, 2 is skipped) | |
| | | H4<br>D5<br><br>H6 | Device address of the first RAD/CD<br>Model number of the first Storage Unit<br>Write protection of the first Storage Unit | 80 – 1FFF   *1F0*<br>7202, 7203, 7204, 7212, 7232, 7251, 7252<br>00XY00ZW (See table for X, Y, Z, W at next page) | |
| | | H7<br>D8<br>H9 | } Same as H4, D5, H6 except for the second RAD/CD | | |
| | | H25<br>D26<br>H27 | } Same as H4, D5, H6 except for the eighth RAD/CD | | |
| **Program Directives – Testing Directives** | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 50, and random exerciser test) | TST0, D1, D2 | D1<br><br>D2 | Number of ordered sequences executed by random exerciser<br>Number of retries | 0 ~ 99999999<br><br>0 ~ 99999999 | 5000 (D1 = 0)<br><br>0 |
| Functional Test | TST1[, D1[, D2]] | D1<br>D2 | The first subtest to be executed<br>Last subtest to be executed | 0 (all subtests)~50<br>1 | 0<br>D1 |
| Random Exerciser Test | TST2, D1, D2 | D1<br>D2 | Number of cycles to be performed<br>Number of retries before next cycle | D1 > 0<br>D2 ≥ 0 | |
| Utility Test | TST3, D1, D2, D3, D4 | D1<br>D2<br><br><br><br><br>D3<br>D4 | Surface test<br>= 0, Write and read (verify data)<br>= 1, Write only<br>= 2, Read only (verify data)<br>= 3, Read only (no data verification)<br>= 4, Checkwrite<br>Number of retries<br>Number of reads after write (when D2 = 0) | 1<br>0 ~ 4<br><br><br><br><br>D3 ≥ 0<br>D4 > 0 | |
| **Program Directives – Optional Directives** | | | | | |
| Pattern selection (for Utility Test) | DATA, D1, H2, H3 | D1<br><br><br><br>H2<br>H3 | = 0, Fixed Pattern<br>= 1, Incremental Pattern<br>= 2, Random Pattern<br>= 3, Current Seek Address<br>Pattern seed (for D1 = 0, 1, 2)<br>Incrementing constant (for D = 1) | 0 ~ 3<br><br><br><br>} 00000000 ~ FFFFFFFF | |
| Usable surface area limitation | SEEK, D1, D2, D3, D4 | D1<br>D2<br>D3<br>D4 | Starting track (band) address<br>Starting sector address<br>Ending track (band) address<br>Ending sector address | 0 ~ 511 (0 ~ 63)<br>0 ~ 15 (0 ~ 81)<br>0 ~ 511 (0 ~ 63)<br>0 ~ 15 (0 ~ 81) | |
| Limitation of Error printouts | LIMT, D1, D2 | D1<br><br>D2 | = 1 Limit Compare error printouts/sector to D2<br>Maximum number of printouts (No limit if D2 = 0) | 1<br><br>D2 ≥ 0 | |
| Pass Control and Pass Count Printout for TST0, 2, 3 | LIMT, D1, D2, D3 | D1<br>D2<br><br>D3 | = 2 effect pass control only<br>Number of passes after which pass count is to be printed out.<br>Total number of passes to be completed. | 2<br>D2 ≥ 0<br><br>D3 ≥ 0 | |
| I/O buffer area definition | MEM [, H1, H2] | H1<br>H2 | First location of I/O buffer area<br>Last location of I/O buffer area | Obtainable by typing in MEM/ | Area between Diag. Prog. and DPM |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal

## DIRECTIVES (Continued)

Write Protection Parameter in SYST directive

| Models 7202, 7203, 7204 (16 sectors/track) 7232 (12 sectors/track) | | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| XY | Protected Tracks | Track Available | | | | ZW | Protected Tracks |
| | | 7202 | 7203 | 7204 | 7232 | | |
| 00 | None | – | – | – | – | 00 | None |
| 01 | 0 – 31 | – | – | – | – | 01 | All |
| 02 | 0 – 63 | – | – | – | – | 02 | 32 – 511 |
| 03 | 0 – 95 | – | – | – | – | 03 | 64 – 511 |
| 04 | 0 – 127 | – | – | – | – | 04 | 96 – 511 |
| 05 | 0 – 159 | | – | – | – | 05 | 128 – 511 |
| 06 | 0 – 191 | | – | – | – | 06 | 160 – 511 |
| 07 | 0 – 223 | | – | – | – | 07 | 192 – 511 |
| 08 | 0 – 255 | | – | – | – | 08 | 224 – 511 |
| 09 | 0 – 287 | | | – | – | 09 | 256 – 511 |
| 10 | 0 – 319 | | | – | – | 10 | 288 – 511 |
| 11 | 0 – 315 | | | – | – | 11 | 320 – 511 |
| 12 | 0 – 383 | | | – | – | 12 | 352 – 511 |
| 13 | 0 – 415 | | | – | – | 13 | 384 – 511 |
| 14 | 0 – 447 | | | – | – | 14 | 416 – 511 |
| 15 | 0 – 479 | | | – | – | 15 | 448 – 511 |
| 16 | All | | | – | – | 16 | 480 – 511 |

| Model 7212 (64 bands available) (82 sectors/bank) | | | |
|---|---|---|---|
| XY | Protected Bands | ZW | Protected Bands |
| 00 | None | 00 | None |
| 01 | 0 – 3 | 01 | All |
| 02 | 0 – 7 | 02 | 4 – 63 |
| 03 | 0 – 11 | 03 | 8 – 63 |
| 04 | 0 – 15 | 04 | 12 – 63 |
| 05 | 0 – 19 | 05 | 16 – 63 |
| 06 | 0 – 23 | 06 | 20 – 63 |
| 07 | 0 – 27 | 07 | 24 – 63 |
| 08 | 0 – 31 | 08 | 28 – 63 |
| 09 | 0 – 35 | 09 | 32 – 63 |
| 10 | 0 – 39 | 10 | 36 – 63 |
| 11 | 0 – 43 | 11 | 40 – 63 |
| 12 | 0 – 47 | 12 | 44 – 63 |
| 13 | 0 – 51 | 13 | 48 – 63 |
| 14 | 0 – 55 | 14 | 52 – 63 |
| 15 | 0 – 59 | 15 | 56 – 63 |
| 16 | All | 16 | 60 – 63 |

NOTE: For 725X Cartridge Disks, the parameter must be set to zero.

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

| | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Surface Test |
| | TST0 | TST1 | TST2 | TST3 |
| | None | None | TST1 | TST1 |
| Optional Directives | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM, DATA |
| Subtests | All functional subtests (1 50) and random exerciser test | 49 subtests (see error messages for the test types) | 1. Exerciser Initiation: Random data written on entire surface 2. Random Selection of: a. Device b. Order Sequences c. Buffer Areas d. Buffer Length e. Data | WRITE only READ only (Verify data) READ only (No data verification) CHECKWRITE WRITE/READ TEST |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX 2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

## PROGRAM TEST DESCRIPTION

Test descriptions of each functional test are included at the beginning of each subtest error number in the Functional Subtest and Related Error Message Section.

## ORDER CODES

| | |
|---|---|
| X'01' | WRITE |
| X'02' | READ RECORD (Report any transmission error of "count done") |
| X'03' | SEEK |
| X'04' | SENSE |
| X'05' | CHECKWRITE |
| X'12' | READ SECTOR (Terminate data transfer and report any transmission error at end of current sector if error is encountered) |
| X'13' | TEST |

## TDV AND AIO STATUS

| BITS | | | | | | | |
|---|---|---|---|---|---|---|---|
| 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| Data Overrun | Not Used | Sector Unavailable | Write–Protect Violated - | No Syncronization * | ← | NOT USED | → |

* For TDV on extended RAD controller and 725X only.

## TEST MODE DATA BYTE

For Models 7201-3, 7231-3 and 7250 only

TDV Status        Test Modes

| 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |

Unassigned

TDV Status Byte – Track registers 5-7
                   Sector registers 0-3

TDV Status Byte –
      Bit 0   WRITE-READ enable
      Bit 1   1 one-byte interface
             0 two or four-byte interface
      Bits 2~7 Track registers 0-4

TDV Status Byte – Parity registers as responsed

Test Mode 1 – Buffer turnaround test

Test Mode 2 – Data turnaround at controller
                    side of storage unit interface

Modifier Bit – Parity error reporting check

## ADDRESSING FORMAT

1. The format of the two byte sent to the RAD by a SEEK order is:

Model 720X, 723X, 725X

| Byte 1 | | Byte 2 |
|---|---|---|
| 000 | Track | Sector |

0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7

Model 7211

| Byte 1 | Byte 2 |
|---|---|
| Band | Sector |

0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7

2. The format of the bytes received on a SENSE order is:

Model 720X, 723X, 725X

| S | 00 | Track | Sector | /////// | Current Sector |
|---|---|---|---|---|---|
| | Byte 1 | | Byte 2 | | Byte 3 |

0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7

Model 7211

| S | Band | Sector | // | Current Sector | Failing Track |
|---|---|---|---|---|---|
| | Byte 1 | Byte 2 | | Byte 3 | Byte 4 |

0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7   0 1 2 3 4 5 6 7

Where:    S   is the setting of the write-protect switch for the indicated track (band) (0   not write-protected; 1   write-protected)
    Track (Band)   is the track (band) number selected by the RAD controller address register
         Sector   is the sector number selected by the RAD controller address register
  Current Sector   is the current sector position of the RAD
    Failing Track   bits 0-7 indicate that track 0-7, respectively, have failed (8 tracks/band)

NOTE: Bits 0, 1, and 2 of the track address are not used.

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES
### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

XX in the following messages indicates test number.
XX00  Watchdog timer trap
XX90  A control fault was detected by the Test Mode Reset subroutine.
XX91  A control fault was detected by the Set Test Mode 1 subroutine.
XX92  A control fault was detected by the Set Test Mode 2 subroutine.
XX95  A control fault was detected during the execution of the 'SEEK' subroutine.
XX96  A control fault was detected during the execution of the 'WRITE' subroutine.
XX97  A control fault was detected during the execution of the 'SENSE' subroutine.

TST1, 01 Interrupt Pending Test

0115  HIO did not reset pending interrupt, no reset generated.

TST1, 02 Valid Controller Address but Invalid Storage Unit Address
        Test (Bypassed if H3 0 of SYST Directive)

0210  Testing HIO, CC1 was 0 should be 1
      a.  Condition Code error
      b.  Device address recognition where one shouldn't exist.
0211  Testing HIO, CC2 was 1 should be 0
      a.  Condition Code error
      b.  Controller should indicate controller address recognition but
          not device address.

TST1, 03 HIO Instruction Recognition Test

0310  Testing HIO, CC1 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
031]  Testing HIO, CC2 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
      c.  I/O address recognized and device controller was busy
0312  Device status byte error during execution of HIO, only "device
      automatic" bit should be set.

TST1, 04 TIO Instruction Recognition Test

0410  Testing TIO, CC1 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
0411  Testing TIO, CC2 was 1 should be 0
      a.  Condition Code error
      b.  I/O address recognized but SIO can't be accepted
      c.  I/O address not recognized
0412  Device status byte error during execution of SIO, only "device
      automatic" bit should be set.

TST1, 05 TDV Instruction Recognition Test

0510  Testing TDV, CC1 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
0511  Testing TDV, CC2 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
      c.  I/O address recognized but previous operation was terminated
          due to a fault condition.
0512  Testing TDV, status bits should be all zeros but were not.

TST1, 06 SIO Instruction Recognition Test

0610  Testing SIO, CC1 was 1 should be 0
      a.  Condition Code error
      b.  I O address not recognized
0611  Testing SIO, CC2 was 1 should be 0
      a.  Condition Code error
      b.  I O address not recognized
      c.  I O address recognized but SIO not accepted.  (RAD was
          busy or device interrupt pending)
0612  Device status byte error from SIO, only "device automatic" bit
      should be set.
0613  Testing SIO, byte count was reduced by "STOP" order, should
      not be.
0615  Testing SIO, status bytes of TDV were not returned as all zeros.
      They should be.
0616  RAD was in "BUSY" state when it was halted.
0617  Device status byte erroneously returned from HIO, only "unusual
      end" and "device automatic" should be set.
0619  "Unusual end" bits were not reset by HIO, but should be.

TST1, 07 Back to Back SIO Test – RAD should accept back to back
        "STOP" SIO's without watchdog timer trapping or returning
        incorrect status (Order STOP; Flags SKIP; Byte Count
        Variable).

0710  SIO, CC2 was 1 should be 0
      a.  Condition Code error
      b.  I/O address not recognized
0711  Byte count should not be reduced between SIO's, but was.
0712  Device status byte error from SIO, only "device automatic" and
      "unusual end" bits should be set but were not.

TST1, 08 Interrupt Generation Test – RAD should generate an interrupt
        and return status and condition code (Order STOP; Flags UE,
        SKIP; Byte Count Variable).

0810  Device status byte error from TIO, only "device automatic" and
      "unusual end" bits should be set but were not.
0811  "Interrupt pending" bit was not set by TIO, but should be.
0812  TIO, CC2 was 0 should be 1
      a.  Condition Code error
      b.  RAD in "ready" condition with no interrupt pending
      c.  I/O address not recognized
0813  Operational status byte error of TIO, all bits should be 0 but were
      not.
0814  No interrupt occurred despite an actual interrupt pending.
0815  TDV, CC2 was 1 should be 0
      a.  Condition Code error
      b.  Previous operation terminated due to a fault condition
0816  TDV status bits were not returned as all 0's but should be
0817  "Interrupt pending" bit in TIO status should be reset by HIO but
      was not.
0818  Pending interrupt should be reset by HIO but was not (may be
      caused by not having HIO reset mode in IOP)

TST1, 09 AIO Instruction Test – RAD should generate an interrupt with
        a "STOP" order then clear it with an "AIO".  (Order
        STOP; Flags UE, SKIP; Byte Count Variable)

0910  Device status byte error from TIO, only "device automatic",
      "interrupt pending", and "unusual end" bits should be set.
0911  "Interrupt pending" bit was not set during TIO, but should be.
0912  TIO, CC2 was 0 should be 1
      a.  Condition Code error
      b.  RAD is in "ready" condition with no device interrupt
          pending.
0913  Interrupt did not occur, even though one was pending.
0914  AIO did not clear the pending interrupt.

TST1, 09 (Continued)

0915 AIO, CC1 was 1 should be 0
   a. Condition Code error
   b. Interrupt not recognized
0916 AIO returned address did not compare with the expected.
0917 AIO, CC1 was 0 should be 1
   a. Condition Code error
   b. Abnormal interrupt was not recognized
0918 "Unusual end" bit was not set during AIO, but should be.
0919 "Interrupt pending" bit of TIO was not reset by AIO, but should be.

TST1, 10 SEEK Test 1 – Verify order recognition, count done recognition, order-in generation, terminal order generation and length testing logic.

1010 Verifying execution of SEEK order, HTE flag, byte count equals 2. Check error message.
1015 Data in the output buffer was altered by the SEEK.
1020 Verifying execution of SEEK order, IUE flag, byte count equals 2. Check error message.
1030 Verifying execution of SEEK order, IZC flag, byte count equals 2. Check error message.
1040 Verifying execution of SEEK order, ICE flag, byte count equals 2. Check error message.

TST1, 11 SEEK Test 2 – Verify order recognition, count done recognition, order-in generation and length testing logic by SEEK operation with byte count less than 2.

*Do not apply to high speed RAD*

1110 Verifying "incorrect length" response to SEEK order, IUE flag, byte count equals 1. Check error message.
1115 Data in the output buffer was altered by the SEEK.
1120 Verifying "incorrect length" and "unusual end" response to SEEK order, HTE flag, byte count equals 1. Check error message.
1130 Verifying "channel end" response to SEEK order, ICE flag, byte count equals 1. Check error message.

TST1, 12 SEEK Test 3 – Verify order recognition, count done recognition, order-in generation, terminal order generation and length testing logic by SEEK operation with byte count greater than 2.

*Do not apply to high speed RAD or RAD on SIOP.
*Specify SIOP with SYST directive parameter 2.

1210 Verifying "incorrect length" and "channel end" response to SEEK order, ICE flag, byte count equals 3. See error message.
1215 Data in the output buffer was altered by the SEEK.
1220 Verifying "incorrect length" and "unusual end" response to SEEK order, HTE flag, byte count equals 3. See error message.
1230 Verifying RAD not reporting "unusual end" in response to SEEK order, IUE flag, byte count equals 3. See error message.
1240 Verifying RAD not reporting "zero byte count" in response to SEEK order, IZC flag, byte count equals 3. See error message.

TST1, 13 SENSE Test 1 – Verify order recognition, count done recognition, order-in generation and length testing logic by SENSE operation with byte count of 4 (for Model 7212) or 3 (for others).

1310 Verifying proper execution of SENSE order, IUE flag, byte count equals 4 (or 3). See error message.
1315 Data in the input buffer was not altered by the SENSE operation.
1316 More data was altered in input buffer than was expected by the SENSE operation.
1320 Verifying proper execution of SENSE order, HTE flag, byte count equals 3 (or 4). See error message.
1330 Verify "zero byte count" response to SENSE order, IZC flag, byte count equals 3 (or 4). See error message.
1340 Verifying 'channel end' response to SENSE order, ICE flag, byte count equals 3 (or 4). See error message.

TST1, 14 Sense Test 2 – Verify order recognition, count done recognition, order-in generation and length testing logic by SENSE operation with byte count less than required.

'Do not apply to high speed RAD'

1410 Verifying 'incorrect length' response to SENSE order, IUE flag, byte count equals 2. See error message.
1415 Data in the input buffer was not altered by the SENSE operation.
1416 More data was altered in input buffer than was expected by the SENSE operation.
1420 Verifying 'incorrect length' and 'unusual end' response to the SENSE order, HTE flag, byte count equals 2. See error message.
1430 Verifying 'channel end' response to the SENSE order, ICE flag, byte count equals 2. See error message.

TST1, 15 SENSE Test 3 – Verify order recognition, count done recognition, order-in generation and length testing logic by SENSE operation with byte count more than required.

1510 Verifying "incorrect length" and "channel end" response to SENSE order, ICE flag, byte count equals 5 (or 4). See error message.
1515 Data in the input buffer was not altered by the SENSE operation.
1516 More data was altered in input buffer than was expected by the SENSE operation.
1520 Verifying 'incorrect length' and 'unusual end' response to the SENSE order, HTE flag, byte count equals 4 (or 5). See error message.
1530 Verifying 'unusual end' response to the SENSE order, IUE flag, byte count equals 4 (or 5). See error message.
1540 Verifying no 'zero byte count' response to the SENSE order, IZC flag, byte count equals 4 (or 5). See error message.

TST1, 16 BUSY/NOT BUSY Test – Device is made busy and then ready.

*Do not apply to high speed RAD*
*Error message may be reported if an XP or MS RAD is connected to a SIOP*

1610 TIO, CC2 was 0 (ready) should be 1 (not ready).
1620 At the time of TIO, RAD storage unit and controller were NOT BUSY should be BUSY.
1630 TIO, CC2 was 1 (not ready) should be 0 (ready) after SEEK was accepted.
1640 RAD storage unit or controller remained BUSY after SEEK was accepted but should be NOT BUSY.
*Apply to Model 7201-3, 7231-3, 725X only*

TST1, 17 TEST Mode Test – Verify that controller can be set into and out of TEST Mode.

1710 Reset TEST Mode test, flags HTE, IUE and ICE, byte count = 1. A control fault occurred during accepting and decoding a TEST mode reset operation.
1715 Reset TEST mode test, TDV was issued, CC2 = 1 should be 0. Controller has falsely entered a TEST mode state. (To clear TEST mode, press RESET on the PCP).
1720-1727 Set TEST mode order test, flags HTE, IUE and ICE, byte count 1. A control fault occurred during accepting the TEST mode order and entering the TEST mode state. The last digit of the error number (0-7) identifies the one-bit in the TEST Mode Data Byte.
1730-1737 Set TEST mode order test, TDV was issued, CC2 = 0 should be 1. Controller has not entered a TEST mode state. The last digit of the error number (0-7) identifies the one-bit in the TEST Mode Data Byte.
1740-1747 Reset TEST mode order test, flags HTE, IUE and ICE, byte count 1. A control fault occurred during order execution. The last digit of the error number (0-7) identifies the one-bit in the TEST Mode Data Byte which was used to set the controller into TEST mode. TEST Mode Data Byte = X'00' when reset.
1750-1757 Reset TEST mode order test, TDV was issued. CC2 = 1 should be 0. Controller remains in TEST mode after a TEST mode reset. The last digit of the error number (0-7) indicates the one-bit of the TEST Mode Data Byte which was used to set the controller into TEST mode.

TST1, 17 (Continued)

1760 Set TEST mode order test, TEST Mode Status Byte = X'40'. Bit 1 of TDV Status Byte was 0 should be 1 (one-byte interface).

TST1, 18 Byte 'A' Data Path Test – The sequence of input data flow is as follows: IOP to 'CA' register to 'J' register to track and sector registers. When data is retrieved via the TDV TEST mode path, data flow is from the track and sector registers to the function response lines of the I/O bus. When data is retrieved via the SENSE operation, the output data flow is as follows: track and sector registers to 'K' register to 'DA' register to IOP.

*Apply to Model 7201-3, 7231-3, 725X only*

1825 Data or transfer fault in data path for byte 'A'. The following assumptions can be made about a single fault, as a likely cause of the fault:

| TDV | | SENSE | | |
|--------|--------|--------|--------|--------|
| Byte 1 | Byte 2 | Byte 1 | Byte 2 | Conclusion |
| Good | Good | Good | Good | Test Passed |
| Bad | Bad | Good | Good | If single bit fault, check corresponding function response line. If multiple bit fault, check transfer term to function response lines. |
| Bad | Good | Good | Good | Check transfer logic from track register to function response lines. |
| Good | Bad | Good | Good | Check transfer logic from track/sector register to function response lines. |
| Good | Good | Bad | Bad | If single bit fault, check corresponding bit in 'K' register, 'DA' register, data line driver. If multiple bit fault, check transfer logic for 'K' to 'DA' register and 'DA' to data line drivers. |
| Good | Good | Bad | Good | Check transfer logic from track register to 'K' register. |
| Good | Good | Good | Bad | Check transfer logic from track/sector register to 'K' register. |
| Bad | Bad | Bad | Bad | If single bit fault, check corresponding bit of data line receiver, 'CA' register and 'J' register. If multiple bit fault, check transfer logic from data line receivers to 'CA' register and 'CA' register to 'J' register. |
| Bad | Good | Bad | Good | If single bit fault, check corresponding track register FF. If multiple bit fault, check transfer logic from 'J' register to track reg. |
| Good | Bad | Good | Bad | If single bit fault, check corresponding track/sector register FF. If multiple bit fault, check transfer logic from 'J' register to track/sector register. |

TST1, 19 Current Sector Test – All sectors of the RAD can be sensed. Each sector is sensed once. When error occurs, a table will be output showing the number of times each sector was sensed.

TST1, 20 SEEK/SENSE Test – All sectors and tracks (bands) can be SEEKed then SENSEd. When error occurs, a table will be output showing the number of times each sector or track (band) was sensed.

2010 A sector was not found or was found more than once during SEEK and SENSE operations. (A table would be output).

2020 A track (band) was not found or was found more than once during SEEK and SENSE operations. (A table would be output).

TST1, 21 Track (Band) Availability and Not Write-Protect Test – All tracks (bands) allocated to the functional test are both available and not write-protected.

2110 The track (band) number listed on the printout should be available but was not.

2120 The track (band) number listed on the printout was reported write-protected in the TDV status but should not be.

2130 The track (band) number listed on the printout was reported write-protected in the returned sense word but should not be.

TST1, 22 Unavailability Test – Sector unavailable will be reported whenever an unavailable sector or track (band) is SEEKed.

2210 This test seeks unavailable sector. Check error message for the type of failures. (Does not apply to Model 7201, MS RAD).

2220 This test seeks unavailable track (band). Check error message for the type of failures.

TST1, 23 Command Chaining Test – The ability to detect and respond to command chaining.

2310 Command chaining did not occur properly.

2311 Command chaining did not take place after execution of HIO.

2312 Device did not stop on STOP order.

2320 Command chaining occurred on a STOP order. Check error message for the type of failure.

2321 Command chaining took place on a STOP order.

TST1, 24 FAM Write/READ Byte Count Test – This test is designed to operate the controller in TEST mode 1. It transfers from 1 to 16 bytes of data from the I/O buffer which starts on a word boundary to the FAM in the controller and subsequently transfers 1 to 16 bytes from the FAM to the I/O buffer.

*Apply to Model 7201-3, 7231-3, 725X only*

2421-2436 WRITE byte transfer test (test mode 1): Flags IUE, ICE; byte count 1 to 16. Error numbers 2421 to 2436 define the corresponding byte count of 1 to 16 which was used for the WRITE operation during which a control fault occurred.

2441-2456 READ byte transfer test (test mode 1): Flags IUE, ICE; byte count 1 to 16. Error numbers 2441 to 2456 define the corresponding byte count of 1 to 16 which was used for the READ operation during which a control fault occurred.

TST1, 25 FAM WRITE/READ Data Test–This test is designed to operate the controller in Test mode 1. This test checks the data path to and from the FAM and the 4-byte data path to and from the IOP.

*Apply to Model 7201-3, 7231-3, 725X only*

2510 WRITE test; Flags IUE, ICE and DC; byte count = 1. This test checks that 16 IOCD's can be executed to fill the FAM over the byte 'A' data path without control faults.

2511 WRITE test; Flags IUE and ICE, byte count = 16. This test checks that 16 bytes can be transferred to fill the FAM over the 4 byte interface (if it is installed) without control errors.

2512 WRITE test; Flags IUE, ICE and DC; byte count = 1. This test checks that 16 IOCD's can be executed to fill the FAM over the byte 'A' data path without control faults.

2520 READ test; Flags IUE, ICE and DC; byte count = 1. This test checks that 16 IOCD's can be executed to read the FAM via the byte 'A' data path without control faults.

2521 READ test; Flags IUE, ICE and DC; byte count = 1. This test checks that 16 IOCD's can be executed to read the FAM via the byte 'A' data path without control faults.

2522 READ test; Flags HTE, IUE and ICE; byte count = 16. This test checks that data can be transferred from the FAM via the 4 byte interface (if it is installed) without control faults.

2530 Data or transfer failure in data path 'A'. The failure is most likely in the output of the J register, the FAM, the input to the K register or in the associated control logic.

TST1, 25 (Continued)

2531 Data or transfer failure in data path 'B,C,D'. The failure is most likely in the input path from the data lines to the 'CB', 'CC' 'CD' registers or in the transfer logic to the J register.

2532 Data or transfer failure in data path 'B, C, D'. The failure is most likely in the output path to the IOP, the 'CB','CC','CD' registers, the 'DB','DC','DD' registers or associated control logic.

TST1, 26 FAM WRITE/READ Byte Alignment Test – This test is designed to operate the controller in TEST mode 1. It tests the ability of the controller to handle data patterns that do not start on word boundaries in memory.

*Apply to Model 7201-3, 7231-3, 725X only*

2620 WRITE alignment test; Flags IUE and ICE; byte count = 16. This test checks that a WRITE operation starting at byte 1 can be executed without control faults.

2621 WRITE alignment test; Flags IUE and ICE; byte count = 16. This test checks that a WRITE operation starting at byte 2 can be executed without control faults.

2622 WRITE alignment test; Flags IUE and ICE; byte count = 16. This test checks that a WRITE operation starting at byte 3 can be executed without control faults.

2623-2625 WRITE alignment test; Flags IUE and ICE; byte count = 16. These tests fill the FAM for the READ alignment test. Error indicates a control fault during the execution of a WRITE.

2630-2632 READ alignment test; Flags IUE, ICE; byte count = 16. These tests empty the FAM for this WRITE alignment test. Error indicates a control fault during the execution of a READ.

2633 READ alignment test; Flags IUE, ICE; byte count = 15. This test checks that a READ operation starting at byte 1 can be executed without control faults.

2634 READ alignment test; Flags IUE and ICE; byte count = 14. This test checks that a READ operation starting at byte 2 can be executed without control faults.

2635 READ alignment test; Flags HTE, IUE and ICE; byte count = 13. This test checks that a READ operation starting at byte 3 can be executed without control faults.

2640 Compare alignment data failure; WRITE starts with byte 1 and consists of 16 bytes; READ starts on word boundary and consists of 16 bytes. See compare printout for failing bytes.

2641 Compare alignment data failure; WRITE starts with byte 2 and consists of 16 bytes, READ starts on word boundary and consists of 16 bytes. See compare printout for failing bytes.

2642 Compare alignment data failure; WRITE starts with byte 3 and consists of 16 bytes, READ starts on word boundary and consists of 16 bytes. See compare printout for failing bytes.

2643 Compare alignment data failure; WRITE starts on word boundary and consists of 16 bytes, READ starts with byte 1 and consists of 15 bytes. See compare printout for failing bytes.

2644 Compare alignment data failure; WRITE starts on word boundary and consists of 16 bytes, READ starts with byte 2 and consists of 14 bytes. See compare printout for failing bytes.

2645 Compare alignment data failure; WRITE starts on word boundary and consists of 16 bytes, READ starts with byte 2 and consists of 13 bytes. See compare printout for failing bytes.

TST1, 27 READ Byte Counter Register Test – This test verifies the byte counter, the parity register, the data register, the data path from the parity register and the associated control logic. This test starts with a READ order of 1 byte. After each READ operation the byte count is incremented by 1 and another READ operation is performed. When the byte count equals 1 sector, the data is also verified.

*Apply to Model 7201-3, 7231-3, 725X only*

2710 READ byte counter test; Flags HTE, IUE and ICE; 1 ≤ byte count ≤ (BYTCURR). This test checks that all byte counts from 1 to (BYTCURR) can be performed. Error indicates that a control fault occurred during the execution of a READ.

2720 READ byte counter test; Flags HTE, IUE and ICE, byte count = (BYTCURR). This test checks that data for 1 sector can be READ. Error indicates that a control fault occurred during the execution of a READ.

2725 Data compare error after reading 1 sector in test mode 2. The READ data is generated by the byte counter. The data flow is from the byte counter to the parity register, data register, and J register and finally into the FAM. See compare printout for expected and observed data.

TST1, 28 Parity Error Test – This test verifies that the controller can detect and respond correctly to forced parity errors. Both READ X'02' and X'12' orders are executed for single and multiple sectors to verify correct data transfer termination.

*Apply to Model 7201-3, 7231-3, 725X only*

2810 Parity error test; order = X'02'; Flags HTE, IUE and ICE; byte count = 1 sector. This test checks that the modifier bit was set and detected by controller, and that the controller can detect and respond correctly to a parity error. Error indicates a control or detection fault occurred during the execution of the READ.

2820 Parity error test; order = X'02'; Flags HTE, IUE and ICE; byte count = 2 sectors. This test checks that the controller can detect and respond correctly to parity errors in multi length sectors.

2830 Parity error test; order = X'12', Flags HTE, IUE, ICE; byte count = 1 sector. This test checks that the controller can detect and respond correctly to parity errors in a single sector.

2840 Parity error test; order = X'12', Flags HTE, IUE, ICE; byte count = 1 sector + 3. This test checks that the controller can detect and respond correctly to parity errors in multi length sectors.

TST1, 29 WRITE Parity Generate Test – This test verifies the data path from the 'K' register to the data register, the parity generating logic, the preamble generating logic and its transfer to the data register and the generation of the WRITE enable signal. This test first writes data in a normal fashion to the controller, it then retrieves the resulting parity byte generated via the TDV test mode path.

*Apply to Model 7201-3, 7231-3, 725X only*

2910 WRITE parity generate test; Flags HTE, IUE and ICE; byte count = 1 sector. This test checks that a WRITE operation can be performed without control faults. No data will be written on the RAD.

2915 Parity generation or data transfer fault; the sequence of events tested by this test is as follows: The 'K' register is transferred to the data register, the data register is shifted one byte at a time to the parity generator logic, the parity register is shifted to store new generated parity bit. The error comparison printout displays 4 differently generated parity bytes compared to 4 expected parity bytes. If an error exists in the same 1 bit position for each parity byte the fault is most likely in the 'K' register. Otherwise the fault can be either in the shifting of the data register or parity register or in the parity generating logic.

2935 WRITE enable test; TDV status indicates that WRITE enable is true while the controller is in a READY state.

2940 WRITE enable test; error indicates, byte count was never decremented for WRITE operation.

2945 WRITE enable test; TDV status indicates that WRITE enable is false while the controller is writing.

TST1, 30 CHECKWRITE Byte Count Register Test – This test verifies that the checkwriting logic works properly. It first CHECKWRITEs patterns that are in error by 1 bit to verify that the error detection logic does indeed detect and report errors. It also CHECKWRITEs a good pattern to verify that the CHECKWRITE logic does not report errors on a matching pattern.

*Apply to Model 7201-3, 7231-3, 725X only*

3010 CHECKWRITE error test; Flags HTE, IUE and ICE; byte count = 1 sector. This test checks the ability of the controller to generate and report the detection of a data error when a bit from the IOP = 1 and the bit from the byte count register = 0.

3020 CHECKWRITE error test; flags HTE, IUE and ICE, byte count = 1 sector. This test checks the ability of the controller to generate and report the detection of a data error when a bit from the IOP = 0 and the bit from the byte count register = 1.

TST1, 30 (Continued)

3030    CHECKWRITE test; Flags HTE, IUE and ICE; byte count = 1 sector. This test checks the ability of the controller to compare the pattern generated by the byte counter with an identical pattern sent from the IOP. Error indicates a data error.

TST1, 31 WRITE Test 1 – The ability to correctly receive and respond to WRITE a sector.

\ 3110    Order WRITE, Flags HTE and IUE, byte count = 1 sector of data. Check error message.
3115    Data was altered in the output buffer by the WRITE operation.
3120    Order WRITE, flag IZC, byte count = 1 sector of data. Check error message.
3130    Order WRITE, Flag HTE and IUE, byte count = 2 sectors of data. Check error message.
3140    Order WRITE, Flag IZC, byte count = 2 sectors of data. Check error message.

TST1, 32 WRITE Test 2 – The ability to correctly receive and respond to WRITE less than a sector.

3210    Order WRITE, Flags HTE, IUE and ICE, byte count = less than 1 sector of data. Check error message.
3215    Data was altered in the output buffer by the WRITE operation.

TST1, 33 WRITE Test 3 – The ability to correctly receive and respond to WRITE greater than a sector.

3310    Order WRITE, Flags HTE, IUE and ICE, byte count = more than 1 sector of data. Check error message.
3315    Data was altered in the output buffer by the WRITE operation.

TSTJ, 34 Sector Increment Test – Verify that the SEEK address register can be incremented. Each sector or track (band) is SEEKed once. Any error detected a table will be output showing the number of times a particular sector or track (band) was observed.

3410    A sector was not found or was found more than once per track (band) during the execution of WRITE a sector and SENSE the increment of address register until the entire track (band) is attempted. A table should be output.
3420    A track (band) was not found or was found more than once during the execution of WRITE a sector and SENSE the increment of address register to the next higher track (band) until all tracks (bands) specified by 'SYST' and 'SEEK' directives are attempted. A table should be output.
3430    RAD did not report sector unavailable when the address register is incremented past the end of logical surface. This test is performed only if the end of the logical surface is available and not limited by 'SYST' and 'SEEK' directives.

TST1, 35 READ Test 1 – Ability to correctly receive and respond to READ (order X'02') a sector.

3510    No track (band) anywhere on the RAD has a sync pattern after being written.
3516    Searches the tracks (bands) on the RAD until one good track (band) is located. Error reports a good track (band) could not be found. Check error message.
3520    Order READ (X'02'), Flag IZC, byte count = 1 sector of data. Check error message.

TST1, 36 READ Test 2 – Ability to correctly receive and respond to READ (order X'02') less than a sector.

3610    A good track (band) could not be found.
3616    A good track (band) could not be located by the test. Check error message.
3620    Order READ (X'02'), Flag IZC, byte count = less than 1 sector of data. Check error message.

TST1, 37 READ Test 3 – Ability to correctly receive and respond to READ (order X'02') greater than a sector.

3710    A good track (band) could not be found.
3716    A good track (band) could not be located by the test. Check error message.
3720    Order READ (X'02'), Flag IZC, byte count = more than 1 sector of data. Check error message.

TST1, 38 WRITE-READ Test – Ability to WRITE and READ a pattern. Only preamble and the data transferred is tested. First, find a good track (band). If none exists, the test assumes the surface area is good but the logic is failing.

3810    A good track (band) could not be found.
3816    A good track (band) could not be located by the test. Check error message. (Either the logic generates or the logic checks the preamble is defective).
3820    The byte count was not reduced to zero by the test.
3825    Order READ (X'02'), Flag IZC, byte count = 1 sector of data. This test compares the data pattern received from a track of no preamble error against the increment pattern written there. If an error is detected, another track of no preamble error will be tried. After 10 tries, if the data received still in error, hardware failure is assumed. Check error message.

TST1, 39 Parity Test. Test the parity checking logic of the RAD.

3910    A good track could not be found.
3916    A good track could not be located by the test. Check error message.
3920    Verify that the pattern (X'55AA55AA', X'AA55AA55', X'55AA55AA', etc.) may be written/read without parity errors. Check error message. (Order READ (X'02'), Flag ICE, byte count = 1 sector of data).
3930    Verify that the pattern (X'AA55AAAA', X'AA55AA55', X'55AA55AA', etc.) may be written/read without parity errors. Check error message. (Order READ (X'02'), Flag ICE, byte count = 1 sector of data).
3940    Verify that the pattern (X'55AA5555', X'AA55AA55', X'55AA55AA', etc.) may be written/read without parity errors. Check error message. (Order READ (X'02'), Flag ICE, byte count = 1 sector of data).
3950    Verify that the pattern X'00000000', X'00000000', X'00000000', etc.) may be written/read without parity errors. Check error message. (Order READ (X'02'), Flag ICE, byte count = 1 sector of data).
3960    Verify that the pattern (X'FFFFFFFF', X'FFFFFFFF', X'FFFFFFFF', etc.) may be written/read without parity errors. Check error message. (Order READ (X'02'), Flag ICE, byte count = 1 sector of data).

TST1, 40 WRITE/READ (X'02') Test. READ an entire sector to verify that in writing less than a sector, the remaining sector is written with zeros.

4010    The RAD could not find a good track.
4016    A good track could not be located by the test. Check error message.
4020    Verify that the RAD has reduced byte count to zero. Check error message. (Order READ (X'02'), Flags ICE, byte count = 1 sector of data).
4025    Data written in shortened sector was not correct. Check error message.
4035    The zeros were not written in remaining sector area.
4040    Parity error was reported due to this operation.

TST1, 41 TRACK (BAND) SEARCH Test 1. Tests the ability of the RAD to WRITE and READ all tracks (bands) per sectors from the lowest to the highest available track (band).

4107    Error appeared during the execution of writing on all zero pattern on the RAD starting at the lowest available track (band). Check error message for type and location of failure.

TST1, 41 (Continued)

4108    Error appeared during the execution of reading an all zero pattern from the RAD starting at the lowest available track (band). Check error message for type and location of failure.

4109    Surface or addressing error, detected during the testing of the zero pattern read from the disc surface. See table printouts to determine types and locations of failures.

4110    Error appeared during the writing of a random pattern on the RAD starting at the lowest available track (band) to highest available track (band). Check error message.

4111    Error appeared during the reading of a random pattern from the RAD starting at the lowest available track (band) to highest available track (band). Check error message.

4112    Surface or address error was detected during the testing of the disc surface. Check error message.

TST1, 42 TRACK (BAND) SEARCH Test 2. Tests the ability of the RAD to WRITE and READ all tracks (bands) per sector from the highest to lowest available track (band).

4210    Error appeared during writing of a random pattern on the RAD starting at the highest available track (band) to lowest available track (band). Check error message.

4211    Error appeared during the reading of a random pattern on the RAD starting at the lowest available track (band) to the highest available track (band). Check error message.

4212    Surface or address error was detected during the testing of the disc surface. Check error message.

TST1, 43 READ (X'12') Test. Tests the ability of the RAD to receive and respond correctly to READs (Order X'12') of a sector.

4310    The RAD did not respond and receive correctly to READ of a sector.

4320    Verifies that RAD will report "incorrect length" to byte transfer. of greater than a sector but less than 2 sectors. Check error message. (Order READ (X'12'), Flags IZC, byte count = greater than 1 sector of data).

TST1, 44 CHECKWRITE 1 Test. Find a good track, build a pattern, write this pattern on one sector of the RAD and then check this pattern with a CHECKWRITE. A comparison is expected.

4410  The RAD could not find a good track.

4416  A good track could not be located by the operations. Check error message.

4420  Verify that no errors are detected when a pattern of all zeros is compared to an identical pattern by means of a CHECKWRITE.

4430  Bit 0 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4431  Bit 1 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4432  Bit 2 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4433  Bit 3 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4434  Bit 4 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4435  Bit 5 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4436  Bit 6 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4437  Bit 7 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4440  Verify that no errors are detected when a pattern of all ones is compared to an identical pattern by means of a CHECKWRITE.

4450  Bit 0 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4451  Bit 1 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4452  Bit 2 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4453  Bit 3 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4454  Bit 4 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4455  Bit 5 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4456  Bit 6 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

4457  Bit 7 of sense byte 4 (failing track) was a "1" should be "0". Test applies to H.S. RAD (7212) only.

TST1, 45 CHECKWRITE 2 Test. Find a good track, build a pattern, WRITE this pattern on one sector of the RAD and then alter this pattern so that 1 bit a pass will cause an error.

4510  The RAD could not find a good track.

4516  A good track could not be located by the operation. Check error message.

4520  Bit 0 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4521  Bit 1 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4522  Bit 2 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4523  Bit 3 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4524  Bit 4 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4525  Bit 5 from IOP was a "1" and from the RAD was c "0", but no transmission error was detected.

4526  Bit 6 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4527  Bit 7 from IOP was a "1" and from the RAD was a "0", but no transmission error was detected.

4530  Bit 0 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4531  Bit 1 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4532  Bit 2 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4533  Bit 3 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4534  Bit 4 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4535  Bit 5 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4536  Bit 6 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4537  Bit 7 of sense byte 4 (failing track) was a "0" should be a "1". Test applies to H.S. RAD (7212) only.

4540  Bit 0 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4541  Bit 1 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4542  Bit 2 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4543  Bit 3 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4544  Bit 4 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4545  Bit 5 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4546  Bit 6 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4547  Bit 7 from the IOP was a "0" and from the RAD was a "1", but no transmission error was detected.

4550  Bit 0 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4551  Bit 1 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4552  Bit 2 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4553  Bit 3 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4554  Bit 4 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4555  Bit 5 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4556  Bit 6 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

4557  Bit 7 of sense byte 4 (failing track) was a "0" but should be a "1". Test applies to H.S. RAD (7212) only.

# Section 7

## SIGMA 5 - 9
## REMOVABLE DISK STORAGE
## TEST (724X)

### PROGRAM NO. 705534

## Section 7

## CONTENTS

7

**SUBJECT MODEL** -- Removable Disk Controller, Model number 7240, Removable Disk Storage Units, Model numbers 7242, 7246

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer

**PROGRAM PREREQUISITES**

None

**GENERAL OPERATING PROCEDURES**

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | | |
|------|--------|-----------|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) | |
| Program Directives – Environmental Directives | | | | | | |
| System Environment | SYST, D1, D2, <br><br> H3, H4, H5, H6 <br> ,H7 ...,H17,H18 | D1 <br> D2 <br> H3 <br> H4 <br> H5 <br> H6 <br> : <br> : <br> H17 <br> H18 | Controller model number <br> Revision number <br> Storage Unit Device Address (1st) <br> Available cylinders (1st) <br> Storage Unit Device Address (2nd) <br> Available cylinders (2nd) <br><br><br> Same as H3, H4 except for <br> 8th Storage Unit | 7240 <br> 0 <br> 80 ~ 1FFF <br> 00XY00ZW <br> 80 ~ 1FFF <br> 00XY00ZW <br><br><br> XY · 1st cylinder <br> ZW · last cylinder | | |
| Program Directives – Testing Directives | | | | | | |
| Comprehensive Test (all functional tests, 1 70, and random exerciser Test) | TST0, D1, D2 | D1 <br><br> D2 | Number of ordered sequences executed by random exerciser <br> Number of retries | 0 ~ 99999999 <br><br> 0 ~ 99999999 | 5000 (D1 = 0) <br><br> 0 | |
| Functional Test | TST1 [, D1 [, D2]] | D1 <br> D2 | The first subtest to be executed <br> Last subtest to be executed | 0 (all subtests) ~ 70 <br> 1 | 0 <br> D1 | |
| Random Exerciser Test | TST2, D1, D2 | D1 <br> D2 | Number of cycles to be performed <br> Number of retries before next cycle | D1 ~ 0 <br> D2 ~ 0 | | |
| Utility Test | TST3, D1, D2, D3, H4 | | D1 – Utility Test selection <br> D2 – Function selection or serial number <br> D3 – Retry count; not used if D1 = 3 <br><br> D1 = 1 Surface Test <br>      D2 = 0 Write and then read all sectors <br>      D2 = 1 Write all sectors <br>      D2 = 2 Read all sectors <br>      D2 = 3 Read all sectors (no data check) <br>      D2 = 4 Checkwrite all sectors <br>      D2 = 5 Write and then checkwrite all sectors <br> D1 = 2 Header Test <br>      D2 = 0 Write and then read all headers <br>      D2 = 1 Write all headers <br>      D2 = 2 Read all headers <br>      D2 = 3 Read all headers (no data check) <br> D1 = 3 Disk Initialization <br>      D2 = Pack serial Number <br>      D3 = 0 – Not used <br>      H4 = Date = 00MMDDYY <br> D1 = 4 Flaw A Track <br>      D2 = Alternate Cylinder Address <br>      D3 = Alternate Head ADR | <br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br> 200 ~ 202 <br> 0 - 19 | | |
| Program Directives – Optional Directives | | | | | | |
| Pattern selection (for Utility Test) | DATA, D1, H2, H3 | D1 <br><br><br><br> H2 <br> H3 | = 0, Fixed Pattern <br> = 1, Incremental Pattern <br> = 2, Random Pattern <br> = 3, Current Seek Address <br> Pattern seed (for D1 = 0, 1, 2) <br> Incrementing constant (for D = 1) | 0 ~ 3 <br><br><br><br> 00000000 ~ <br> FFFFFFFF | | |
| Usable surface area limitation | SEEK, D1, D2, D3, D4 | D1 <br> D2 <br> D3 <br> D4 | Starting cylinder address <br> Starting head address <br> Starting sector address <br> Additional sectors to be used after starting address D1, D2, D3 | 0 ~ 202 <br> 0 ~ 19 <br> 0 ~ 5 <br> (0 ~ 81) | | |
| Limitation of Error printouts | LIMT, D1, D2 | D1 <br><br> D2 | = 1 Limit Compare error printouts/sector to D2 <br> Maximum number of printouts (No limit if D2 = 0) | 1 <br><br> D2 ~ 0 | | |
| I/O buffer area definition | MEM [, H1, H2] | H1 <br> H2 | First location of I/O buffer area <br> Last location of I/O buffer area | Obtainable by typing in MEM/ | Area between Diag. Prog. & DPM | |
| I/O Reset | RSET | 0 | | | Not available | |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Surface Test |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM, DATA |
| Subtests | All functional subtests (1 ~ 70) and random exerciser test | 70 subtests (see error messages for the test types) | 1. Exerciser Initiation: Random data written on entire surface<br>2. Random Selection of:<br>  a. Device<br>  b. Order Sequences<br>  c. Buffer Areas<br>  d. Buffer Length<br>  e. Data | WRITE only<br>READ only (Verify data)<br>READ only (No data verification)<br>READ header<br>CHECKWRITE<br>WRITE/READ TEST<br>WRITE header |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX<br>2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

Procedure 2 of Restart Procedure of DPM should normally be used to clear a wait from a watchdog timer trap.

## PROGRAM TEST DESCRIPTION

Test descriptions of each functional test are included at the beginning of each subtest error number in the Functional Subtest and Related Error Message Section.

## ORDER CODES

| | |
|---|---|
| X'00' | STOP |
| X'01' | WRITE |
| X'02' | READ 2 (Report any transmission error at "count done") |
| X'03' | SEEK |
| X'04' | SENSE |
| X'05' | CHECKWRITE |
| X'12' | READ 1 (Terminate data transfer and report any transmission error at end of current sector if error is encountered) |
| X'13' | SELECT TEST MODE |
| X'80' | STOP AND INTERRUPT (at location X'5C') |
| X'09' | HEADER WRITE |
| X'0A' | HEADER READ |
| X'33' | RESTORE CARRIAGE |
| X'23' | RELEASE |

## TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| REM DISK | Data Overrun | Flaw Mark | Sector Unavailable | Unassigned | Header Verification Error | Head On Cylinder | Seek Timeout Error | Header Parity Error |

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| REM DISK | Data Overrun | ◄──── UNASSIGNED ────► | | | Device Interrupt | Head On Cylinder | Seek Timeout Error | Unassigned |

## TEST MODE DATA BYTE



```
                                        Test Modes
                                          ┌───┴───┐
        0    1    2    3    4    5    6    7
      ┌────────────────────────────────────────┐
      │                                         │
      └────────────────────────────────────────┘
         └──────────────┘    ↑    ↑    ↑   ↑
                                              └──Test Mode 1 - Buffer turnaround test
               Unassigned ──────┘       └── Test Mode 2 - Data turnaround at controller side
                                                              of storage unit interface
         Modifier Bit - Parity error reporting check ───┘
```

## ADDRESSING FORMAT

1. The format of the four byte sent to the Disk Pack by a SEEK order is:

Model 7240

| Byte 0 | Byte 1 | Byte 2 | Byte 3 | |
|---|---|---|---|---|
| 0 | Cylinder | 0 | Head | 0 | S |

where S signifies sector number.

2. The format of the bytes received on a SENSE order is:
SENSE (X'04')

The Sense order causes the controller to transmit up to 10 bytes of information to the IOP, as follows:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 | |
|---|---|---|---|---|
| 0 | Cylinder | 0 | Head | 0 | S |

| Byte 4[†] | | Byte 5 | Byte 6 | Byte 7 |
|---|---|---|---|---|
| M | 0 | CS | Diagnostic Status Bytes | |

| Byte 8 | Byte 9 |
|---|---|
| Diagnostic Status Bytes | |

where
  S    signifies sector number
  M    signifies modifier bit
  CS   signifies current sector number

[†]Three bits of byte 4 indicate current sector number, but if the most significant bit (M) is a 1, the arm was in motion at time of sense and current sector number is meaningless. If the head number is nonexistent, (M) will also be a 1.

3. The format of the 8 bytes sent to the Disk Pack by a WRITE header order is:
HEADER WRITE (X'09')
The Header Write order causes the controller to consider all subsequent data bytes as header information. Each header requires the following bytes:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|---|---|---|---|
| Flaw Mark | 0 | Cylinder | 0 | Head |

| Byte 4 | Byte 5 | Byte 6 | Byte 7 |
|---|---|---|---|
| 0 | S | Alt. Cylinder | 0 | Alt. Head | 0 |

Sense Status Bytes 8 and 9

| Byte No. | Bit No. | Function |
|---|---|---|
| 8 | 0 | Data parity error |
| | 1 | Check-Write error |
| | 2 | Sector verification error |
| | 3 | Head verification error |
| | 4 | Cylinder verification error |
| | 5 | Sector address not zero at start of header write operation |
| | 6 | Difference select sent to device |
| | 7 | Sector select sent to device |
| 9 | 0 | Control select sent to device |
| | 1 | Head select sent to device |
| | 2 | Cylinder select sent to device |
| | 3 | Seek forward set |
| | 4 | Read gate sent to device |
| | 5 | Write and erase gate sent to device |
| | 6 | Read cylinder select sent to device |
| | 7 | Not used |

Note: Bytes 8 and 9 are used by diagnostic programs.

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES

### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

System error numbers
8500    Controller did not return to Ready condition after Test Mode order.
8501    Controller not in Test Mode after Test Mode order.  TDV CC = 0.
8502    Controller in Test Mode after resetting Test Mode.  TDV CC = 4.
8510    Controller did not return to Ready condition after Restore order.
8511    Device not on cylinder after a Restore order.

TST1, 01 AIO, HIO, TIO, TDV instruction recognition.

0110    AIO Condition Code error.  No interrupt recognition expected.
0111    HIO Condition Code or Status error.  See print-out.
0112    TIO Condition Code or Status error.  See print-out.  Preceding HIO did not reset Status.
0113    TDV Condition Code error.  See print-out.

TST1, 02 SIO Invalid Order Test

0210    SIO for Invalid order not accepted.  See print-out.
0211    Controller not ready after Invalid order (00 or F8).  Order output and order input phases must be executed.
0212    Status error after Invalid order.  UE expected.
0213    Byte count was changed during execution of Invalid order.  Data phase not required.

TST1, 03 Test Mode Selection Test.  A TDV instruction is used to verify setting and resetting of Test Mode.

0301    Test Mode byte = X'FF'.
0302    Test Mode byte = X'01'.
0303    Test Mode byte = X'02'.
0310    TDV CC2 reset.  Device controller not in Test Mode.
0311    Output buffer changed during Test Mode order (Select).  Data in phase not expected.
0312    TDV CC2 set.  Device controller remains in Test Mode.  CC2 = 0 expected.
0313    Output buffer contains ones after Test Mode order (Reset).
0315    TIO CC1 or CC2 set.  Controller not ready after Test Mode order.
0316    TDV, TIO Status error or byte count error.  See preceding print-out.  Operation: Order out (X'13'), data out (1 byte), order in.
0321, 0322, 0323 TST1, 3 Data byte of FF, 01, and 02 was used during data output phase.  See preceding print-out.

TST1, 04 Interrupt generation and HIO, AIO Instruction Test.  The following orders will be issued: X'00', X'13' (data byte = 01), X'1' (data byte = 00) in order to set Interrupt Pending due to IUE, ICE and IZC respectively.  Each order will be repeated once to allow resetting of IP with an HIO and an AIO instruction.

0410    TIO Status error during TST1, 4 after SIO.  IP must be set and controller and device must be ready.  IUE, ICE, and IZC flags are used.
0411    HIO did not reset IP.  No reset generated.
0412    AIO Status error during TST1, 4.  Preceeding SIO resulted in IP.
0413    AIO did not reset IP.  No reset generated.
0421, 0422, 0423 TST1, 4 IOP flags for IUE, ICE, and IZC used respectively.  See print-out.

TST1, 05 IO Interrupt Test.  A Test Mode order with ICE flag will be issued and tests will be performed to verify that the program is only interrupted if the IO Interrupt is armed and enabled.

0510    TIO Status error during TST1, 5 after SIO.  IP must be set.  IO Interrupt is disarmed/disabled.  Program should not be interrupted.

0511    Program was interrupted while IO Interrupt was disarmed/disabled.
0512    Program was interrupted while IO Interrupt was armed/disabled.
0513    Program was not interrupted while IO Interrupt was armed/enabled.

TST1, 06 Command Chaining Test.  Two Test Mode orders will be Command Chained.  Command Chaining will be tested.  Invalid order Command Chained to a Test Mode order should not result in Command Chaining.

0610    TIO Status error during TST1, 6 after Command Chaining or Command Chaining not performed.  See preceding printout.
0611    TIO Status error during TST1, 6.  Status error or Command Chaining not inhibited by UE from Invalid order.

TST1, 07 FAM Write/Read Byte Count Test.  Write and Read orders with byte counts varying sequentially from 1 to 16 are issued in Test Mode 1.  Zero byte count expected.

0710    Controller not ready after Write order in TM1.
0711    Controller not ready after Read order in TM1.
0712    Byte count not equal to zero after Write order in TM1.
0713    Byte count not equal to zero after Read order in TM1.

TST1, 08 FAM Write/Read Data Test.  Write Command-Chain Read orders will be issued with varying data pattern.  The Read data will be compared to the Write data.  During the 2nd part of the test 4 Write/CC/Read orders with counts of 13 will be issued to test the byte alignment logic.

0810    Controller not ready after Write/CC/Read order in TM1.
0811    Compare errors during TST1, 8.  Output buffer: IOBF1, Input buffer: IOBUF.
0812    Controller not ready after Write/CC/Read (BC = 13) Test Mode 1.
0813-0816   Read Data compare error following Write/CC/Read (BC = 13)
        If last digit is 3, data started on word boundary
        If last digit is 4, data started at byte 1
        If last digit is 5, data started at byte 2
        If last digit is 6, data started at byte 3

TST1, 09 Test Mode 2 - Seek Order Byte Count Test.  Seek orders with byte counts of 3, 4, 5 are issued to the controller and the status response is tested.

0910    Controller not ready after Seek order in Test Mode 2.
0911    Status error after Seek order in Test Mode 2.  Expected: IL, UE, zero byte count, on-cylinder.  See printout.
0912    Status error after Seek order in Test Mode 2.  Expected: Not IL, zero byte count, on cylinder.  See printout.
0913    Status error after Seek order in Test Mode 2.  Expected: IL, byte count = 1, on-cylinder.  See printout.
0914    Output buffer (:IOBF1) altered during Seek in TM2.

TST1, 10 Test Mode 2 - Seek Order Interrupt Address Test.  Seek orders will be to device 0 through 7 in sequence and the address returned with the AIO Status will be verified.  Change above mask from X'04000000' to X'0C000000' if Device Interrupt Engineering Order is available.

1010    Status error after Seek order with Interrupt Modifier bit.  Expected: IP, zero byte count, on cylinder.  See printout.
1011    AIO Status error after Seek order with Interrupt Modifier bit.  IP set prior to AIO.  Expected: Address verification.  See printout.
1012    Preceding AIO did not clear Seek complete interrupt (TIO/IP 0).

TST1, 13 Test Mode 2 - Sense Order Byte Count Test.  Sense orders with byte counts of 1 through 11 are issued to the controller and the Status Response is tested.

1310    Controller not ready after Sense order in Test Mode 2.

TST1, 13 (Continued)

1311 Status error after Sense order in Test Mode 2. No unusual status expected. See print-out.

1312 Byte count not equal to zero after a Sense order with a byte count ≤ 10. See print-out.

1314 First 8 bytes of input buffer (IOBF1) not changed during Sense order. Data input expected.

TST1, 15 Test Mode 2 – Seek Tag Line Test. See/Command Chain/ Sense orders are executed and the Tag Line information in byte 8 of the Sense data is verified.

1510 Controller not ready after Seek/CC/Sense order in Test Mode 2.

1511 Status error after Sense order or Command Chaining not performed. See print-out

1512 Seek Tag Line error or Sense order not functioning properly. Sense buffer: IOBF1. See print-out.

TST1, 16 Test Mode 2 – Head and Sector Address Test. Seek/CC/ Sense orders are issued sequentially varying the Device Address from 0 – 7. Sense data is verified. Sense orders are issued sequentially to all devices to insure that the addresses are not changed. The same sequence is repeated with the Device Address varied from 7 – 0. The complement of the data pattern in pass 1 is used in Pass 2. A unique pattern is used for each device.

1610 Controller not ready after Seek/CC/Sense order in Test Mode 2.

1611 Controller not ready after Sense order in Test Mode 2.

1620-1627 Head and Sector Address obtained during Sense not equal to original data. Last digit of error number indicates Device Address used. Address sequence 0 - 7. Order sequence: Seek/ CC/Sense.

1630-1637 Head and Sector Address obtained during Sense not equal to original data. Check addressing of Head and Sector FAM. Last digit of error number indicates Device Address used.

1640-1647 Same as 1620-1627. Address sequence 7 - 0.

1650-1657 Same as 1630-1637.

TST1, 17 Test Mode 2 – Head and Sector Address Validy Test. Seek and Sense are issued 203 times varying the Sector Address from 0-7 and the Head Address from 0-25. Sector unavailable will be tested for Sector Address > 5 and Head Address > 19. The combined Sector and Head Address which is returned as Cylinder Address during Seek will be verified.

1710 Controller not ready after Seek order in Test Mode 2.

1711 Status error after Seek order in Test Mode 2 with illegal sector Address (7). UE, sector unavailable, on cylinder expected.

1712 See 1711. Illegal Head Address was issued during Seek.

1713 Status error after Seek order in Test Mode 2. Legal Head and Sector Address were used. See print-out.

1714 Controller not ready after Sense order in Test Mode 2.

1715 Seek/Sense compare error. The Head/Sector Address was not returned correctly as the Cylinder Address. See print-out.

TST1, 19 Test Mode 2 – Cylinder Difference Logic Test. Seek and Sense orders are issued systematically varying the Cylinder and Head/Sector Address. 5 passes will be performed:
1. Cyl and Hd/Sect = 0 - 202.
2. Cyl = 0 - 202, Hd/Sect = 0
3. Cyl = 0, Hd/Sect = 0 - 202
4. Cyl = 202 - 0, Hd/Sect = 0
5. Cyl = 0, Hd/Sect = 202 - 0

1910 Controller not ready after Seek order in Test Mode 2.

1911 Controller not ready after Sense order (Byte count = 10) in Test Mode 2.

1912 The difference between Head/Sector and the Cylinder Address returned in byte 7 of the Sense order is not correct. See print-out.

1913 Controller not ready after the 2nd Seek order in Test Mode 2. Two Seek orders are required to obtain the correct difference in byte 7 of the Sense data.

TST1, 20 Test Mode 2 – Illegal Cylinder Address Test. Seek orders are issued with illegal Cylinder Address (203 - 255) and the Status Response is verified.

2010 Controller not ready after Sense order in Test Mode 2.

2011 Status error after Seek order in Test Mode 2 with Illegal Cylinder Address (203 - 255). UE, sector unavailable, on cylinder expected.

TST1, 23 Test Mode 2 – Restore Order Test. A Seek/CC/Restore and Sense order sequence is sequentially issued to all devices (0 - 7). The test verifies the status after the Restore orders and verifies with a Sense order (Byte count = 10) that the Head and Sector Address in the FAM are cleared to zero and that the Restore order generated the correct Tag Lines.

2310 Controller not ready after Seek/CC/Restore orders in Test Mode 2.

2311 Status error after Restore order in Test Mode 2. Not UE, byte count = 1 (no changes). See print-out.

2312 Controller not ready after Sense order in Test Mode 2.

2313 Bytes 2 (Head) and 3 (Sector) of Sense data not 0. Preceding Restore order did not clear controller registers (FAM).

2314 Restore Tag Line error. Sense buffer: IOBF1. See print-out.

TST1, 24 Test Mode 2 – Release Order Test. A Release order and a Sense order is issued. The test verifies the status after the Release and verifies with a Sense order (Byte count = 10) that the Release order generated the correct Tag Lines.

2410 Controller not ready after Release order in Test Mode 2.

2411 Status error after Release order in Test Mode 2. Not UE, byte count = 1 (No change) expected. See print-out.

2412 Controller not ready after Sense order in Test Mode 2.

2413 Release Tag Line error. Sense buffer: IOBF1. See print-out.

TST1, 25 Test Mode 2 – Read Order Tag Line and Data Test. Read orders X'02' and X'12' are issued in sequence. The status and byte count are verified. The Read data is compared to the expected information. A Sense order verifies that the Tag Lines are correctly generated for a Read order.

2510 Controller not ready after Read order (02) in Test Mode 2.

2511 See 2510. Read order (12).

2512 Status error after Read order in Test Mode 2. Not UE, not IL, not TE, byte count = 0 expected. See print-out.

2513 See 2512. Read order (12).

2514 Data compare error in Test Mode 2; Read order (02). See print-out.

2515 See 2514. Read order (12).

2516 Controller not ready after Sense order in Test Mode 2.

2517 Read (02) Tag Line error. Sense buffer: IOBF1. See print-out.

2518 See 2517. Read order (12).

2519 Status error in diagnostic Sense byte (byte 8 of Sense data) defines Read error.

2520 See 2519. Read order (12).

TST1, 26 Test Mode 2 – Read Order Incorrect Length Test. Read orders are issued with byte count sequentially varied from 1008 to 1025 (not 1024). The status will be verified. For byte counts < 1024 the test verifies that the controller terminates data-in at the correct byte count.

2610 Controller not ready after Read order (02) in Test Mode 2.

2611 Remaining byte count after Read order with incorrect length not zero. See print-out.

2612 Status error after Read order in Test Mode 2. IL expected. See print-out.

2613 Data compare error in Test Mode 2; Read order (02). For byte count < 1024 the remaining bytes in input buffer must be zero.

TST1, 27 Test Mode 2 – Read Order/Head and Sector Incrementation Test. Seek/CC/Read and Sense order sequences are issued with a Read byte count of 1024. Sector and Head Address incrementation is verified.

TST1, 27 (Continued)

2710  Controller not ready after Seek/CC/Read (02) orders in Test Mode 2.
2711  Status error after Seek/CC/Read in Test Mode. No abnormal status expected. See print-out.
2712  Controller not ready after Sense order in Test Mode 2.
2713  Address received during Sense not expected. Head or Sector Address may not increment properly. See print-out.

TST1, 28 Test Mode 2 – Read Order Cylinder Boundary Test. A Read order with a byte count of 1025 is issued starting at Head 19, Sector 5. Read operation will terminate after 1 sector and sector unavailable will be reported.

2810  Controller not ready after Seek/CC/Read (02) orders in Test Mode 2.
2811  Status error after Read order (Seek Address = Head 19. Sector 5, byte count = 1025). UE, sector unavailable, byte count = 1 expected: See print-out.

TST1, 29 Test Mode 2 – Header Read Order Test. Seek/CC/Header Read orders sequences are issued with Header Read byte count of 8. The status and byte count are verified. The Header Read data is compared to the expected information. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address are incremented correctly.

2910  Controller not ready after Seek/CC/Header-Read orders in Test Mode 2.
2911  Status error after Header Read order. No abnormal status expected. See print-out.
2912  Header data compare error in Test Mode 2. See print-out.
2913  Controller not ready after Sense order in Test Mode 2. See print-out.
2914  Header Read Tag Line error. Sense buffer: IOBUF. See print-out.
2915  Status error in diagnostic Sense byte (Byte 8 of Sense data) defines Header Read error.
2916  Address received during Sense not expected. Head or Sector Address may not increment properly. See print-out.

TST1, 30 Test Mode 2 – 120 Sector Header Read Test. A Seek/CC/ Header Read order with a Header Read byte count of 960 is issued. The Header data is verified. No data error indicates that the Head and Sector Incrementation Logic performs correctly.

3010  Controller not ready after Header Read order in Test Mode 2.
3011  Byte count not zero after Header Read order (960 bytes).
3012  Status error after Header Read order. No abnormal status expected.
3013  Header data compare error in Test Mode 2. See print-out.

TST1, 31 Test Mode 2 – Header Read Byte Count Test. Header Read orders with byte counts of 7 and 9 are issued to the controller and the Status Response is tested.

3110  Controller not ready after Header Read order in Test Mode 2.
3111  Status error after Header Read order (byte count 7). Expected: IL, no UE, byte count = 0. See print-out.
3112  See 3111. Header Read order byte count = 9.

TST1, 32 Test Mode 2 – Header Read Order Cylinder Boundary Test. A Header Read order with a byte count of 9 is issued starting at Head 19 Sector 5. Read operation will terminate after one sector and sector unavailable will be reported.

3210  Controller not ready after Header Read order in Test Mode 2.
3211  Status error after Header Read order (Seek address = Head 19, Sector 5, byte count = 9). UE, sector unavailable, byte count = 1 expected.

TST1, 35 Test Mode 2 - Header Write Order Test. Seek/CC/Header Write order sequences are issued with Header Write byte counts of 48. The Header data consists of a X'A5A5A5A5' pattern. The status and byte count are verified. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increment correctly.

3510  Controller not ready after Seek/CC/Header-Write orders in Test Mode 2.
3511  Status error after Header Write order. No abnormal status expected. See print-out.
3512  Controller not ready after Sense order in Test Mode 2.
3513  Header Write Tag Line error. Sense buffer: IOBF1. See print-out.
3514  Status error in diagnostic Sense byte (byte 8 of Sense data) defines Header Write error.
3515  Address received during Sense not expected. Head or Sector Address may not increment properly. See print-out.

TST1, 36 Test Mode 2 - 120 Sector Header Write Test. A Seek/CC/ Header Write order sequence with a Header Write byte count of 960 is issued. A Sense order is issued to verify that the Head and Sector Address are incremented to Head 20 Sector 0.

3610  Controller not ready after Seek/CC/Header-Write orders in Test Mode 2.
3611  Byte count not zero after Header Write order (960 bytes).
3612  Status error after Header Write order. No abnormal status expected.
3613  Controller not ready after Sense order in Test Mode 2.
3614  Address received during Sense not expected. Header or Sector Address have not been incremented past Head 19 Sector 5.

TST1, 37 Test Mode 2 - Header Write Byte Count Test. Header Write orders with byte counts of 7 and 9 are issued to the controller and the Status Response is tested.

3710  Controller not ready after Seek/CC/Header-Write order in Test Mode 2.
3711  Status error after Header Write order (byte count 4). Expected: IL, no UE, byte count = 0. See print-out.
3712  See 3711. Header Write order byte count = 9.

TST1, 38 Test Mode 2 - Header Write Order Cylinder Boundary Test. A Header Write order with a byte count of 49 is issued starting at Head 19 Sector 0. Write operation will terminate after 6 sectors and sector unavailable will be reported.

3810  Controller not ready after Header Write order in Test Mode 2.
3811  Status error after Header Write order (Seek Address = Head 19, Sector 0, byte count = 49). UE, sector unavailable, byte count = 0 expected.

TST1, 39 Test Mode 2 - Header Write Starting Address Test. Header Write orders with Starting Sector Address of 0 through 5 are sequentially issued. For all Starting Addresses except 0, byte 8 of the Sense data will indicate Header Address error.

3910  Controller not ready after Header Write order in Test Mode 2.
3911  Status error after Header Write order. No abnormal status expected.
3912  Controller not ready after Sense order in Test Mode 2.
3920-3925 Status error in diagnostic Sense byte (byte 8 of Sense data). The least significant digit of error number reflects the Starting Sector Address of the Header-Write operation. Header-Address error is expected for all Starting Address except Sector 0.

TST1, 40 Test Mode 2 – Write Order Test. Seek/CC/Write order sequences are issued with Write byte count 3 or 1024. The Write data consists of byte values starting at 224, with each successive byte = byte (N) + 1. These values reflect the byte counter in the controller at the time of writing each byte. Status and byte count are verified. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increment correctly.

4010    Controller not ready after Seek/CC/Write orders in Test Mode 2.
4011    Status error after Write order. No abnormal status expected.
4012    Controller not ready after Sense order in Test Mode 2.
4013    Write Tag Line error. Sense buffer: IOBF1. See print-out.
4014    Status error in diagnostic Sense byte (byte 8 of Sense data) defines Write error.
4015    Address received during Sense not expected. Head and Sector Address may not increment properly. See print-out.

TST1, 41 Test Mode 2 – Write Order Incorrect Length Test. Seek/CC/Write order sequences are issued with byte counts sequentially varied from 1008 to 1025 (not 1024). The status will be verified.

4110    Controller not ready after Write order in Test Mode 2.
4111    Remaining byte count after Write order with Incorrect Length not zero. See print-out.
4112    Status error after Write order in Test Mode 2. IL expected. See print-out.

TST1, 42 Test Mode 2 – Write Order Cylinder Boundary Test. A Write order with a byte count of 1025 is issued starting at Head 19 Sector 5. The Write operation will terminate after 1 sector and sector unavailable will be reported.

4210    Controller not ready after Write order in Test Mode 2.
4211    Status error after Write order (Seek Address = Head 19, Sector 5 byte count 1025). UE, sector unavailable, byte count = 0 expected.

TST1, 45 Test Mode 2 – Check-Write Order Test. Seek/CC/Check-Write order sequences are issued with byte counts of 1024. The Check Write data consists of byte values starting at 224, with each successive byte = byte (N) +1. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increments correctly.

4510    Controller not ready after Seek/CC/Check-Write orders in Test Mode 2.
4511    Status error after Check-Write order. No abnormal status expected. See print-outs.
4512    Controller not ready after Sense order in Test Mode 2.
4513    Check-Write Tag Line error. Sense buffer: IOBF1. See print-out.
4514    Status error in diagnostic Sense byte (byte 8 of Sense data) defines Check-Write error.
4515    Address received during Sense not correct. Head or Sector Address may not increment properly. See print-out.

TST1, 46 Test Mode 2 – Check-Write Order Incorrect Length Test. Seek/CC/Check-Write order sequences are issued with byte counts sequentially varied from 1008 to 1025 (not 1024). The status will be verified.

4610    Controller not ready after Seek/CC/Check-Write order in Test Mode 2.
4611    Remaining byte count after Check-Write order with Incorrect Length not zero. See print-out.
4612    Status error after Check-Write order in Test Mode 2. IL expected. See print-out.

TST1, 47 Test Mode 2 – Check-Write Order Cylinder Boundary Test. A Check-Write order with a byte count of 1025 is issued starting at Head 19 Sector 5. The Check-Write operation will terminate after one sector and sector unavailable will be reported.

4710    Controller not ready after Check-Write order in Test Mode 2.
4711    Status error after Check-Write order (Seek address = Head 19, Sector 5, byte count 1025). UE, sector unavailable, byte count = 0 expected.

TST1, 48 Test Mode 2 – Check-Write Transmission Error Test. Seek/CC/Check-Write order sequences with byte counts of 2048 are issued. The Check-Write data consists of byte values starting at 224 (X'E0'), with each successive byte = byte (N) + 1. During the first 8 passes one bit in byte 32 (X'FF') is sequentially dropped starting with bit 0 ending with bit 7. During the 2nd 8 passes one bit in byte 33 (X'00') is sequentially picked-up starting with bit 0, ending with bit 7. The test verifies that a single bit failure in a sector is detected and reported as TE and that the operation terminates after the first sector. The remaining byte count must be ≥ 1000.

4810    Controller not ready after Seek/CC/Check-Write order in Test Mode 2.
4811    Remaining byte count after Check-Write order (2048 bytes) less than 1008. Check-Write operation did not terminate after one sector.
4812    Controller not ready after Sense order in Test Mode 2.
4813    Address received during Sense not correct. Head or Sector Address may have been incremented by two sectors.
4814    Status error in diagnostic Sense byte (byte 8 of Sense data) should indicate Check-Write error.
4820–4827 Status error after Check-Write order. TE and not IL or UE expected. The least significant digit of the error number indicates which bit of byte 32 of the Check-Write data was dropped to induce a Check-Write error.
4830–4837 See 4820–4827. The least significant digit of the error number indicates which bit of byte 33 of the Check-Write data was added to induce a Check-Write error.

TST1, 49 Test Mode 2 – Halt On Transmission Error Test. Seek/CC/Write order sequences with byte counts of 1020 are issued to test setting of UE, IL and IOP/Halt. Seek/CC/Check-Write order is issued to check setting of TE.

4910    Controller not ready after Seek/CC/Write (or Check-Write) in Test Mode 2.
4911    Status error after Write order in Test Mode 2. UE, IL and IOP/Halt setting expected.
4912    Status error after Write order in Test Mode 2. IL and not UE and not IOP/Halt setting expected.
4913    Status error after Check-Write order in Test Mode 2. UE, TE and IOP/Halt setting expected.

TST1, 50 Test Mode 3 (Parity) – Read Order 12 Parity Test. A Sense/CC/Read 12 order sequence is issued with a Read byte count of 2048. The controller will generate a parity error. The test verifies the status (TE and not UE) and verifies with a Sense order that the Read order terminated after a sector. The remaining byte count must be = 1024.

5010    Controller not ready after Seek/CC/Read 12 order in Parity Test Mode.
5011    Remaining byte count after Read 12 order (2048 bytes) not equal to 1024. Read 12 operation did not terminate after one sector.
5012    Status error after Read 12 order. TE and not IL or UE expected. See Print-out.
5013    Controller not ready after Sense order in Parity Test Mode.
5014    Status error in diagnostic Sense byte (byte 8 of Sense data) should indicate data parity error.
5015    Address received during Sense not correct. Head or Sector Address may have been incremented by 2 sectors.

TST1, 51 Test Mode 3 (Parity) - Read Order 02 Parity Test. A Sense/
CC/Read 02 order sequence is issued with a Read byte count
of 3072 (3 data-chain operation). The test verifies that
Reading continues until the byte count = zero. The
expected status is TE, not UE.

5110    Controller not ready after Seek/CC/Read02/DC/Read02/DC/
        Read02 in Parity Test Mode.
5111    Status error after Read02 order. TE and not IL or UE and byte
        zero and Current Command Address = Starting Address + 3
        expected.
5112    Controller not ready after Sense order in Parity Test Mode.
5113    Address received during Sense not correct. Head or Sector
        Address did not increment correctly.

TST1, 52 Normal Mode - Restore Order Test. A Restore order is
issued to the storage unit. The test verifies that the
controller and device are ready and that positioning is
complete and that no time out error has occurred.

5210    Controlled not ready after Restore order.
5211    On cylinder bit TDV(5) not received after Restore order.
5212    Status error after Device order. See print-out.

TST1, 53 Normal Mode - Seek Order Test. A Restore order is issued
to the storage unit. The test proceeds to issue Seek orders
for all sectors on cylinder 0. No head motion is involved
except possibly during the Restore order. The test verifies
that Seek orders can be completed without errors.

5310    Controller not ready after Seek order.
5311    On-cylinder bit TDV(5) not received after Seek order. No head
        motion required.
5312    Status error after Seek order. See print-out.

TST1, 54 Normal Mode - Release Order Test. A Release order is
issued. The test verifies the status after the release.

5410    Controller not ready after Restore order in normal mode.
5411    Status error after Restore order in normal mode. Not UE, byte
        count = 1 (no change) expected. See print-out.

TST1, 55 Header Read - Failure Isolation Test. A Restore order is
issued to position the heads at cylinder 0. Seek/CC/
Header-Read sequences will be issued for all 120 sectors of
cylinder 0. No errors will be reported until all operations
are completed. A summary of all errors will be printed.
The test will proceed to loop on the first failure with
immediate error print-outs. Information other than zeros
in the flaw byte or alternate Address byte will not be
considered an error.

5510    Controller not ready after Seek/CC/Header Read order.
5511    Status error after Header-Read order. See print-out.
5512    Compare error of Header data. Bytes 0, 5 and 6 of each
        Header are not tested.

TST1, 56 Normal Mode - Sense Order/Angular Position. A Restore
order is issued to the storage unit. The test issues a Sense
order and verifies the status. The test proceeds to issue up
to 6 Sense orders in order to verify angular position 0.
Following position 0, 5 Sense orders are issued to verify
angular position 1-5.

5610    Controller not ready after Sense order.
5611    Status error after Sense order. See print-out.
5612    Controller not ready after Sense order.
5613    6 attempts failed to find angular position of 0 in byte 4 of
        Sense data.
5621-5625  Controller not ready after Sense order. The least
        significant digit of the error number indicates the current
        angular position expected in the Sense data.
5631-5635  The expected angular position as indicated by the least
        significant digit of the error number not in byte 4 of Sense
        data.

TST1, 57 Normal Mode - Sense Order Test. A Restore order is issued
to position the heads at cylinder 0. Seek/CC/Sense
sequences will be issued for all 120 sectors of cylinder 0.
The test verifies that the Address returned during the Sense
operation is correct and that normal status is returned.

5710    Controller not ready after Sense order.
5711    Status error after Sense order. See print-out.
5712    Compare error of Seek and Sense data. See print-out.
5713    Status error in diagnostic Sense byte (byte 8 of Sense data) should
        indicate no errors.

TST1, 58 Sequential Head Positioning Test. Sequential Seek orders
are issued to the disk storage unit. After verifying successful
completion of each Seek order, a Sense order is issued to
verify the Seek operation. If a Header parity error is
detected during the Sense order, the Sense operation will be
automatically retried six additional times before an error is
reported. If the cylinder Address obtained is correct, the
next Seek/Sense sequence will be initiated. On retries
after a cylinder compare error, the Seek Address will be
decremented by 1 (not < 0) and a Restore order will be issued
prior to retry.

5810    Controller not ready after a Seek order.
5811    Controller not ready after Sense order. Arm was in motion
        execution of Sense order.
5812    Arm in motion bit in byte 4 of Sense data not received.
5813    On cylinder bit TDV(5) not received after Seek order. The Seek
        order intiated head motion.
5814    Controller not ready after Sense order. Arm motion was
        previously completed. TDV(5) = 1.
5815    All six Sense orders issued to the drive unit indicate that a
        Header parity error was detected.
5816    Compare error of Seek and Sense data. See print-out.

TST1, 60 Complex Head Positioning, Seek Access Timing and Seek
Complete Interrupt Test. This test consists of four passes.
The passes differ by the type of head motion.
    1.  Seek (M) Sense Seek (N) Sense 203 times. M varies
        from 0 to 202, N is always = 0.
    2.  Seek (M) Sense Seek (N) Sense 203 times. M is always
        202. N varies from 202 to 0.
    3.  Seek (M) Sense Seek (N) Sense 203 times. M varies
        from 0 to 202, N varies from 202 to 0.
    4.  Seek (R) Sense Seek (R) Sense 203 times. R is a random
        number.
    During retries the last successful Seek/Sense sequence is
    repeated. Average Seek access time is computed and if it
    exceeds the limit, it is printed out. The test is initialized
    if retry is requested.

6010    Controller not ready after Seek order.
6011    Expected Seek complete interrupt was not received.
6012    Status error after Seek complete interrupt has been received.
        See print-out.
6013    Controller not ready after Sense order.
6014    Header parity error indicated by bit 7 of TDV following Sense
        orders. The Sense order has been issued 7 times to automatically
        recover from the problem. Possible bad Headers on the disk.
6015    Head positioning error. See preceding print-out. The expected
        Sense data defines the Seek Address. The observed Sense data
        defines the Current Address in the controller. Prior to the Seek
        operation.
6016    Average Head positioning time greater than 95 msec. All Seek
        operations in this test are used in the computation of the average
        time.

TST1, 63 Comprehensive Write/Read/Checkwrite Test. During the
first phase of this test, attempts are made to locate a cylinder
with error-free Headers. The cylinders used are determined
by the SYST-directive entry for each device. Once a good
cylinder has been located, a Write/Read/Checkwrite pass
will be performed 3 times, each time with a different pattern.
Pass 1: Fixed pattern of X'AA55AA55'
Pass 2: Incremented pattern of X'00010203', X'04050607',
        X'08090A0B'

TST1, 63 (Continued)

Pass 3: Current Seek Address X'00000000' for cyl = 0, HD: 0, Sect 0, X'00NN0803' for cyl NN, HD 08, Sect 3. Any recoverable error (6 retries are automatically attempted) or solid failure will cause the selection of another cylinder. The objective of this procedure is to avoid looping on an error which may be caused by surface flaws.

6310    Attempts to find a cylinder (120 sectors) with good Headers and no assigned Alternate Addresses not successful. Program used only those cylinders which were made available to the program with the SYST directive.

6311    Controller not ready after Header Read order of 120 sectors.

6312    Byte count after Header Read order not reduced to zero.

6313    Status error after Header Read order. No unusual status expected.

6314    Header data compare error. See print-out. If a flaw byte or an Alternate Address is found in the Header, the current cylinder will not be used for the Write/Read/Checkwrite portion of this test.

6315    Header Read operation not successful for current cylinder. Errors 6311 through 6314 describe the nature of the failure. Next cylinder will be automatically selected.

6320    Controller not ready after Seek order.

6321    Controller not ready after Sense order.

6322 .   Seek/Sense compare error. See expected and observed data. The Sense order was issued after a Write, Read, or Checkwrite order. The Sense data should reflect the current Address.

6330    Controller not ready after Write order. Preceding Seek order successful.

6331    Status error after Write order. No unusual status expected. The Write order will be automatically retried 6 times.

6332    Status error after Write order. The diagnostic Sense byte (byte 8 of Sense data) should indicate no errors.

6333-6335  See 6330 through 6332, respectively. Current order was a Read. The sector in error may have been incorrectly written.

6336    Read compare error. See print-out. The error may result from incorrect writing of the data.

6337-6339  See 6330 through 6332, respectively. Current order was a Checkwrite. The sector in error may have been incorrectly written if Read errors are detected.

6340    Write errors on current cylinder. If Sense Switch 1 is reset and 3 set, the Read and Check-Write portion of this test will be skipped and a new cylinder will be selected. Fixed pattern of X'AA55AA55AA5...'.

6341    Read errors on current cylinder. If Sense Switch 1 is off and 3 on, the Checkwrite portion of this test will be skipped and a new cylinder will be selected. Fixed pattern of X'AA55AA55AA5...'.

6342    Checkwrite errors on current cylinder. If Sense Switch 1 is off and 3 on, a new cylinder will be selected. Fixed pattern of X'AA55AA55AA5...'.

6343    See 6340. Write errors. Incremented pattern X'00010203040506..'

6344    See 6341. Read errors. Incremented pattern X'00010203040506..'

6345    See 6342. Check-Write errors. Incremented pattern X'00010203040506...'.

6346    See 6340. Write errors. Current Seek Address used as pattern.

6347    See 6341. Read errors. Current Seek Address used as pattern.

6348    See 6342. Check-Write errors. Current Seek Address used as pattern.

TST1, 64 Short Record Write Test. During the first phase of this test, attempts are made to locate a sector which can be recorded and verified. Once a good sector has been located, a 4 byte record is written and verified with a Read order. Bytes 4 through 1023 are expected to be zero.

6410    Controller not ready after Seek/CC/Write order.

6411    Status error after Write order. Normal termination expected.

6412    Controller not ready after Seek/CC/Read order.

6413    Status error after Read order. Normal termination expected.

6414    Data compare error on current sector.

6415    Controller not ready after Seek/CC/Write order (4 bytes). The remaining bytes of the current sector should contain zeros.

6416    Status error after Write order (4 bytes). Only IL is expected.

6417    Controller not ready after Seek/CC/Read order (1024 bytes). The preceding Write order recorded only 4 bytes of data.

6418    Status error after Read order. Normal termination expected.

6419    Data compare error on current sector. If word count of compare error MSG > 0, the controller failed to write zeros for bytes 4 through 1023.

6420    Write or Read errors on current sector. Another sector, if available, will be selected.

6430    Device not ready after Seek/CC/Read (BC 253)/CC/Sense.

6431    Status error after Seek/CC/Read (BC 253)/CC/Sense. Normal termination expected.

6432    Device failed to report correct sector on sense at least once in 256 cycles of: Seek/CC/Read (BC 253)/CC/Sense.

TST1, 65 Header Write Test. This test will only be executed if cylinder 202 is made available to the test program with the SYST directive. The test will write all Headers on cylinder 202 for Heads 16 through 19. The original Headers will be saved at the start of the test and restored at the end of the test.

6510    Controller not ready after Seek/CC/Header Write order (6 sectors).

6511    Status error after Header Write order. Normal termination expected.

6512    Controller not ready after Seek/CC/Header Read order (6 sectors).

6513    Status error after Header Read order. Normal termination expected. Headers may have been incorrectly written.

6514    Header compare errors. Each Header consists of 8 bytes. Headers may have been incorrectly written.

6515    Controller not ready after Sense order.

6516    Status in diagnostic Sense byte (byte 8 Sense data) should indicate no errors.

6517    Attempts to save 24 Headers starting at cylinder 202, Head 16, Sector 0 not successful. Remainder of this test will be skipped.

TST1, 66 Header Error Detection Test. This test will only be executed if cylinder 202 is made available to the test program with the SYST directive. The test consists of the following 3 sections:

1. Headers with flaw bytes are written for cylinder 202, Head 17 Sense, Header Read, and Read orders are issued to verify the detection of the flaw byte and setting of UE (UE will not be set during Header Read).

2. Headers with a cylinder address of 225 are written for cylinder 202, Head 18. A Sense order is issued to verify the setting of verification error, UE, and cylinder compare error (byte 8 of Sense data).

3. Headers for cylinder 202, Head 19 contain the following information: Sector 0 OK, Sector 1 OK, Sector 2 OK, Sector 3 cylinder wrong, Sector 4 Head wrong, Sector 5 sector wrong.

4. Header Read and Read orders are issued to verify that cylinder, head, and sector compare errors are set (byte 8 of Sense data) and that the orders terminate correctly after detection of an erroneous Header. The original Headers will be saved at the start of the test and restored at the end of the test.

6610    See 6517

6611    Controller not ready after Seek/CC/Header Write order (24 sectors).

6612    Status error after Header Write order. Normal termination expected.

6620    Controller not ready after Seek/CC/Sense order. All six headers starting at cylinder 202, Head 17 have flaw bytes recorded from preceding Write Pass.

6621    Status error after Sense order. UE, flaw byte (TDV bit 1) and not TE expected. All six headers starting at cylinder 202, Head 17 have flaw bytes recorded from preceding Write Pass.

6622    Controller not ready after Seek/CC/Header Read order. See also 6620.

6623    Status error after Header Read order. Flaw byte, not UE or TE expected. See also 6621.

6624    Controller not ready after Seek/CC/Read order. See also 6620.

TST1, 66 (Continued)

6625 Status error after Read order. UE, flaw byte (TDV bit) and not TE expected. See also 6621.

6626 Controller not ready after Seek/CC/Sense order. All six headers starting at cylinder 202, Head 18 have a wrong cylinder Address (cylinder 255) recorded from preceding Write order.

6627 Status error after Sense order. UE, verification error (TDV bit 4) not UE, and byte count - 0 expected. See 6626 for header data.

6628 Controller not ready after Seek order.

6629 Controller not ready after Sense order. Status after Sense order will not be tested.

6630 Controller not ready after Header Read order at cylinder 202, Head 19, Sector 3. Header of Sector 3 was previously written with wrong cylinder Address.

6631 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6630 for Seek Address and data.

6632 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6630 for Seek Address and data.

6633 Controller not ready after Header Read order at cylinder 202, Head 19, Sector 4. Header of Sector 4 was previously written with wrong Head Address.

6634 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6653 for Seek Address and data.

6635 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Head compare error. See also 6633 for Seek Address and data.

6636 Controller not ready after Header Read order at cylinder 202, Head 19, Sector 5. Header of Sector 5 was previously written with wrong Sector Address.

6637 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6636 for Seek Address and data.

6638 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6636 for Seek Address and data.

6639 Controller not ready after Header Read order (17 bytes) at cylinder 202, Head 19, Sector 2. Header of Sector 2 OK, Header of Sector 3 was previously written with the wrong Cylinder Address.

6640 Status error after Header Read order (17 bytes). UE, verification error, and byte count = 1 expected. Headers for Sectors 2 and 3 should be read. See also 6639 for Seek Address and data.

6641 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6639 for Seek Address and data.

6642 Controller not ready after Read order (1 byte) at cylinder 202, Head 19, Sector 3. Header of Sector 3 was previously written with wrong Cylinder Address.

6643 Status error after Read order. UE, verification error, byte count 1 expected. See also 6642 for Seek Address and data.

6644 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6642 for Seek Address and data.

6645 Controller not ready after Read order (1025 bytes) at cylinder 202, Head 19, Sector 2. Header of Sector 2 OK, Header of Sector 3 was previously written with wrong Cylinder Address.

6646 Status error after Read order. UE, verification error, byte count 1 expected. See also 6645 for Seek Address and data.

6647 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6645 for Seek Address and data.

6648 Controller not ready after Read order (1 byte) at cylinder 202, Head 19, Sector 5. Header of Sector 5 was previously written with wrong Cylinder Address.

6649 Status error after Read order. UE, verification error, byte count = 1 expected. See also 6648 for Seek Address and data.

6650 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6648 for Seek Address or data.

6660 Controller not ready after Seek order (cylinder 202, Head 17, Sector 0)//CC// HD Read//CC//Seek (cylinder 202, Head 18, Sector 0)//Read.

6661 Status error. No UE, no flawmark, Command Address +3 expected.

TST1, 70 Dual Controller Test. An SIO order is sent to the first controller which will reserve the device until a Release order is issued. The second controller will now try to influence that device while the first controller is in both Busy and Ready state. After the test sequence is completed, the second controller is tested in the same way. Device Address must be entered with the SYST directive:

SYST, D1, X2, X3, X4, X5, X6, X7, X8, X9, X10
where each pair (X3, X5), (X7, X9), etc., must have the same device on different controllers. A minimum of 1 pair must be entered (maximum 4 pairs).

Example: SYST, 7240, 0, F0, 202, 1F0, 202
Or: SYST, 7240, 0, F0, 202, E0, 202

7010 Expected 2 or more Device Addresses entered by 'SYST' directive.

7011 Release order for device 2 not accepted. See print-out.

7012 Release order for device 1 not accepted. See print-out.

7013 SIO to device 1 not accepted. See print-out.

7014 IO order to device 2 was accepted, should have been rejected. See print-out.

7015 IO interrupt did not occur within time limit.

# Section 8

## SIGMA 5 - 9
## REMOVABLE DISK STORAGE
## TEST (7270/71)

### PROGRAM NO. 706424

**Section 8**

**CONTENTS**

**SUBJECT MODEL** -- Removable Disk Controller Model number 7270, Removable Disk Storage Units, Model number 7271, Removable Disk Controller Modified, Model number 7240, Removable Disk Storage Unit, ISS Model number 715X, 715DX

**REQUIRED EQUIPMENT**--Minimum Memory Size:  16K;  Input Device:  Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device:  Keyboard Printer or Line Printer

**PROGRAM PREREQUISITES**
None

**GENERAL OPERATING PROCEDURES**
General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|--|--|--|
| | | ID | Definition | Value Range | Standard Value (default) |
| *Program Directives - Environmental Directives* | | | | | |
| System Environment | SYST, D1, D2, <br><br> H3, H4, H5, H6 <br>  ,H7 ...,H17,H18 | D1<br>D2<br>H3<br>H4<br>H5<br>H6<br><br><br>H17<br>H18 | Controller model number<br>Revision number<br>Storage Unit Device Address (1st)<br>Available cylinders (1st) *405*<br>Storage Unit Device Address (2nd)<br>Available cylinders (2nd) *405*<br><br><br>⎱ Same as H3, H4 except for<br>⎰ 8th Storage Unit | 7270, 7240<br>0<br>80 ~ 1FFF<br>→00XY00ZW<br>80 ~ 1FFF<br>→00XY00ZW<br><br><br>XY = 1st cylinder<br>ZW = last cylinder | |
| *Program Directives - Testing Directives* | | | | | |
| Comprehensive Test (all functional tests, 1 thru 70, and random exerciser Test) | TST0, D1, D2 | D1<br><br>D2 | Number of ordered sequences executed by random exerciser<br>Number of retries | 0 ~ 99999999<br><br>0 ~ 99999999 | 5000 (D1 = 0)<br><br>0 |
| Functional Test | TST1 [, D1 [, D2]] | D1<br>D2 | The first subtest to be executed<br>Last subtest to be executed | 0 (all subtests) ~ 70<br>1 | 0<br>D1 |
| Random Exerciser Test | TST2, D1, D2 | D1<br>D2 | Number of cycles to be performed<br>Number of retries before next cycle | D1 ~ 0<br>D2 ~ 0 | |
| Utility Test | TST3, D1, D2, D3, H4<br><br><br><br>*TST3.2.0* ---- | | D1 – Utility Test selection<br>D2 – Function selection or serial number<br>D3 – Retry count; not used if D1 = 3<br><br>D1 = 1 Surface Test<br>  D2 = 0 Write and then read all sectors<br>  D2 = 1 Write all sectors<br>  D2 = 2 Read all sectors<br>  D2 = 3 Read all sectors (no data check)<br>  D2 = 4 Checkwrite all sectors<br>  D2 = 5 Write and then checkwrite all sectors<br>→D1 = 2 Header Test<br>  D2 = 0 Write and then read all headers<br>  D2 = 1 Write all headers<br>  D2 = 2 Read all headers<br>  D2 = 3 Read all headers (no data check)<br>D1 = 3 Disk Initialization<br>  D2 = Pack serial Number<br>  D3 = 0 – Not used<br>  H4 = Date = 00MMDDYY<br>D1 = 4 Flaw A Track<br>  D2 = Alternate Cylinder Address<br>  D3 = Alternate Head ADR | <br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br>400 ~ 405<br>0 - 19 | |
| *Program Directives - Optional Directives* | | | | | |
| Pattern selection (for Utility Test) | DATA, D1, H2, H3 | D1<br><br><br><br>H2<br>H3 | = 0, Fixed Pattern<br>= 1, Incremental Pattern<br>= 2, Random Pattern<br>= 3, Current Seek Address<br>Pattern seed (for D1 = 0, 1, 2)<br>Incrementing constant (for D = 1) | 0 ~ 3<br><br><br><br>⎱ 00000000 ~<br>⎰ FFFFFFFF | |
| Usable surface area limitation | SEEK, D1, D2, D3, D4 | D1<br>D2<br>D3<br>D4 | Starting cylinder address<br>Starting head address<br>Starting sector address<br>Additional sectors to be used after starting address<br>D1, D2, D3 | 0 ~ 405<br>0 ~ 19<br>0 ~ 5<br>(0 ~ 81) | |
| Limitation of Error printouts | LIMT, D1, D2 | D1<br><br>D2 | = 1 Limit Compare error printouts/sector to D2<br>Maximum number of printouts (No limit if D2 = 0) | 1<br><br>D2 ~ 0 | |
| I/O buffer area definition | MEM [, H1, H2] | H1<br>H2 | First location of I/O buffer area<br>Last location of I/O buffer area | Obtainable by typing in MEM | Area between Diag. Prog. & DPM |
| I/O Reset | RSET | 0 | | | Not available |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

| | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Surface Test |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM | SEEK, LIMT, MEM, DATA |
| Subtests | All functional subtests (1 ~ 70) and random exerciser test | 70 subtests (see error messages for the test types) | 1. Exerciser Initiation: Random data written on entire surface<br>2. Random Selection of:<br>    a. Device<br>    b. Order Sequences<br>    c. Buffer Areas<br>    d. Buffer Length<br>    e. Data | WRITE only<br>READ only (Verify data)<br>READ only (No data verification)<br>READ header<br>CHECKWRITE<br>WRITE/READ TEST<br>WRITE header |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX<br>2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

3. Procedure 2 of Restart Procedure of DPM should normally be used to clear a wait from a watchdog timer trap.

## PROGRAM TEST DESCRIPTION

Test descriptions of each functional test are included at the beginning of each subtest error number in the Functional Subtest and Related Error Message Section.

## ORDER CODES

X'00'  STOP
X'01'  WRITE
X'02'  READ 2 (Report any transmission error at count done)
X'03'  SEEK
X'04'  SENSE
X'05'  CHECKWRITE
X'12'  READ 1 (Terminate data transfer and report any
       transmission error at end of current sector if error is
       encountered)
X'13'  SELECT TEST MODE
X'80'  STOP AND INTERRUPT (at location X'5C')
X'09'  HEADER WRITE
X'0A'  HEADER READ
X'33'  RESTORE CARRIAGE
X'23'  RELEASE
X'83'  SEEK (and cause a device interrupt
       on position complete or time out)

## TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| REM DISK | Data Overrun | Flaw Mark | Sector Unavailable | Unassigned | Header Verification Error | Head On Cylinder | Seek Timeout Error | Header Parity Error |

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| REM DISK | Data Overrun | ←——— UNASSIGNED ———→ | | | Device Interrupt | Head On Cylinder | Seek Timeout Error | Unassigned |

## TEST MODE DATA BYTE



Test Modes

0  1  2  3  4  5  6  7

Unassigned

Modifier Bit – Parity error reporting check

Test Mode 1 – Buffer turnaround test

Test Mode 2 – Data turnaround at controller side of storage unit interface

## ADDRESSING FORMAT

1. The format of the four byte sent to the Disk Pack by a SEEK order is:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|--------|--------|--------|--------|
| 0 | Cylinder | 0  Head | 0  S |

where S signifies sector number.

2. The format of the bytes received on a SENSE order is:
   SENSE (X'04')

The Sense order causes the controller to transmit up to 10 bytes of information to the IOP, as follows:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|--------|--------|--------|--------|
| 0 | Cylinder | 0  Head | 0  S |

| Byte 4[†] | Byte 5 | Byte 6 | Byte 7 |
|--------|--------|--------|--------|
| M  0  CS | Diagnostic Status Bytes | | |

| Byte 8 | Byte 9 |
|--------|--------|
| Diagnostic Status Bytes | |

where
S   signifies sector number
M   signifies modifier bit
CS   signifies current sector number

[†]Three bits of byte 4 indicate current sector number, but if the most significant bit (M) is a 1, the arm was in motion at time of sense and current sector number is meaningless. If the head number is nonexistent, (M) will also be a 1.

3. The format of the 8 bytes sent to the Disk Pack by a WRITE header order is:
   HEADER WRITE (X'09')
The Header Write order causes the controller to consider all subsequent data bytes as header information. Each header requires the following bytes:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|--------|--------|--------|--------|
| Flaw Mark | 0 | Cylinder | 0  Head |

| Byte 4 | Byte 5 | Byte 6 | Byte 7 |
|--------|--------|--------|--------|
| 0  S | Alt. Cylinder* Index 0–5 | 0  Alt. Head | 0 |

*The alternate cylinder index (8 bits) represents a cylinder index into cylinder 400–405.

Sense Status Bytes 8 and 9

| Byte No. | Bit No. | Function |
|----------|---------|----------|
| 8 | 0 | Data parity error |
|   | 1 | Check-Write error |
|   | 2 | Sector verification error |
|   | 3 | Head verification error |
|   | 4 | Cylinder verification error |
|   | 5 | Sector address not zero at start of header write operation |
|   | 6 | Difference select sent to device |
|   | 7 | Sector select sent to device |
| 9 | 0 | Control select sent to device |
|   | 1 | Head select sent to device |
|   | 2 | Cylinder select sent to device |
|   | 3 | Seek forward set |
|   | 4 | Read gate sent to device |
|   | 5 | Write and erase gate sent to device |
|   | 6 | Read cylinder select sent to device |
|   | 7 | Not used |

Note: Bytes 8 and 9 are used by diagnostic programs.

FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

System error numbers
8500   Controller did not return to Ready condition after Test Mode order.
8501   Controller not in Test Mode after Test Mode order. TDV CC = 0.
8502   Controller in Test Mode after resetting Test Mode. TDV CC = 4.
8510   Controller did not return to Ready condition after Restore order.
8511   Device not on cylinder after a Restore order.


TST1, 01 AIO, HIO, TIO, TDV instruction recognition.

0110   AIO Condition Code error. No interrupt recognition expected.
0111   HIO Condition Code or Status error. See printout.
0112   TIO Condition Code or Status error. See printout. Preceding HIO did not reset Status.
0113   TDV Condition Code error. See printout.


TST1, 02 SIO Invalid Order Test

0210   SIO for Invalid order not accepted. See printout.
0211   Controller not ready after Invalid order (00 or F8). Order output and order input phases must be executed.
0212   Status error after Invalid order. UE expected.
0213   Byte count was changed during execution of Invalid order. Data phase not required.


TST1, 03 Test Mode Selection Test. A TDV instruction is used to verify setting and resetting of Test Mode.

0301   Test Mode byte = X'FF'.
0302   Test Mode byte = X'01'.
0303   Test Mode byte = X'02'.
0310   TDV CC2 reset. Device controller not in Test Mode.
0311   Output buffer changed during Test Mode order (Select). Data in phase not expected.
0312   TDV CC2 set. Device controller remains in Test Mode. CC2 = 0 expected.
0313   Output buffer contains ones after Test Mode order (Reset).
0315   TIO CC1 or CC2 set. Controller not ready after Test Mode order.
0316   TDV, TIO Status error or byte count error. See preceding printout. Operation: Order out (X'13'), data out (1 byte), order in.
0321, 0322, 0323 TST1, Three data byte of FF, 01, and 02 was used during data output phase. See preceding printout.


TST1, 04 Interrupt generation and HIO, AIO Instruction Test. The following orders will be issued: X'00', X'13' (data byte = 01), X'1' (data byte = 00) in order to set Interrupt Pending due to IUE, ICE and IZC, respectively. Each order will be repeated once to allow resetting of IP with an HIO and an AIO instruction.

0410   TIO Status error during TST1, 4 after SIO. IP must be set and controller and device must be ready. IUE, ICE, and IZC flags are used.
0411   HIO did not reset IP. No reset generated.
0412   AIO Status error during TST1, 4. Preceding SIO resulted in IP.
0413   AIO did not reset IP. No reset generated.
0421, 0422, 0423 TST1, 4 IOP flags for IUE, ICE, and IZC used, respectively. See printout.


TST1, 05 IO Interrupt Test. A Test Mode order with ICE flag will be issued and tests will be performed to verify that the program is only interrupted if the IO Interrupt is armed and enabled.

0510   TIO Status error during TST1, 5 after SIO. IP must be set. IO Interrupt is disarmed/disabled. Program should not be interrupted.

0511   Program was interrupted while IO Interrupt was disarmed/disabled.
0512   Program was interrupted while IO Interrupt was armed/disabled.
0513   Program was not interrupted while IO Interrupt was armed/disabled.


TST1, 06 Command Chaining Test. Two Test Mode orders will be Command Chained. Command Chaining will be tested. Invalid order Command Chained to a Test Mode order should not result in Command Chaining.

0610   TIO Status error during TST1, 6 after Command Chaining or Command Chaining not performed. See preceding printout.
0611   TIO Status error during TST1, 6. Status error or Command Chaining not inhibited by UE from Invalid order.


TST1, 07 FAM Write/Read Byte Count Test. Write and Read orders with byte counts varying sequentially from 1 to 16 are issued in Test Mode 1. Zero byte count expected.

0710   Controller not ready after Write order in TM1.
0711   Controller not ready after Read order in TM1.
0712   Byte count not equal to zero after Write order in TM1.
0713   Byte count not equal to zero after Read order in TM1.


TST1, 08 FAM Write/Read Data Test. Write Command–Chain Read orders will be issued with varying data pattern. The Read data will be compared to the Write data. During the second part of the test 4 Write/CC/Read orders with counts of 13 will be issued to test the byte alignment logic.

0810   Controller not ready after Write/CC/Read order in TM1.
0811   Compare errors during TST1, 8. Output buffer: IOBF1, Input buffer: IOBUF.
0812   Controller not ready after Write/CC/Read (BC = 13) Test Mode 1.
0813-0816   Read Data compare error following Write/CC/Read (BC = 13).
           If last digit is 3, data started on word boundary
           If last digit is 4, data started at byte 1
           If last digit is 5, data started at byte 2
           If last digit is 6, data started at byte 3


TST1, 09 Test Mode 2 – Seek Order Byte Count Test. Seek orders with byte counts of 3, 4, 5 are issued to the controller and the status response is tested.

0910   Controller not ready after Seek order in Test Mode 2.
0911   Status error after Seek order in Test Mode 2. Expected: IL, UE, zero byte count, on-cylinder. See printout.
0912   Status error after Seek order in Test Mode 2. Expected: Not IL, zero byte count, on cylinder. See printout.
0913   Status error after Seek order in Test Mode 2. Expected: IL, byte count = 1, on-cylinder. See printout.
0914   Output buffer (:IOBF1) altered during Seek in TM2.


TST1, 10 Test Mode 2 – Seek Order Interrupt Address Test. Seek orders will be to device 0 through 7 in sequence and the address returned with the AIO Status will be verified. Change above mask from X'04000000' to X'0C000000' if Device Interrupt Engineering Order is available.

1010   Status error after Seek order with Interrupt Modifier bit. Expected: IP, zero byte count, on cylinder. See printout.
1011   AIO Status error after Seek order with Interrupt Modifier bit. IP set prior to AIO. Expected: Address verification. See printout.
1012   Preceding AIO did not clear Seek complete interrupt (TIO/IP=0).

TST1, 13 Test Mode 2 - Sense Order Byte Count Test. Sense orders with byte counts of 1 through 11 are issued to the controller and the Status Response is tested.

1310    Controller not ready after Sense order in Test Mode 2.
1311    Status error after Sense order in Test Mode 2. No unusual status expected. See printout.
1312    Byte count not equal to zero after a Sense order with a byte count ≤10. See printout.
1314    First 8 bytes of input buffer (IOBF1) not changed during Sense order. Data input expected.

TST1, 15 Test Mode 2 - Seek Tag Line Test. See/Command Chain/ Sense orders are executed and the Tag Line information in byte 8 of the Sense data is verified.

1510    Controller not ready after Seek/CC/Sense order in Test Mode 2.
1511    Status error after Sense order or Command Chaining not performed. See printout.
1512    Seek Tag Line error or Sense order not functioning properly. Sense buffer: IOBF1. See printout.

TST1, 16 Test Mode 2 - Head and Sector Address Test. Seek/CC/ Sense orders are issued sequentially varying the Device Address from 0 - 7. Sense data is verified. Sense orders are issued sequentially to all devices to insure that the addresses are not changed. The same sequence is repeated with the Device Address varied from 7 - 0. The complement of the data pattern in pass 1 is used in pass 2. A unique pattern is used for each device.

1610    Controller not ready after Seek/CC/Sense order in Test Mode 2.
1611    Controller not ready after Sense order in Test Mode 2.
1620-1627   Head and Sector Address obtained during Sense not equal to original data. Last digit of error number indicates Device Address used. Address sequence 0 - 7. Order sequence: Seek/ CC/Sense.
1630-1637   Head and Sector Address obtained during Sense not equal to original data. Check addressing of Head and Sector FAM. Last digit of error number indicates Device Address used.
1640-1647   Same as 1620-1627. Address sequence 7 - 0.
1650-1657   Same as 1630-1637.

TST1, 17 Test Mode 2 - Head and Sector Address Validity Test. Seek and Sense are issued 406 times varying the Sector Address from 0-7 and the Head Address from 0-25. Sector unavailable will be tested for Sector Address > 5 and Head Address > 19. The combined Sector and Head Address which is returned as Cylinder Address during Seek will be verified.

1710    Controller not ready after Seek order in Test Mode 2.
1711    Status error after Seek order in Test Mode 2 with illegal sector Address (7). UE, sector unavailable, on cylinder expected.
1712    See 1711. Illegal Head Address was issued during Seek.
1713    Status error after Seek order in Test Mode 2. Legal Head and Sector Address were used. See printout.
1714    Controller not ready after Sense order in Test Mode 2.
1715    Seek/Sense compare error. The Head/Sector Address was not returned correctly as the Cylinder Address. See printout.

TST1, 19 Test Mode 2 - Cylinder Difference Logic Test. Seek and Sense orders are issued systematically varying the Cylinder and Head/Sector Address. Five passes will be performed:
1. Cyl and Hd/Sect 0 - 405.
2. Cyl 0 - 405, Hd/Sect 0
3. Cyl 0, Hd/Sect 0 - 405
4. Cyl 405 - 0, Hd/Sect 0
5. Cyl 0, Hd/Sect 405 - 0

1910    Controller not ready after Seek order in Test Mode 2.
1911    Controller not ready after Sense order (Byte count 10) in Test Mode 2.
1912    The difference between Head/Sector and the Cylinder Address returned in byte 7 of the Sense order is not correct. See printout.

1913    Controller not ready after the second Seek order in Test Mode 2. Two Seek orders are required to obtain the correct difference in byte 7 of the Sense data.

TST1, 20 Test Mode 2 - Illegal Cylinder Address Test. Seek orders are issued with illegal Cylinder Address (406 - 511) and the Status Response is verified.

2010    Controller not ready after Sense order in Test Mode 2.
2011    Status error after Seek order in Test Mode 2 with Illegal Cylinder Address (406 - 511). UE, sector unavailable, on cylinder expected.

TST1, 23 Test Mode 2 - Restore Order Test. A Seek/CC/Restore and Sense order sequence is sequentially issued to all devices (0 - 7). The test verifies the status after the Restore orders and verifies with a Sense order (Byte count = 10) that the Head and Sector Address in the FAM are cleared to zero and that the Restore order generated the correct Tag Lines.

2310    Controller not ready after Seek/CC/Restore orders in Test Mode 2.
2311    Status error after Restore order in Test Mode 2. Not UE, byte count 1 (no changes). See printout.
2312    Controller not ready after Sense order in Test Mode 2.
2313    Bytes 2 (Head) and 3 (Sector) of Sense data not 0. Preceding Restore order did not clear controller registers (FAM).
2314    Restore Tag Line error. Sense buffer: IOBF1. See printout.

TST1, 24 Test Mode 2 - Release Order Test. A Release order and a Sense order is issued. The test verifies the status after the Release and verifies with a Sense order (Byte count = 10) that the Release order generated the correct Tag Lines.

2410    Controller not ready after Release order in Test Mode 2.
2411    Status error after Release order in Test Mode 2. Not UE, byte count = 1 (No change) expected. See printout.
2412    Controller not ready after Sense order in Test Mode 2.
2413    Release Tag Line error. Sense buffer: IOBF1. See printout.

TST1, 25 Test Mode 2 - Read Order Tag Line and Data Test. Read orders X'02' and X'12' are issued in sequence. The status and byte count are verified. The Read data is compared to the expected information. A Sense order verifies that the Tag Lines are correctly generated for a Read order.

2510    Controller not ready after Read order (02) in Test Mode 2.
2511    See 2510. Read order (12).
2512    Status error after Read order in Test Mode 2. Not UE, not IL, not TE, byte count 0 expected. See printout.
2513    See 2512. Read order (12).
2514    Data compare error in Test Mode 2; Read order (02). See printout.
2515    See 2514. Read order (12).
2516    Controller not ready after Sense order in Test Mode 2.
2517    Read (02) Tag Line error. Sense buffer: IOBF1, See printout.
2518    See 2517. Read order (12).
2519    Status error in diagnostic Sense byte (byte 8 of Sense data) defines Read error.
2520    See 2519. Read order (12).

TST1, 26 Test Mode 2 - Read Order Incorrect Length Test. Read orders are issued with byte count sequentially varied from 1008 to 1025 (not 1024). The status will be verified. For byte counts 1024 the test verifies that the controller terminates data-in at the correct byte count.

2610    Controller not ready after Read order (02) in Test Mode 2.
2611    Remaining byte count after Read order with incorrect length not zero. See printout.
2612    Status error after Read order in Test Mode 2. IL expected. See printout.
2613    Data compare error in Test Mode 2; Read order (02). For byte count 1024 the remaining bytes in input buffer must be zero.

TST1, 27 Test Mode 2 - Read Order/Head and Sector Incrementation Test. Seek/CC/Read and Sense order sequences are issued with a Read byte count of 1024. Sector and Head Address incrementation is verified.

2710 Controller not ready after Seek/CC/Read (02) orders in Test Mode 2.
2711 Status error after Seek/CC/Read in Test Mode. No abnormal status expected. See printout.
2712 Controller not ready after Sense order in Test Mode 2.
2713 Address received during Sense not expected. Head or Sector Address may not increment properly. See printout.

TST1, 28 Test Mode 2 - Read Order Cylinder Boundary Test. A Read order with a byte count of 1025 is issued starting at Head 19, Sector 5. Read operation will terminate after 1 sector and sector unavailable will be reported.

2810 Controller not ready after Seek/CC/Read (02) orders in Test Mode 2.
2811 Status error after Read order (Seek Address – Head 19. Sector 5, byte count – 1025). UE, sector unavailable, byte count – 1 expected. See printout.

TST1, 29 Test Mode 2 - Header Read Order Test. Seek/CC/Header Read orders sequences are issued with Header Read byte count of 8. The status and byte count are verified. The Header Read data is compared to the expected information. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address are incremented correctly.

2910 Controller not ready after Seek/CC/Header-Read orders in Test Mode 2.
2911 Status error after Header Read order. No abnormal status expected. See printout.
2912 Header data compare error in Test Mode 2. See printout.
2913 Controller not ready after Sense order in Test Mode 2. See printout.
2914 Header Read Tag Line error. Sense buffer: IOBUF. See printout.
2915 Status error in diagnostic Sense byte (Byte 8 of Sense data) defines Header Read error.
2916 Address received during Sense not expected. Head or Sector Address may not increment properly. See printout.

TST1, 30 Test Mode 2 - 120 Sector Header Read Test. A Seek/CC/Header Read order with a Header Read byte count of 960 is issued. The Header data is verified. No data error indicates that the Head and Sector Incrementation Logic performs correctly.

3010 Controller not ready after Header Read order in Test Mode 2.
3011 Byte count not zero after Header Read order (960 bytes).
3012 Status error after Header Read order. No abnormal status expected.
3013 Header data compare error in Test Mode 2. See printout.

TST1, 31 Test Mode 2 - Header Read Byte Count Test. Header Read orders with byte counts of 7 and 9 are issued to the controller and the Status Response is tested.

3110 Controller not ready after Header Read order in Test Mode 2.
3111 Status error after Header Read order (byte count 7). Expected: IL, no UE, byte count – 0. See printout.
3112 See 3111. Header Read order byte count – 9.

TST1, 32 Test Mode 2 - Header Read Order Cylinder Boundary Test. A Header Read order with a byte count of 9 is issued starting at Head 19, Sector 5. Read operation will terminate after one sector and sector unavailable will be reported.

3210 Controller not ready after Header Read order in Test Mode 2.

3211 Status error after Header Read order (Seek address Head 19, Sector 5, byte count 9). UE, sector unavailable, byte count 1, expected.

TST1, 35 Test Mode 2 - Header Write Order Test. Seek/CC/Header Write order sequences are issued with Header Write byte counts of 48. The Header data consists of a X'A5A5A5A5' pattern. The status and byte count are verified. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increment correctly.

3510 Controller not ready after Seek/CC/Header-Write orders in Test Mode 2.
3511 Status error after Header Write order. No abnormal status expected. See printout.
3512 Controller not ready after Sense order in Test Mode 2.
3513 Header Write Tag Line error. Sense buffer: IOBF1. See printout.
3514 Status error in diagnostic Sense byte (byte 8 of Sense data) defines Header Write error.
3515 Address received during Sense not expected. Head or Sector Address may not increment properly. See printout.

TST1, 36 Test Mode 2 - 120 Sector Header Write Test. A Seek/CC/Header Write order sequence with a Header Write byte count of 960 is issued. A Sense order is issued to verify that the Head and Sector Address are incremented to Head 20, Sector 0.

3610 Controller not ready after Seek/CC/Header-Write orders in Test Mode 2.
3611 Byte count not zero after Header Write order (960 bytes).
3612 Status error after Header Write order. No abnormal status expected.
3613 Controller not ready after Sense order in Test Mode 2.
3614 Address received during Sense not expected. Header or Sector Address have not been incremented past Head 19, Sector 5.

TST1, 37 Test Mode 2 - Header Write Byte Count Test. Header Write orders with byte counts of 7 and 9 are issued to the controller and the Status Response is tested.

3710 Controller not ready after Seek/CC/Header-Write order in Test Mode 2.
3711 Status error after Header Write order (byte count 4). Expected: IL, no UE, byte count – 0. See printout.
3712 See 3711. Header Write order byte count 9.

TST1, 38 Test Mode 2 - Header Write Order Cylinder Boundary Test. A Header Write order with a byte count of 49 is issued starting at Head 19, Sector 0. Write operation will terminate after six sectors and sector unavailable will be reported.

3810 Controller not ready after Header Write order in Test Mode 2.
3811 Status error after Header Write order (Seek Address Head 19, Sector 0, byte count – 49). UE, sector unavailable, byte count – 0 expected.

TST1, 39 Test Mode 2 - Header Write Starting Address Test. Header Write orders with Starting Sector Address of 0 through 5 are sequentially issued. For all Starting Addresses except 0, byte 8 of the Sense data will indicate Header Address error.

3910 Controller not ready after Header Write order in Test Mode 2.
3911 Status error after Header Write order. No abnormal status expected.
3912 Controller not ready after Sense order in Test Mode 2.
3920-3925 Status error in diagnostic Sense byte (byte 8 of Sense data). The least significant digit of error number reflects the Starting Sector Address of the Header-Write operation. Header-Address error is expected for all Starting Address except Sector 0.

TST1, 40 Test Mode 2 - Write Order Test. Seek/CC/Write order sequences are issued with Write byte count 3 or 1024. The Write data consists of byte values starting at 224, with each successive byte  byte (N) + 1. These values reflect the byte counter in the controller at the time of writing each byte. Status and byte count are verified. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increment correctly.

4010    Controller not ready after Seek/CC/Write orders in Test Mode 2.
4011    Status error after Write order. No abnormal status expected.
4012    Controller not ready after Sense order in Test Mode 2.
4013    Write Tag Line error. Sense buffer: IOBF1. See printout.
4014    Status error in diagnostic Sense byte (byte 8 of Sense data) defines Write error.
4015    Address received during Sense not expected. Head and Sector Address may not increment properly. See printout.

TST1, 41 Test Mode 2 - Write Order Incorrect Length Test. Seek/CC/Write order sequences are issued with byte counts sequentially varied from 1008 to 1025 (not 1024). The status will be verified.

4110    Controller not ready after Write order in Test Mode 2.
4111    Remaining byte count after Write order with Incorrect Length not zero. See printout.
4112    Status error after Write order in Test Mode 2. IL expected. See printout.

TST1, 42 Test Mode 2 - Write Order Cylinder Boundary Test. A Write order with a byte count of 1025 is issued starting at Head 19, Sector 5. The Write operation will terminate after 1 sector and sector unavailable will be reported.

4210    Controller not ready after Write order in Test Mode 2.
4211    Status error after Write order (Seek Address  Head 19, Sector 5 byte count 1025). UE, sector unavailable, byte count  0 expected.

TST1, 45 Test Mode 2 - Check-Write Order Test. Seek/CC/Check-Write order sequences are issued with byte counts of 1024. The Check Write data consists of byte values starting at 224, with each successive byte  byte (N) + 1. A Sense order verifies that the Tag Lines are correctly generated and that the Head and Sector Address increments correctly.

4510    Controller not ready after Seek/CC/Check-Write orders in Test Mode 2.
4511    Status error after Check-Write order. No abnormal status expected. See printouts.
4512    Controller not ready after Sense order in Test Mode 2.
4513    Check-Write Tag Line error. Sense buffer: IOBF1. See printout.
4514    Status error in diagnostic Sense byte (byte 8 of Sense data) defines Check-Write error.
4515    Address received during Sense not correct. Head or Sector Address may not increment properly. See printout.

TST1, 46 Test Mode 2 - Check-Write Order Incorrect Length Test. Seek/CC/Check-Write order sequences are issued with byte count sequentially varied from 1008 to 1025 (not 1024). The status will be verified.

4610    Controller not ready after Seek/CC/Check-Write order in Test Mode 2.
4611    Remaining byte count after Check-Write order with Incorrect Length not zero. See printout.
4612    Status error after Check-Write order in Test Mode 2. IL L L expected. See printout.

TST1, 47 Test Mode 2 - Check-Write Order Cylinder Boundary Test. A Check-Write order with a byte count of 1025 is issued starting at Head 19, Sector 5. The Check-Write operation will terminate and after one sector and sector unavailable will be reported.

4710    Controller not ready after Check-Write order in Test Mode 2.
4711    Status error after Check-Write order (Seek address  Head 19, Sector 5, byte count 1025). UE, sector unavailable, byte count 0 expected.

TST1, 48 Test Mode 2 - Check-Write Transmission Error Test. Seek/CC/Check-Write order sequences with byte counts of 2048 are issued. The Check-Write data consists of byte values starting at 224 (X'EO'), with each successive byte  byte (N) + 1. During the first 8 passes one bit in byte 32 (X'FF') is sequentially dropped starting with bit O and ending with bit 7. During the second 8 passes one bit in byte 33 (X'00') is sequentially picked-up starting with bit 0 and ending with bit 7. The test verifies that a single bit failure in a sector is detected and reported as TE and that the operation terminates after the first sector. The remaining byte count must be ≥1000.

4810    Controller not ready after Seek/CC/Check-Write order in Test Mode 2.
4811    Remaining byte count after Check-Write order (2048 bytes) less than 1008. Check-Write operation did not terminate after one sector.
4812    Controller not ready after Sense order in Test Mode 2.
4813    Address received during Sense not correct. Head or Sector Address may have been incremented by two sectors.
4814    Status error in diagnostic Sense byte (byte 8 of Sense data) should indicate Check-Write error.
4820-4827 Status error after Check-Write order. TE and not IL or UE expected. The least significant digit of the error number indicates which bit of byte 32 of the Check-Write data was dropped to induce a Check-Write error.
4830-4837 See 4820-4827. The least significant digit of the error number indicates which bit of byte 33 of the Check-Write data was added to induce a Check-Write error.

TST1, 49 Test Mode 2 - Halt On Transmission Error Test. Seek/CC/Write order sequences with byte counts of 1020 are issued to test setting of UE, IL and IOP/Halt. Seek/CC/Check-Write order is issued to check setting of TE.

4910    Controller not ready after Seek/CC/Write (or Check-Write) in Test Mode 2.
4911    Status error after Write order in Test Mode 2. UE, IL and IOP/Halt setting expected.
4912    Status error after Write order in Test Mode 2. IL and not UE and not IOP/Halt setting expected.
4913    Status error after Check-Write order in Test Mode 2. UE, TE and IOP/Halt setting expected.

TST1, 50 Test Mode 3 (Parity) - Read Order 12 Parity Test. A Sense/CC/Read 12 order sequence is issued with a Read byte count of 2048. The controller will generate a parity error. The test verifies the status (TE and not UE) and verifies with a Sense order that the Read order terminated after a sector. The remaining byte count must be  1024.

5010    Controller not ready after Seek/CC/Read 12 order in Parity Test Mode.
5011    Remaining byte count after Read 12 order (2048 bytes) not equal to 1024. Read 12 operation did not terminate after one sector.
5012    Status error after Read 12 order. TE and not IL or UE expected. See Printout.
5013    Controller not ready after Sense order in Parity Test Mode.
5014    Status error in diagnostic Sense byte (byte 8 of Sense data) should indicate data parity error.
5015    Address received during Sense not correct. Head or Sector Address may have been incremented by two sectors.

TST1, 51 Test Mode 3 (Parity) - Read Order 02 Parity Test. A Sense/CC/Read 02 order sequence is issued with a Read byte count of 3072 (3 data-chain operation). The test verifies that Reading continues until the byte count  zero. The expected status is TE, not UE.

5110    Controller not ready after Seek/CC/Read02/DC/Read02/DC/Read02 in Parity Test Mode.

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TST1, 51 (Continued)

5111    Status error after Read02 order. TE and not IL or UE and byte
        zero and Current Command Address · Starting Address + 3
        expected.
5112    Controller not ready after Sense order in Parity Test Mode.
5113    Address received during Sense not correct. Head or Sector
        Address did not increment correctly.


TST1, 52 Normal Mode – Restore Order Test. · A Restore order is
        issued to the storage unit. The test verifies that the
        controller and device are ready and that positioning is
        complete and that no time out error has occurred.

5210    Controlled not ready after Restore order.
5211    On cylinder bit TDV (5) not received after Restore order.
5212    Status error after Device order. See printout.


TST1, 53 Normal Mode – Seek Order Test. A Restore order is issued
        to the storage unit. The test proceeds to issue Seek orders
        for all sectors on cylinder 0. No head motion is involved
        except possibly during the Restore order. The test verifies
        that Seek orders can be completed without errors.

5310    Controller not ready after Seek order.
5311    On-cylinder bit TDV (5) not received after Seek order. No head
        motion required.
5312    Status error after Seek order. See printout.


TST1, 54 Normal Mode – Release Order Test. A Release order is
        issued. The test verifies the status after the release.

5410    Controller not ready after Restore order in normal mode.
5411    Status error after Restore order in normal mode. Not UE, byte
        count · 1 (no change) expected. See printout.


TST1, 55 Header Read – Failure Isolation Test. A Restore order is
        issued to position the heads at cylinder 0. Seek/CC/
        Header-Read sequences will be issued for all 120 sectors of
        cylinder 0. No errors will be reported until all operations
        are completed. A summary of all errors will be printed.
        The test will proceed to loop on the first failure with
        immediate error printouts. Information other than zeros
        in the flaw byte or alternate Address byte will not be
        considered an error.

5510    Controller not ready after Seek/CC/Header-Read order.
5511    Status error after Header-Read order. See printout.
5512    Compare error of Header data. Bytes 0, 5 and 6 of each
        Header are not tested.


TST1, 56 Normal Mode – Sense Order/Angular Position. A Restore
        order is issued to the storage unit. The test issues a Sense
        order and verifies the status. The test proceeds to issue up
        to 6 Sense orders in order to verify angular position 0.
        Following position 0, 5 Sense orders are issued to verify
        angular position 1-5.

5610    Controller not ready after Sense order.
5611    Status error after Sense order. See printout.
5612    Controller not ready after Sense order.
5613    Six attempts failed to find angular position of 0 in byte 4 of
        Sense data.
5621-5625 Controller not ready after Sense order. The least
        significant digit of the error number indicates the current
        angular position expected in the Sense data.
5631-5635 The expected angular position as indicated by the least
        significant digit of the error number not in byte 4 of Sense data.


TST1, 57 Normal Mode – Sense Order Test. A Restore order is issued
        to position the heads at cylinder 0. Seek/CC/Sense
        sequence will be issued for all 120 sectors of cylinder 0.
        The test verifies that the Address returned during the Sense
        operation is correct and that normal status is returned.

5710    Controller not ready after Sense order.
5711    Status error after Sense order. See printout.
5712    Compare error of Seek and Sense data. See printout.
5713    Status error in diagnostic Sense byte (byte 8 of Sense data) should
        indicate no errors.


TST1, 58 Sequential Head Positioning Test. Sequential Seek orders
        are issued to the disk storage unit. After verifying successful
        completion of each Seek order, a Sense order is issued to
        verify the Seek operation. If a Header parity error is
        detected during the Sense order, the Sense operation will be
        automatically retried six additional times before an error is
        reported. If the cylinder Address obtained is correct, the
        next Seek/Sense sequence will be initiated. On retries
        after a cylinder compare error, the Seek Address will be
        decremented by 1 (not · 0) and a Restore order will be
        issued prior to retry.

5810    Controller not ready after a Seek order.
5811    Controller not ready after Sense order. Arm was in motion
        execution of Sense order.
5813    On cylinder bit TDV (5) not received after See order. The Seek
        order initiated head motion.
5814    Controller not ready after Sense order. Arm motion was
        previously completed. TDV(5)  1.
5815    All six Sense orders issued to the drive unit indicate that a
        Header parity error was detected.
5816    Compare error of Seek and Sense data. See printout.


TST1, 60 Complex Head Positioning, Seek Access Timing and Seek
        Complete Interrupt Test. This test consists of four passes.
        The passes differ by the type of head motion.
        1.  Seek (M) Sense Seek (N) Sense 406 times. M varies
            from 0 to 405, N is always · 0.
        2.  Seek (M) Sense Seek (N) Sense 406 times. M is always
            405. N varies from 405 to 0.
        3.  Seek (M) Sense Seek (N) Sense 406 times. M varies
            from 0 to 405, N varies from 405 to 0.
        4.  Seek (R) Sense Seek (R) Sense 406 times. R is a random
            number.
        During retries the last successful Seek/Sense sequence is
        repeated. Average Seek access time is computed and if it
        exceeds the limit, it is printed out. The test is initialized
        if retry is requested.

6010    Controller not ready after Seek order.
6011    Expected Seek complete interrupt was not received.
6012    Status error after Seek complete interrupt has been received.
        See printout.
6013    Controller not ready after Sense order.
6014    Header parity error indicated by bit 7 of TDV following Sense
        orders. The Sense order has been issued seven times to automat-
        ically recover from the problem. Possible bad Headers on the
        disk.
6015    Head positioning error. See preceding printout. The expected
        Sense data defines the Seek Address. The observed Sense data
        defines the Current Address in the controller. Prior to the Seek
        operation.
6016    Average Head positioning time greater than 48 ms. All Seek
        operations in this test are used in the computation of the average
        time.


TST1, 63 Comprehensive Write/Read/Checkwrite Test. During the
        first phase of this test, attempts are made to locate a cylinder
        with error-free Headers. The cylinders used are determined
        by the SYST-directive entry for each device. Once a good
        cylinder has been located, A Write/Read/Checkwrite pass
        will be performed three times, each time with a different
        pattern.
        Pass 1:  Fixed pattern of X'AA55AA55'
        Pass 2:  Incremented pattern of X'00010203', X'04050607',
                 X'08090A0B'
        Pass 3:  Current Seek Address X'00000000' for cyl  0, HD 0,
                 Sect 0, X'00NN0803' for cyl NN, HD 08, Sect 3.
        Any recoverable error six retries are automatically attempted)
        or solid failure will cause the selection of another cylinder.
        The objective of this procedure is to avoid looping on an
        error which may be caused by surface flaws.

TST1, 63 (Continued)

6310    Attempts to find a cylinder (120 sectors) with good Headers and no assigned Alternate Addresses not successful. Program used only those cylinders which were made available to the program with the SYST directive.

6311    Controller not ready after Header Read order of 120 sectors.

6312    Byte count after Header Read order not reduced to zero.

6313    Status error after Header Read order. No unusual status expected.

6314    Header data compare error. See printout. If a flaw byte or an Alternate Address if dound in the Header, the current cylinder will not be used for the Write/Read/Checkwrite portion of this test.

6315    Header Read operation not successful for current cylinder. Errors 6311 through 6314 describe the nature of the failure. Next cylinder will be automatically selected.

6320    Controller not ready after Seek order.

6321    Controller not ready after Sense order.

6322    Seek/Sense compare error. See expected and observed data. The Sense order was issued after a Write, Read, or Checkwrite order. The Sense data should reflect the current Address.

6330    Controller not ready after Write order. Preceding Seek order successful.

6331    Status error after Write order. No unusual status expected. The Write order will be automatically retried six times.

6332    Status error after Write order. The diagnostic Sense byte (byte 8 of Sense data) should indicate no errors.

6333-6335 See 6330 through 6332, respectively. Current order was a Read. The sector in error may have been incorrectly written.

6336    Read compare error. See printout. The error may result from incorrect writing of the data.

6337-6339 See 6330 through 6332, respectively. Current order was a Checkwrite. The sector in error may have been incorrectly written if Read errors are detected.

6340    Write errors on current cylinder. If Sense Switch 1 is reset and 3 set, the Read and Check-Write portion of this test will be skipped and a new cylinder will be selected. Fixed pattern of X'AA55AA55AA5 . . . '.

6341    Read errors on current cylinder. If Sense Switch 1 is off and 3 on, the Checkwrite portion of this test will be skipped and a new cylinder will be selected. Fixed pattern of X'AA55AA55AA55. . . '.

6342    Checkwrite errors on current cylinder. If Sense Switch 1 is off and 3 on, a new cylinder will be selected. Fixed pattern of X'AA55AA55AA55. . . '.

6343    See 6340. Write errors. Incremented pattern X'00010203040506..'

6344    See 6341. Read errors. Incremented pattern X'00010203040506..'

6345    See 6342. Check-Write errors. Incremented pattern X'00010203040506 . . . '.

6346    See 6340. Write errors. Current Seek Address used as pattern.

6347    See 6341. Read errors. Current Seek Address used as pattern.

6348    See 6342. Check-Write errors. Current Seek Address used as pattern.

TST1, 64 Short Record Write Test. During the first phase of this test, attempts are made to locate a sector which can be recorded and verified. Once a good sector has been located, a 4 byte record is written and verified with a Read order. Bytes 4 through 1023 are expected to be zero.

6410    Controller not ready after Seek/CC/Write order.

6411    Status error after Write order. Normal termination expected.

6412    Controller not ready after Seek/CC/Read order.

6413    Status error after Read order. Normal termination expected.

6414    Data compare error on current sector.

6415    Controller not ready after Seek/CC/Write order (4 bytes). The remaining bytes of the current sector should contain zeros.

6416    Status error after Write order (4 bytes). Only IL is expected.

6417    Controller not ready after Seek/CC/Read order (1024 bytes). The preceding Write order recorded only 4 bytes of data.

6418    Status error after Read order. Normal termination expected.

6419    Data compare error on current sector. If word count of compare error MSG> 0, the controller failed to write zeros for bytes 4 through 1023.

6420    Write or Read errors on current sector. Another sector, if available, will be selected.

6430    Device not ready after Seek/CC/Read (BC 253)/CC/Sense.

6431    Status error after Seek/CC/Read (BC 253)/CC/Sense. Normal termination expected.

6432    Device failed to report correct sector on sense at least once in 256 cycles of: Seek/CC/Read (BC 253)/CC/Sense.

TST1, 65 Header Write Test. This test will only be executed if cylinder 405 is made available to the test program with the SYST directive. The test will write all Headers on cylinder 405 for Heads 16 through 19. The original Headers will be saved at the start of the test and restored at the end of the test.

6510    Controller not ready after Seek/CC/Header Write order (6 sectors).

6511    Status error after Header Write order. Normal termination expected.

6512    Controller not ready after Seek/CC/Header Read order (6 sectors).

6513    Status error after Header Read order. Normal termination expected. Headers may have been incorrectly written.

6514    Header compare errors. Each Header consists of 8 bytes. Headers may have been incorrectly written.

6515    Controller not ready after Sense order.

6516    Status in diagnostic Sense byte (byte 8 Sense data) should indicate no errors.

6517    Attempts to save 24 Headers starting at cylinder 405, Head 16, Sector 0 not successful. Remainder of this test will be skipped.

TST1, 66 Header Error Detection Test. This test will only be executed if cylinder 405 is made available to the test program with the SYST directive. The test consists of the following 3 sections:

   1. Headers with flaw bytes are written for cylinder 405, Head 17 Sense, Header Read, and Read orders are issued to verify the detection of the flaw byte and setting of UE (UE will not be set during Header Read).

   2. Headers with a cylinder address of 445 are written for cylinder 405, Head 18. A Sense order is issued to verify the setting of verification error, UE, and cylinder compare error (byte 8 of Sense data).

   3. Headers for cylinder 405, Head 19 contain the following information: Sector 0 OK, Sector 1 OK, Sector 2 OK, Sector 3 cylinder wrong, Sector 4 Head wrong, Sector 5 sector wrong.

   4. Header Read and Read orders are issued to verify that cylinder, head, and sector compare errors are set (byte 8 of Sense data) and that the orders terminate correctly after detection of an erroneous Header.

The original Headers will be saved at the start of the test and restored at the end of the test.

6610    See 6517

6611    Controller not ready after Seek/CC/Header Write order (24 sectors).

6612    Status error after Header Write order. Normal termination expected.

6620    Controller not ready after Seek/CC/Sense order. All six headers starting at cylinder 405, Head 17 have flaw bytes recorded from preceding Write Pass.

6621    Status error after Sense order. UE, flaw byte (TDV bit 1) and not TE expected. All six headers starting at cylinder 405, Head 17 have flaw bytes recorded from preceding Write Pass.

6622    Controller not ready after Seek/CC/Header Read order. See also 6620.

6623    Status error after Header Read order. Flaw byte, not UE or TE expected. See also 6621.

6624    Controller not ready after Seek/CC/Read order. See also 6620.

6625    Status error after Read order. UE, flaw byte (TDV·bit) and not TE expected. See also 6621.

6626    Controller not ready after Seek/CC/Sense order. All six headers starting at cylinder 405, Head 18 have a wrong cylinder Address (cylinder 455) recorded from preceding Write order.

6627    Status error after Sense order. UE, verification error (TDV bit 4) not UE, and byte count 0 expected. See 6626 for header data.

6628    Controller not ready after Seek order.

TST1, 66 (Continued)

6629 Controller not ready after Sense order. Status after Sense order will not be tested.

6630 Controller not ready after Header Read order at cylinder 405, Head 19, Sector 3. Header of Sector 3 was previously written with wrong cylinder Address.

6631 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6630 for Seek Address and data.

6632 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6630 for Seek Address and data.

6633 Controller not ready after Header Read order at cylinder 405, Head 19, Sector 4. Header of Sector 4 was previously written with wrong Head Address.

6634 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6653 for Seek Address and data.

6635 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Head compare error. See also 6633 for Seek Address and data.

6636 Controller not ready after Header Read order at cylinder 405, Head 19, Sector 5. Header of Sector 5 was previously written with wrong Sector Address.

6637 Status error after Header Read order. UE, verification error, and byte count = 0 expected. See also 6636 for Seek Address and data.

6638 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6636 for Seek Address and data.

6639 Controller not ready after Header Read order (17 bytes) at cylinder 405, Head 19, Sector 2. Header of Sector 2 OK, Header of Sector 3 was previously written with the wrong Cylinder Address.

6640 Status error after Header Read order (17 bytes). UE, verification error, and byte count = 1 expected. Headers for Sectors 2 and 3 should be read. See also 6639 for Seek Address and data.

6641 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6639 for Seek Address and data.

6642 Controller not ready after Read order (1 byte) at cylinder 405, Head 19, Sector 3. Header of Sector 3 was previously written with wrong Cylinder Address.

6643 Status error after Read order. UE, verification error, byte count = 1 expected. See also 6642 for Seek Address and data.

6644 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6642 for Seek Address and data.

6645 Controller not ready after Read order (1025 bytes) at cylinder 405, Head 19, Sector 2. Header of Sector 2 OK, Header of Sector 3 was previously written with wrong Cylinder Address.

6646 Status error after Read order. UE, verification error, byte count = 1 expected. See also 6645 for Seek Address and data.

6647 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate cylinder compare error. See also 6645 for Seek Address and data.

6648 Controller not ready after Read order (1 byte) at cylinder 405, Head 19, Sector 5. Header of Sector 5 was previously written with wrong Cylinder Address.

6649 Status error after Read order. UE, verification error, byte count = 1 expected. See also 6648 for Seek Address and data.

6650 Status in diagnostic Sense byte (byte 8 of Sense data) should indicate Sector compare error. See also 6648 for Seek Address or data.

6660 Controller not ready after Seek order (cylinder 405, Head 17, Sector 0)//CC//HD Read//CC//Seek (cylinder 405, Head 18, Sector 0)//Read.

6661 Status error. No UE, no flawmark, Command Address ±3 expected.

TST1, 70 Dual Controller Test. An SIO order is sent to the first controller which will reserve the device until a Release order is issued. The second controller will now try to influence that device while the first controller is in both Busy and Ready state. After the test sequence is completed, the second controller is tested in the same way. Device Address must be entered with the SYST directive:

SYST, D1, X2, X3, X4, X5, X6, X7, X8, X9, X10
where each pair (X3, X5), (X7, X9), etc., must have the same device on different controllers. A minimum of 1 pair must be entered (maximum 4 pairs).

Example: SYST, 7270, 0, F0, 202, 1F0, 202
Or: SYST, 7270, 0, F0, 202, E0, 202

7010 Expected 2 or more Device Addresses entered by 'SYST' directive.

7011 Release order for device 2 not accepted. See printout.

7012 Release order for device 1 not accepted. See printout.

7013 SIO to device 1 not accepted. See printout.

7014 IO order to device 2 was accepted, should have been rejected. See printout.

7015 IO interrupt did not occur within time limit.

# Section 9

## SIGMA 5 - 9
## ROTATING MEMORY
## TEST (726X/7275)

### PROGRAM NO. 706249

9

## Section 9

## CONTENTS

9

**SUBJECT MODEL** -- Rotating Memory Devices with Removable Disk Storage System Model 726X and 7275 through 7277

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader, or Magnetic Tape Units; Output Device: '
Keyboard Printer or Line Printer.

**PROGRAM PREREQUISITES**

Disk Packs with Prerecorded Headers Without Flawmarks and with alternate cylinder and head fields containing ones if the alternate
address field is not used.

    a.    If a Disk Pack has flawmarks written in some of its headers, some subtests of the functional test will report errors. e.g.: Flawmark in
        sector zero of head zero and cylinder zero will make the subtests 70, 71, 73, 82, 83, 84, 86, 87, 88, 90, 93, 95 and 100 fail.

    b.    Using a Selector IOP might cause error printout in some subtests of the functional test for the 726X.

TST1, 98 and 99 are dual access tests and require explicit release mode.
TST1, 79, 87  89 and 90 cannot be interrupted. If interrupted, the original header at cylinder 202, head 0, sector 0 is lost.
TST1, 106 requires a CE Pack and the tester.

**GENERAL OPERATING PROCEDURES**

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor apply to this program.

**DIRECTIVES** – directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| *Program Directives – Environmental Directives* | | | | | |
| System Environment | SYST,D1,X2,D3,X4, X5,,,X24 | D1 | Controller model number | 7260 or 7275 | |
| | | X2 | 0 | 0 | |
| | | D3 | Device type | 5, 7 | |
| | | | 5: Disk A: 203 Cyl, 20 Heads, 11 Sect/Track | | |
| | | | 7: Disk 33: 411 Cyl, 19 Heads, 11 Sect/Track | | |
| | | X4 | Description Device Number 1 | | |
| | | | Bit 0: IOP Type | | |
| | | |    0 Multiplexor    Dual | | |
| | | |    1 Selector     Access B | | |
| | | | Bits 1-15: Device Address | | |
| | | | Bit 16: IOP Type    Dual | | |
| | | |    (same above)    Access | | |
| | | | Bits 17-31: Device Address   A | | |
| | | X5 | Description Device Number 2 | | |
| | | . | | | |
| | | . | | | |
| | | D(N) | Device type | 5, 7 | |
| | | X(NH) | Description Device Number 1 | | |
| *Program Directives – Testing Directives* | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 99, and random exerciser test) | TST0 | | | | |
| Functional Test | TST1 ⎰,D1[,D2],D3,D4⎱ | D1 | 1st Subtest | 1 ~ 106 | D1   1 |
| | | D2 | Last Subtest | D2 > D1 | D2   99 |
| | | D3 | Loop count | 1 ~ 999 | 1 |
| | | D4 | Message suppress mask | 0 - FFFF | 0 |
| Random Exerciser Test | TST2,D1,D2 | D1 | Number of I/O operations to perform | 1 ~ 65535 | |
| | | D2 | Retry count | 0 ~ 99 | |
| Utility Test | TST3,D1,D2,D3,D4 | D1 | 1 Surface Test | D2   0,1,2,3,4,5 | |
| | | | 2 Header Test | D2   0,1,2,3 | |
| | | | 3 Disk Pack Initialization and Flawing | D2   0 or alternate address in Hex to be assigned. Bits 8-15 cylinder, bits 16-23 head, bits 24-31   0 | |
| | | D2 | 0 Write, Read and Verify | | |
| | | | 1 Write | | |
| | | | 2 Read and Verify | | |
| | | | 3 Read | | |
| | | | 4 Checkwrite | | |
| | | | 5 Write and Read | | |
| | | D3 | Retry count | 0 ~ 99 | |
| | | D4 | Read after Write count | 0 ~ 65535 | (TST3,1,0 TST3,1,5 TST3,2,0 only) |

**DIRECTIVES** - (Continued)

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives - Optional Directives | | | | | |
| Pattern Selection | DATA, D1[, H2, D3] | D1<br>D1<br>H2<br>D3<br><br>D1<br>H2<br>D3<br>D1<br>H2<br>D3<br>D1<br>H2<br>D3 | Pattern type<br>0, Fixed Pattern<br>Pattern<br>0<br><br>1, Incrementing Pattern<br>Starting Pattern<br>Increment<br>2, Random Pattern<br>Starting Seed<br>0<br>3, Seek Address Fixed Pattern<br>0<br>0 | 0,1,2,3<br><br>0 ~ FFFFFFFF<br><br><br>0 ~ FFFFFFFF<br>0 ~ FFFFFFFF<br><br>0 ~ FFFFFFFF | D1 - 0<br>H2 - 0<br>D3 - 0 |
| Limitation Parameter | LIMT, D1, D2[, D3, H4] | D1<br><br>D1<br>D2<br><br><br><br>D3<br><br>D1<br>D2<br><br><br><br><br><br>D1<br><br>D2<br>D3<br>H4<br><br><br>Bit<br>0<br>1<br>2<br>3<br>4<br>5<br>6<br>7<br>8<br>9<br>10<br>11<br>12<br>13<br>14<br>15<br>16<br>17<br>18<br>19<br>20<br>21<br>22<br>23<br>24<br>25<br>26<br>27<br>28<br>29<br>30<br>31 | 1, Limit the compare error print-<br>out to D2 lines.<br>2, Summary message, pass control<br>0 Inhibit cycle summary<br>message(s).<br>N Print pass summary message<br>every N passes.<br>N Total number of passes to<br>perform.<br>3<br>0 Reset<br>1 Display unconditional<br>(Test 1 only)<br>2 Suppress constant part of<br>messages.<br>4 Suppress stepping tests.<br>4 TST2, TST3 error message print/<br>inhibit.<br>0<br>0<br>32-bit message mask<br>(Bit 0-Suppress; Bit 1-Print)<br><br>Message<br>TSTX IO Address XXXX<br>--------------------<br>Time<br>(Test Description), NL, ***<br>Interrupt Not Expected<br>SIO Not Expected<br>Timeout<br>Status Error<br>Data Error<br>***<br>***Start of Operation***<br>SIO Status<br>TDV Status<br>Start Time<br>Seek Address<br>Command Word Address<br>IOCD<br>***<br>***Status at End of Oper.***<br>Interrupt Not Received<br>AIO Status<br>TIO Status<br>TDV Status<br>Current Command Doubleword<br>Remaining Byte Count<br>Status Correct<br>(Sense Data Avail. Flag)<br>Sense Data (W Issue)<br>***<br>***Data at End of Oper.***<br>(Compare Data)<br>(System Status) | | D2 = 5<br><br><br><br><br><br>D2 - 1, D3 - 1<br><br><br><br><br><br><br>D2 - 0<br>H4 - X'FFFFFFFF' |

DIRECTIVES - (Continued)

| Name | Format | Parameter | | | |
|------|--------|-----------|--|--|--|
| | | ID | Definition | Value Range | Standard Value (default) |
| Memory Limitation for I/O Buffer | MEM,H1,H2 | H1<br>H2 | Starting Buffer Word Address<br>Ending Buffer Word Address | 0 ~ Mex Mem<br>H1 < H2 | Maximum avail-able memory reset to default value. Set by SYST directive. |
| Surface Limitation | SEEK,D1,D2,D3,D4 | D1<br><br>D2<br><br>D3<br>D4 | Starting Cylinder or Track<br><br>Starting Head or 0<br><br>Starting Sector<br>Number of Sectors to be tested | 0 ~ 202 (Disk A)<br>0 ~ 410 (Disk 33)<br>0 ~ 19  (Disk A)<br>0 ~ 18  (Disk 33)<br>0 ~ 10<br>0 ~ 44660 (Disk A)<br>0 ~ 85899 (Disk 33) | The Entire Surface |

## START PROCEDURE

1.  Sense Switch Options, Monitor Directives Options, and Environmental Directives – Refer to DPM Manual No. 901649
2.  Test Strategy Selections

|  | Comprehensive Test | Functional Test | Random Exerciser | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem | Intermittent Failure Detection | Surface Test |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | SEEK, LIMT, MEM | LIMT, DATA (Test 104 Only) | SEEK, LIMT, MEM | SEEK, LIMT, MEM, DATA |
| Subtests | Functional test 1 ~ 99 and Random Exerciser | 106 subtests Four of them require operator intervention. See description. | 1. Surface Initialization<br>2. Random Exercising<br>3. Surface Verification | 1. Surface Test<br>2. Header Test (Disk Pack)<br>3. Disk Pack Initialization and Flawing |
| Error Message Format | Self-explanatory | Self-explanatory | Self-explanatory | Self-explanatory |

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the Rotating Memory Controller Test Program.

TST0 Comprehensive Test
This directive selects the functional test 1~99 and the random exerciser and executes them with reporting of Start and End of the tests.

Parameters:    None

TST1 Functional Test
The functional test performs testing on one or more devices one device at a time.

Parameters:    P1    Number of first subtest
               P2 – Number of last subtest
               P3    Loop count
               P4    Message suppress flag

Default Values:    For TST1:    P1 1, P2 99, P3 1 and P4 0

The functional test consists of over 100 subtests. These subtests are arranged in a sequence in order to perform the basic functions first and then the more complex ones:

| Number | Subject of Test | Mode |
|---|---|---|
| 1– 5 | Basic IOP and cont. functions | Normal/test mode |
| 6– 9 | FAM buffer tests | Buffer test mode |
| 10– 64 | Controller functions | Contr./Incr. contr. TM |
| 65– 99 | Device and contr. functions | Normal/device test mode |
| 100–106 | Special tests with manual intervention | |

There are three ways of selecting these subtests with the directive 'TST1':

1. No Parameter, e.g., TST1 (Equal to TST1, 0, 0)
   All subtests from 1 to 99 are performed sequentially.
2. One Parameter, e.g., TST1, 15
   Only one subtest is performed.
3. Two Parameters, e.g., TST1, 10, 15
   The subtests from subtest parameter 1 to subtest parameter 2 are performed sequentially.

When the selected subtest(s) is (are) finished, the next device (according to SYST directive) will be tested. The subtests 1 to 64 are testing only controller functions. They are issued with the controller address 'XXXF'. No actual device is needed to perform these subtests. Yet a model number and a device address are to be inserted with the SYST directive. This determines the device type. According to this device type are the controller functions tested.

Print out will not occur, if the subtests run successfully and display mode was not selected. (Exception: subtests 101, 102, and 103, which need manual intervention)

The error printout is controlled by the sense switches and the limit-directive.

The interrupt and reset buttons on the CPU Control Panel should not be used to stop the execution of a subtest. The use of these buttons might cause errors in the next selected subtest because controller and device are not reset to the initial state.

Definition of the Sense Switches

| SSW | 1 | 2 | 3 | 4 | Definition |
|---|---|---|---|---|---|
| | X | X | X | 1 | Print inhibit |
| | X | 0 | 0 | X | Wait after test sequence(if error)/sequence of subtests |
| | 0 | 0 | 1 | X | Continue with next test sequence(if error)/return to DPM |
| | 1 | 0 | 1 | X | Loop on test sequence(if error)/sequence of subtests |
| | X | 1 | X | X | Loop on intermittent error |

A test sequence consists of one or more I/O instructions and tests on data. It is the smallest unit in the functional test on which looping and reporting is performed. A sequence of subtests consists of the subtests selected thru the parameters 1 and 2 of the TST1-directive.

Priorities of Looping and Printing Control

| Priority | Means of Control |
|---|---|
| | Printing |
| 1 | Sense switch 4: Print inhibit |
| 2 | Display directive: Print unconditionally |
| 3 | Print inhibit set by program |
| 4 | Print of errors |
| | Looping |
| 1 | Loop inhibit set by program |
| 2 | Sense switch 1,2 and 3 in functional test driver |
| 3 | Loop count after subtest |
| 4 | Sense switch 1,3 after subtest |

The third parameter (P3) of the TST1-directive specifies a loop count. It specifies how often a subtest shall be repeated, before the next subtest can be performed.

Default Value:    1    (0 is set equal 1)

The fourth parameter (P4) of the TST1-directive specifies a suppress flag. The suppress flag is a 16 bit mask written as a hexadecimal number. Each bit in this mask stands for one of 16 functional test subroutines:

| Bit | Mask | | |
|---|---|---|---|
| 0 | 8000 | T1APT | Pattern spread routine |
| 1 | 4000 | T1ATM | Test mode selection routine |
| 2 | 2000 | T1ASK | Seek routine |
| 3 | 1000 | T1AIS | Instruction sequence routine |
| 4 | 0800 | T1AEX | Execution routine |
| 5 | 0400 | T1AES1 | Escape routine 1 (special testing) |
| 6 | 0200 | T1ASIO | Start I/O routine |
| 7 | 0100 | T1AWT | Wait for IO completion routine |
| 8 | 0080 | T1AES2 | Escape routine 2 (special testing) |
| 9 | 0040 | T1AST | Stepping routine |
| 10 | 0020 | T1AIO1 | IO instruction routine 1 (TIO,TDV,HIO,AIO) |
| 11 | 0010 | T1AIO2 | IO instruction routine 2 (TIO,TDV,HIO,AIO) |
| 12 | 0008 | T1AIO3 | IO instruction routine 3 (TIO,TDV,HIO,AIO) |
| 13 | 0004 | T1ASN | Sense routine |
| 14 | 0002 | T1ACP | Compare routine |
| 15 | 0001 | T1AES3 | Escape routine 3 (special testing) |

If the corresponding bit is set, no report is made for this subroutine. If any bit is set, the heading with subtest number and IO address is suppressed also, e.g., 'FFFC' suppresses all but the printout of the compare routine and the escape routine. See error printout example for the use or parameters.

Default Value:    0

Some subtests are performed under certain conditions: Subtest 98 and 99 are only performed for a dual access configuration.

Different Modes to be used in TST1

Display Mode
In display mode a report is printed out after each execution of a test sequence, this mode is selected by the Limit directive.
e.g., LIMT,3,1 Sets display,    LIMT,3,0 Resets display

Suppress Mode

In suppress mode all constant text is suppressed in the printout. Only the decimal, hexadecimal or binary numbers are printed. This mode is selected by the Limit directive.
e.g., LIMT,3,2 Sets suppress mode,    LIMT,3,0 Resets

Suppress Stepping Tests

In this mode all tests using stepping mode are suppressed. This mode is selected by the LIMT directive.
E.G.: LIMT,3,4 sets suppress stepping tests
The selection of TST2 or TST3 also causes a suppression of these tests. The suppression by TST2 or TST3 selection cannot be reset, because the memory area containing the expected stepping data is used as buffer area for TST2 and TST3.

TST2 Random Exerciser
The random exerciser performs testing on one or more devices in a pseudo random manner. All devices are kept as busy as possible.

Parameters:    P1    Number of I/O operations to perform
               P2    Retry count

Example:       TST2, 5000, 1
               Perform the exerciser for 5000 operations.
               Retry of errors: one

The exercising consists of three parts:
1. Surface Initialization  – Random data is placed on all surface (or surface limited by seek directive).
2. Random Exercising       – Individual and combinations (DC and CC) of operations are performed on randomly selected surfaces.
3. Surface Verification    – Surface is read and data re-verified.

Flaw marks are acceptable (correct termination status is checked). Status or data errors cause operation to be repeated P2 times. Status errors inhibit checking of corresponding data. Exercising is controlled (in order of precedence) by:
1. Number of IO operations specified in TST2 directive.
2. Number of passes to perform specified in LIMT directive.
3. Looping controlled by sense switch 1.

All available memory is used unless limited by the MEM directive. However, a minimum of 1025 words are required for buffer area. The LIMT directive may be used to suppress all error message constants and/ or suppress any portion of the error message.

TST3 Utility Tests
The utility tests consist of a set of tests to perform sequential surface and header testing and disk pack initialization/flawing.

Parameters:    P1  1  Surface Test
                   P2  0  Write, Read and Verify
                   P2  1  Write
                   P2  2  Read and Verify
                   P2  3  Read (No Verify)
                   P2  4  Checkwrite
                   P2  5  Write and Read (No Verify)
               P1  2  Header Test (Disk Pack Only)
                   P2  0  Write, Read and Verify
                   P2  1  Write
                   P2  2  Read and Verify
                   P2 = 3  Read
               P1  3  Disk Pack Initialization and Flawing
                   P2  0  or Alternate (in HEX) to be assigned
                          (Bits 8-15    CYL; Bits 16-23    Head)
               P3 = Retry Count (0 < P3 < 99)
                    Default    0
               P4 = Read after Write Count (TST3,1,0 and TST3,1,5
                    and TST3,2,0 Only)
                    (0 = P4   65535)

Surface Testing  –  All surface is used unless limited by Seek directive. Status errors are retried a maximum of P3 times. Data errors with no accompanying status errors cannot be retried. Data used is specified by the data directive. Flaw marks are acceptable (correct termination status is checked).

Header Testing  –  All surface is used unless limited by Seek directive. Status errors are retried a maximum of P3 times. Header data errors (including flaw marks in header) with no accompanying status errors cannot be retried. Therefore flaw marks are reported as errors.

Disk Pack Init and Alternate Assignment Flawing  –  Initialization consists of one pass each: Write Header, Read Header, Write Data, Read Data. All surface is used unless limited by Seek directive. Data used is specified by Data directive. Header status errors cause premature termination of test. Surface errors are retried a maximum of P3 times. Failure after P3 retries causes all sectors of the failing track (CYL,HEAD) to be flawed (Flaw mark placed in headers of sectors 0 thru N). Flawing of more than 6 tracks (CYL,HEAD) causes premature test termination. No alternates are assigned.

Alternate assignment/flawing consists of writing of headers in sectors 0 thru N of the cylinder and head specified in the Seek directive. The headers written contain flaw marks and alternate CYL, head assignments specified by TST3 directive P2. Note that P2 non-zero selects the assignment/flawing operation. Therefore CYL  0, HEAD  0 cannot be used as alternates.

Speed of testing is a function of the type of data used. All available memory is used unless limited by the MEM directive. However, a minimum of 770 words are required for buffer area.

Testing is controlled (in order of precidence) by:
1. Number of sectors specified
2. Read after Write count specified by TST3 directive P4 (TST3,1,0 and TST3,1,5 and TST3,2,0 only)
3. Number of passes to perform specified in LIMT directive.
4. Looping controlled by sense switch 1.

Example:    Sense Switch 1 = 0
            LIMT,2,1,2 Entered
            SEEK,0,0,0,220 Entered
            DATA,2, 12345678
            TST3,1,0,4,50 Entered

Result:     All sectors of cylinder 0 are written with random data, then all sectors of cylinder 0 are read and data is verified, then all sectors of cylinder 0 are read and verified 50 additional times, then all above is repeated once again (since LIMT directive pass count set to 2). All status errors result in operation retries not to exceed 4.

The LIMT directive may be used to suppress all error message constants and/or suppress any portion of the error messages.

A particular random pattern found failing on particular sector(s) during the random exercising may be used during the surface test by limiting the surface with the Seek directive and specifying Data,2,P2 directive with P2 equal to the value of the "Base Seed" printed in the error message of TST2.

## ORDER CODES

| | |
|---|---|
| X'01' | WRITE |
| X'02' | READ 2 |
| X'03' | SEEK |
| X'04' | SENSE |
| X'05' | CHECKWRITE |
| X'07' | RESERVE |
| X'09' | HEADER WRITE |
| X'0A' | HEADER READ |
| X'0F' | CONDITION RELEASE INTERRUPT |
| X'12' | READ 1 |
| X'13' | SELECT TEST MODE (See Test Mode Data Bytes) |
| X'1F' | CONDITION RELEASE INTERRUPT (and Set a CIL on Device Release) |
| X'17' | RELEASE |
| X'33' | RESTORE CARRIAGE |
| X'83' | SEEK (and Cause a Device Interrupt on Positioning Complete or SEEK Timeout Error) |
| X'B3' | RESTORE CARRIAGE (and cause a Device Interrupt on Positioning Complete) |

## TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| RMC | Not Assigned | Flaw Detection | Programming Error | Write Protect Violation | Parity Error (IOP) | Operational Error | Verification Error | Header Parity Error |

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| RMC | Rate Error (Data overrun) | Attention Interrupt | Release Interrupt | Not Assigned | On-Sector Interrupt | Not Assigned | Seek Timeout Error Interrupt | Not Assigned |

### DETAILED DESCRIPTION OF TDV STATUS

| Bit Position | Function | Value | |
|---|---|---|---|
| 1 | | 1 | **TDV Bit 1 -- Flaw Detection**<br><br>Flaw byte detected during Header Read, Write, Read, or Checkwrite |
| 2 | | 1 | **TDV Bit 2 -- Programming Error**<br><br>Invalid order detected; or illegal address (address X'F' used for orders other than Select Test Mode or Conditional Release Interrupt); or invalid Seek address; or address incremented out of limits while attempting a Read or Write order; or invalid test mode; or Seek order received while arm was in motion; or first seven bits of Seek order were not zero; or incorrect length detected for Seek, Sense, Header Read, or Header Write order. |
| | | | **TDV Bit 3 -- Write Protect Violation**<br><br>Write-protect violation |
| | | | **TDV Bit 4 -- Parity Error (IOP)**<br><br>Order parity error detected; or Seek address parity error detected; or even parity received on a terminal order; or IOP detected an address parity error (channel address parity error). |
| | | | **TDV Bit 5 -- Operational Error**<br><br>Device interface error detected; or missing an on-sector signal from device during a multi-sector Read or Write; or missing Read or Write clock, command strobe, or status request acknowledgement from the device; or detection of Seek address transfer verification comparison error during Seek, Read, or Write; or device unavailable error, or "not operational" signal detected from device by the controller, or a seek error during a Read or Write. |
| 6 | Verification | 1 | **TDV Bit 6 -- Verification Error**<br><br>Head address verification error detected; or sector address verification error detected; or cylinder address verification error detected. |
| 7 | Header check byte | 1 | **TDV Bit 7 -- Header Parity Error**<br><br>Header check byte error |

## TEST MODE DATA BYTE

Test mode order puts the controller in test mode and requests two data bytes from the IOP.

1st Data Byte    Test Mode
2nd Data Byte    Device type or diagnostic conditions

1st DATA BYTE

| Bits | Meaning |
|---|---|
| When Set | |
| 7 | Buffer Test Mode |
| 6 | Controller Test Mode |
| 5 | Device Test Mode |
| 4 | Incremental Clock Test Mode |
| 3 | Force Device I/O Parity Error |
| 2 | Force Read Data Error |
| 1 | Force IOP Input Parity Error |
| 0 | Force IOP Output Parity Error |

(Bits 0-7   0   Invalid Test Order)

2nd DATA BYTE

| Bits | Meaning |
|---|---|
| 0-7 | Diagnostic Test Conditions for the Device (In Device Test Mode only) |
| 5-7 | Device Type Code (In Controller Test Mode only) X'5' = Disk Drive A X'7' = Disk 33 |

## ADDRESSING FORMAT

1.  The format of the four bytes seek address is:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|---|---|---|---|
| ◄── Cylinder ──► | | Head | Sector |

Description of Parameters:
Cylinder   0 ~ 202 (Disk Drive A)
           0 ~ 411 (Disk Drive 33)
Head   0 - 19 (Disk Drive A)
       0 ~ 18 (Disk Drive 33)
Sector = 0 ~ 10

2.  The format of the sixteen bytes of information to be received by the IOP when a sense order is issued is:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|---|---|---|---|
| W 0 0 0 0 0 0 | ◄── Cylinder ──► 0 0 0 | Head 0 0 0 | Sector |

0 1 2 3 4 5 6 7 0          7 0 1 2 3     7 0 1 2 3          7

| Byte 4 | Byte 5 | Byte 6 | Byte 7 |
|---|---|---|---|
| M R Angular Position | Configuration | Device Status | 0 ─────── 0 |

0 1 2        7 0        7 0        7        7

| Byte 8 | Byte 9 | Byte 10 | Byte 11 |
|---|---|---|---|
| Faults | Faults | Seek Modifier Bits | |

0        7 0        7 0          7 8          15

| Byte 12 | Byte 13 | Byte 14 | Byte 15 |
|---|---|---|---|
| Check Bytes | | Difference | |

0                15 0                    15

These four words describe the controllers current state.

Description of Parameters:
W    Write Protect Bit.
     If set, current address is Write Protected.
Cylinder   9-Bit Cylinder Address
Head   Head Address
Sector   Sector Address
M = Modifier Bit.
    If set, arm is in motion and file inaccesible.

R    Reserve/Release Mode.
     If set:    Implicit reserve, explicit release in effect
     If reset:  Implicit reserve and release in effect
Angular Position:  A Sector Number.
                   When this equal to sector address, file is
                   accessible.
Configuration   Bit 0 (Set) = Addressed device has the dual access
                              feature.
                Bits 1-3   Device Type
                           X'5'   Disk Drive A
                           X'7' = Disk Drive 33
                Bits 4-7   Device Physical Address
Device Status   Status Received
Faults   Diagnostic Fault Data. Resulted from 'Transmission Errors'
         and 'Unusual End' terminations. They are as follows:

Byte 8

| Bit 0 | Bit 1 | Bit 2 | Bit 3 | Bit 4 | Bit 5 | Bit 6 | Bit 7 |
|---|---|---|---|---|---|---|---|
| Check Write Error | Data Check Byte Error | IOP Parity Error | Rate Error (Data Over-run) | Head Address Incre-mented Out of Limits | Arm in Motion Error | Order Parity Error | Test Mode Order Error |

Byte 9

| Bit 0 | Bit 1 | Bit 2 | Bit 3 | Bit 4 | Bit 5 | Bit 6 | Bit 7 |
|---|---|---|---|---|---|---|---|
| Seek Address Trans-fer Error | Device Error | Head Address Verifi-cation Error | Sector Address Verifi-cation Error | Cyl. Address Verifi-cation Error | Unas-signed | Channel Address Error | Read/Write Error |

Seek Modifier Bits    Seek/Restore Carriage Modifier Bits.
                      Bit 0   Device Address 0
                      Bit 14   Device Address X'E'
                      A "One" set in any bit position means an
                      interrupt is pending or seek timeout.
Checkbytes   Last check bytes received by controller.
Difference   Difference last computed by controller during a seek
             order execution.
             Least Sig. Bit   Bit 15
             Most Sig. Bit   Bit 7

**ADDRESSING FORMAT** (Continued)

3.  The format of the eight bytes header size is:

| Byte 0 | Byte 1 | Byte 2 | Byte 3 |
|--------|--------|--------|--------|
| Flow   | ◄——— Cylinder ———► | | Head   |

0          7

| Byte 4 | Byte 5 | Byte 6 | Byte 7 |
|--------|--------|--------|--------|
| Sector | Alternate Cylinder | Alternate Head | 0 ———— 0 |

Description of Parameters:

Flow    Flow Byte. This is written X'FF' in every sector header
        of a track in which a flaw is detected. If no flaws, the
        flaw byte is all zeros.

Cylinder    Current Cylinder Address.

Head    Current Head Address.

Sector    Current Sector Address.

Alternate Cylinder    Address of an alternate cylinder should this
                      sector be flawed, otherwise it is all ones.

Alternate Head    Address of alternate head should this sector be
                  flawed. Otherwise it is all ones.

## FUNCTIONAL SUBTESTS

### FUNCTIONAL SUBTESTS – DESCRIPTION

TST1,01 HIO, TIO, TDV Recognition Test

Mode: Normal Mode

HIO, TIO and TDV instructions are issued. I/O address recognition and normal status expected. This subtest and the subtest 02 to subtest 64 are using a modified device address to select only the controller. The least significant 4 bits are set to X'F'.

TST1,02 Invalid Order Test

Mode: Normal Mode

SIO instructions are issued with all valid orders except test mode selection order and condition release interrupt order. With device address 'F' these orders are terminated as invalid orders with TIO bit 4 and TDV bit 2 set. The byte count is 1. It is expected that the byte count is not changed.

An Hio is used to reset the TIO/TDV status. The reset is verified with another TIO/TDV.
Test Variations:
1. Check of TIO status
2. Check of TDV status

TST1,03 Test Mode Selection Test

Mode: Buffer/Controller/Device Test Mode

Test mode selection orders are issued with the bytes X'01', X'02', and X'04' in order to switch the controller in buffer-, controller-, and device-test mode. Set and reset of the test mode indication is verified by a sequence of TDV, HIO and TDV instructions.
Test Variations:
1. First Testmode Byte = 01
2. First Testmode Byte = 02
3. First Testmode Byte = 04

TST1,04 Interrupt Generation Test

Mode: Normal Mode

Test mode selection orders are issued with 1 Byte equal zero. There-fore unusual end is always expected. The interrupt flags are set to test interrupts on unusual end, channel end and zero byte count. In three passes, the following conditions are tested:
Test Variations:
1. Interrupt disarmed, reset in int. pend. by HIO
2. Interrupt disarmed, reset of int. pend. by AIO
3. Interrupt armed, reset of int. pend. by AIO, another AIO is issued to check for no int. recogn.

TST1,05 Command Chaining Test

Mode: Normal Mode

Two test mode selection orders are issued command chained.
Test Variations:
1. Testmode Byte = 0, no CC expected
2. Testmode Byte = 1, CC expected
TIO and TDV instructions are used to verify the correct execution.

TST1,06 FAM Write/Read: Byte Count Test

Mode: Buffer Test Mode

Write and Read orders are issued. The byte counts 1 thru 32 are used. Final byte count of zero is expected. A TIO instruction is used to verify the correct execution.

TST1,07 FAM Write/Read: Interface Test

Mode: Buffer Test Mode

Write and Read orders are issued to test the byte alignment logic of the controller.
Test Variations:
1. 4 IOCDS (2 Write,BC=2 and 2 Read,BC=2)
2. 3 IOCDS (2 Write,BC=2 and 1 Read,BC=4)
3. 3 IOCDS (1 Write,BC=4 and 2 Read,BC=2)
4. 2 IOCDS (1 Write,BC=4 and 1 Read,BC=4)
A TIO instruction is used to verify the correct execution. The observed data are compared with the expected data.

Four passes are executed with the data: X'010203041', X'F1F2F3F4', X'1F2F3F4F', X'A55AC33C'

TST1,08 FAM Write/Read: Byte Alignment Test

Mode: Buffer Test Mode

Write and Read orders are issued with byte counts equal 13 to test the byte alignment logic of the controller and the IOP.

The 4 byte alignment cases are exercised in 4 passes. Before each pass the 1st and the 4th words of the Read Data Buffer are filled with the pattern X'FFFFFFFF'. A TIO instruction is used to verify the correct execution. The observed data are compared with the expected data.

TST1,09 FAM Write/Read: Random Data Test

Mode: Buffer Test Mode

A Write order command chained to a read order is issued. The byte count is 32.

A TIO instruction is used to verify the correct execution. The observed data are compared with the expected data.

The test sequence is repeated 100 times with random data.

TST1,14 Sense Test

Mode: Incremental Controller Test Mode

A Sense order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus.

Phase Data, Byte count data and device command data are verified by comparison with expected data. Bus data are not checked.

TST1,15 Sense Test

Mode: Controller Test Mode
Test Variations:
1. Sense orders are issued with byte counts 1 thru 16. TIO and TDV instructions are used to verify the correct execution.
2. A Sense order is issued. Controller fault bits and interrupt modifier bits are checked for zeros.

TST1,16 Condition Release Interrupt Test

Mode: Controller Test Mode

A condition release interrupt order is issued. TIO and TDV instructions and a sense order are used to verify the correct execution of the order.

TST1,17 Release Test

Mode: Controller Test Mode

A Release order is issued. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,18 Restore Test

Mode: Incremental Controller Test Mode

A Restore order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,19 Restore Test

Mode: Controller Test Mode

A Restore order is issued. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,20 Seek Test

Mode: Incremental Controller Test Mode

A Seek order is issued. The Seek address consists of the pattern X'FFFFAA00'. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,21 Seek Test

Mode: Controller Test Mode

A Seek order is issued. The Seek address is Cylinder - 0, Head - 0, Sector - 0. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,24 Seek: Incorrect Length Test

Mode: Controller Test Mode

Seek orders are issued. The Seek address is 0/0/0. Incorrect length is checked with the byte counts of 1,2,3 and 5. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,25 Seek: Incorrect Address Test

Mode: Controller Test Mode
Seek orders are issued. The Seek address is always incorrect.
Test Variations:
1. Incorrect Sector Address
2. Incorrect Head Address
3. Incorrect Cylinder Address
TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,26 Seek: Difference Test

Mode: Controller Test Mode
Two Seek orders are issued. The Seek address of the first Seek order is constant: Cylinder - 0, Head 0, Sector 0. The Seek address of the second Seek order is changing the Cylinder address from 0 to N, Head 0 and Sector 0. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.
N   202 for Disk A
N   410 for Disk 33

TST1,27 Seek: Device Interface Error Test

Mode: Controller Test Mode

Seek orders are issued in controller testmode with Seek addresses different from zero. Sense orders are issued to verify that address transfer error is set (Sense byte 9, bit 0).
Test Variations:
1. Cylinder Address   1
2. Head Address   1
3. Sector Address   1

TST1,28 Seek: Address Buffer Test

Mode: Controller Test Mode

Seek orders are issued with all device addresses and the Seek address consisting of the following patterns:
Disk: X'00000F07' and X'00001008'
RAD: X'01FF000B' and X'01AA0007'
Sense orders are issued to read these addresses back for verification.

TST1,29 IOP Device Address Parity Error Test

Mode: Controller Test Mode
Sigma 9 Only
Test Variations:
1. The test mode selection order is set to force a device parity error during ASC. The parity of forced to '1'. Therefore, all addresses with odd parity will result in a parity error.
2. The test mode selection order is set to force a device parity error for I/O instructions. If the device is in the busy state, the parity line is forced to a '0'. Therefore, all addresses with even parity will result in parity errors.

TST1,32 Header Write Test

Mode: Incremental Controller Test Mode

A Header Write order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,33 Header Write Test

Mode: Controller Test Mode

A Header Write order is issued. The byte count is 8. TIO and TDV instructions and a sense order are used to verify the correct execution of the order.

TST1,34 Header Read Test

Mode: Incremental Controller Test Mode

A Header Read order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,35 Header Read Test

Mode: Controller Test Mode

A Header Read order is issued. The byte count is 8. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order. The Header data are verified. All data in controller test mode consist of the repetitive pattern X'803FD56A'.

TST1,36 Read Test

Mode: Incremental Controller Test Mode

A Read order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,37 Read Test

Mode: Controller Test Mode

A Read order is issued. The byte count is 1024. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order. The Read data are compared with the expected data.

TST1,38 Write Test

Mode: Incremental Controller Test Mode

A Write order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,39 Write Test

Mode: Controller Test Mode

A Write order is issued. The byte count is 1024. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,40 Check Write Test

Mode: Incremental Controller Test Mode

A Check Write order is issued. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data, device command data and data bus data are verified by comparison with expected data.

TST1,41 Check Write Test

Mode: Controller Test Mode

A Check Write order is issued. The byte count is 1024. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,42 Short Record Test

Mode: Controller Test Mode

Read, Write and Check Write orders are issued. The byte counts are 2. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order. The Read data are compared with the expected data.

TST1,43 Checkwrite Error Test

Mode: Controller Test Mode

A Check Write order is issued. The byte count is 1024.
Test Variations:
1. Checkwrite error in 1st byte
2. Checkwrite error in 1024th byte
TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,45 Header Write,...: Incorrect Length Test

Mode: Controller Test Mode

Header Write and Header Read orders are issued. Incorrect length is checked with the byte counts of 6,7,9 and 10. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,46 Write,...: Incorrect Length Test

Mode: Controller Test Mode

Write, Check Write and Read orders are issued. The byte counts are number of bytes per sector plus -2, -1, +1, +2. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,47 IOP Halt Test

Mode: Controller Test Mode

Write, Check Write and Read orders are issued command chained to a double transfer in channel. An IOP halt is forced during the execution of the orders by the double transfer in channel. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order. The test is repeated with the byte counts of 512, 256, 128, 64, 32, 16, 8 and 4.

TST1,48 HIO Halt Test

Mode: Controller Test Mode

Write, Check Write and Read orders are issued. An HIO is issued during the execution of the orders. TIO and TDV instructions are used to verify the correct termination.

TST1,49 IOP Output Parity Error Test

Mode: Controller Test Mode

The test mode selection order is set to force IOP output parity errors: in five passes the following subjects are tested:
Test Variations:
1. Failure in Order Out, Seek Order X'03' (Sigma 9 Only)
2. Failure in Data Out, Seek Order X'83'
3. Failure in Data Out, Write Order
4. Failure in Data Out, Write Order (Sigma 9 Only)
5. Failure in Terminal Order, Read Order (Sigma 9 Only)

TST1,50 IOP Input Parity Error Test

Mode: Controller Test Mode

The test mode selection order is set to force IOP input parity errors.
1. Read order is issued with a byte count of 1024.
2. Write order is issued with a byte count of 1023. (Sigma 9 Only)
TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

TST1,51 Rate Error Test

Mode: Controller Test Mode

Write, Check Write and Read orders are issued with a byte count of 1 and data chaining. The continuous data chaining and transfer in channel slow the IOP down in its byte transfer rate to cause rate error. TIO and TDV instructions and a Sense order are used to verify the correct execution of the order.

# 9. SIGMA 5–9 ROTATING MEMORY TEST (726X/7275)

**600P81036**

### TST1,53 Interrupt Modifier Bit Test

Mode: Controller Test Mode

The interrupt modifier bit test verifies the correct setting of the Seek modifier bits on Seek orders X'83' or Restore orders X'83' (Disk Only) and the correct resetting by AIO's for all device addresses. This test also verifies for all device addresses:
1. The generation of interrupt pending
2. The rejection of SIO's to addresses with interrupt pending
3. The execution of SIO's while interrupts are pending for other addresses.

### TST1,54 Write, ...: Address Incrementing

Mode: Controller Test Mode

Write, Check Write, Read, Header Write and Header Read orders are issued to check the address incrementing. TIO and TDV instructions and a Sense order are issued to verify the correct execution. The Seek address is varied in two passes:
Test Variations:
1. Cyl/Head/Sect - 0/0/0
2. Cyl/Head/Sect - 0/0/9

### TST1,56 Write,...: Address Boundary Test

Mode: Controller Test Mode

Write, Check Write, Read, Header Write and Header Read orders are issued to check the boundary. TIO and TDV instructions and a Sense order are issued to verify the correct execution. The byte count is 1024.
Test Variations:
1. The Seek address is set to Write,... at the last sector of Cyl. 0
2. Another Write, ... order is issued without a previous Seek order.

### TST1,57 Controller Busy Test

Mode: Controller Test Mode

A Read order is issued with the device address 'F'. During the execution of this order SIO, TIO, TDV and HIO instructions are issued with device addresses 0 to E.

### TST1,65 Invalid Order Test

Mode: Normal Mode

SIO instructions with invalid orders are issued. All invalid orders are used.
Test Variations:
1st Test of TIO status
2nd Test of TDV status

### TST1,66 Sense Test

Mode: Incremental Device Test Mode

TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data and device command data are verified by comparison with expected data. Bus data are not checked.

### TST1,67 Sense Order and Angular Position Test

Mode: Normal Mode

Sense orders are issued. TIO and TDV instructions are issued to verify the correct execution. All Sense data are verified, except byte 5, bit 0 (Dual Access Configuration Flag), byte 5, bit 4-7 (Hardware Device Address) and byte 12 and 15.
Test Variations:
1. A maximum of 11 Sense orders are issued to find sector zero.

2. With 10 Sense orders, angular position 1 thru 10 is checked.

### TST1,68 Seek Test

Mode: Incremental Device Test Mode

A Seek order is issued. The Seek address consists of the pattern X'00CA1309'. TDV instructions are used to increment the controller clock and to collect data from the following modules of the controller: Phase Register, Byte Count Register, Device Command Register and Data Bus. Phase data, byte count data and device command data are verified by comparison with expected data. Bus data are not checked.

### TST1,69 Seek Test

Mode: Normal Mode

Seek orders are issued. TIO and TDV instructions and a Sense order are issued to verify the correct execution.
Test Variations:
1. Seek address: Sector 0 thru 10
2. Seek address: Head 0 thru 19 (Disk A)
             0 thru 18 (Disk 33)

### TST1,70 Header Read Test

Mode: Normal Mode

The sequence of orders Seek – Header Read is issued. TIO and TDV instructions and a Sense order are issued to verify the correct execution. The byte count is 8. The Header data are expected to be zero. The data buffer for observed data (Buffer B) is filled with the pattern X'FFFFFFFF', X'FF0000FF'.

### TST1,71 Write, Check Write and Read Test

Mode: Normal Mode

The sequences of orders Seek – Write, Seek – Check Write, and Seek – Read are issued. TIO and TDV instructions and a Sense order are issued to verify the correct execution.
Test Variations:
1. Write order
2. Check Write order
3. Read order
The byte count is 1024. The Read data are compared with the expected data.

### TST1,72 Reserve and Release Test

Mode: Normal Mode

1. A SIO instruction is issued with a reserve order. TIO and TDV instructions are used to verify the correct execution.
2. A SIO instruction is issued with a release order. TIO and TDV instructions are used to verify the correct execution.
No operation is expected by these orders.

### TST1,73 Matrix Test

Mode: Normal Mode

The matrix test is supposed to check all heads and to print errors in the form of a matrix.

Header Read orders are issued to all heads. The errors unusual end, verification error, flaw mark and the observed header data are printed out for each faulty head.
e.g.:
```
     UE V F HEADER DATA
Head 001  1 1 1 FF 00  0001 0000 0000
```

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TST1,74 Restore and Seek Test

Mode: Normal Mode

Restore and Seek orders are issued. TIO and TDV instructions and a
Sense order are issued to verify the correct execution. The Seek address
is Cyl   N, Head   0, Sector   0. Test Variations:
1.  Restore order
2.  Seek order
3.  Restore order
4.  Seek order /CC/ Restore order
Address and difference of Sense are tested.
N    202 for Disk A
N    410 for Disk B

TST1,75 Seek Order: Interrupt Test

Mode: Normal Mode

Seek orders are issued. (Seek with interrupt on Sector Flag.) TIO and
TDV instructions and a Sense order are issued to verify the correct
execution. Test Variations:
1.  Check for interrupt
2.  Check for withdrawal of interrupt during one revolution

TST1,76 Restore Order: Interrupt Test

Mode: Normal Mode

Restore orders are issued. (Restore with interrupt on Sector.) TIO and
TDV instructions and a Sense order are issued to verify the correct
execution. Test Variations:
1.  Check for interrupt
2.  Check for withdrawal of interrupt during one revolution

TST1,77 Seek Order: Head Moving Test

Mode: Normal Mode

Seek orders with command chained Sense orders are issued. TIO and
TDV instructions are issued to verify the correct execution. The
Cylinder address is incremented from 0 to N and then decremented
from N to 0. Head and Sector address are zero. Byte 4 Bit 0 of
the Sense data is checked (Head in motion bit).
N    202 for Disk A
N ⁻ 410 for Disk B

TST1,78 Seek Order: Head Positioning Test

Mode: Normal Mode

Seek orders are issued. (Seek Interrupt Flag.) TIO and TDV
instructions are issued to verify the correct execution. Header Read
orders are issued to verify the Seek position. Two Seek addresses are
used in sequence. These two addresses Addr. 1 and Addr. 2 are va
varying the Cylinder address part in four passes. The Head and Sector
parts of the addresses are zero. Test Variations:
1.  Addr. 1 is increm. from 0 to N, Addr. 2   0
2.  Addr. 1 is decrem. from N to 0, Addr. 2   N
3.  Addr. 1 is increm. and Addr. 2 is decremented
4.  Random addresses for Addr. 1 and Addr. 2 (N+1 times).

After each pass the average access time is computed. An averaoe
access time greater than M mSec is an error which causes a printout.
N = 202 for Disk A          M = 57 msec (Disk A)
N = 410 for Disk 33         M = 48 msec (Disk 33)

TST1,79 Header Write and Header Read Test

Mode: Normal Mode

The sequences of orders Seek – Header Read and Seek – Header Write
are issued. TIO and TDV instructions and a Sense order are issued to
verify the correct execution. The Seek address is Cyl   202, Head   0,
Sector = 0. The byte count is 8. Test Variations:
1.  Header Write: Data = 0, 0, 202, 0, 0, X'FFFF00'
2.  Header Read with compare
3.  Header Write: Data   0, 0, 202, 0, 0, 0, 0, 0
4.  Header Read with compare

TST1,82 Write Order: Multiple Sector Write Test

Mode: Normal Mode

Write orders are issued to Write all sectors of Cyl. 0. TIO and TDV
instructions and a Sense order are issued to verify the correct
execution. The byte count is 1024. The Write order is repeated by
using data chaining and transfer in channel until an interrupt on
unusual end occurs because of boundary error. The minimal time for
this operation is:
25 Msec/Sect x 30 Tracks/Cyl   500 Msec/Cyl

TST1,83 Header Read Order: Multiple Sector Read Test

Mode: Normal Mode

Header Read orders are issued to Read the Headers of all sectors of the
first cylinder. TIO and TDV instructions and a Sense order are issued
to verify the correct execution. The byte count is 8. The Header Read
order is repeated by using data chaining and transfer in channel until
an interrupt on unusual end occurs because of boundary error. The
minimal time for this operation is:
25 Msec/Sect x 20 Tracks/Cyl   500 Msec/Cyl

TST1,84 Short Record Test

Mode: Normal Mode

The sequences of orders Seek – Write, Seek – Checkwrite and Seek –
Read are issued. TIO and TDV instructions and a Sense order are issued
to verify the correct execution. Test Variations:
1.  Short Record Write: Byte count   4
2.  Short Record Checkwrite: Byte count   4
3.  Short Record Read: Byte count   4
4.  Checkwrite: Byte count   1024
5.  Read: Byte count   1024, compare of data

TST1,86 Surface Test

Mode: Normal Mode

The sequences of orders Seek – Write and Seek – Read are issued. TIO
and TDV instructions and a Sense order are issued to verify the correct
execution. Random data pattern are used. The seed for the random
pattern is a random number combined with the Seek address by an
exclusive or operation. The Read data are compared with the expected
data. Test Variations:
Disk:  1.  Write on all sectors of Cyl. 1,78,201,0,2,77,79,200,202
       2.  Read from all sectors of Cyl. 1,78,201,0,2,77,79,200,202

TST1,87 Header Read: Check Byte Error Test

Mode: Device Test Mode

A Header Write order is issued to Write a flaw mark on Header Cyl   202,
Head   0, Sect   0. The test mode selection order is set to force check
byte errors on the following Header Read order. (The first two bits are
forced to zero.) TIO and TDV instructions and a Sense order are used
to verify the correct execution of the order.

TST1, 88 Read: Check Byte Error Test

Mode: Controller Test Mode

A Write order is issued to Write a data pattern. The test mode
selection order is set to force check byte errors on the following Read
orders (X'02' and X'12'). (The first two bits are forced to zero.)
Test Variations:
1.  Byte count is 2048
2.  Buffer address not multiple 4
TIO and TDV instructions and a Sense order are used to verify the
correct execution of the order.

TST1,89 Flaw Mark Test

Mode: Normal Mode

The sequences of orders Seek – Header Write and Seek – Header Read
are issued. TIO and TDV instructions and a Sense order are issued to
verify the correct execution. The Seek address is Cyl   202, Head   0,
Sector , 0.
Test Variations:
1. A Header with a flaw mark is written
2. Header Read order
3. Write, Check write and Read orders
4. The Header of Cyl. 202, Head 0, Sector 0 is rewritten;
Byte 0 – 3 of the Sense data (Address) is verified.


TST1,90 Wrong Address Simulation Test

Mode: Normal Mode


The sequences of orders Seek – Header Write, Seek – Header Read,
Seek – Write, Seek – Check write and Seek – Read are issued. TIO
and TDV instructions and a Sense order are issued to verify the correct
execution. The Seek address is Cyl = 202, Head = 0, Sector = 0.
Test Variations:
1. Header with Cyl. = 0
2. Header with Head = 1
3. Header with Sector = 1
4. Rewrite Header only
In the first three passes, Write, Check write, Read and Header Read
orders are issued and the error indication verified.


TST1,94 Double Seek Test

Mode: Normal Mode

A Seek order (X'03') command chained to another Seek order is issued.
TIO and TDV instructions and a Sense order are issued to verify the
correct execution. The Seek address is Cyl/Head/Sect  202/0/0.


TST1,95 Write: HIO and Device Reset Test

Mode: Device Test Mode

This subtest verifies that the HIO instruction and the device reset
command are not destroying any data.
Test Variations:
1. Write, Disk Cyl. 0,1,2,3
2. Write, Address = X'020000', HIO during phase 'Write Data'
3. Read and Verify
4. Write, Disk Cyl. 0,1,2,3
5. Write, Address = X'020000', Dev. reset phase 'Write Data'
6. Read and Verify


TST1,96 Device Address Parity Test

Mode: Device Test Mode

A Seek order is issued. A previous test mode selection order has set
the condition for a device address parity error simulation. The device
will go 'not operational'. A device reset order is issued to clear the
device again.


TST1,97 Seek Order: Time Out Test

Mode: Device Test Mode

1. A Seek order is issued with the address Cyl   12 (190)
2. The device is set in incremental device test mode and a second
   Seek order is issued with a Cylinder addr. 0 (202). The Seek
   operation is performed only to the point where the address is
   stored in the device.
3. Seek time out interrupt is expected
4. A restore order is issued


TST1,98 Reserve and Release Test

Mode: Normal Mode

(This test is valid only in dual access configurations with explicit
release feature installed)
An SIO instruction with a Reserve order reserves device A. TIO and
TDV instructions are used to verify the correct execution. A TIO
instruction is issued to device B to verify the reservation. A Release,
order is issued to device A. TIO and TDV instructions are used to
verify the correct execution. A TIO instruction is issued to device B
to verify the release. Sense data are checked for dual access flag
(byte 5, bit 0) and explicit release flag (byte 4, bit 1).
Explanation:
Device A   Access to disk with controller A
Device B   Access to disk with controller B


TST1,99 Reserve and Release: Interrupt Test

Mode: Normal Mode

(This test is valid only in dual access configurations with explicit
release feature installed)
An SIO instruction with a Seek order is issued to reserve device A.
A condition release interrupt order is issued to controller B. A Release
order is then issued to device A.
Test Variations:
1. Condition rel. with interrupt modif. bit interrupt expected.
   Verification of device address.
2. Condition rel. without interrupt modif. bit no interrupt expected.
Sense data are checked for dual access flag (byte 5, bit 0) and explicit
release flag (byte 4, bit 1).
Explanation:
Device A   Access to disk with controller A
Device B   Access to disk with controller B


TST1,100 Device Power Down Test

Mode: Device Test Mode

The sequences of orders Seek – Write and Seek – Read are issued. This
subtest verifies that data is not destroyed during a power down sequence.
The power down sequence is forced by the TDV address 'B' (set diagnostic
condition) and the 2nd Test mode byte X'80'.
Test Variations:
1. Write, Disk Cyl. 0,1,2,3
2. Write, Address   X'020000', TDV during phase 'Write Data'
3. Read and Verify


TST1,101 Write Protect Test

Mode: Normal Mode, Device Test Mode

The sequence of orders Seek – Write is issued twice. TIO and TDV
instructions and a Sense order are issued to verify the correct execution.
Test Variations:
1. Write Protection by Controller
2. Write Protection by Device
This subtest prints the message: 'Set All Write Protect Switches For This
Test'. After setting these switches, the operator has to inset any
character at the KSR to continue the test.


TST1,102 Attention Interrupt Test

Mode: Normal Mode

Wait for attention interrupt. This subtest prints the message: 'Set
Attention Interrupt'. After setting attention interrupt, the operator has
to insert any character at the KSR to continue the test.

TST1,103 Not Operational Test

Mode: Device Test Mode

This subtest prints the message: 'Set Any Error: Interlock Error, Envir. Error'. After setting any of these errors, the operator has to insert any character at the KSR to continue the test. A printout of this test sequence occurs for this subtest independent from errors. The operator has to verify the correct setting of the corresponding bits.

TST1,104 Write, Read, Check Write: Surface Test

Mode: Normal Mode

This subtest is designed to perform a complete and fast test of the disk surface. In order to achieve the desired operational speed, data chaining plus transfer-in-channel back to the first IOCD is used. The data chaining operation is performed until an interrupt on unusual end terminates the sequences. There are three reactions on this termination: Error Recoveries:
1.   Cylinder End: Continue with next Cylinder. No error, no report
2.   Flaw Mark: Continue with next Track (Addr. derived from Sense data.) No error, no report
3.   Any other error: Issue a Restore and continue with next sector (Addr. derived from Sense error: reporting, summary)
After writing the entire surface with the same data pattern which was specified by the Data directive, the entire surface is Read (Check Written) in the same way with data chaining. At the termination of the chaining sequence, a data comparison of the last data is made. The error recovery is the same as in the Write operation. The following operations are performed:
1.   Write the surface once ⎫
2.   Read the surface once ⎬ Default
3.   Check write the surface once ⎭
4.   Read the surface 8 more times
At program load time, the default value is set to 2 for one Write and one Read pass. The default value may be changed to a value from 1 to 11. A value of 10 performs item 1. 2. and 3. above and 7 Read passes of item 4.

TST1, 105 Read Strobe Test

Mode: Device Test Mode / Normal Mode
Device Type: Disk

This subtest executes write, read and checkwrite operations in a similar fashion as subtest 104. The operations write, read, checkwrite. . . . are executed twice in two passes.
Pass1: Read Strobe Advanced
Pass2: Read Strobe retarded
The read strobe advanced / retarded mode is set for each I/O operation separately. The write, read, or checkwrite operations are executed in normal controller mode.
The default value for the loop count is 2. The loop count can be changed with the alt-directive. By changing location X'242'. For example: Alt, 242, N.   N   A value 3-11 indicating the number of reads.

TST1, 106 Head Alignment Test

Mode: Device Test Mode
Device Type: Disk 33

This subtest requires a CE Pack and the tester.

The test performs the following steps:
1.   1500 seek operations are performed to cylinders 240 and 245.
2.   The offset values for each head are determined in the following sequence:
Reverse direction and positive polarity
Forward direction and positive polarity
Reverse direction and negative polarity
Forward direction and negative polarity

The initial and final sign values as well as the offset values are saved for all head for evaluation in Step 3.

3.   The offset value is computed using the following formula:
((+OR-POSITIVE OFFSET) - (+OR-NEGATIVE OFFSET)/2
The polarity of the offset is determined by the sign at 0 offset position.

A summary of all heads is reported. Offset values greater than +OR- 150 micro inches are indicated by ***. The out of range messages means that there was no sign change within +OR- 1200 micro inches.

TST1 - EXAMPLE OF ERROR REPORTING

| Printout | Printed by the Functional Subroutine |
|---|---|
| TST1,037    IO ADDRESS 04AF<br>----------------------------<br>*** ERROR ***<br>READ TEST<br>*** | Header (Supplied by Test Driver) |
| ***<br>SPREAD DATA<br>PATTERN TYPE : 0<br>BUFFER : 003192<br>CLEAR BUFFER B : 003294<br>*** | Pattern Spread Routine (X'8000') |
| TEST MODE SELECTION EXECUTED , BYTES 0205<br>*** | Test Mode Selection Routine (X'4000') |
| SEEK EXECUTED , ADDRESS 0000 00 00<br>*** | Seek Routine (X'2000') |
| *** START OF IO OPERATION ***<br>SIO STATUS<br>    01234567 89ABCDEF CC(1-4)<br>EXP 0XX1X000 XXXXXXXX 00XX<br>OBS 00010000 00000000 0000<br>COMMAND WORD ADDRESS 001E32<br>IOCD 0200CA50 08000400<br>*** STATUS AT END OF IO OPERATION ***<br>TIO STATUS<br>    01234567 89ABCDEF CC(1-4)<br>EXP X001X000 XXXXXXXX 0XXX<br>OBS 00010000 00000000 0010<br>CURRENT COMMAND DOUBLE WORD ADDRESS EXP 000F19 OBS 000F19<br>REMAINING BYTE COUNT EXP 0000 OBS 0000<br>*** | Execution Routine (X'0800') |
| TIO STATUS<br>    01234567 89ABCDEF CC(1-4)<br>EXP 00010000 00000000 00XX<br>OBS 00010000 00000000 0010<br>*** | IO Routine 1 (X'0020') |
| TDV STATUS<br>    01234567 89ABCDEF CC(1-4)<br>EXP 01000011 XXXXXXXX 01XX<br>OBS 01000011 00000000 0110<br>*** | IO Routine 2 (X'0010') |
| *** ERROR ***<br>SENSE DATA<br>BYTE  0   1   2   3     4   5   14   15<br>EXP   XX  XX  XX  XX    XX  XX  XX   XX<br>OBS   00  00  00  01    00  00  00   00<br>DEVICE FAULTS (BYTE 6)<br>EXP     XXXX XXXX<br>OBS     0000 0000<br>CONTROLLER FAULTS (BYTE 8,9)<br>EXP    0100 0000 0011 1000<br>OBS    0000 0000 0011 1000<br>INTERRUPT BITS (BYTE 10,11)<br>EXP    0000 0000 0000 0000<br>OBS    0000 0000 0000 0000<br>CHECK BYTES (BYTE 12,13)<br>EXP    1000 0000 0011 1111<br>OBS    0000 0000 0000 0000<br>*** | Sense Routine (X'0004') |
| *** ERROR ***<br>COMPARE OF DATA<br>BUFFER A : 003192<br>BUFFER B : 003294<br>COMPARE ERROR<br>    *BYTE 0 * *BYTE 1 * *BYTE 2 * *BYTE 3 * WD CNT<br>EXP 1000 0000 0011 1111 1101 0101 0110 1010   0000<br>OBS 0000 0000 0000 0000 0000 0000 0000 0000<br>EXP 1000 0000 0011 1111 1101 0101 0110 1010   0001<br>OBS 0000 0000 0000 0000 0000 0000 0000 0000<br>EXP 1000 0000 0011 1111 1101 0101 0110 1010   0002<br>OBS 0000 0000 0000 0000 0000 0000 0000 0000<br>EXP 1000 0000 0011 1111 1101 0101 0110 1010   0003<br>OBS 0000 0000 0000 0000 0000 0000 0000 1010<br>EXP 1000 0000 0011 1111 1101 0101 0110 1010   0015<br>OBS 1000 0000 0000 0000 0000 0000 0000 0000<br>PRINT LIMIT : ERROR COUNT 0239 | Compare Routine (X'0002') |
| *** END *** | END (Supplied by Test Driver) |

GENERAL EXPLANATION

1. The underlined test heading defines the failing test and unit.
2. The line following the heading indicates that the test failed if the '*** ERROR ***' line is printed. If display is selected and the current test did not fail, '*** DISPLAY ***' is indicated.
3. Groups of lines are separated by a '***' line. Each group of lines is printed by a functional test subroutine. The name of each functional test subroutine responsible for the output of the above example is indicated. The hexadecimal number following the subroutine name indicates the mask value which must be entered with parameter 4 of TST1 in order to suppress the corresponding lines.
4. Those functional test subroutines which detected an error during testing will display an '*** ERROR ***' line following the '***' line which is a group separator.
   In the preceding example (page 1-18), errors were detected in the Sense Routine and the Compare Routine.
5. Expected data bits which represent a 'don't care' condition, are indicated by an 'X'.

ANALYSIS

1. From the test subroutine description for TST1,37, it can be seen that a read order in test mode was attempted.
2. From the test mode selection routine printout, it can be seen that the test mode data bytes are X'0205'. From the test mode data byte description, this test mode is a controller test mode for device, type 5 (see also SYST directive).
3. The IOCD line of the execution routine printout indicates that a read order of X'400' bytes (1024) was used during this test and that the operation terminated with a byte count of zero.
4. The first error is indicated by the Sense Routine. The controller fault bytes indicate that the second bit of byte 8 is in error and from the sense data byte description, the error is a "data check byte error". Bytes 12 and 13 of the sense order show the expected and observed check bytes and confirm that the check bytes do not match.
5. The subsequent compare error printout shows that the data received from the controller is all zeros.
6. Conclusion:
   Since the read operation itself operated correctly and terminated with a byte count of zero, the only problem appears to be that the simulated read data from the controller turnaround operation was not generated properly.

# Section 10

# SIGMA 5 - 9
# 9 - CHANNEL
# MAGNETIC TAPE TEST

### PROGRAM NO. 705542

**Section 10**

**CONTENTS**

10

**SUBJECT MODEL** -- Magnetic Tape Controller Model numbers 7320, 7321.  Magnetic Tape Storage Units Model numbers 7322, 7323.
Potter Magnetic Tape Units Speeds 75, 120, 150.

**REQUIRED EQUIPMENT**  -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device:
Keyboard Printer or Line Printer

**PROGRAM PREREQUISITES**
None

**GENERAL OPERATING PROCEDURES**
General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

**DIRECTIVES** – directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives | | | | | |
| System Environment | SYST,D1,D2,D3 [,D4,D5,D6,D7 ,D8,D9,D10] | D1<br>D2<br>D3<br><br>D4<br>:<br>D10 | Device station model number<br>= 0<br>Valid IOP, Controller and device address of first unit<br>Device address of the second unit<br><br>Device address of the eighth unit | 7322, 7323, 75*, 120*, 150*<br>0<br>80 ~ 1FFFF<br><br>80 ~ 1FFFF<br><br>80 ~ 1FFFF | NOTE:<br>Intermixing of tape stations of 75 IPS and 150 IPS during TST0 or TST1 is not allowed |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (Functional tests, 1 ~ 37, and random exerciser test. Functional tests 38–41 are not executed) | TST0,D1,D2 | D1<br><br>D2 | Number of ordered sequences executed by random exerciser<br>Number of retries in the random exerciser | 0 ~ 99999999 | 000 (D1 = 0) |
| Functional Test | TST1 [,D1 [,D2]] | D1<br>D2 | The first subtest to be executed<br>Last subtest to be executed | 0 (all subtests)~41<br>1 ~ 41 | 0<br>41 |
| Random Exerciser Test | TST2,D1,D2 | D1<br>D2 | Number of cycles to be performed<br>Number of retries on error | D1 > 0<br>D2 ≥ 0 | |
| Utility Test | TST3,D1,D2,D3,D4 | D1<br><br><br><br><br><br><br><br><br><br><br><br>D1<br><br><br><br><br><br><br><br><br><br>D1<br><br><br><br><br><br><br><br><br>D1 | = 1 Tape Test<br>D2 = 0 Write, Rewind, Read Forward, Read Backward D3 Records<br>  = 1 Write D3 records<br>  = 2 Read forward D3 records<br>  = 4 Read forward and backward D3 records in sequence<br>D3 = 0 Continue operation until EOT or BOT is reached<br>D4   Delay in milliseconds between operation sets<br>= 2 Deskew Test<br>D2 = 0, 1 Write to EOT and rewind<br>  = 2 Read forward to EOT and rewind<br>  = 3 Read backward to BOT<br>  = 4 Read forward to EOT and backward to BOT<br>  = 5 Capstan slippage exerciser<br>= 3 Sync on a Character Test<br>D2 = 1 Read forward and space record backward<br>  = 2 Read backward and space record forward<br>D3   Byte to sync on<br>D4   Delay in milliseconds between syncs<br>= 4 Compatibility and Noise Pattern Test<br>D2 = 0, 1 Write, Read backward, read forward all records<br>  = 2 Space forward, read forward, read backward all records<br>  = 3 Read forward, read backward, space forward all records<br>  = 4 Read forward all records<br>  = 5 Write all records<br>D3 = No of Records | <br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br>(1-1500) | NOTE:<br>To alter retry count in TST3, 1; change Loc. X'240' for writing and Loc. X'241' for reading. Preset value for both = 5. |

## DIRECTIVES

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Testing Directives (Continued) | | | | | |
| | | D1 | = 5 Read/Space Test<br>D2 = 0 Rewind and read forward N records<br>= 1 Rewind and space forward N records<br>= 2 Read forward N records<br>= 3 Space forward N records<br>= 4 Space backward N records<br>D3 Number of records (N)<br>D4 = 0 Do not print record<br>= 1 Print record in error<br>= 2 Print record N | | |
| Program Directives – Optional Directives | | | | | |
| Pattern selection (for Utility Test TST3,1) | DATA,D1,H2,H3,H4 | D1<br><br><br>H2<br><br>H3<br>H4 | = 0, Fixed Pattern<br>= 2, Random Pattern<br>= 5, Bit Crowding Pattern<br>Pattern seed (for D1 = 0, 2)<br>Two Track Numbers (for D1 = 5)<br>Byte string for first track D1 = 5<br>Byte string for second track | 0 ~ 5<br><br><br>0 ~ FFFFFFFF<br>01 ~ 78<br>0 ~ FFFFFFFF | |
| Length of record selection (for Utility Test TST3, 1) | LEN,D1 | D1 | Length of Record in Bytes | Min. = 0<br>Max. = Function of Memory Size | |
| Limitation of Error printouts | LIMT,D1,D2 | D1<br><br>D2 | = Limit Compare error printouts/record to D2<br>Maximum number of printouts (No limit if D2 = 0) | 1<br><br>D2 ≥ 0 | |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Deskew Adjustment, Threshold check, Capstan Ramp Adjustment, Compatibility Check |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT | LIMT | LIMT | LIMT, LEN, DATA |
| Subtests | Functional subtests (1 ~ 37) and random exerciser test | 41 subtests (see error messages for the test types) | Random selection of: Order sequence Buffer length Data The identical operation is performed on each selected device in turn, then the next operation is begun. | See program directive TST3 |
| Error Message Format | 1. ERROR NO. DDDD 2. Self-explanatory | ERROR NO. DDDD | Self-explanatory | Self-explanatory |

## ORDER CODES

X'01'  Write
X'02'  Read Record (Forward)
X'03'  Set Correction ⎫ Not used with Potter units
X'04'  Sense          ⎭
X'0C'  Read Record Backward
X'13'  Rewind and Interrupt
X'23'  Rewind Off Line
X'33'  Rewind
X'43'  Space Record Forward
X'4B'  Space Record Backward
X'53'  Space File Forward
X'5B'  Space File Backward
X'63'  Set Erase
X'73'  Write Tape Mark

## TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4* | 5 | 6 | 7 |
| 7322/3 | Rate Error | Write Permitted | Write Protect Error | End of File | Uncorrectable Read Error | Load Point | End of Tape | Rewind On-Line |

*TDV bit 4 always set for Potter units.

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7322/3 | Rate Error | Device End | Write Protect Error | End of File | Uncorrectable Read Error | ← NOT USED → | | |

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES

### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

### DESCRIPTIVE ERROR MESSAGES
Error numbers can be preceded by descriptive messages which will aid in the isolation of failures.

### FUNCTIONAL TEST

TST1, 1 AIO, HIO, TIO, TDV Test
Check the ability of the 9-track mag tape system to correctly respond to the AIO, HIO and the TDV instructions. AIO will only check the no interrupt pending condition. Verify address recognition and status response to these instructions. Any error in this test may indicate a possible problem in the sub-controller area.

0101 AIO condition code error. No interrupt recognition expected.
0102 HIO condition code or status error. See printout.
0103 TIO condition code or status error. See printout.
0104 TDV condition code or status error. See printout.

TST1, 2 Invalid Order Test
Check the invalid order detection by issuing two SIO's with invalid order codes (X'09', X'7B'). This test is designed to check order decoding, order-output and order-input phases in the controller and unusual end detection. The remaining byte count will be tested to verify that no data phases were executed. Check the ability of the HIO to reset UE condition.

0201 SIO for invalid order not accepted. Condition code error.
0202 SIO for invalid order status error. UE and no interrupt pending expected. (WRITE backward)
0203 HIO did not reset interrupt pending bit in status.
0204 SIO for invalid order not accepted, condition code error.
0205 SIO for invalid order status error. UE and no interrupt pending expected. (WRITE TM backward)

TST1, 3 Erase Order Test
Check the execution of the first valid order. This test is designed to further check order decoding, order-output and order-input phase in the controller, and order termination without unusual end. The remaining byte count will be tested to verify that no data phases were executed. The status response will be tested.

0301 SIO condition code error on set erase.
0302 TIO status error on set erase. No UE or byte count reduction expected. No data phases executed.

TST1, 4 Set Correction Order Test (Bypassed for Potter Units)
This test is designed to verify the data-output phase in the controller and order termination.
Three set corrections will be used:
1. Byte count = 1, Data byte = X'FF'
2. Byte count = 1, Data byte = X'00'
3. Byte count = 2
The remaining byte count will be tested to verify that data transfer can be terminated by the controller and that a data-output operation was actually performed. The status response will be tested.

0401 SIO for set correction condition code error. (BC = 1, INFO = 00)
0402 TIO for set correction status error. No UE or INT pend expected.
0403 SIO for set correction caused information to change from 00.
0404 SIO for set correction condition code error. (BC = 1, INFO = FF)
0405 TIO for set correction status error. No UE or INT pend expected.

0406 SIO for set correction caused information to change from FF.
0407 SIO for set correction condition code error. (BC = 2, INFO = 00)
0408 TIO for set correction status error. BC = 1, No UE and no INT pend expected.
0409 SIO for set correction caused information to change from 00.

TST1, 5 Sense Order Test (Bypassed for Potter Units)
This test is designed to verify the data-input phase in the controller and order termination.
Three sense orders will be used:
1. Byte count = 1, Data byte in buffer = X'FF'
2. Byte count = 1, Data byte in buffer = X'00'
3. Byte count = 2
The remaining byte count will be tested to verify that data transfer can be terminated by the controller and that a data input operation was actually performed. The status response will be tested.

0501 SIO for sense condition code error. (BC = 1, INFO = 00)
0502 TIO for sense status error. BC = 0, No UE expected.
0503 SIO for sense caused information to change from 00.
0504 SIO for sense condition code error. (BC = 1, INFO = 00)
0505 TIO for sense status error. BC = 0, No UE expected.
0506 SIO for sense should cause information to change from FF to 00.
0507 SIO for sense condition code error.
0508 TIO for sense status incorrect. BC = 1, no UE expected.
0509 SIO for sense caused information to change from 00.

TST1, 7 Interrupt on UE, CE, ZBC, and AIO (Bypassed for Potter Units)
Check the ability of the controller to generate an interrupt on unusual end, channel end, and zero byte count using a WRITE backward, erase, and sense order respectively. Check the execution of the AIO instruction. Verify that AIO and HIO can reset the interrupt pending condition. All status responses will be tested.

0701 SIO for invalid order condition code error. (WRITE BKW, UE set)
0702 No UE interrupt on invalid WRITE backward with UE set.
0703 No UE set on AIO after invalid order or INT pending not reset after AIO.
0704 SIO for set erase condition code error. (Erase, CE set)
0705 No CE interrupt on erase with CE set.
0706 No interrupt pending set after HIO following the erase order.
0707 SIO for sense condition code error. (Sense, BC = 1, IZC set)
0708 No IZC interrupt on sense with IZC set.
0709 No interrupt pending reset after AIO following sense order or IZC not set in AIO status.
0710 HIO status response error following AIO. UE or IP should not be set.
0711 TIO status response error following HIO. IP should not be set.

TST1, 8 I/O Interrupt Test
Check the ability of the IOP and CPU to interrupt the program whenever an interrupt call is generated by the controller. Verify proper operation of interrupt arm/disarm and enable/disable modes.

0801 TIO status response error after an invalid order. IP and UE should be set. (WRITE BKW, UE set with INT disarmed)
0802 TIO status response error after interrupt armed and disabled.
0803 No interrupt received on invalid order with UE set after interrupt armed and enabled.

TST1, 9 Command Chaining (Bypassed for Potter Units)
Test the command chaining ability of the controller by issuing an erase/set correction/sense order sequence. Test the termination of the command chaining sequence by issuing a WRITE-backward/sense order sequence. All status responses will be tested.

0901    SIO condition code error on command chaining order (erase set correction, and sense).
0902    No interrupt on command chaining erase, set correct, and sense.
0903    The last double word address is incorrect on command chaining. The address should be sense.
0904    SIO condition code on command chaining order. (WRITE BKW, sense).
0905    No interrupt received on command chaining WRITE BKW, erase.
0906    The last double word address is incorrect on command chaining. The address should be WRITE backward.

TST1, 11 Rewind Test
Check the execution of a rewind on-line order. The test will verify that the tape is positioned at load point after completion of the rewind order. Check the execution of a rewind and interrupt order. This test will verify that the tape remains at load point and that the device initiates on interrupt request. Verify that an AIO and HIO instruction can reset the interrupt pending condition in the tape controller and the tape station. Verify that device end status is returned during the AIO. All status responses will be tested.

1101    TDV status error after rewind on line. No load point bit set.
1102    TIO status error after rewind and interrupt. No interrupt pending set.
1103    TIO status error after HIO on rewind with interrupt.
1104    TIO status error after rewind with interrupt. Interrupt pending not set.
1105    AIO status error after rewind with interrupt. Device end not set.
1106    TIO status error after AIO. Interrupt pending not reset.
1107    TDV status error after rewind with interrupt. No load point set.

TST1, 12 READ, Space Record and File Backward from BOT Test
Check the execution of a READ, space record, and space file order in the backward direction with tape positioned at load point. Verify that the controller responds with unusual end, end of file (TDV and AIO) and load point status. The test will check that the tape remains at load point. The byte count for all orders specified must remain unchanged.

1201    No interrupt received after READ backward at load point. (BC=2)
1202    TIO or TDV status error on READ BKW at load point. UE, load point, and BC = 2 expected.
1203    No interrupt on space backward at load point. (BC = 2)
1204    TIO or TDV status error on space BKW at load point. UE, load point, and BC = 2 expected.
1205    No interrupt received on space file backward at load point.
1206    TIO or TDV status error on space file BKW at load point. UE, load point, and no EOF expected.

TST1, 13 WRITE Tape Mark Test at BOT
Check the execution of a WRITE tape mark order. The test will verify that tape can be moved off load point and that the order can be terminated with both controller and station returning to ready. If tape run-away, issue HIO. Rewind tape and test load point. End of file status will not be tested. The byte count for the order must remain unchanged.

1301    No interrupt on WRITE tape mark at load point. (CE and BC = 2 set)
1302    TIO or TDV status error on WRITE tape mark at load point. EOF and BC = 2 expected.

TST1, 14 Space Record Forward Test
Check the execution of a space forward order. The test will verify that tape can be moved off the load point and that the order can be terminated with both controller and station returning to ready. If tape run-away, issue HIO. Rewind tape and test for load point. End of file and unusual end status will not be tested. The byte count for the order must remain unchanged.

1401    No interrupt received on WRITE tape mark after rewind.
1402    No interrupt received on space forward over a tape mark at load point. (CE and BC 2 set.)
1403    Byte count on space FWD at load point error. Should be 2.
1404    TIO status error on space FWD at load point. No error expected.

TST1, 15 WRITE Test (Byte 1 to 64)
Check the execution of WRITE orders using X'FF' as data pattern and a starting at a byte count of one up to a maximum byte count of 64. The test will verify that tape can be moved off the load point, that the order can be terminated with both controller and tape station returning to ready, that a data-output operation is actually performed, and that the byte count is always reduced to zero. Verify that incorrect length is not detected. Rewind tape and test for load point. TE (Transmission errors) not checked in this test.

1501    TIO or TDV status error on WRITE records 1-64 byte length. No incorrect length or UE expected, BC = 00.

TST1, 16 READ Test
Test the execution of READ orders using a starting byte count of one up to a maximum count of 64. WRITE 64 records with a fixed byte count of 100 bytes (Pattern = X'FF') and rewind tape. This test will check the response to a READ forward operation (off load point, zero). Rewind tape and test load point. TE (Transmission errors) not checked in this test.

1601    TIO or TDV status error on writing 100 bytes all bits on. No incorrect length or UE expected, BC = 00.
1602    TIO or TDV status error on READ forward 100 bytes all bits on with Byte count 1-64. Incorrect length and no IZC expected.

TST1, 17 EOF Test (Potter Units Only)

1701    Record write error (no UE, write permitted, no data error, zero byte count).
1702    Incorrect load point indication.
1703    Load point expected.
1704    Read backward error (device and controller not ready, no UE, no incorrect length, zero byte count, write permitted.
1705    Space file backward error (no UE, EOF, no data error).
1706    Space file forward error (no UE, EOF, no data error).
1707    Read forward error (same as 1704 read backward error).
1708    Incorrect record number.
1709    Double EOF detected.

TST1, 18 WRITE READ Data Test
WRITE N records with a fixed byte count and data pattern of X'FF'. Rewind tape and READ N records in the forward direction. Verify that data can be recorded and READ from each track. TE (transmission errors) not checked in this test.

1801    TIO or TDV status error on writing 100 bytes all bits on. No incorrect length or UE expected, BC 00.

TST1, 19 WRITE, READ Data Test (Data X'00' to X'80')
WRITE N records with a fixed byte count and the current data pattern data will be varied from X'00' through X'80'. Rewind tape and READ N records in the forward direction. Verify for each pass that only one track contains information and that all other tracks are zero. After each pass, loop on the data pattern which has caused an error and continue testing until a successful pass has been made.

1901    WRITE, READ forward, on information errors when saturating one track. 100 records of 100 bytes pattern 00, 01, 02, 04, 08, 10, 20, 40, 80.

TST1, 20 Set Erase-WRITE Test

Check the capability of the tape station to skip over an area on the tape by checking the delay between the start of the WRITE order and the start of the data transfer.

2001     Erase time set too long. See message printout.
2002     Erase time set too short. See message printout.
2003     No interrupt on zero byte count occurred within 9 ms.

TST1, 21 WRITE, Space FWD and BKW Test

WRITE N records with a fixed byte count. Rewind tape to load point. Space one record in the forward and backward direction. Space another record in the backward direction and check load point indicator. Space N records in the forward direction and then the reverse direction. Check all status response. Rewind to load point.

2101     TIO or TDV status error on writing 100 bytes all bits on.
2102     TIO or TDV status error on spacing forward over 100 bytes at load point.
2103     TIO or TDV status error on spacing backward over 100 bytes one record beyond load point. No UE or load point expected.
2104     TIO or TDV status error on spacing backward one record at load point. UE and load point expected.
2105     TIO or TDV status error on spacing forward over 100 bytes all bits on. No UE or error expected, BC = 00.
2106     TIO or TDV status error on spacing backward over 100 bytes all bits on. No UE or error expected, BC = 00.

TST1, 22 WRITE Tape Mark Test

WRITE N tape marks and verify that end of file status is reported after each order. All tape marks are read forward and backward.

2201     TIO or TDV status error on writing a tape mark. Tape mark and no UE expected.
2202     TIO or TDV status error on reading backward over 100 tape marks. Tape mark and UE expected.
2203     TIO or TDV status error on reading forward over 100 tape marks. Tape mark and UE expected.

TST1, 23 WRITE Tape Mark – Space File and Space Record Test

WRITE N tape marks and rewind to load point. Space file in the forward direction and verify end of file and no unusual end status. Space file backward and check end of file and no unusual end. Space file backward again and check end of file, beginning of tape and no unusual end. Verify all other status. Verify that unusual end and end of file status is reported when spacing or reading over a tape mark. WRITE N records followed by a tape mark. Verify space record in both directions.

2301     TIO or TDV status error on writing a tape mark. Tape mark and no UE expected.
2302     TIO or TDV status error on space file forward. Tape mark and no UE expected.
2303     TIO or TDV status error on space file backward. Tape mark and no UE expected.
2304     TIO or TDV status error on space file backward at load point. Load point, tape mark, and no UE expected.
2305     TIO or TDV status error on writing a record 100 bytes. No error expected, BC = 00.
2306     TIO or TDV status error on writing a tape mark. No error expected, tape mark.
2307     TIO or TDV status error on spacing backward over a tape mark. UE and tape mark expected.
2308     TIO or TDV status error on spacing forward over a tape mark. UE and tape mark expected.

TST1, 24 Tape Loop Test

Rewind with command chain. Write with data chain 27,000 words loop back to rewind. This sequence is repeated 10 times in an effort to cause the tape to loop out in the vacuum columns.

2401     TIO or TDV status error after rewinding and writing a record of 27,000 words, looping 10 times. No error expected.

TST1, 25 WRITE, READ Backward Data

WRITE N records with a fixed byte count. READ N records backward and verify data and status. READ another record backward and test beginning of tape status.

2501     TIO or TDV status error on writing a record of 100 bytes. No UE expected, BC = 00.
2502     TIO or TDV status error on reading 100 bytes backward. No UE expected, BC = 00.
2503     Incorrect information on reading 100 bytes backward all bits on.
2504     TIO or TDV status error on reading a record backward at load point. UE, load point and EOF expected.

TST1, 26 Incorrect Length Test

WRITE a record and READ in both directions by using byte count -1 byte count +1 for the READ orders. Verify incorrect length and all other status indications. Suppress incorrect length feature in the IOP will also be tested.

2601     TIO or TDV status error on writing 100 bytes all bits on. No errors expected, BC = 00, no incorrect length.
2602     TIO or TDV status error on reading a record backward. No error expected, BC = 00. No incorrect length.
2603     TIO or TDV status error on reading a record forward. No error expected, BC = 00, no incorrect length.
2604     TIO or TDV status error on reading a 100 byte record backward with a BC = 99. Incorrect length, UE and BC = 00 expected.
2605     TIO or TDV status error on reading a 100 byte record forward with a BC = 99. Incorrect length, UE and BC = 00 expected.
2606     TIO or TDV status error on reading a 100 byte record backward with suppress inc length, BC = 101. Inc length, BC = 1, no UE expected.
2607     TIO or TDV status error on reading a 100 byte record forward with suppress inc length, BC = 101. Inc length, BC = 1, no UE expected.
2608     TIO or TDV status error on reading forward a 100 byte record with suppress inc length, BC = 99. Inc length, BC = 0, no UE expected.

TST1, 27 Data Chaining Test

Test the data chaining capability of the IOP using WRITE and READ orders.

2701     TIO or TDV status error on writing 2 bytes data chain 98. No errors expected, BC = 00.
2702     TIO or TDV status error on reading backward 6 bytes data chain chain 94. No error expected, BC = 00.
2703     Information error on reading a record BKW 6 bytes data chain 94.
2704     TIO or TDV status errors on reading forward 48 bytes data chain 52. No error expected, BC = 00.
2705     Information error on reading a record FWD 48 bytes data chain 52.

TST1, 28 Byte Boundary Test

This test performs READ and WRITE operations from all possible memory boundaries. For Potter tape units, the minimum byte count = 11 instead of 4.

2801     TIO or TDV status error when writing from WA, WA+1 byte, WA+2 bytes, WA+3 bytes.
2802     TIO or TDV status error when reading BKW into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.
2803     Information error when reading BKW into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.
2804     TIO or TDV status error when reading FWD into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.
2805     Information error when reading FWD into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.
2806     TIO or TDV status error on writing a record 4, 16, 32, 64, ... bytes in length.
2807     TIO or TDV status error on reading a record BKW 4, 16, 32, 64, ... bytes in length.
2808     Information error on reading backward 4, 16, 32, 64, ... bytes.
2809     TIO or TDV status error on reading a record FWD 4, 16, 32, 64, ... bytes in length.
2810     Information error on reading forward 4, 16, 32, 64, ... bytes.

TST1, 29 Data Test Noise Patterns and Bit Crowding
This test will WRITE and READ variable data patterns. The
sequence will always be WRITE, READ reverse and READ
forward. The record size will be varied after each record.
Noise sensitive and bit crowding data pattern will be used.
WRITE and READ retries will be allowed if sense switch 1 is
set.

2901 TIO or TDV status error on writing an incremented record with
saturated tracks and noise pattern.
2902 TIO or TDV status error on reading backward on incremented
record with saturated tracks and noise patterns.
2903 Information error on reading BKW incremented record with special
saturated tracks and noise patterns.
2904 TIO or TDV status error on reading forward an incremented record
with saturated tracks and noise patterns.
2905 Information error on reading forward an incremented record with
saturated tracks and noise pattern.

TST1, 31 CRC Test (Bypassed for Potter Units)
Check the ability to set all bits in the CRC character. A
blank CRC character will also be written, READ FWD, and
READ BKW 100 times. CRC register bits 123456789
Where 1 = Parity Bit
Where 2 = MSB
Where 9 = LSB

3101 TIO or TDV status error on writing a record with one bit set in the
CRC character.
3102 TIO or TDV status error on reading a record backward with one bit
set in the CRC character.
3103 Information error on reading a record FWD with one bit set in the
CRC character.
3104 TIO or TDV status error on reading a record forward with one bit
set in the CRC character.
3105 Information error on reading a record BKW with one bit set in the
CRC character.
3106 TIO or TDV status error on writing a record with a blank CRC
character.                                    •
3107 TIO or TDV status error on reading a record backward with a blank
CRC character.
3108 Information error on reading a record BKW with a blank CRC char.
3109 TIO or TDV status error on reading a record forward with a blank
CRC character.
3110 Information error on reading a record FWD with a blank CRC char.

TST1, 32 READ - Set Correction Test (Bypassed for Potter Units)
The test will WRITE one error free record and sequentially set
one bit at a time in the error pattern register for both forward
and reverse READ modes. The data will be verified after each
READ order to insure that the data remains unchanged.

3201 TIO or TDV status error on writing a record 100 bytes. No error
expected.
3202 TIO or TDV status error on reading a record backward with 100 bytes.
No error expected.
3203 Information error on reading a record BKW with 100 bytes.
3204 TIO and TDV status error on reading a record forward with 100
bytes. No error expected.
3205 Information error on reading a record FWD with 100 bytes.
3206 TIO or TDV status error on set correction bytes 01-80.
3207 TIO or TDV status error on READ backward with set correction.
3208 Information error on reading BKW with set correction bytes 01-80.
3209 TIO or TDV status error on set correction bytes 01-80.
3210 TIO or TDV status error on READ forward with set correction.
3211 Information error on reading FWD with set correction bytes 01-80.

TST1, 33 READ - Sense Test (Bypassed for Potter Units)
WRITE one error free record in both directions. The sense
order after each READ order should return a byte of all zeros
to the IOP.

3301 TIO or TDV status error on writing a 100 byte record.
3302 TIO or TDV status error on reading a record BKW with 100 bytes.
3303 Information error on reading a record backward with 100 bytes.

3304 TIO or TDV status error on sense with information byte 00.
3305 Information error on sense. Should not change from 00.
3306 TIO or TDV status error on reading a record FWD with 100 bytes.
3307 Information error on reading a record forward with 100 bytes.
3308 TIO or TDV status error on sense with information byte 00.
3309 Information error on sense. Should not change from 00.

TST1, 34 Ready - Busy Test
Check the busy condition after issuance of an order. The test
will also attempt to issue an SIO to a busy controller and to
a ready controller and a busy station.

3401 TIO error. Device should be busy while writing 1000 bytes.
3402 No interrupt received after writing 1000 bytes.
3403 TIO or TDV status error on writing a 1000 byte record.
3404 TIO error. Controller should be busy whil reading 1000 bytes..
3405 No interrupt received after reading a record BKW with 1000 bytes.
3406 SIO error. Controller should be busy on initiating rewind.
3407 TIO error. Device should be busy on rewinding.

TST1, 35 Tape Creep Test
This test will WRITE one record followed by a set erase order
and another WRITE order. A space record backward and
rewrite sequence will now be repeated N times. After
reading and verifying the data of the first record, READ the
second record and compute the delay between the start of the
READ order and the start of the data transfer. The direction
of the creep will be determined by comparing the delay to the
original value.

3501 TIO or TDV error on writing a 100 byte record.
3502 TIO or TDV error on spacing backward over a 16 byte record.
3503 TIO or TDV error on writing a 16 byte record.
3504 TIO or TDV error on spacing backward over a 16 byte record.
3505 TIO or TDV status error on spacing backward over 100 bytes.
3506 TIO or TDV status error on reading a 100 byte record forward.
3507 Information error on reading a 100 byte record forward.
3508 Tape creep tolerance exceeded in the tape creep test.
3509 Tape creep negative in the tape creep test.

TST1, 36 Erase Verification Test
This test will test the erase order by rewinding tape and then
writing N one byte records. The records are followed by a
tape mark. After a rewind, WRITE one record, set erase, and
WRITE one record. The tape is rewound. The records are
counted to verify the erase order execution.

3601 The erase order did not remove the correct number of records when
verifying the erase order.

TST1, 37 Gap Length Timing Test
This routine verifies gap timing and is intended as a scoping
aid for adjusting the forward and reverse ramp. The test can
only be run on a system with a real time clock.
Operator intervention required if SS1 is set.

3701 TIO or TDV status error on writing 16 bytes in the I.R.G.* test.
3702 TIO or TDV status error on spacing backward over 16 bytes.
3703 TIO or TDV status error on writing 16 bytes in the I.R.G. test.
3704 TIO or TDV status error on spacing backward over 16 bytes.
3705 I.R.G. time is incorrect. See printout.
*I.R.G.   Inter Record Gap

TST1, 38 End of Tape Test (Bypassed for Potter Units)
This test will continue to WRITE records until the end of tape
indicator is detected. One additional record will be recorded
and the EOT condition will be verified again. Two records
will be READ in the backward direction. After the second
READ order, the EOT indicator should be reset. The tape
will be rewound.

3801 TIO or TDV error writing 1000 bytes in the end of tape test.
3802 TIO or TDV error writing 1000 bytes beyond EOT indication.
End of tape flag should be set.

TST1, 38 (Continued)

3803 TIO or TDV error reading backward 1000 bytes at EOT. The EOT flag should be set.

3804 TIO or TDV error reading backward 1000 bytes near EOT. The EOT flag should be reset.

TST1, 39 Set Correction Test (Bypassed for Potter Units)
This routine requires the user to force a READ error as specified by the program. This test will verify that READ errors can be corrected and that a noncorrectable status will be returned if the error is caused by at least two tracks. For the READ with correction test to prevent setting READ register F/F when the AR signal is missing in all dual threshold:
Put jumper from GND to 7W43
GND to 15W41
GND to 15W07

To install jumpers for recoverable READ errors:
Track 1 (CH 0 – Data Bit 0) 3V23 (LRCT) to 19W43
Track 2 (CH 1 – Data Bit 1) 3V23 (LRCT) to 19W28
Track 3 (CH 2 – Data Bit 2) 3V23 (LRCT) to 19W12
Track 4 (CH 3 – Data Bit 3) 3V23 (LRCT) to 19W33
Track 5 (CH 4 – Data Bit 4) 3V23 (LRCT) to 19W17
Track 6 (CH 5 – Data Bit 5) 3V23 (LRCT) to 19W02
Track 7 (CH 6 – Data Bit 6) 3V23 (LRCT) to 18W13
Track 8 (CH 7 – Data Bit 7) 3V23 (LRCT) to 18W33
Track 9 (CH P – Data Parity) 3V23 (LRCT) to 18W18
Operator intervention required

3901 TIO or TDV status error on writing 100 bytes.
3902 TIO or TDV status error on reading backward 100 bytes.
3903 TIO or TDV status error on reading forward 100 bytes.
3904 Error when reading backward with a track error forced. An uncorrectable TE is expected.
3906 Status error on sense in the track correction test.
3907 Information from sense is incorrect. (80, 40, 20, 10, 08, 04, 02, 01, 00).
3908 Status error on set correction in the track correction test.
3909 Status error on READ BKW and correct in the track correction test.
3910 Error when reading forward with a track error forced. A correctable TE is expected.
3911 Error when reading forward with 2 track errors forced. An uncorrectable TE is expected.
3912 Status error on sense in the track correction test.
3913 Information from sense is incorrect. (80, 40, 20, 10, 08, 04, 02, 01, 00).
3914 Status error on set correction in the track correction test.
3915 Status error on READ FWD and correct in the track correction test.
3916 Information error verifying 100 bytes in the BKW direction.
3917 Information error verifying 100 bytes in the FWD direction.
3918 Information error reading BKW and correcting 100 bytes.
3919 Information error reading FWD and correcting 100 bytes.

TST1, 40 Operator Control Panel Test
This test will check every switch on the operator control panel in the sequence specified by the program and verify the WRITE protect feature. Messages are printed describing the action required by the operator.
Operator intervention required.

4001 Status error on writing a record designation unit 0, 1, 2, 3, 4, 5, 6, 7.
4002 Status error on reading BKW with designation unit 0, 1, 2, 3, 4, 5, 6, 7.
4003 Information error reading BKW record from unit 0, 1, 2, 3, 4, 5, 6, 7.
4004 Status error on reading FWD with designation unit 0, 1, 2, 3, 4, 5, 6, 7.
4005 Information error reading FWD record from unit 0, 1, 2, 3, 4, 5, 6, 7.
4006 Status error when trying to WRITE on a unit with the WRITE ring removed. A WRITE protect is expected.
4007 Status error when trying to WRITE a tape mark with the WRITE ring removed. A WRITE protect is expected.
4008 No interrupt was received when the attention button was set by the operator.

4009 Status error on rewind and put off line. The device should be manual and the controller ready.
4010 TDV status incorrect. Load point and ready expected.

## RANDOM EXERCISER TEST AND RELATED ERROR MESSAGES

TST2 RANDOM EXERCISER TEST

This test provides a means of operating a magnetic tape system with pseudo-random operation, order sequence, data pattern, I/O area, time delay, and record size for the purpose of detecting intermittent failures and exercising all tape units. All Potter units are rewound and put off-line at the end of test.

The random exerciser test will report errors as they occur, but only as to the function that failed. No error looping is provided except for limited retries.

D1 = Number of cycles, set to 1000 IF 0.
D2 = Number of error retries.

From the random seed the following masks are used to get type of operation, word size of record, and time delay in milliseconds.
X'00003FF0' To get random record word size
X'001F0000' To get random time delay in milliseconds
X'0000000F' To get random operation set

Random Operation Sets
0 WRITE, WRITE, WRITE, WRITE, WRITE
1 WRITE, WRITE, WRITE, WRITE, READ BKW
2 WRITE, WRITE, WRITE, WRITE, Space BKW
3 WRITE, WRITE, WRITE, READ BKW, READ BKW
4 WRITE, WRITE, WRITE, READ BKW, Space BKW
5 WRITE, WRITE, WRITE, Space BKW, READ BKW
6 WRITE, WRITE, WRITE, Space BKW, Space BKW
7 WRITE, WRITE, WRITE, Space BKW, READ FWD
8 WRITE, WRITE, WRITE, READ BKW, Space FWD
9 WRITE, WRITE, READ BKW, READ BKW, READ FWD
A WRITE, WRITE, READ BKW, READ BKW, Space FWD
B WRITE, WRITE, Space BKW, Space BKW, READ FWD
C WRITE, WRITE, Space BKW, READ BKW, Space FWD
D WRITE, READ BKW, READ FWD, READ BKW, READ FWD
E WRITE, READ BKW, READ FWD, Space BKW, READ FWD
F WRITE, Space BKW, Space FWD, READ BKW, READ FWD

Descriptive Error Messages

Note: Most of those error messages listed under TST1 may occur during TST2
Terminating Message
(Normally printed at the end of TST0 and printed at the end of TST2 if errors have been detected)

Device XXXX Perm WRT TALY AAAA Temp WRT TALY BBBB
Perm R B TALY CCCC Temp R B TALY DDDD Perm RF
TALY EEEE Temp R F TALY FFFF
Device XXXX Reported the following errors:
AAAA Permanent WRITE errors (retries unsuccessful)
BBBB Temporary WRITE errors (retries successful)
CCCC Permanent READ backward errors (retries unsuccessful)
DDDD Temporary READ backward errors (retries successful)
EEEE Permanent READ forward errors (retries unsuccessful)
FFFF Temporary READ forward errors (retries successful)

Random Exerciser Standard Error Messages

Rand Word AAAAAAAA Dev. XXXX PASS HEX PPPPPPPP
Failing Seq: S,S,S,S,S
Device XXXX Failed pass PPPPPPPP using random Data
Seed AAAAAAAA while executing sequence of operations
S,S,S,S,S

## UTILITY TESTS

### TST3 UTILITY TESTS

The utility test routine allows the user to select a specific function and to control the data pattern (see data directive) and the record length (see 'LEN' directive).

Parameters    D1 = Utility test selection
              D1 = 1 tape test
              D1 = 2 deskew test
              D1 = 3 sync on a character test
              D1 = 4 compatibility and noise pattern test
              D1 = 5 read/space test
              D2 = operations requested according to test
              D3 = parameter requested according to test
              D4 = parameter requested according to test

### TST3, 1 TAPE TEST

This test allows the user to WRITE, READ forward, READ backward, READ forward and then backward, or WRITE followed by rewind and READ forward and READ backward N records or until EOT is reached.

Parameters    D1 = 1 tape test
              D2 = 0 WRITE, rewind, READ forward, READ backward D3 records
                   1 WRITE D3 records
                   2 READ forward D3 records
                   3 READ backward D3 records
                   4 READ forward and backward D3 records in sequence
              D3 = number of records to be written or read.
                   If D3 = 0 continue until EOT or BOT is reached
              D4 = delay in milliseconds between operation sets

Example     TST3, 1, 1, 1000, 5
            WRITE 1000 records with a 5 millisecond delay after each WRITE operation

### TST3, 2 DESKEW UTILITY TEST

This test is provided as a scoping aid during checking and adjusting the READ/WRITE skew. A pattern of all ones will be recorded as a continuous record. At EOT the tape will be rewound.

Parameters    D1 = 2 Deskew test
              D2 = 0, 1 WRITE until EOT is reached and rewind
                   2 READ forward until EOT and rewind
                   3 READ backward until BOT is reached
                   4 READ FWD till EOT, READ BKW till BOT, no rewinds
                   5 capstan slippage exerciser
              D3 = not used
              D4 = not used

Example     TST3, 2, 2
            READ forward until EOT and rewind

### TST3, 3 SYNC ON A CHARACTER UTILITY

This test is provided as a scoping aid by executing a unique I/O instruction (TDV) after the byte count specified in the test has been reached.

Parameters    D1 = 3 SYNC on a character test
              D2 = 1 READ forward and space record backward
                   2 READ backward and space record forward
              D3 = Byte to SYNC on
              D4 = Delay in milliseconds between SYNCS

Example     TST3, 3, 1, 375, 10
            READ forward 375 bytes, signal (TDV) and wait 10 milliseconds. Space backward

### TST3, 4 COMPATIBILITY AND NOISE PATTERN TEST

This test allows the user to WRITE, READ forward, READ backward, or READ forward and backward a predetermined incremented noise pattern.

Parameters    D1 = 4 compatibility and noise pattern test
              D2 = 0, 1 WRITE, READ backward, and READ forward all records
                   2 space forward, READ backward, READ forward all records
                   3 READ forward, READ backward, space forward all records
                   4 READ forward all records
                   5 WRITE all records
              D3 = number of records (1-1500)
              D4 = not used

Example     TST3, 4, 5
            WRITE all records

### TST3, 5 READ/SPACE TEST

This test allows the user to READ or space N records with or without rewind. Only non-recoverable transmission errors will cause error printout, backspace and a halt.

Parameters    D1 = 5 READ/space test
              D2 = 0 rewind and READ FWD N records
                   1 rewind and space FWD N records
                   2 don't rewind, READ FWD N records
                   3 don't rewind, space FWD N records
                   4 don't rewind, space BKW N records
              D3 = number of records to READ or space
              D4 = 0 don't printout record
                   1 printout record in error
                   2 printout nth record

Example     TST3, 5, 0, 100, 1
            Rewind, READ 100 records, print error records

## OPTIONAL DIRECTIVES

**DATA**        The directive selects a pattern type to be used during the tape test (TST3, 1 only).

Parameters    D1 = pattern type
                   0 fixed pattern
                   2 random pattern
                   5 bit crowding pattern
              D2 = if D1 = 0 fixed pattern
                   if D1 = 2 random pattern seed
                   if D1 = 5 two track numbers
              D3 = if D1 = 5 byte string for 1st track
              D4 = if D1 = 5 byte string for 2nd track

Examples    DATA, 2, 12876541
            Generate random pattern starting with seed 12876541
            DATA, 5, 37, FF00FF00, 00FF00FF
            Generate a bit string FF00FF00 on track 3,
            Generate a bit string 00FF00FF on track 7

**LIMT**        The directive limits specific operation during execution of the test.

Parameters    D1 = limit type
              D2 = limit count
              D1 = 1 limit compare error printout
                   D2 = number of compare errors to be reported in each record

Example     LIMT, 1, 5
            Report up to 5 compare errors for each record

**LEN**         This directive selects the byte length of the record to be used in the tape test (TST3, 1 only).

Parameters    D1 = byte length of record
              D2 = not used
              D3 = not used
              D4 = not used

Example     LEN, 980
            Generate a record of 980 bytes

# Section 11

# SIGMA 5 - 9
# 7 - CHANNEL
# MAGNETIC TAPE TEST

## PROGRAM NO. 705735

**Section 11**

**CONTENTS**

**SUBJECT MODEL** -- Magnetic Tape Stations, Model numbers 7362, 7372, Magnetic Tape Controllers, Model numbers 7361/7365, 7371/7374.

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer.

## PROGRAM PREREQUISITES
None

## GENERAL OPERATING PROCEDURES
General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives *RWTH - 7322* | | | | | |
| System Environment Example:<br>SYST,7372,0,81,83,87<br>Tape devices 81,83,87 on 7372 (75 IPS)<br>SYST,7362,0,80<br>Tape devices 80 on 7362 (37.5 IPS) | SYST,D1,D2,D3 [,D4,D5,D6,D7 ,D8,D9,D10] | D1<br><br>D2<br>D3<br><br>D4<br><br>⋮<br><br>D10 | Device station number<br><br>= 0<br>Valid IOP, controller and device address of first unit<br>Device address of 2nd unit<br><br><br><br>Device address of 10th unit | 7362, 7365 (37.5 IPS)<br>7372, 7374 (75 IPS)<br>0<br><br><br>80 ~ 1FFFF | NOTE:<br>Intermixing of tape stations of 37.5 IPS and 75 IPS during the functional test is not allowed |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 37 and random exerciser test) | TST0,D1,D2 | D1<br><br>D2 | Number of loops on the random exerciser<br>Number of retries on the random exerciser | 0 ~ 99999999 | If D1 = 0 1000 loops and 5 retries |
| Functional Test | TST1[,D1,D2] | D1<br>D2 | The first subtest to be executed<br>Last subtest to be executed | 1 ~ 40 | |
| Random Exerciser Test | TST2,D1,D2 | D1<br>D2 | Number of passes to be executed<br>Number of retries if any errors | 0 ~ 99999999 | |
| Utility Test | TST3,D1,D2[,D3,D4] | D1<br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br><br>D1<br><br><br><br><br><br><br><br><br><br><br><br><br><br>D1 | = 1 Tape test<br>D2 = 0 Write, rewind, read forward, space backward D3 records<br>  1 Write D3 records<br>  2 Read forward D3 records<br>  3 Space backward D3 records<br>  4 Read forward and space backward D3 records in sequence<br>  8 Write, rewind, read fwd, space backward D3 records (BCD)<br>  9 Write D3 records (BCD)<br>  10 Read fwd D3 records (BCD)<br>  12 Read fwd, space bkw D3 records (BCD)<br>D3 = Number of records to be written or read. If D3 = 0 continue until EOT or BOT is reached<br>D4 = Delay in milliseconds between operation sets<br>= 2 Deskew test<br>D2 = 0, 1 Write until EOT is reached and rewind<br>  2 Read forward until EOT and rewind<br>  3 Space backward until BOT is reached<br>  4 Read fwd until EOT, space bkw until BOT, no rewinds<br>  5 Capstan slippage exerciser<br>D3 = Not used<br>D4 = Not used<br>= 3 Sync on a character test<br>D2 = 1 Read forward and space record backward<br>  2 Space backward and space record forward<br>D3 = Byte to sync on<br>D4 = Delay in milliseconds between syncs | | |

**DIRECTIVES** (continued)

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| **Program Directives – Testing Directives (Continued)** | | | | | |
| | | D1 | = 4 Compatibility and noise pattern test | | |
| | | | D2 = 0, 1 Write, space backward, and read forward all records | | |
| | | | 2 Space forward, space backward, read forward all records | | |
| | | | 3 Read forward, space back-ward, space forward all records | | |
| | | | 4 Read forward all records | | |
| | | | 5 Write all records | | |
| | | | D3 = The number of records to be written (1 – 1500) | | |
| | | | D4 = Not used | | |
| | | D1 | = 5 Read/space test | | |
| | | | D2 = 0 Rewind and read fwd N records | | |
| | | | 1 Rewind and space fwd N records | | |
| | | | 2 Don't rewind, read fwd N records | | |
| | | | 3 Don't rewind, space fwd N records | | |
| | | | 4 Don't rewind, space bkw N records | | |
| | | | 8 Rewind, read fwd N records with even parity, decimal (BCD) | | |
| | | | 10 Don't rewind, read fwd with even parity, decimal (BCD) | | |
| | | | D3 = Number of records to read or space | | |
| | | | D4 = 0 Don't printout record | | |
| | | | 1 Printout record in error | | |
| | | | 2 Printout Nth record | | |
| **Program Directives – Optional Directives** | | | | | |
| Pattern selection (for Utility Test) (TST3, 1 only) Example: DATA,2,12876541 Generate random pattern starting with seed 12876541. DATA,5,36, FF00FF00, 00FF00FF. Generate a bit string FF00FF00 on track 3. Generate a bit string 00FF00FF on track 6. | DATA,D1,H2 [,H3,H4] | D1<br><br><br>H2<br><br>H3<br>H4 | Pattern type<br>0 = Fixed pattern<br>2 = Random pattern<br>5 = Bit crowding pattern<br>Pattern seed (for D1 = 0, 2)<br>two track number (for D1 = 5)<br>Byte string for 1st track (for D1=5)<br>Byte string for 2nd track (for D1=5) | 0,2,5<br><br><br>0 ~ FFFFFFFF<br>01 ~ 78<br>0 ~ FFFFFFFF | |
| Byte length of record for TST3, 1 only Example: LEN,980 Generate a record of 980 bytes | LEN,D1 | D1 | Byte length of record | 0 ~ (Function of memory size) | |
| Limitation Example: LIMT,1,5 Report up to 5 compare errors for each record | LIMT,D1,D2 | D1<br><br>D2 | Limit type<br>1 = Limit compare error printout<br>Number of compare errors to be reported on each record (for D1=1) | 1<br><br>D2 ≥ 0 (No limit if D2 = 0) | |

Note: Parameter of any directive beginning with a D means decimal, with an H means hexadecimal

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.
2. Test Strategy Selection

| | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Deskew adjustment Threshold check Capstan ramp adjustment Compatibility check |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT | LIMT | LIMT | LIMT, LEN, DATA |
| Subtests | All function subtests (1~37) and random exerciser test | 40 subtests (see error messages for the test types) | Random selection of order sequence buffer length data. The identical operation is performed on each selected device in turn, then the next operation begins. | See program directive TST3 |
| Error Message Format | 1. Error No. DDDD LOC XXXX 2. Self-explanatory | Error No. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the Magnetic Tape Test program.

### TST1 Functional Test

The functional test performs a systematic test of all logic functions of the tape controller and all tape devices specified by the SYST directives. The functional test consists of a number of subtests which may be selected individually or in groups. The functional tests can be run at any density if 75 IPS. The tape creep test (TST1, 35) and the gap length timing test (TST1, 37) tolerance is set for 800 BPI.

When a fault has been detected, automatic error looping thru sense switch control is implemented whenever possible. Write and read retries will only be done in the data test (TST1, 33).

For a description of individual subtests refer to the Functional Subtest and Related Error Messages Section. Each subtest is preceded by a test description.

### TST2 Random Exerciser Test

This test provides a means of operating a Magnetic Tape System with pseudo-random operation, order sequence, data pattern, I/O area, time delay, and record size for the purpose of detecting intermittent failures and exercising all tape units. The random exerciser test will report errors as they occur, but only as to the function that failed. No error looping is provided except for limited retries.

### TST3 Utility Test Routines

The utility test routine allows the user to select a specific function and to control the data pattern (see DATA directive ) and the record length (see 'LEN' directive). The utility tests can be run at any density if 75 IPS.

1. Tape Test
This test allows the user to write, read forward, read backward, read forward and then backward, or write followed by rewind and read forward and read backward N records or until EOT is reached.

2. Deskew Test
This test is provided as a scoping aid during checking and adjusting the read/write skew. A pattern of all ones will be recorded as a continuous record. At EOT the tape will be rewound.

3. Sync On Character Test
This test is provided as a scoping aid by executing a unique I/O instruction (TDV) after the byte count specified in the test has been reached.

4. Compatibility and Noise Pattern Test
This test allows the user to write, read forward, read backward, or read forward and backward a predetermined incremented noise pattern.

5. Read/Space Test
This test allows the user to write, read, or space N records, with or without rewind. Only nonrecoverable transmission errors will cause error printout, backspace, and a halt.

## ORDER CODES

X'01'  Write packed (binary)
X'02'  Read packed (binary)
X'05'  Write (binary)
X'06'  Read (binary)
X'0D'  Write decimal (BCD)
X'0E'  Read decimal (BCD)
X'13'  Rewind and interrupt
X'23'  Rewind off line
X'33'  Rewind
X'43'  Space record forward
X'4B'  Space record backward
X'53'  Space file forward
X'5B'  Space file backward
X'63'  Set erase
X'73'  Write tape mark

## TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7362/72 | Rate Error | Write Permitted | Write Protect Error | End of File | Not Used | Load Point | End of Tape | Rewind On-Line |

## AIO STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7362/72 | Rate Error | Device End | Write Protect Error | End of File | ← | NOT USED | | → |

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES
### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

TST1, 1 AIO, HIO, TIO, TDV Test - Check the ability of the 7-track mag tape system to correctly respond to the AIO, HIO and the TDV instructions. AIO will only check the no interrupt pending condition. Verify address recognition and status response to these instructions. Any error in this test may indicate a possible problem in the sub-controller area.

0101 AIO condition code error. No interrupt recognition expected.
0102 HIO condition code or status error. See printout.
0103 TIO condition code or status error. See printout.
0104 TDV condition code or status error. See printout.

TST1, 2 Invalid Order Test - Check the invalid order detection by issuing two SIO's with invalid order codes (X'0C', X'03). This test is designed to check order decoding, order-output and order-input phases in the controller and unusual end detection. The remaining byte count will be tested to verify that no data phases were executed. Check the ability of the HIO to reset UE condition.

0201 SIO for invalid order not accepted. Condition code error.
0202 SIO for invalid order status error. UE and no interrupt pending expected (read backward).
0203 HIO did not reset interrupt pending bit in status.
0204 SIO for invalid order not accepted. Condition code error.
0205 SIO for invalid order status error. UE and no interrupt pending expected (set correction).

TST1, 3 Erase Order Test - Check the execution of the first valid order. This test is designed to further check order decoding, order-output and order-input phases in the controller, and order termination without unusual end. The remaining byte count will be tested to verify that no data phases were executed. The status response will be tested.

0301 SIO condition code error on set erase.
0302 TIO status error on set erase. No UE or byte count reduction are expected. No data phases executed.

TST1, 7 Interrupt on UE, CE and AIO - Check the ability of the controller to generate an interrupt on unusual end and channel end using a read backward and the set erase order in that sequence. Check the execution of the AIO instruction. Verify that AIO and HIO can reset the interrupt pending condition. All status responses will be tested.

0701 SIO for invalid order condition code error (read bkw. UE set).
0702 No UE interrupt on invalid read backward with UE set.
0703 No UE set on AIO after invalid order or interrupt pending not reset after AIO.
0704 SIO for set erase condition code error (erase, CE set).
0705 No CE interrupt on erase with CE set.
0706 No interrupt pending set after HIO following the erase order.
0710 HIO status response error following AIO. UE or IP should not be set.
0711 TIO status response error following HIO. IP should not be set.

TST1, 8 I/O Interrupt Test - Check the ability of the IOP and CPU to interrupt the program whenever an interrupt call is generated by the controller. Verify proper operation of interrupt arm/disarm and enable/disable modes.

0801 TIO status response error after an invalid order. IP and UE should be set (read bkw, UE set with INT disarmed).
0802 TIO status response error after interrupt armed and disabled.
0803 No interrupt received on invalid order with UE set after interrupt armed and enabled.

TST1, 9 Command Chaining - Test the command chaining ability of the controller by issuing a set erase/read backward order sequence. Test the termination of the command chaining sequence by issuing a read-bkw/set erase order sequence. All status responses will be tested.

0901 SIO condition code error on command chaining order (erase read backward).
0902 No interrupt on command chaining erase, read backward.
0903 The last double word address is incorrect on command chaining. The address should be read backward.
0904 SIO condition code on command chaining order (read bkw, sense).
0905 No interrupt received on command chaining read bkw, erase.
0906 The last double word address is incorrect on command chaining. The address should be read backward.

TST1, 11 Rewind Test - Check the execution of a rewind on-line order. The test will verify that the tape is positioned at load point after completion of the rewind order. Check the execution of a rewind and interrupt order. This test will verify that the tape remains at load point and that the device initiates an interrupt request. Verify that an AIO and HIO instruction can reset the interrupt pending condition in the tape controller and the tape station. Verify that device end status is returned during the AIO. All status responses will be tested.

1101 TDV status error after rewind on line. No load point bit set.
1102 TIO status error after rewind and interrupt. No interrupt pend set.
1103 TIO status error after HIO on rewind with interrupt.
1104 TIO status error after rewind with interrupt. Inter/pend not set.
1105 AIO status error after rewind with interrupt. Device end not set.
1106 TIO status error after AIO. Interrupt pending not reset.
1107 TDV status error after rewind with interrupt. No load point set.

TST1, 12 Space Record and File Backward from BOT Test - Check the execution of space record and space file orders in the backward direction with tape positioned at load point. Verify that the controller responds with unusual end, end of file (TDV and AIO) and load point status. The test will check that the tape remains at load point. The byte count for all orders specified must remain unchanged.

1203 No interrupt on space backward at load point. (BC - 2)
1204 TIO or TDV status error on space bkw at load point. UE, load point, and BC = 2 expected.
1205 No interrupt received on space file backward at load point.
1206 TIO or TDV status error on space file bkw at load point. UE, load point, and no EOF expected.

TST1, 13 Write Tape Mark Test at BOT - Check the execution of a write tape mark order. The test will verify that tape can be moved off load point and that the order can be terminated with both controller and station returning to ready. If tape run-away, issue HIO. Rewind tape and test load point. End of file status will not be tested. The byte count for the order must remain unchanged.

1301 No interrupt on write tape mark at load point. (CE and BC-2 set)
1302 TIO or TDV status error on write tape mark at load point. EOF and BC - 2 expected.

TST1, 14 Space Record Forward Test - Check the execution of a space forward order. The test will verify that tape can be moved off the load point and that the order can be terminated with both controller and station returning to ready. If tape run-away, issue HIO. Rewind tape and test for load point. End of file and unusual end status will not be tested. The byte count for the order must remain unchanged.

TST1, 14 (Continued)

1401    No interrupt received on write tape mark after rewind.
1402    No interrupt received on space forward over a tape mark at load point. (CE and BC 2 set)
1403    Byte count on space fwd at load point error. Should be 2
1404    TIO status error on space fwd at load point. No error expected.

TST1, 15 Write Test (Byte 1 to 64) - Check the execution of write orders using X'FF' as data pattern and a starting at a byte of one up to a maximum byte count of 64. The test will verify that tape can be moved off the load point, that the order can be terminated with both controller and tape station returning to ready, that a data-output operation is actually performed, and that the byte count is always reduced to zero. Verify that incorrect length is not detected. Rewind tape and test for load point.
TE (transmission errors) not checked in this test.
Interrupt on ZBC checked in this subtest.

1501    TIO or TDV status error on write records 1-64 byte length. No incorrect length or UE expected, BC = 00.
1502    No interrupt received on writing 64 bytes with interrupt on ZBC.
1503    AIO or TIO status error on writing 64 bytes with interrupt on ZBC set.

TST1, 16 Read Test - Test the execution of read orders using a starting byte count of one up to a maximum count of 64. Write 64 records with a fixed byte count of 100 bytes (pattern = X'FF') and rewind tape. This test will check the response to a read forward operation (off load point, order transmission, data input operation, byte count reduced to zero). Rewind tape and test load point.
TE (Transmission errors) not checked in this test.

1601    TIO or TDV status error on writing 100 bytes all bits on. No incorrect length or UE expected, BC = 00.
1602    TIO or TDV status error on read forward 100 bytes all bits on with byte count 1-64. Incorrect length and no IZC expected.

TST1, 18 Write Read Data Test - Write N records with a fixed byte count and data pattern of X'FF'. Rewind tape and read N records in the forward direction. Verify that data can be recorded and read from each track.
TE (transmission errors) not checked in this test.

1801    TIO or TDV status error on writing 100 bytes all bits on, No incorrect length or UE expected, BC = 00.

TST1, 19 Write, Read Data Test (Data X'00' to X'20') - Write N records with a fixed byte count and the current data pattern data will be varied from X'00' thru X'20'. Rewind tape and read N records in the forward direction. Verify for each pass that only one track contains information and that all other tracks are zero. After each pass, loop on the data pattern which has caused an error and continue testing until a successful pass has been made.

1901    Write, Read forward, or information errors when saturating one track. 100 records of 100 bytes pattern 00, 01, 02, 04, 08, 10, 20.

TST1, 20 Set Erase-Write Test - Check the capability of the tape station to skip over an area on the tape by checking the delay between the start of the write order and the start of the data transfer.

2001    Erase time set too long. See message printout.
2002    Erase time set too short. See message printout.
2003    No interrupt on zero byte count occurred within 9ms.

TST1, 21 Write, Space FWD and BKW Test - Write N records with a fixed byte count. Rewind tape to load point. Space one record in the forward and backward direction. Space another record in the backward direction and check load point indicator. Space N records in the forward direction and then the reverse direction. Check all status response. Rewind to load point.

2101    TIO or TDV status error on writing 100 bytes all bits on.
2102    TIO or TDV status error on spacing forward over 100 bytes at load point.
2103    TIO or TDV status error on spacing backward over 100 bytes one record beyond load point. No UE or load point expected.
2104    TIO or TDV status error on spacing backward one record at load point. UE and load point expected.
2105    TIO or TDV status error on spacing forward over 100 bytes all bits' on. No UE or error expected, BC = 00.
2106    TIO or TDV status error on spacing backward over 100 bytes all bits on. No UE or error expected, BC = 00.

TST1, 22 Write Tape Mark Test - Write N tape marks and verify that end of file status is reported after each order. All tape marks are read forward and space bkw.

2201    TIO or TDV status error on writing a tape mark. Tape mark and no UE expected.
2202    TIO or TDV status error on spacing backward over 100 tape marks. Tape mark and UE expected.
2203    TIO or TDV status error on reading forward over 100 tape marks. Tape mark and UE expected.
2204    Timeout error while command chaining set erase and space backward. No interrupt received from set erase or TM flag missing when spacing over a TM.
2205    TIO or TDV error when command chaining set erase and space backward over a tape mark. UE and TM expected.

TST1, 23 Write Tape Mark - Space File and Space Record Test - Write N tape marks and rewind to load point. Space file in the forward direction and verify end of file and no unusual end status. Space file backward and check end of file and no unusual end. Space file backward again and check end of file, beginning of tape and no unusual end. Verify all other status. Verify that unusual end and end of file status is reported when spacing or reading over a tape mark. Write N records followed by a tape mark. Verify space record in both directions.

2301    TIO or TDV status error on writing a tape mark. Tape mark and no UE expected.
2302    TIO or TDV status error on space file forward. Tape mark and no UE expected.
2303    TIO or TDV status error on space file backward. Tape mark and no UE expected.
2304    TIO or TDV status error on space file backward at load point. Load point, tape mark, and no UE expected.
2305    TIO or TDV status error on writing a record 100 bytes. No error expected, BC = 00.
2306    TIO or TDV status error on writing a tape mark. No error expected, tape mark.
2307    TIO or TDV status error on spacing backward over a tape mark. UE and tape mark expected.
2308    TIO or TDV status error on spacing forward over a tape mark. UE and tape mark expected.

TST1, 24 Tape Loop Test - Rewind with command chain. Write with data chain 27,000 words, loop back to rewind. This sequence is repeated 10 times in an effort to cause the tape to loop out in the vacuum columns.

2401    TIO or TDV status error after rewinding and writing a record of 27,000 words, looping 10 times. No error expected.

TST1, 26 Incorrect Length Test - Write a record and read in the forward direction using a byte count - 1, byte count + 1 for the read orders. Verify incorrect length and all other status indications. Suppress incorrect length feature in the IOP will also be tested.

2601    TIO or TDV status error on writing 96 bytes all bits on. No errors expected, BC = 00. No incorrect length.
2602    TIO or TDV status error on spacing a record backward. No error expected.

TST1, 26 (Continued)

2603 TIO or TDV status error on reading a record forward. No error expected. BC = 00. No incorrect length.

2604 TIO or TDV status error on spacing a 96 byte record backward. No error expected.

2605 TIO or TDV status error on reading a 96 byte record forward with a BC · 95 incorrect length, UE and BC · 00 expected.

2606 TIO or TDV status error on spacing a 96 byte record backward. No error expected.

2607 TIO or TDV status error on reading a 96 byte record forward with suppress inc length, BC = 97. Inc. length BC ‑ 1, no UE expected.

2608 TIO or TDV status error on spacing bkw over record. No UE expected.

2609 TIO or TDV status error on reading forward a 96 byte record with suppress inc. length, BC · 95. Inc. length, BC 0, no UE expected.

TST1, 27 Data Chaining Test – Test the data chaining capability of the IOP using write and read orders.

2701 TIO or TDV status error on writing 2 bytes data chain 94. No errors expected, BC ‑ 00.

2702 TIO or TDV status error on spacing backward over record (2 bytes data chain 94). No error expected.

2704 TIO or TDV status errors on reading forward 48 bytes data chain 48 bytes. No error expected, BC = 00.

2705 Information error on reading a record fwd 48 bytes data chain 48.

TST1, 28 Byte Boundary Test – This test performs read and write operations from all possible memory boundaries.

2801 TIO or TDV status error when writing from WA, WA+1 byte, WA+2 bytes, WA+3 bytes.

2802 TIO or TDV status error on spacing backward. No error expected.

2804 TIO or TDV status error when reading fwd into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.

2805 Information error when reading fwd into WA, WA+1 byte, WA+2 bytes, WA+3 bytes.

2806 TIO or TDV status error on writing a record 4,16,32,64....bytes in length.

2807 TIO or TDV status error on spacing bkw over 4,16,32,64,128.... bytes in length.

2809 TIO or TDV status error on reading a record fwd 4,16,32,64.... bytes in length.

2810 Information error on reading forward 4,16,32,64....bytes.

TST1, 29 Decimal (BCD) Mode Data Test – This test will write data using translation. The data will be read and the information verified with and without translation. Transmission errors will be expected on reading without translation.

2901 TIO or TDV status error when writing the BCD character set. No error expected.

2902 TIO or TDV status error when spacing backward over BCD record. No error expected.

2903 TIO or TDV status error when reading the BCD character set. No error expected.

2904 Information error on the BCD character set record.

2905 TIO or TDV status error when spacing over the BCD character set.

2906 TIO or TDV status error when reading the BCD character set without translation. Transmission errors expected.

2907 Information error on BCD record read without translation.

2908 TIO or TDV error when writing a 4 byte record checking zero translation. No error expected.

2909 TIO or TDV error when spacing bkw over zero translation record.

2911 TIO or TDV error when reading 4 byte zero translation record. No error expected.

2912 Information error on zero translation record. Information expected X'F0F0F0F0'.

TST1, 30 Binary Mode Data Test – This test will write data using the binary mode. The data will be read and the information verified with and without translation. Transmission errors will be expected on reading with translation.

3001 TIO or TDV status error when writing a binary record X'00'-X'3F'.

3002 TIO or TDV status error when spacing bkw over binary record.

3003 TIO or TDV status error when reading a binary record X'00'-X'3F'.

3004 Information error on reading binary record X'00'-X'3F'.

3005 TIO or TDV status error spacing bkw over binary record.

3006 TIO or TDV status error when reading binary record with BCD. Transmission error expected.

3007 Information error when reading binary record with BCD.

TST1, 31 Packed Binary Data Test – This test will write data X'00' – X'FF' using the packed binary mode. The data will be read and verified. This subtest will be bypassed if not applicable to the system.

3101 TIO or TDV status error when writing a packed binary record X'00' – X'FF'. No error expected.

3102 TIO or TDV status error when spacing bkw over a packed binary record X'00' – X'FF'.

3103 TIO or TDV status error when reading a packed binary record X'00' – X'FF'.

3104 Information error when reading a packed binary record.

3105 TIO or TDV status error writing packed binary record of 6,7,8 bytes to test the packed binary end condition.

3106 TIO or TDV status error when spacing bkw over packed binary record.

3107 TIO or TDV status error reading a packed binary record of 6,8,9 bytes to test the end condition.

3108 Information error on packed binary record checking end condition.

TST1, 32 LRC Test – Check the ability to set all bits in the LRC character. The LRC will be tested in the packed binary, binary, and decimal (BCD) mode. Any section not applicable to the unit being tested will be bypassed.

3201 TIO or TDV status error writing a packed binary record to set one bit at a time in the LRC character.

3202 TIO or TDV status error spacing bkw over packed binary record.

3203 TIO or TDV status error reading a packed binary record to set one bit at a time in the LRC character.

3204 Information error on packed binary record that sets a bit at a time in the LRC character.

3205 TIO or TDV status error writing a binary record to set one bit at a time in the LRC character.

3206 TIO or TDV status error spacing backward over a binary record.

3207 TIO or TDV status error reading a binary record to set one bit at a time in the LRC character.

3208 Information error on binary record that sets a bit in the LRC.

3209 TIO or TDV status error writing a BCD record with a blank LRC, then sets a particular bit and the parity bit in the LRC char.

3210 TIO or TDV status error spacing bkw over BCD record.

3211 TIO or TDV status error reading the BCD record with a blank LRC, then sets a particular bit and the parity bit in the LRC char.

3212 Information error reading a BCD record with a blank LRC, and particular bits in the LRC character.

TST1, 33 Data Test Noise Patterns and Bit Crowding – This test will write and read variable data patterns. The sequence will always be write, space reverse and read forward. The record size will be varied after each record. Noise sensitive and bit crowding data pattern will be used. Write and read retries will be allowed.

3301 TIO or TDV status error on writing an incremented record with saturated tracks and noise pattern.

3302 TIO or TDV status error on space backward over an incremented record with saturated tracks and noise patterns.

3303 TIO or TDV status error on reading forward an incremented record with saturated tracks and noise patterns.

3304 Information error on reading forward an incremented record with saturated tracks and noise patterns.

TST1, 34 Ready – Busy Test – Check the busy condition after issuance of an order. The test will also attempt to issue an SIO to a busy controller and to a ready controller and a busy station.

**TST1, 34 (Continued)**

3401  TIO error. Device should be busy while writing 1000 bytes.
3402  No interrupt received after writing 1000 bytes.
3403  TIO or TDV status error on writing a 1000 byte record.
3404  TIO error. Controller should be busy while reading 1000 bytes.
3405  No interrupt received after reading a record bkw. with 1000 bytes.
3406  SIO error. Controller should be busy on initiating rewind.
3407  TIO error. Device should be busy on rewinding.

**TST1, 35 Tape Creep Test** – This test will write one record followed by
a set erase order and another write order. A space record
backward and rewrite sequence will now be repeated N times.
After reading and verifying the data of the first record, read
the second record and compute the delay between the start of
the read order and the start of the data transfer. The direc-
tion of the creep will be determined by comparing the delay
to the original value. The tolerance is set for 800 BPI if 75
IPS.

3501  TIO or TDV status error on writing a 96 byte record.
3502  TIO or TDV status error when writing a 12 byte record.
3503  TIO or TDV status error when writing a 12 byte record.
3504  TIO or TDV status error when spacing backward over a 12 byte
record.
3505  TIO or TDV status error spacing backward over 96 bytes.
3506  TIO or TDV status error reading a 96 byte record.
3507  Information error reading a 96 byte record.
3508  Tape creep tolerance exceeded in the tape creep test.
3509  Tape creep negative in the tape creep test.

**TST1, 36 Erase Verification Test** – This test will test the erase order by
rewinding tape and then writing N one byte records. The
records are followed by a tape mark. After a rewind, write
one record, set erase, and write one record. The tape is
rewound. The records are counted to verify the erase order
execution.

3601  The erase order did not remove the correct number of records when
verifying the erase order.

**TST1, 37 Gap Length Timing Test** – This routine verifies gap timing and
is intended as a scoping aid for adjusting the forward and
reverse ramp. The test can only be run on a system with a
real time clock. The tolerance is set for 800 BPI if 75 IPS.

3701  TIO or TDV status error writing 12 bytes in the I.R.G. Test.
3702  TIO or TDV status error on spacing backward over 12 bytes.
3703  TIO or TDV status error writing 12 bytes in the I.R.G. test.
3704  TIO or TDV status error on spacing backward over 12 bytes.
3705  I.R.G. time is incorrect. See printout.

**TST1, 38 End of Tape Test** – This test will continue to write N records
until the end of tape indicator is detected. One additional
record will be recorded and the EOT condition will be
verified again. Two records will be spaced in the backward
direction. After the second space, the EOT indicator should
be reset. The tape will be rewound.

3801  TIO or TDV error writing 1000 bytes in the end of tape test.
3802  TIO or TDV error writing 1000 bytes beyond EOT indication. End
of tape flag should be set.
3803  TIO or TDV status error spacing backward over 1000 bytes at EOT.
EOT flag should be set.
3804  TIO or TDV status error spacing bkw. over 1000 bytes near EOT.
EOT flag should be reset.

**TST1, 40 Operator Control Panel Test** – This test will check every
switch on the operator control panel in the sequence specified
by the program and verify the write protect feature.

4001  Status error on writing a record designating unit 0,1,2,3,4,5,6,7.
4002  Status error spacing bkw. with unit designation 1,2,3,4,5,6,7.
4004  Status error on reading fwd. with designation unit 0,1,2,3,4,5,6,7.
4005  Information error reading fwd. record from unit 0,1,2,3,4,5,6,7.

4006  Status error when trying to write on a unit with the write ring
removed. A write protect is expected.
4007  Status error when trying to write a tape mark with the write ring
removed. A write protect is expected.
4008  No interrupt was received when the attention button was set by
the operator.
4009  Status error on rewind and put off line. The device should be
manual and the controller ready.
4010  TDV status incorrect. Load point and ready expected.
4013  The density dial is set incorrectly or the actual density of the
1000 byte record was incorrect.
4014  TIO or TDV status error on writing a 96 byte record with the
density dial set to a particular density.
4015  TIO or TDV status error on spacing backward over a record with
the density dial set at a particular density.
4016  TIO or TDV status error reading 96 bytes with the density dial set
at a particular density.
4017  Information error on the 96 byte record read with the density dial
set at a particular density.

## TST2 RANDOM EXERCISER TEST

This test provides a means of operating a magnetic tape system with
pseudo-random operation, order sequence, data pattern, I/O area, time
delay, and record size for the purpose of detecting intermittent failures
and exercising all tape units.

The random exerciser test will report errors as they occur, but only as to
the function that failed. No error looping is provided except for limited
retries.

Parameters    D1 = Number of cycles, set to 1000 if 0
              D2 = Number of error retries

From the random seed, the following masks are used to get type of
operation, word size of record, and time delay in milliseconds.
     X'00003FF0' To get random record word size
     X'001F0000' To get random time delay in milliseconds
     X'0000000F' To get random operation set

Random Operation Sets

    0   Write, write, write, write, write
    1   Write, write, write, write, space bkw
    2   Write, write, write, space bkw, space bkw
    3   Write, write, write, space bkw, read fwd
    4   Write, write, space bkw, read fwd, space bkw
    5   Write, write, space bkw, space bkw, read fwd
    6   Write, write, space bkw, space bkw, space fwd
    7   Write, space bkw, read fwd, write, write
    8   Write, space bkw, read fwd, write, space bkw
    9   Write, space bkw, write, space bkw, read fwd
    A   Write, space bkw, read fwd, space bkw, write
    B   Write, space bkw, read fwd, space bkw, read fwd
    C   Write, space bkw, space fwd, write, write
    D   Write, space bkw, write, space bkw, space fwd
    E   Write, space bkw, read fwd, space bkw, read fwd
    F   Write, space bkw, space fwd, space bkw, read fwd

## TST3 UTILITY TESTS

The utility test routine allows the user to select a specific function and
to control the data pattern (see data directive) and the record length (see
'LEN' directive).

Parameters    D1 = Utility test selection
              D1 = 1 Tape test
              D1 = 2 Deskew test
              D1 = 3 Sync on a character test
              D1 = 4 Compatibility and noise pattern test
              D1 = 5 Read/space test
              D2 = Operations requested according to test
              D3 = Parameter requested according to test
              D4 = Parameter requested according to test

### TST3, 1 Tape Test

This test allows the user to write, read forward, space backward, read forward and space backward, or write followed by rewind, read forward and space backward N records or until EOT is reached.

| | |
|---|---|
| Parameters | D1 = 1 Tape Test |
| | D2 = 0 Write, rewind, read forward, space backward D3 records |
| | 1 Write D3 records |
| | 2 Read forward D3 records |
| | 3 Space backward D3 records |
| | 4 Read forward and space backward D3 records in sequence |
| | 8 Write, rewind, read fwd, space bkw D3 records (BCD) |
| | 9 Write D3 records (BCD) |
| | 10 Read fwd D3 records (BCD) |
| | 12 Read fwd, space bkw D3 records (BCD) |
| | D3 = Number of records to be written or read. If D3=0 continue until EOT or BOT is reached. |
| | D4 = Delay in milliseconds between operation sets |
| Example | TST3, 1, 1, 1000, 5 |
| | Write 1000 records with a 5 millisecond delay after each write operation. |

### TST3, 2 Deskew Utility Test

This test is provided as a scoping aid during checking and adjusting the read/write skew. A pattern of all ones will be recorded as a continuous record. At EOT the tape will be rewound.

| | |
|---|---|
| Parameter | D1 = 2 Deskew test |
| | D2 = 0, 1 Write until EOT is reached and rewind |
| | 2 Read forward until EOT and rewind |
| | 3 Space backward until BOT is reached |
| | 4 Read fwd until EOT, space bkw until BOT, no rewinds |
| | 5 Capstan slippage exerciser |
| | D3 = Not used |
| | D4 = Not used |
| Example | TST3, 2, 2 |
| | Read forward until EOT and rewind. |

### TST3, 3 Sync on a Character Utility Test

This test is provided as a scoping aid by executing a unique I/O instruction (TDV) after the byte count specified in the test has been reached.

| | |
|---|---|
| Parameters | D1 = 3 Sync on a character test |
| | D2 = 1 Read forward and space record backward |
| | D3 = Byte to sync on |
| | D4 = Delay in milliseconds between syncs |
| Example | TST3, 3, 1, 375, 10 |
| | Read forward 375 bytes, signal (TDV) and delay 10 milliseconds. Space backward. |

### TST3, 4 Compatibility and Noise Pattern Test

This test allows the user to write, read forward, read backward, or read forward and backward a predetermined incremented noise pattern.

| | |
|---|---|
| Parameters | D1 = 4 Compatibility and noise pattern test |
| | D2 = 0, 1 Write, space backward, and read forward all records |
| | 2 Space forward, space backward, read forward all records |
| | 3 Read forward, space backward, space forward all records |
| | 4 Read forward all records |
| | 5 Write all records |
| | D3 = Not used |
| | D4 = Not used |
| Example | TST3, 4, 5 |
| | Write all records. |

### TST3, 5 Read/Space Test

This test allows the user to read or space N records, with or without rewind. Only non-recoverable transmission errors will cause error printout, backspace, and a halt.

| | |
|---|---|
| Parameters | D1 = 5 Read/space test |
| | D2 = 0 Rewind and read fwd N records |
| | 1 Rewind and space fwd N records |
| | 2 Don't rewind, read fwd N records |
| | 3 Don't rewind, space fwd N records |
| | 4 Don't rewind, space bkw N records |
| | 8 Rewind, read fwd N records with even parity, decimal (BCD) |
| | 10 Don't rewind, read fwd with even parity, decimal (BCD) |
| | D3 = Number of records to read or space |
| | D4 = 0 Don't printout record |
| | 1 Printout record in error |
| | 2 Printout Nth record |
| Example | TST3, 5, 0, 100, 1 |
| | Rewind, read 100 records. Printout error record. |

# Section 12

# SIGMA 5 - 9
# COMPREHENSIVE LINE PRINTER
# TEST (744X - 745X)

**PROGRAM NO. 706167**

**Section 12**

**CONTENTS**

**SUBJECT MODEL** -- Line Printer Model Numbers 3451, 7440/7445, 7441, 7446, 7450, 7442

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer

## PROGRAM PREREQUISITES

The vertical format tape must be removed when running the function test (TST1) on model 7441, 7446, and 7442

## GENERAL OPERATING PROCEDURES

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

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**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives | | | | | |
| System Environment | SYST, D1, X2, X3 | D1 | Device model number | 7440, 7441, 7442, 7445 7446, 7450, 3451 | 7441 |
| | | X2 | Revision number of controller | 0 for all printers | |
| | | X3 | IOP and Device address | 01 ~ 1F7F | |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 73, and random exerciser test) | TST0 | | | | |
| Functional Test | TST1 [,D1 [,D2] | D1 | The first subtest to be executed | 0 (all subtests) ~ 73 | 0 |
| | | D2 | Last subtest to be executed | | |
| Random Exerciser Test | TST2, D1 | D1 | Number of cycles to be performed | D1 > 0 | 1 |
| Utility Test | TST3, D1, D2, D3, D4 | D1 | = 0 Hammer registration  D2=Line count | D2 Not entered = Print continuously  D2=0 Print 1 line  D2≠0 Print D2 lines | Size of character sets: 7440/45=40 7441 =42 7446 =42 7450 =44 7442 =42 3451 =40 |
| | | | = 1 Checkerboard pattern  D2=Line count | D2 Not entered=Print continuously  = 0 Print 1 line  ≠ 0 Print D2 lines | |
| | | | = 2 Ripple pattern  D2=Line count | D2 Not entered=Print continuously  = 0 Print 1 line  ≠ 0 Print D2 lines | |
| | | | = 3 Printer speed test  D2=Character set count  7450 ONLY | 7450 Only  1 ≤ D2 ≤ 63 | |
| | | | = 4 Printer load test  D2=Line count | D2 Not entered=Print continuously  = 0 Print 1 line  ≠ 0 Print D2 lines | |
| | | | = 5 Broadside pattern  D2=Line count | D2 Not entered=Print continuously  = 0 Print 1 line  ≠ 0 Print D2 lines | |
| | | | = 6 Selectable pattern/position (Data determined by DATA directive)  D2=Number of lines to be printed  D3=Number of lines to be printed as a group  D4=Number of blank lines between groups | D2 Not entered=Print continuously  D2=0 Print 1 line  D2≠0 Print D2 lines  D3=0 Print continuous lines  ≠0 No. lines/group  0 < D4 | |
| | | | = 7 Space lines (space orders are issued to each of the 15 possible positions in sequence) | | |
| | | | = 8 Channel search  D2=Channel number | D2 Not entered Skip to all channels in sequence  0 < D2 < 7 | |
| | | | = 9 All Utility tests in sequence  D2=Line count | D2=0 Print 1 line  D2≠0 Print D2 lines | |
| | | | = 10 Line printer cleaner  D2=Line count | D2=0 Print 1 line  D2≠0 Print D2 lines | |

**DIRECTIVES** (Continued)

| Name | Format | Parameter | | | |
|---|---|---|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Optional Directives | | | | | |
| Pattern selection (for Utility Test )(TST3, 6) | DATA, D1, D2, D3, D4 | D1<br>D2<br>D3<br>D4 | = 4 Variable pattern<br>Starting column<br>Ending column<br>EBCDIC character string<br>(up to 4 EBCDIC characters) | -4<br>1 ~ 132<br>1 ~ 132<br>Any printable codes<br>00 ~ FF<br>(F0F1F2F3) | |
| Limitation of program parameters | LIMT, D1, D2, D3 | D1 | = 1 Limit compare error printouts<br>D2=Maximum number of compare<br>     error printouts | 1, 2<br><br>0 ≤ D2 | |
| | | | = 2 Limit delay time<br>D2=Minimum delay time<br>D3=Maximum delay time | -6<br>0 ≤ D2 ≤ D3 | |

Note:  Parameter of any directive beginning with a D means decimal; with an H means hexadecimal.

## START PROCEDURE

1. Sense Switch Options, Monitor Directive Options, and Environmental Directives – Refer to DPM section of this manual.  .
2. Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Print Quality Verification |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT | LIMT | LIMT | LIMT, DATA |
| Subtests | All functional subtests (1 ~ 73) and random exerciser test | 73 subtests (see error messages for the test types) | Prints a predetermined set of test patterns | Prints one or all of predetermined patterns |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX 2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

3. System reset should normally be used in order to insure the resetting of controller test mode logic.

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the Comprehensive Line Printer test program.

### TST0

The directive selects the comprehensive test consisting of the functional test (subtests 1–73) and the random exerciser test.

Parameters:   None

Example:   TST0
1. The functional test will be run on the printer in sequence (subtest 1 through 73).
2. The random exerciser will run until six cycles have been completed. If a failure is encountered, an error message is printed and the exercising continues.

### TST1

The directive selects the entire functional test (no parameters entered) or selects one or more contiguous functional subtests.

Parameters:   D1 – First functional subtest
D2 – Last functional subtest

where $0 < D1 \leq D2 \leq 73$

Examples:   Run all functional subtests.

TST1, 35, 49

Run functional subtests 35 through 49.

### TST2

The directive selects the random exerciser test.

Parameters:   D1 – Number of cycles to be executed by random exerciser

Example:   TST2, 3

The random exerciser will run until three cycles have been completed.

### TST3

The utility test routine allows the user to select a specific utility function and/or print patterns which aid the operator in printer adjustments.

Parameters:   D1 – Utility test selection
D2 – Defined by the utility test selected
D3 – Defined by the utility test selected
D4 – Defined by the utility test selected

D1 = 0 Hammer registration
D2 = Line count

Generates pattern of broadside character 'E' (same character in all positions) continuously as a reference in checking printer hammer alignment

D1 = 1 Checkerboard pattern
D2 = Line count

Generates a worst-case pattern to expose ghost character printing. The pattern consists of alternating character 'E' and blanks.

TST3(Continued)

D1 = 2 Ripple pattern
D2 = Line count

Generates a pattern consisting of all characters per line, each succeeding line having the characters shifted one position to the left

D1 = 3 Printer speed test
D2 = Character count (7450 only)

A 36-line pattern of characters is printed to produce maximum print rate. The average time to print and upspace is calculated and the printer speed is determined and reported.

D1 = 4 Printer load test
D2 = Line count

Generates a pattern of an increasing number of character 'E' each line until 132 positions are printed, then a decreasing number of character 'E' each line

D1 = 5 Broadside pattern
D2 = Line count

Generates a 64-line pattern of all printable characters broadside

D1 = 6 Selectable pattern/position
D2 = Line count
D3 = Group/line count
D4 = Group/space count

Generates a selectable character and position(s) pattern

D1 = 7 Space lines
D2 = Unused

Space orders are issued to each of the 15 possible positions in sequence.

D1 = 8 Channel search
D2 = Channel number

Channel searches are issued to the operator-specified channel.

D1 = 9 Utility test
D2 = Line count

Run all utility tests in sequence

D1 = 10 Line Printer Cleaner
D2 = Line count

Print ripple pattern with inhibit upspace

Examples:   TST3, 7

Space orders are issued to each of the 15 possible positions in sequence.

TST3, 8, 4

Exercise the printer VFU control. Channel 4 is to be searched.

## ORDER CODES

| | |
|---|---|
| X'01' | Print a line |
| X'41' | Print a line – interrupt at data transmission complete |
| X'03' | Format order (see format codes) |
| X'43' | Format order – interrupt at data transmission complete (see format codes) |
| X'05' | Print with format |
| X'45' | Print with format – interrupt at data transmission complete |
| X'04' | Diagnostic sense (7441, 7442 and 7446) |
| X'44' | Diagnostic sense (7441, 7442 and 7446) – interrupt at data transmission complete |
| X'07' | Diagnostic control (7441, 7442 and 7446) (see diagnostic control bytes) |
| X'47' | Diagnostic control (7441, 7442 and 7446) – interrupt at data transmission complete (see diagnostic control bytes) |

## NORMAL TDV STATUS
TDV SET 1

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7440/7445 3451 | Not Used | Print Fault | Paper Low | Top of Page | Paper Moving | Paper Runaway | Not Used | Not Used |
| 7450 | Not Used | Typeline in Odd Sector = 1 | Paper Low | Top of Page | Paper Moving | Paper Runaway | Print Order Expected | Maintenance Panel Used |
| 7441 7442 | Not Used | Buffer Parity Error | Paper Low | Top of Page | Interlock | Paper Runaway | IO Parity Error | Hammer Drive Supply Low |
| 7446 | Not Used | Recovery Mode 1 | Recovery Mode 2 | Top of Page | Buffer Parity Error | Code Disc Parity Error | IO Parity Error | Print Error |

## TEST MODE TDV STATUS

| MODEL/SET | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7441/7446/7442 Printer States/Control Set 2 | State A | State B | State C | State D | State E | Print Complete | Buffer Scan Complete | Control Byte Received |
| 7441/7446/7442 Format Register Set 3 | Search | Space | Inhibit Upspace | Line Marker Clock | Format Register Bit 4 | Format Register Bit 5 | Format Register Bit 6 | Format Register Bit 7 |
| 7441/7442 Paper Motion Control Set 4 | PAPDR | PSCD | PAPSE | LMCLK | ECLB1 | ECLB2 | EBRB1 | EBRB2 |
| 7446 Paper Motion Control Set 4 | Paper Move | Paper Stop | End Hi Speed Boost | End Low Speed Boost | End Brake Boost | Shift | End Format Scan | Paper Clamp |
| 7441/7446/7442 Address Counters Set 5 | X'AD0' | X'AD1' | X'AD2' | X'AD3' | X'AD4' | X'AD5' | X'AD6' | X'AD7' |
| 7446 Vertical Format Channel Set 6 | VFUCH0 | VFUCH1 | VFUCH2 | VFUCH3 | VFUCH4 | VFUCH5 | VFUCH6 | VFUCH7 |
| 7441/7446/7442 Set 7 | ← | | | NOT USED | | | | → |
| 7446 Buffer Output Register Set 8 | SR0 | SR1 | SR2 | SR3 | SR4 | SR5 | SR6 | SR7 |

## AIO STATUS

For Model 7441/7446/7440/7445/7450

| BITS | | | | | | | |
|---|---|---|---|---|---|---|---|
| 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| NOT USED | DATA TRANSMISSION COMPLETE INTERRUPT | ← | | NOT USED | | | → |

## FORMAT CODES FOR FORMAT OPERATIONS

### MODEL 7441/7446 and 7442

| | |
|---|---|
| X'60' | Inhibit automatic space after print |
| X'C0' | Space 0 lines |
| X'C1' | Space 1 line |
| X'C2' | Space 2 lines |
| X'C3' | Space 3 lines |
| X'C4' | Space 4 lines |
| X'C5' | Space 5 lines |
| X'C6' | Space 6 lines |
| X'C7' | Space 7 lines |
| X'C8' | Space 8 lines |
| X'C9' | Space 9 lines |
| X'CA' | Space 10 lines |
| X'CB' | Space 11 lines |
| X'CC' | Space 12 lines |
| X'CD' | Space 13 lines |
| X'CE' | Space 14 lines |
| X'CF' | Space 15 lines |
| X'E0' | Space 0 lines and inhibit automatic upspace |
| X'E1' | Space 1 line and inhibit automatic upspace |
| X'E2' | Space 2 lines and inhibit automatic upspace |
| X'E3' | Space 3 lines and inhibit automatic upspace |
| X'E4' | Space 4 lines and inhibit automatic upspace |
| X'E5' | Space 5 lines and inhibit automatic upspace |
| X'E6' | Space 6 lines and inhibit automatic upspace |
| X'E7' | Space 7 lines and inhibit automatic upspace |
| X'E8' | Space 8 lines and inhibit automatic upspace |
| X'E9' | Space 9 lines and inhibit automatic upspace |
| X'EA' | Space 10 lines and inhibit automatic upspace |
| X'EB' | Space 11 lines and inhibit automatic upspace |
| X'EC' | Space 12 lines and inhibit automatic upspace |
| X'ED' | Space 13 lines and inhibit automatic upspace |
| X'EE' | Space 14 lines and inhibit automatic upspace |
| X'EF' | Space 15 lines and inhibit automatic upspace |
| X'F0' | Skip to channel 0 (bottom of page) |
| X'F1' | Skip to channel 1 (top of page) |
| X'F2' | Skip to channel 2 |
| X'F3' | Skip to channel 3 |
| X'F4' | Skip to channel 4 |
| X'F5' | Skip to channel 5 |
| X'F6' | Skip to channel 6 |
| X'F7' | Skip to channel 7 |

### MODEL 7446

| | |
|---|---|
| X'D0' | Skip to channel 0 (BOP) and inhibit automatic upspace |
| X'D1' | Skip to channel 1 (TOP) and inhibit automatic upspace |
| X'D2' | Skip to channel 2 and inhibit automatic upspace |
| X'D3' | Skip to channel 3 and inhibit automatic upspace |
| X'D4' | Skip to channel 4 and inhibit automatic upspace |
| X'D5' | Skip to channel 5 and inhibit automatic upspace |
| X'D6' | Skip to channel 6 and inhibit automatic upspace |
| X'D7' | Skip to channel 7 and inhibit automatic upspace |

### MODEL 7440/7445 and 3451

| | |
|---|---|
| X'60' | Inhibit automatic space after print |
| X'C0' | Space 0 lines |
| X'C1' | Space 1 line |
| X'C2' | Space 2 lines |
| X'C3' | Space 3 lines |
| X'C4' | Space 4 lines |
| X'C5' | Space 5 lines |
| X'C6' | Space 6 lines |
| X'C7' | Space 7 lines |
| X'C8' | Space 8 lines |
| X'C9' | Space 9 lines |
| X'CA' | Space 10 lines |
| X'CB' | Space 11 lines |
| X'CC' | Space 12 lines |
| X'CD' | Space 13 lines |
| X'CE' | Space 14 lines |
| X'CF' | Space 15 lines |
| X'E0' | Space 0 lines and inhibit automatic upspace |
| X'F0' | Skip to channel 0 (bottom of page) |
| X'F1' | Skip to channel 1 (top of page) |
| X'F2' | Skip to channel 2 |
| X'F3' | Skip to channel 3 |
| X'F4' | Skip to channel 4 |
| X'F5' | Skip to channel 5 |
| X'F6' | Skip to channel 6 |
| X'F7' | Skip to channel 7 |

### MODEL 7450

| | |
|---|---|
| X'60' | Inhibit automatic space after print |
| X'C0' | Space 0 lines |
| X'C1' | Space 1 line |
| X'C2' | Space 2 lines |
| X'C3' | Space 3 lines |
| X'C4' | Space 4 lines |
| X'C5' | Space 5 lines |
| X'C6' | Space 6 lines |
| X'C7' | Space 7 lines |
| X'E0' | Space 0 lines and inhibit automatic upspace |
| X'E1' | Space 1 line and inhibit automatic upspace |
| X'E2' | Space 2 lines and inhibit automatic upspace |
| X'E3' | Space 3 lines and inhibit automatic upspace |
| X'E4' | Space 4 lines and inhibit automatic upspace |
| X'E5' | Space 5 lines and inhibit automatic upspace |
| X'E6' | Space 6 lines and inhibit automatic upspace |
| X'E7' | Space 7 lines and inhibit automatic upspace |
| X'F0' | Skip to channel 0 (bottom of page) |
| X'F1' | Skip to channel 1 (top of page) |

## DIAGNOSTIC CONTROL BYTE (7441 ONLY)

| BIT | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | MEANING |
|---|---|---|---|---|---|---|---|---|---|
| | 1 | - | - | - | - | - | - | - | 0 = Normal<br>1 = Step mode (state register advances on TDV) |
| | - | 1 | - | - | - | - | - | - | 0 = Normal<br>1 = Inhibit print (disable hammers and paper motion) |
| | - | - | 1 | - | - | - | - | - | Unassigned |
| | - | - | - | - | 1 | - | - | - | 0 = Normal<br>1 = Inhibit buffer clear |
| | - | - | - | 1 | - | - | - | - | 0 = Input buffer<br>1 = Input code disk |
| | - | - | - | - | - | X | X | X | Select TDV states 1 through 8 |

## DIAGNOSTIC CONTROL BYTE (7446 ONLY)

| BIT | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | MEANING |
|---|---|---|---|---|---|---|---|---|---|
| | 0 | 0 | 0 | - | - | - | - | - | Normal |
| | 1 | X | 0 | - | - | - | - | - | Step mode (state register advances on TDV) |
| | X | 1 | 0 | - | - | - | - | - | Inhibit print (disable hammers and paper motion) |
| | 0 | 0 | 1 | - | - | - | - | - | Force print error during printing in state C |
| | 0 | 1 | 1 | - | - | - | - | - | Force code disk parity error during printing in state C |
| | 1 | 0 | 1 | - | - | - | - | - | Force buffer parity error during printing in state C |
| | 1 | 1 | 1 | - | - | - | - | - | Force IO parity error on data out in state B or state D |
| | - | - | - | 1 | - | - | - | - | 0 = Input buffer<br>1 = Input code disk |
| | - | - | - | - | 1 | - | - | - | 0 = Normal<br>1 = Inhibit buffer clear |
| | - | - | - | - | - | X | X | X | Select TDV status set 1 through 8 |

## FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES
### FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

NOTE

All functional tests for 7441 also applies for 7442 and all functional tests for 7440/7445 also applies for 3451.

TST1, 1 HIO, TIO, TDV and AIO instruction recognition (7440/7445, 7441, 7446, 7450). HIO, TIO, TDV and AIO instructions are issued and condition codes status tested.

0101 HIO instruction condition codes or status error.
0102 TIO instruction condition codes or status error.
0103 TDV instruction condition codes or status error.
0104 AIO instruction condition code error. Expect no interrupt recognition.

TST1, 2 SIO invalid order (7440/7445, 7441, 7446, 7450). SIO is issued with all invalid orders and controller tested for unusual end.

0201 SIO instruction condition codes not 00 as expected.
0202 SIO instruction status error.
0203 TIO instruction indicates controller busy 50 μs after SIO. Expect UE.
0204 TIO instruction indicates status error after SIO (invalid order). Expected UE, controller not busy.
0205 TIO instruction terminal byte count not = 1 indicating controller accepted one byte for invalid order.

TST1, 3 Test Mode Selection. (7441, 7446). SIO issued to select and reset controller test mode. TDV is used to verify test mode (CC2 = 1—test mode).

0301 SIO instruction condition code or status error.
0302 TIO instruction indicates controller busy beyond normal termination time for select test mode order.
0303 TIO instruction indicates controller terminated with UE for select test mode order.
0304 TIO instruction indicates status error after select test mode order.
0305 Test mode byte not accepted by controller.
0306 Test mode byte disturbed by controller data in operation. Expected data out (one byte) operation.
0307 TDV condition codes not 01. Expected CC1, 2 = 01 (test mode selected).
0308 SIO instruction condition code or status error while controller in test mode.
0309 TIO indicates condition code or status error for reset test mode order.
0310 TDV condition codes not 00 indicating reset test mode order not performed correctly. Expected CC1, 2 = 00.

TST1, 4 interrupt generation and HIO, AIO instruction resetting (7441, 7446). The following orders are issued: X'07', X'07', and X'00' in order to test the generation of ICE, IZC and IUE. AIO and HIO instructions are issued to test the interrupt clearing.

0401 TIO instruction indicates IP status not present after X'07' order issued with ICE flag set.
0402 TIO instruction condition code or status error after X'07' order issued with ICE flag set.
0403 AIO instruction condition code, status or device address error following A X'07' order raising IP.
0404 HIO instruction did not clear IP in controller.
0405 TIO instruction indicates IP not set by X'07' order with IZC flag set.
0406 TIO instruction condition code or status error after X'07' order with IZC flag set.
0407 AIO instruction condition code, status or device address error after X'07' order with IZC flag set.
0408 AIO or HIO instruction did not reset IP status in controller.
0409 TIO indicates X'00' order with IUE flag set did not set IP in controller.

0410 TIO indicates condition code or status error after X'00' order with IUE flag set.
0411 AIO condition code, status or device address error after X'00' order with IUE flag set.
0412 TIO indicates no UE status for X'00' order.
0413 TIO condition code or status error after AIO or HIO issued with IP status present.
0414 AIO did not reset IP status in controller.

TST1, 5 data transmission complete interrupt (7441, 7446). A test mode order with DTC flag (X'47') is used to verify data transmission complete interrupt generation.

0501 Data transmission complete interrupt not generated.
0502 TIO indicates condition code or status error for X'47' order. Expected IP status.
0503 AIO condition code, status or device address error after DTC interrupt generated in controller. Expected AIO status bit 1 set.

TST1, 6 IO Interrupt (7441, 7446). Test mode orders are issued with ICE, IZC and IUE flags to verify the interrupts are received by the IOP and CPU.

0601 Interrupt not received by CPU.
0602 TIO status error after CPU received interrupt from controller.
0603 AIO condition code, status or device address error after interrupt received by CPU.
0604 TIO indicates HIO did not reset IP in controller.
0605 AIO condition code, status or device address error after interrupt received by CPU.
0606 TIO indicates HIO did not reset IP status in controller.
0607 AIO condition code, status or device address error after interrupt received by CPU.
0608 TIO indicates HIO did not reset IP in controller.

TST1, 7 Command Chaining. (7441, 7446) Two test mode orders are command chained and chaining verified. Invalid order command chained to test mode order is tested for command chain termination after the invalid order.

0701 TIO indicates controller busy beyond normal termination time for command chain operation.
0702 TIO indicates status error during command chaining operation.
0703 TIO indicates operational status error following command chain operation.
0704 Byte count not 0 following command chaining operation.
0705 TIO indicates command chaining terminated with first IOCD instead of second IOCD.
0706 Controller busy with invalid order.
0707 TIO indicates UE not generated for invalid order.
0708 TIO status error following invalid order command chained to test mode order.
0709 Terminal byte count not 0 following an invalid order command chained to test mode order.
0710 Command chaining not terminated by UE of invalid order.

TST1, 11 State Progression – Print order (test mode)(7441, 7446). A print order (X'01') is issued in test mode and TDV instruction used to step the controller through states A, B, A. TDV set 2 verifies the state progression. Print, buffer clearing and paper motion is inhibited.

1101 Test mode selection error. Expected TDV CC1, 2 = 01.
1102 TDV set 2 indicates controller not in quiescent state A.
1103 SIO condition code or status error for print order.

TST1, 11 (Continued)

1104    SIO for print order accepted but TIO status does not indicate device, controller busy.

1105    TIO device and controller status inconsistent. Expected device, controller busy for print order (state progression).

1106    TIO status error during a print order (state progression). Expected controller, device busy.

1107    TDV set 2 inconsistent. Expected controller in state B following a data out (one byte) phase.

1108    TDV set 2 indicates controller did not progress from state A to state B for a print order (one byte transfer).

1109    TDV set 2 inconsistent. Expected state A following a data out phase (one byte) in state B.

1110    TDV set 2 indicates controller did not return to state A following a data out phase (one byte) in state B.

1111    TIO status error following a print order (state progression).

1112    Terminal byte count not 0 indicating data byte not taken while controller in data out state B.

1113    TDV set 2 inconsistent. Expected controller in state A following an order out phase.

1114    TDV set 2 indicates controller not in state A following an order out phase.

TST1, 12 State Progression – Format order (test mode) (7441, 7446). A format order (X'03') is issued in test mode and TDV instructions used to step the controller through states A, D, E, A. TDV set 2 verifies the state progression. Printing, buffer clearing and paper motion is inhibited.

1201    Test mode selection error. Expected TDV CC1, 2 = 01.

1202    TDV set 2 indicates controller not in quiescent state A.

1203    SIO status error for format order.

1204    TDV set 2 indicates controller not in state A following an order out phase.

1205    TDV set 2 indicates control byte (format byte) not received while controller in state D. Expected TDV bit 3, 7 set.

1206    TDV set 2 indicates controller did not progress from state D (data out phase, one byte) to state E (paper motion inhibited).

1207    TDV set 2 inconsistent. Expected state A (order in phase) following state E (paper motion inhibited).

1208    TDV set 2 indicates controller did not progress from state E (paper motion inhibited) to state A (order in phase).

1209    TIO status error following a format order.

1210    TIO indicates controller busy after a format order. Expected controller ready and no paper motion.

1211    Terminal byte count not 0 for a format order indicating controller did not accept format byte while in state D.

1212    TDV set 2 indicates controller did not progress from state A (order out phase) to state D (data out phase, one byte).

TST1, 13 State Progression – Print W format order (test mode) (7441, 7446). A print with format order (X'05') is issued in test mode and TDV instructions used to step the controller through states A, D, E, B, A. TDV set 2 verifies the state progression. Printing, buffer clearing and paper motion is inhibited.

1301    Test mode selection error. Expected TDV CC1, 2 = 01.

1302    TDV set 2 indicates controller not in quiescent state A.

1303    SIO status error for print with format order.

1304    TDV set 2 indicates controller not in state A (order out phase).

1305    TDV set 2 indicates controller did not receive control byte (format byte) while in state D.

1306    TDV set 2 indicates controller did not progress from state D (data out, format byte) to state E (paper motion inhibited).

1307    TDV set 2 indicates controller did not progress from state E to state B (data out, one character).

1308    TDV set 2 indicates controller did not progress from state B (data out, one character) to state A (order in).

1309    TIO status error after print with format order.

1310    Controller busy in state A (order in phase).

1311    Terminal byte count not 0 indicating format byte not accepted in state D.

1312    TDV set 2 indicates controller did not progress from state A (order out) to state D (data out, format byte).

TST1, 15 Print Order (test mode) (7441, 7446). Print orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with from 1 through 133 bytes transferred. Terminal status is verified.

1501    Test mode selection error. Expected TDV CC1, 2 = 01.

1502    SIO status error for print order.

1503    Controller busy after normal termination time for print order with indicated byte count.

1504    TIO status error after print order with indicated byte count.

1505    Controller terminated print order with UE.

1506    IOP error for print order with byte count = 132.

1507    IL status set for print order with byte count = 132.

1508    Operational status error for print order with byte count = 132.

1509    TDV set 1 indicates an IO parity error detected by controller during a print order with X'A5' characters transferred.

1512    Terminal byte count for print order not 0.

1513    IL not set by controller for print order with byte count unequal to 132 bytes.

1514    IOP status error indicated for print order.

1515    Operational status error for print order with byte count unequal to 132.

TST1, 16 Print With Format Order (test mode) (7441, 7446). Print with format orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with from 1 through 133 bytes transferred. Terminal status is verified.

1601    Test mode selection error. Expected TDV CC1, 2 = 01.

1602    SIO status error for print with format order.

1603    Controller busy beyond normal termination time for print with format order.

1604    TIO status error after print with format order with indicated byte count.

1605    Controller terminated print with format order with UE.

1606    IOP error after print with format order with byte count = 132.

1607    Operational status error after print with format order with byte count = 133.

1609    TDV set 1 indicates controller detected a buffer parity error for a print with format order with X'A5' bytes transferred.

1610    TDV set 1 indicates controller detected an IO parity error for a print with format order with X'A5' bytes transferred.

1611    IL not set by controller for a print with format order with byte count unequal to 133.

1612    IOP status error for print with format order.

1613    Operational status error for print with format order.

1614    Terminal byte count not 0 for a print with format order.

TST1, 17 Format Order (test mode) (7441, 7446). Format orders are issued in test mode (paper motion inhibit) with byte counts of 1 through 10. Terminal status is verified.

1701    Test mode selection error. Expected TDV CC1, 2 = 01.

1702    SIO status error for format order.

1703    Controller busy beyond normal termination time for format order.

1704    TIO indicates status error for format order with byte count > 1.

1705    TIO indicates UE not received for format order with byte count > 1.

1706    IOP error for format order.

1707    Operational status error for format order with byte count = 1.

1708    IL status set by controller for format order with byte count = 1.

1709    TDV set 1 indicates IO parity error detected for format order with X'C1' byte.

1710    TDV set 1 indicates buffer parity error for format order.

1711    IL status not set by controller for format order with byte count greater than one.

1712    IOP status error for format order with byte count greater than one.

1713    Operational status error for format order with byte count greater than one.

1714    Controller accepted more than one byte for a format order with byte count greater than one.

1715    TIO status error after format order with byte count = 1. Controller ready and no UE expected.

TST1, 20 Address Counter – Print order (test mode) (7441, 7446). Print orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with byte counts of 1 through 132. TDV set 5 verifies the incrementing of the character buffer address counter.

2001 Test mode selection error. Expected TDV CC1, 2 = 01.
2002 Status error after print order with byte count = 132.
2003 TDV set 5 indicates address counter is not incrementing. See printout.
2004 TDV set 5 indicates address counter is not incrementing correctly for a print order. See printout.

TST1, 21 Address Counter – Print with format order (test mode) (7441, 7446). Print with format orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with byte counts of 1 through 133. TDV set 5 verifies the incrementing of the character buffer address counter.

2101 Test mode selection error. Expected TDV CC1, 2 = 01.
2102 Status error for print with format order.
2103 TDV set 5 indicates address counter not incrementing for a print with format order.
2104 TDV set 5 indicates address counter not incrementing correctly for a print with format order. See printout.

TST1, 22 Address Counter – Format order (test mode) (7441, 7446). Format orders are issued in test mode (paper motion inhibited) with byte counts of 1 through 10. TDV set 5 verifies that the character buffer address counter does not increment during the format order.

2201 Test mode selection error. Expected TDV CC1, 2 = 01.
2203 Status error for format order.
2204 TDV set 5 indicates address counter not at X'00' configuration after a format order.
2205 Status error for format order with byte count >1.

TST1, 23 Sense Character Buffer Order (test mode) (7441, 7446). Sense character buffer orders are issued in test mode with byte counts of 1 through 132. Terminal status is tested and all sense bytes (character buffer contents) are verified to be X'00'.

2301 Test mode selection error. Expected TDV CC1, 2 = 01.
2302 SIO status error for sense order.
2303 Controller busy beyond normal termination time for a sense character buffer order.
2304 TIO status indicates controller terminated sense character buffer order with UE.
2305 TIO status error for sense character buffer order.
2306 IOP error for sense character buffer order.
2307 IL status set for sense character buffer order.
2308 Operational status error for sense character buffer order.
2309 Terminal byte count for sense character buffer not = 0.
2310 Sensed character buffer bytes not all X'00'. See printout.

TST1, 24 Character Buffer – Data (test mode) (7441, 7446). Print orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with byte counts of 132 and data bytes of X'00' through X'FF'. Sense character buffer orders are used to verify the contents of the character buffer (character bits 2-7 only).

2401 Test mode selection error. Expected TDV CC1, 2 = 01.
2402 Status error for print order with byte count = 132.
2403 Status error for sense character buffer order with byte count of 132.
2404 Character buffer contents incorrect. See printout.

TST1, 25 Character Buffer – Parity (test mode) (7441, 7446). Print orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with byte counts of 132 and data bytes of X'00' thru X'FF'. Sense character buffer orders are used to verify the contents of the character buffer including odd parity.

2501 Test mode selection error. Expected TDV CC1, 2 = 01.
2502 Status error for print order with byte count = 132.
2503 Status error for sense character buffer order with byte count of 132.
2504 Character buffer parity failure. See printout.

TST1, 26 Character Buffer – Byte Positioning (test mode) (7441, 7446). Print orders are issued in test mode (buffer clearing, printing and paper movement inhibited) with byte counts of 132. Each data pattern of X'40' (blank) characters contains one X'FF' character sequentially, then randomly placed in the pattern. Sense character buffer orders are used to verify character buffer contents.

2601 Test mode selection error. Expected TDV CC1, 2 = 01.
2602 Status error for print order with byte count = 132.
2603 Status error for sense character buffer order with byte count of 132.
2604 Character buffer failure in character positioning. See printout.

TST1, 27 Character Buffer – Blanks (test mode) (7441, 7446). A print order is issued in test mode (buffer clearing, printing and paper motion inhibited) with byte count of 132 and data pattern of X'40' characters. A sense character buffer order is used to verify the character buffer contains X'00' bytes.

2701 Test mode selection error. Expected TDV CC1, 2 = 01.
2702 Status error for print order with byte count of 132.
2703 Status error for sense character buffer order with byte count of 132.
2704 Character buffer contents not X'00'. See printout.

TST1, 31 Format Register – Format Order (test mode) (7441, 7446). Format orders are issued in test mode (paper motion inhibited) with format bytes of X'00' thru X'FF'. TDV set 3 is used to verify the format register and paper motion control values.

3101 Test mode selection error. Expected TDV CC1, 2 = 01.
3102 SIO status error for format order.
3103 Status error for format order with byte count = 1.
3104 TDV set 3 indicates format register contents and/or paper motion control signals incorrect. See printout.
3105 TIO status error after format order with byte count = 2.
3106 TDV set 3 indicates format register contents disturbed by the format byte.
3107 Terminal byte count for a format order (byte count = 2) not = 1.

TST1, 32 Format Register – Print with format order (test mode) (7441, 7446). Print with format orders are issued in test mode (buffer clearing, printing and paper motion inhibited) with byte counts of 1 through 133. Random format bytes are used and TDV set 3 is used to verify the format register contents.

3201 Test mode selection error. Expected TDV CC1, 2 = 01.
3202 SIO status error for print with format order.
3203 Status error for print with format order with byte count = 133.
3204 Status error for print with format order with byte count unequal to 133.
3205 TDV set 3 indicates format register and/or paper control signals incorrect. See printout.

TST1, 35 Code Disk – Sense Order (test mode) (7441, 7446). Code disk sense orders are issued in test mode to transfer from 1 to 129 bytes of code disk information. Terminal status is tested.

TST1, 35 (Continued)

3501   Test mode selection error. Expected TDV CC1, 2 = 01.
3502   SIO status error for sense code disk order X'04'.
3504   TIO indicates controller busy beyond normal termination time for sense code disk order.
3505   Status error for code disk sense order.
3506   TDV set 1 indicates parity error during code disk sense order.

TST1, 36 Code Disk – Data and Parity (test mode) (7441, 7446). A sense code order is issued in test mode to transfer 128 bytes (two code images). Code disk images (including parity) are verified.

3601   Test mode selection error. Expected TDV CC1, 2 = 01.
3602   Status error for code disk sense order.
3603   Code disk images not correct. See printout.

TST1, 37 Code Disk Timing (test mode) (7441, 7446). A sense order is issued in test mode and the transfer time between bytes (initiated by code disk clocks) is verified.

3701   Test mode selection error. Expected TDV CC1, 2 = 01.
3702   Time between code disk clocks has exceeded the nominal 850 μs.

TST1, 40 State Progression – Comparator (test mode) (7441, 7446). A print order is issued (printing and paper motion inhibited) and TDV instruction used to step the controller through states A, B, C, A. TDV set 2 verifies the states and comparator scanning completion.

4001   Test mode selection error. Expected TDV CC1, 2 = 01.
4002   TDV set 2 indicates controller not in state A after order out.
4003   TDV set 2 indicates controller not in state B (data out, 132 bytes) after state A.
4004   TDV set 2 indicates print complete (pseudo indication for test mode) not set for state C (character buffer scanning state).
4005   TDV set 2 indicates controller did not progress from state C (character buffer scan) to state E (paper motion inhibited).
4006   Status error after print order with character buffer scan.
4007   TDV set 2 indicates character buffer scanning was not completed in state C 'blank' characters transferred to character buffer.
4008   TDV set 2 indicates controller did not progress from state B (data out, 132 bytes) to state C (character buffer scan).
4009   TDV set 2 indicates controller did not progress from state E to state A (order in phase).
4010   TDV set 1 indicates status error after print order with character buffer scan.

TST1, 41 Comparator – Character Buffer Clearing (test mode) (7441, 7446). A series of 64 print orders are issued and all 64 printable characters are transferred. Sense character buffer orders are used to verify the comparator for all characters.

4101   Test mode selection error. Expected TDV CC1, 2 = 01.
4102   TIO indicates controller busy for print order with byte count of 132.
4103   TDV set 1 indicates a buffer parity error during character buffer scanning.
4104   Status error for print order with byte count = 132.
4105   Status error for sense character buffer order.
4106   Character buffer not cleared by comparator scanning. See printout.

TST1, 42 State Progression – Format Order/Paper Motion (test mode) (7441, 7446). A format order is issued in test mode and TDV set 4 is used to verify the paper movement control signals for a format byte (X'C1' to X'CF' for 7441 and X'C1' to X'C5' for 7446).

4201   Test mode selection error. Expected TDV CC1, 2 = 01.
4202   TDV set 1 indicates status error after format order with paper motion completion.

4203–4211   TDV set 4 indicates paper motion control error. See printout.

TST1, 43 State Progression – Print Order/Paper Motion (test mode) (7441, 7446). A print order is issued in test mode and TDV instruction used to step the controller through states A, B, C, E, A. TDV set 2 verifies the progression and terminal status and character buffer contents are verified.

4301   TDV set 1 indicates paper low, interlock or hammer driver supply low for 7441. TDV set 1 indicates TDV status error for 7446.
4302   Test mode selection error. Expected TDV CC1, 2 = 01.
4303   TDV set 2 indicates controller not in state A after order out.
4304   TDV set 2 indicates controller did not progress from state A (order out) to state B (data out, 132 bytes).
4305   TDV set 2 indicates controller did not progress from state B to state C (character buffer scan).
4306   TDV set 2 indicates character buffer scan not completed in state C.
4307   TDV set 2 indicates sentinel monitor signal not set in state C.
4308   TDV set 2 indicates control byte received signal in error in state C.
4309   TDV set 2 indicates controller did not progress from state C to state E (paper motion).
4310   Test mode selection error. Expected TDV CC1, 2 = 01.
4311   TDV set 1 indicates interlock error for print order for 7441.
4312   Status error for print order with byte count = 132.
4313   Character buffer not cleared while controller in state E. See printout.
4314   TDV set 1 indicates paper motion/printing error after print order.
4315   TDV set 1 indicates error after sense character buffer order.

TST1, 44 State Progression – Print with format order (test mode) (7441, 7446). A print with format order is issued in test mode and TDV instruction used to step the controller through states A, D, E, B, C, E, A. TDV set 2 verifies the progression.

4401   Test mode selection error. Expected TDV CC1, 2 = 01.
4402   TDV set 2 indicates controller not in state A after order out.
4403   TDV set 2 indicates controller did not progress from state A to state D (data out, format byte).
4404   TDV set 2 indicates controller did not progress from state D to state E (paper motion).
4405   TDV set 2 indicates controller did not progress from state E to state B (data out, 132 bytes).
4406   TDV set 2 indicates controller did not progress from state B to state C (character buffer scan, print).
4407   TDV set 2 indicates controller did not progress from state C to state E (paper motion) or print error occurred.
4408   Status error for print with format order.
4409   Test mode selection error. Expected TDV CC1, 2 = 01.
4410   TDV set 4 indicates paper motion control signal error after paper motion.
4411   TDV set 1 indicates status error after print with format order.
4412   Status error for print with format (no data chain).
4413   TDV set 2 indicates controller did not progress from state E to state A (data chain).
4414   TDV set 2 indicates controller did not progress from state E to state A (no data chain).

TST1, 45 State Progression – Format Order/Paper Motion (high speed slew) (7446). A format order is issued in test mode and TDV set 4 is used to verify the paper movement control signals for a X'C6' to X'CF' format byte.

4501   Test mode selection error. Expected TDV CC1, 2 = 01.
4502   TDV set 1 indicates status error after format order with paper motion completion.
4503–4510   TDV set 4 indicates paper motion control error. See printout.

TST1, 46 Paper Clamp – Print Order/Paper Motion (test mode) (7446). A print order is issued in test mode and TDV instruction used to step the controller through states A, B, C, E, A. TDV set 4 verifies the paper clamp timing.

4601   Test mode selection error. Expected TDV CC1, 2 = 01.
4602-4605   TDV set 4 indicates paper clamp control error (see printout).

TST1, 47 Print Order – Automatic Upspacing (7441, 7446). A print order is issued to print a pattern of 'E' characters. Terminal status is verified.

4701   Status error for print order.
4702   Test mode selection error. Expected TDV CC1, 2 = 01.
4703   TDV set 2 indicates print control error for print order.
4704   TDV set 1 indicates print error for print order (7446).
4705   TDV set 4 indicates print control error for print order.

TST1, 48 Print with Format Order – Inhibit Upspace (7441, 7446). A print with format order is issued to perform a print operation with inhibit upspace format. Terminal status and character buffer verified.

4801   Controller busy beyond normal termination time for print with format order (upspace inhibited).
4802   Status error for print with format order (upspace inhibited).
4803   Test mode selection error. Expected TDV CC1, 2 = 01.
4804   Character buffer not cleared for print with inhibit upspace order.
4805   TDV set 1 indicates status error for print with inhibit upspace.

TST1, 49 Format Order – Space Lines (7441, 7446). A format order (X'C1' to X'CF' byte) is issued and terminal status verified.

4901   Status error for format order.
4902   Test mode selection error. Expected TDV CC1, 2 = 01.
4903   TDV set 4 indicates paper motion control signal error for format order.
4904   TDV set 3 indicates format register error after format order.
4905   TDV set 1 indicates status error for format order.

TST1, 50 Print N Format (7441, 7446). A print with format order is issued to space 2 lines and print line of 'E' characters. Terminal status is verified.

5001   Status error for print with format order.
5002   Test mode selection error. Expected TDV CC1, 2 = 01.
5003   TDV set 4 indicates paper motion control error for print with format order.

TST1, 52 Print Blanks (7441, 7446). A print order is issued to print one line of blanks. Terminal status is tested.

5201   Status error for print blanks.
5202   Test mode selection error. Expected TDV CC1, 2 = 01.
5203   TDV set 2 indicates print control error for print blank line.
5204   TDV set 3 indicates format control error for print blank line.
5205   TDV set 4 indicates paper motion control error for print blank line.
5206   TDV set 5 indicates address counter not at correct terminal state.

TST1, 53 Print Continuous (7441, 7446). A series of 10 lines of 'E' characters are printed. Terminal status is tested.

5301   Status error for print 'E' character lines.
5304   Test mode selection error. Expected TDV CC1, 2 = 01.
5305   TDV set 2 indicates print control error.
5306   TDV set 4 indicates paper motion control error.
5307   TDV set 3 indicates format control error.

TST1, 54 Print Broadside Pattern (7441, 7446). A broadside pattern of all characters are printed. Terminal status is tested.

5401   Status error for broadside line.

TST1, 55 Error Induction/Reporting (7446). Using a print order and test mode to: (1) force print echo error, (2) force buffer parity error, (3) force IO parity error, (4) force code disk parity error. Each time verify that induced error is reported correctly.

5501   Test mode selection error. Expected TDV CC1, 2 = 01.
5502   TDV set 1 indicates no print error reported.
5503   TDV set 1 indicates no buffer parity error reported.
5504   TDV set 1 indicates no IO parity error reported.
5505   TDV set 1 indicates no code disk parity error reported.
5506   TIO status indicates no unusual end reported.

TST1, 56 IO Parity Induction/Reporting (7446). The following orders are issued: 128 X'01', X'03', X'05', and X'01' in order to test for the correct error reporting of data parity and order out for 5/7 and 8/9 computer.

5601   Test mode selection error, expected TDV CC1, 2 = 01.
5602   TDV set 1 indicates incorrect report of data parity error.
5603   TDV set 1 indicates incorrect report of parity error. (Sigma 8/9 order out) (Sigma 5/7 data parity).
5605   TIO indicates incorrect byte count.

TST1, 58 Invalid Character Test (7442 only). Print two lines of invalid characters then two lines of mixed valid and invalid characters. After a long delay for each print, printer should still be busy. No printing occurs for invalid characters.

5801   Line printer not busy after printing invalid character.

TST1, 60 Format Order – Inhibit Upspace (7440/7445, 7450). A format order of a byte count of one, then a byte count of two is issued. Terminal status is verified and that no paper motion has occurred.

6001   SIO status error for format order.
6002   Device, controller busy beyond normal termination time for format order.
6003   Paper motion occurred for a format with inhibit upspace.
6004   Status error for format order.
6005   Byte count did not decrement after format order.

TST1, 61 Interrupt Generation and HIO, AIO Instruction Resetting (7450, 7440/7445). The following orders are issued: X'07', X'07', and X'00' in order to test the generation of ICE, IZC, and IUE. AIO and HIO instructions are issued to test the interrupt clearing.

6101   TIO instruction indicates IP status not present after X'07' order with ICE flag set.
6102   TIO instruction condition code or status error after X'07' order issued with ICE flag set.
6103   AIO instruction condition code, status or device address error following a X'07' order raising IP.
6104   HIO instruction did not clear IP in controller.
6105   TIO instruction indicates IP not set by X'07' order with IZC flag set.
6106   TIO instruction condition code or status error after X'07' order with IZC flag set.
6107   AIO instruction condition code, status or device address error after X'07' order with IZC flag set.
6108   AIO or HIO instruction did not reset IP status in controller.
6109   TIO indicates X'00' order with IUE flag set did not set IP in controller.
6110   TIO indicates condition code or status error after X'00' order with IUE flag set.
6111   AIO condition code, status or device address error after X'00' order with IUE flag set.
6112   TIO indicates no UE status for X'00' order.
6113   TIO condition code or status error after AIO or HIO issued with IP status present.
6114   AIO did not reset IP status in controller.

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TST1, 62 IO Interrupt Generation (7440/7445, 7450). A format with ICE flag is issued. Verify that the program is interrupted when the IO interrupt is armed and enabled.

6201    TIO instruction indicates IP not set by SIO, IO interrupt is disarmed.

6202    Program was interrupted while IO interrupt was disarmed.

6203    Program was not interrupted while IO interrupt was armed/enabled.

6204    TIO indicates IP not cleared by an AIO instruction.

TST1, 63 Print with Format – Inhibit Upspace (blank characters) (7440/7445). A print with format order is issued to perform a print operation with inhibit upspace format. Terminal status and no paper motion is verified. Bytes of 2 through 134 are transferred.

6301    Paper motion has occurred for a print with format order.

6302    Byte count not equal to zero after a print with format order.

6303    IL not set for byte count unequal to 132.

6304    IL set for byte count equal to 132.

6305    Status error for print with format.

6306    SIO status error for print with format.

TST1, 64 Print with Format – Inhibit Upspace (blank characters) (7450). First then second print with format order are issued. Printer expects first then second print order is verified. Byte 2 through 129 are transferred. Terminal status and no paper motion is verified.

6401    Paper motion has occurred for a first print with format order.

6402    Paper motion has occurred for a second print with format order.

6403    Byte count not equal to zero after a first print with format order.

6404    Byte count not equal to zero after a second print with format order.

6405    Status error for first print with format order.

6406    Status error for second print with format order.

6407    SIO status error for first print with format order.

6408    SIO status error for second print with format order.

6409    Expect first print order TDV bit not set for first print order.

6410    Expect first print order TDV bit set for second print order.

6411    Typeline sector error (should always be one).

TST1, 65 Data Transmission Complete (DTC) Interrupt (7440/7445, 7450). Using print with format and interrupt on data transmission complete, verify data transmission complete interrupt is generated.

6501    Data transmission complete interrupt not generated.

6502    TIO indicates condition code or status error for X'45' order. Expected IP status.

6503    AIO condition code, status or device address error after DTC interrupt generated in controller expected AIO status bit 1 set.

6504    Print fault – see printout.

TST1, 66 Command Chaining (7440/7445, 7450) (Sigma 5/7). Using the invalid order, verify the command chaining operation; verify that the UE status terminates the command chaining.

6601    TIO indicates controller busy beyond normal termination time for command chain operation.

6602    TIO indicates status error during command chaining operation.

6603    TIO indicates operational status error following command chain operation.

6604    Byte count not 0 following command chaining operation.

6605    TIO indicates command chaining terminated with first IOCD instead of second IOCD.

6606    Controller busy with invalid order.

6607    TIO indicates UE not generated for invalid order.

6608    TIO status error following invalid order command chained.

6609    Terminal byte count zero following an invalid order command chained.

6610    Command chaining not terminated by UE of invalid order.

6611    SIO status error for invalid order command chained.

6612    SIO status error for command chained.

TST1, 68 Format – Space One Line (7440/7445, 7450). A format order is issued to space one line. Verify that paper motion and no print operation occurs.

6801    Status error for format order.

6802    No paper motion for space one line format order.

TST1, 69 Print with Auto Upspace (7440/7445, 7450). Six print orders are issued to verify each code disk character. Verify that paper motion and no print error occurs.

6901–6906 Status error for a print order.

6907    Paper motion for print with auto upspace.

TST1, 70 Print Broadside Pattern (7440/7445, 7450). A broadside pattern of all characters are printed. Terminal status is tested.

7001    Status error for broadside line.

TST1, 71 Print – Sliding One Column Pattern (7440/7445, 7450). Print with auto upspace is issued with incrementing byte counts of a sliding 1 column pattern. Verify that no print errors occur.

7101    Status error for a print order.

TST1, 73 Pattern and Format Test (7440/7445, 7450). Run a selected set of utility tests in sequence. Verify that no print error or paper fault occur.

7301    Status error for hammer registration.

7302    Status error for checkerboard pattern.

7303    Status error for ripple test pattern.

7304    Status error for printer speed test.

7305    Status error for skip line test.

7306    Status error for channel search test.

TEST/DEVICE REFERENCE TABLE

|  | Subtest | Model Number 7440/7445 3451 | 7441 7442 | 7446 | 7450 | Not Used |
|---|---|---|---|---|---|---|
| TST1 | 1 | X | X | X | X |  |
|  | 2 | X | X | X | X |  |
|  | 3 |  | X | X |  |  |
|  | 4 |  | X | X |  |  |
|  | 5 |  | X | X |  |  |
|  | 6 |  | X | X |  |  |
|  | 7 |  | X | X |  |  |
|  | 8 |  |  |  |  | X |
|  | 9 |  |  |  |  | X |
|  | 10 |  |  |  |  | X |
|  | 11 |  | X | X |  |  |
|  | 12 |  | X | X |  |  |
|  | 13 |  | X | X |  |  |
|  | 14 |  |  |  |  | X |
|  | 15 |  | X | X |  |  |
|  | 16 |  | X | X |  |  |
|  | 17 |  | X | X |  |  |
|  | 18 |  |  |  |  | X |
|  | 19 |  |  |  |  | X |
|  | 20 |  | X | X |  |  |
|  | 21 |  | X | X |  |  |
|  | 22 |  | X | X |  |  |
|  | 23 |  | X | X |  |  |
|  | 24 |  | X | X |  |  |
|  | 25 |  | X | X |  |  |
|  | 26 |  | X | X |  |  |
|  | 27 |  | X | X |  |  |
|  | 28 |  |  |  |  | X |
|  | 29 |  |  |  |  | X |
|  | 30 |  |  |  |  | X |
|  | 31 |  | X | X |  |  |
|  | 32 |  | X | X |  |  |
|  | 33 |  |  |  |  | X |
|  | 34 |  |  |  |  | X |
|  | 35 |  | X | X |  |  |
|  | 36 |  | X | X |  |  |
|  | 37 |  | X | X |  |  |
|  | 38 |  |  |  |  | X |
|  | 39 |  |  |  |  | X |
|  | 40 |  | X | X |  |  |
|  | 41 |  | X | X |  |  |
|  | 42 |  | X | X |  |  |
|  | 43 |  | X | X |  |  |
|  | 44 |  | X | X |  |  |
|  | 45 |  |  | X |  |  |
|  | 46 |  |  | X |  |  |
|  | 47 |  | X | X |  |  |
|  | 48 |  | X | X |  |  |
|  | 49 |  | X | X |  |  |
|  | 50 |  | X | X |  |  |
|  | 51 |  |  |  |  | X |
|  | 52 |  | X | X |  |  |
|  | 53 |  | X | X |  |  |
|  | 54 |  | X | X |  |  |
|  | 55 |  |  | X |  |  |
|  | 56 |  |  | X |  |  |
|  | 57 |  |  |  |  | X |
|  | 58 |  |  |  |  | X |
|  | 59 |  |  |  |  | X |
|  | 60 | X |  |  | X |  |
|  | 61 | X |  |  | X |  |
|  | 62 | X |  |  | X |  |
|  | 63 | X |  |  |  |  |
|  | 64 |  |  |  | X |  |
|  | 65 | X |  |  | X |  |
|  | 66 | X |  |  | X |  |
|  | 67 |  |  |  |  | X |
|  | 68 | X |  |  | X |  |
|  | 69 | X |  |  | X |  |
|  | 70 | X |  |  | X |  |
|  | 71 | X |  |  | X |  |
|  | 72 |  |  |  |  | X |
|  | 73 | X |  |  | X |  |

|  | Subtest | Model Number 7440/7445 3451 | 7441 7442 | 7446 | 7450 | Not Used |
|---|---|---|---|---|---|---|
| TST2 |  | X | X | X | X |  |

| TST3 | D1 X | 7440/7445 3451 | 7441 7442 | 7446 | 7450 |  |
|---|---|---|---|---|---|---|
|  | 1 | X | X | X | X |  |
|  | 2 | X | X | X | X |  |
|  | 3 | X | X | X | X |  |
|  | 4 | X | X | X | X |  |
|  | 5 | X | X | X | X |  |
|  | 6 | X | X | X | X |  |
|  | 7 | X | X | X | X |  |
|  | 8 | X | X | X | X |  |
|  | 9 | X | X | X | X |  |

FUNCTIONAL TEST (TST1) (SS1 = 0, SS3 = 1)
INITIALIZING CONDITIONS AND EXPECTED RESULTS

1. Initializing Conditions: None
2. Expected Results:

|  | Subtest | Results |
|---|---|---|
| Models 7441, 7442 and 7446 | 42 | Space 1 to 15 lines in sequence (7441 only) / Space 1 to 5 lines in sequence (7446 only) |
|  | 43 | Print 1 line broadside character 'E' |
|  | 44 | Space 1 line and print 1 line broadside character 'E' |
|  | 45 | Space 6 to 15 lines in sequence |
|  | 47 | Print 15 lines of blank characters / Print 132 lines of sliding one column pattern of character 'E' / Print 30 lines of one character 'E' random positioning / Print 10 lines broadside character 'E' / Print 30 lines random column, random number of columns |
|  | 48 | Print with inhibit upspace |
|  | 49 | Space 1 to 15 lines in sequence |
|  | 50 | Space 2 lines and print 1 line broadside character 'E' |
|  | 52 | Print 1 line of blank characters |
|  | 53 | Print 10 lines broadside character 'E' |
|  | 54 | Print 64 lines broadside pattern of all printable characters |
| Model 7440/7445 7450 and 3451 | 68 | Space 1 line |
|  | 69 | Print 1 character per line: characters A, B, D, H &, – |
|  | 70 | Print 64 lines broadside pattern of all printable characters |
|  | 71 | Print 132 sliding one column pattern |
|  | 73 | Print 32 lines broadside character 'E' / Print 32 lines of alternating blank and character 'E' / Print 132 lines of ripple test pattern / Print 36 lines of printer speed test / Print 263 lines of printer load test pattern / Space 1 to 7 lines in sequence (7450 only) / Space 1 to 15 lines in sequence (7440/7445 only) / Skip to top and bottom of page (7450 only) / Skip to all 7 channels in sequence (7440/7445 only) |

HAMMER DRIVER MODULE LOCATION CHART

| COLUMN NUMBER | MODULE LOCATION | | | |
|---|---|---|---|---|
| | 7440/7445 3451 | 7441/7442 See note 1 | 7446 See note 2 | 7450 |
| 1 | 25G | 13HJ | 12HJ | 13HJ |
| 2 | 25G | 13HJ | 12HJ | 13HJ |
| 3 | 25G | 13HJ | 12HJ | 13HJ |
| 4 | 24G | 13HJ | 12HJ | 13HJ |
| 5 | 24G | 13HJ | 12HJ | 13HJ |
| 6 | 24G | 13HJ | 12HJ | 13HJ |
| 7 | 23G | 13HJ | 12HJ | 13HJ |
| 8 | 23G | 13HJ | 12HJ | 13HJ |
| 9 | 23G | 12HJ | 11HJ | 13HJ |
| 10 | 22G | 12HJ | 11HJ | 12HJ |
| 11 | 22G | 12HJ | 11HJ | 12HJ |
| 12 | 22G | 12HJ | 11HJ | 12HJ |
| 13 | 21G | 12HJ | 11HJ | 12HJ |
| 14 | 21G | 12HJ | 11HJ | 12HJ |
| 15 | 21G | 12HJ | 11HJ | 12HJ |
| 16 | 20G | 12HJ | 11HJ | 12HJ |
| 17 | 20G | 13HJ | 10HJ | 12HJ |
| 18 | 20G | 12HJ | 10HJ | 12HJ |
| 19 | 19G | 13HJ | 10HJ | 12HJ |
| 20 | 19G | 12HJ | 10HJ | 12HJ |
| 21 | 19G | 12HJ | 10HJ | 13HJ |
| 22 | 18G | 13HJ | 10HJ | 13HJ |
| 23 | 18G | 12HJ | 10HJ | 13HJ |
| 24 | 18G | 13HJ | 10HJ | 13HJ |
| 25 | 17G | 11HJ | 9HJ | 11HJ |
| 26 | 17G | 11HJ | 9HJ | 11HJ |
| 27 | 17G | 11HJ | 9HJ | 11HJ |
| 28 | 16G | 11HJ | 9HJ | 11HJ |
| 29 | 16G | 11HJ | 9HJ | 11HJ |
| 30 | 16G | 11HJ | 9HJ | 11HJ |
| 31 | 15G | 11HJ | 9HJ | 11HJ |
| 32 | 15G | 11HJ | 9HJ | 11HJ |
| 33 | 15G | 10HJ | 8HJ | 10HJ |
| 34 | 14G | 10HJ | 8HJ | 10HJ |
| 35 | 14G | 10HJ | 8HJ | 10HJ |
| 36 | 14G | 10HJ | 8HJ | 10HJ |
| 37 | 13G | 10HJ | 8HJ | 10HJ |
| 38 | 13G | 10HJ | 8HJ | 10HJ |
| 39 | 13G | 10HJ | 8HJ | 10HJ |
| 40 | 12G | 10HJ | 8HJ | 10HJ |
| 41 | 12G | 11HJ | 6HJ | 10HJ |
| 42 | 12G | 10HJ | 6HJ | 10HJ |
| 43 | 11G | 11HJ | 6HJ | 10HJ |
| 44 | 11G | 10HJ | 6HJ | 10HJ |
| 45 | 11G | 10HJ | 6HJ | 11HJ |
| 46 | 10G | 11HJ | 6HJ | 11HJ |
| 47 | 10G | 10HJ | 6HJ | 11HJ |
| 48 | 10G | 11HJ | 6HJ | 11HJ |
| 49 | 9G | 9HJ | 5HJ | 9HJ |
| 50 | 9G | 9HJ | 5HJ | 9HJ |
| 51 | 9G | 9HJ | 5HJ | 9HJ |
| 52 | 8G | 9HJ | 5HJ | 9HJ |
| 53 | 8G | 9HJ | 5HJ | 9HJ |
| 54 | 8G | 9HJ | 5HJ | 9HJ |
| 55 | 7G | 9HJ | 5HJ | 9HJ |
| 56 | 7G | 9HJ | 5HJ | 9HJ |
| 57 | 7G | 8HJ | 4HJ | 8HJ |
| 58 | 6G | 8HJ | 4HJ | 8HJ |
| 59 | 6G | 8HJ | 4HJ | 8HJ |
| 60 | 6G | 8HJ | 4HJ | 8HJ |
| 61 | 5G | 8HJ | 4HJ | 8HJ |
| 62 | 5G | 8HJ | 4HJ | 8HJ |
| 63 | 5G | 8HJ | 4HJ | 8HJ |
| 64 | 4G | 8HJ | 4HJ | 8HJ |
| 65 | 4G | 9HJ | 3HJ | 8HJ |
| 66 | 4G | 8HJ | 3HJ | 8HJ |
| 67 | 3G | 9HJ | 3HJ | 8HJ |
| 68 | 3G | 8HJ | 3HJ | 8HJ |
| 69 | 3G | 8HJ | 3HJ | 9HJ |
| 70 | 2G | 9HJ | 3HJ | 9HJ |
| 71 | 2G | 8HJ | 3HJ | 9HJ |
| 72 | 2G | 9HJ | 3HJ | 9HJ |
| 73 | 1G | 7HJ | 12HJ | 7HJ |
| 74 | 1G | 7HJ | 13HJ | 7HJ |
| 75 | 1G | 7HJ | 13HJ | 7HJ |
| 76 | 1F | 7HJ | 13HJ | 7HJ |
| 77 | 1F | 7HJ | 13HJ | 7HJ |
| 78 | 1F | 7HJ | 13HJ | 7HJ |
| 79 | 2F | 7HJ | 13HJ | 7HJ |
| 80 | 2F | 7HJ | 13HJ | 7HJ |
| 81 | 2F | 6HJ | 12HJ | 6HJ |
| 82 | 3F | 6HJ | 12HJ | 6HJ |
| 83 | 3F | 6HJ | 12HJ | 6HJ |
| 84 | 3F | 6HJ | 12HJ | 6HJ |
| 85 | 4F | 6HJ | 13HJ | 6HJ |
| 86 | 4F | 6HJ | 13HJ | 6HJ |
| 87 | 4F | 6HJ | 13HJ | 6HJ |
| 88 | 5F | 6HJ | 13HJ | 6HJ |
| 89 | 5F | 7HJ | 10HJ | 6HJ |
| 90 | 5F | 6HJ | 10HJ | 6HJ |
| 91 | 6F | 7HJ | 10HJ | 6HJ |
| 92 | 6F | 6HJ | 10HJ | 6HJ |
| 93 | 6F | 6HJ | 11HJ | 7HJ |
| 94 | 7F | 7HJ | 11HJ | 7HJ |
| 95 | 7F | 6HJ | 11HJ | 7HJ |
| 96 | 7F | 7HJ | 11HJ | 7HJ |
| 97 | 8F | 5HJ | 8HJ | 5HJ |
| 98 | 8F | 5HJ | 8HJ | 5HJ |
| 99 | 8F | 5HJ | 8HJ | 5HJ |
| 100 | 9F | 5HJ | 8HJ | 5HJ |
| 101 | 9F | 5HJ | 9HJ | 5HJ |
| 102 | 9F | 5HJ | 9HJ | 5HJ |
| 103 | 10F | 5HJ | 9HJ | 5HJ |
| 104 | 10F | 5HJ | 9HJ | 5HJ |
| 105 | 10F | 4HJ | 7HJ | 4HJ |
| 106 | 11F | 4HJ | 7HJ | 4HJ |
| 107 | 11F | 4HJ | 7HJ | 4HJ |
| 108 | 11F | 4HJ | 7HJ | 4HJ |
| 109 | 12F | 4HJ | 7HJ | 4HJ |
| 110 | 12F | 4HJ | 7HJ | 4HJ |
| 111 | 12F | 4HJ | 7HJ | 4HJ |
| 112 | 13F | 4HJ | 7HJ | 4HJ |
| 113 | 13F | 5HJ | 6HJ | 4HJ |
| 114 | 13F | 4HJ | 6HJ | 4HJ |
| 115 | 14F | 5HJ | 6HJ | 4HJ |
| 116 | 14F | 4HJ | 6HJ | 4HJ |
| 117 | 14F | 4HJ | 7HJ | 5HJ |
| 118 | 15F | 5HJ | 7HJ | 5HJ |
| 119 | 15F | 4HJ | 7HJ | 5HJ |
| 120 | 15F | 5HJ | 7HJ | 5HJ |
| 121 | 16F | 3HJ | 4HJ | 3HJ |
| 122 | 16F | 3HJ | 4HJ | 3HJ |
| 123 | 16F | 3HJ | 4HJ | 3HJ |
| 124 | 17F | 3HJ | 4HJ | 3HJ |
| 125 | 17F | 3HJ | 5HJ | 3HJ |
| 126 | 17F | 3HJ | 5HJ | 3HJ |
| 127 | 18F | 3HJ | 5HJ | 3HJ |
| 128 | 18F | 3HJ | 5HJ | 3HJ |
| 129 | 18F | 3HJ | 3HJ | |
| 130 | 19F | 3HJ | 3HJ | |
| 131 | 19F | 3HJ | 3HJ | |
| 132 | 19F | 3HJ | 3HJ | |

Notes:

1. In 7441/7442 printers, the front hammer driver chassis is for the odd-numbered columns; the rear for the even.
2. In 7446 printers, the front hammer driver chassis is for the even-numbered columns; the rear for the odd.

# Section 13

# SIGMA 5 - 9

# LINE PRINTER DIAGNOSTIC (746X)

## PROGRAM NO. 706473

13

**Section 13**

## CONTENTS

13

**SUBJECT MODEL** -- Line Printer Model Numbers 7461, 7462, 7463, 7464, 7465, 7466

**REQUIRED EQUIPMENT** -- Minimum Memory Size: 16K; Input Device: Card Reader, Paper Tape Reader or Magnetic Tape Unit; Output Device: Keyboard Printer or Line Printer

## PROGRAM PREREQUISITES

Need vertical format tape with all channels punched.

## GENERAL OPERATING PROCEDURES

General operating procedures of the Xerox Sigma 5 through 9 Diagnostic Program Monitor (DPM) apply to this program.

**DIRECTIVES** - directives are entered after a "!" is typed out

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Environmental Directives | | | | | |
| System Environment | SYST, D1, X2, X3 | D1 | Device model number | 7461, 7462, 7463, 7464, 7465, 7466 | |
| | | X2 | Revision number of controller | 0 for all printers | |
| | | X3 | IOP and Device address | 01 ~ 1F7F | 7461 |
| Program Directives – Testing Directives | | | | | |
| Comprehensive Test (all functional tests, 1 ~ 20, and random exerciser test) | TST0 | | | | |
| Functional Test | TST1 \|,D1 [,D2]\| | D1 | The first subtest to be executed | 0 (all subtests) ~22 | 0 |
| | | D2 | Last subtest to be executed | | |
| Random Exerciser Test | TST2, D1 | D1 | Number of cycles to be performed | D1 > 0 | 1 |
| Utility Test | TST3, D1, D2, D3, D4 | D1 | = 0 Hammer registration D2=Line count | D2 Not entered = Print continuously D2=0 Print 1 line D2≠0 Print D2 lines | |
| | | | = 1 Checkerboard pattern D2=Line count | D2 Not entered=Print continuously = 0 Print 1 line ≠ 0 Print D2 lines | |
| | | | = 2 Ripple pattern D2=Line count | D2 Not entered=Print continuously = 0 Print 1 line ≠ 0 Print D2 lines | |
| | | | = 3 Printer speed test D2 =Character set count | 1 ≤ D2 ≤ 95 | |
| | | | = 4 Printer load test D2=Line count | D2 Not entered=Print continuously = 0 Print 1 line ≠ 0 Print D2 lines | |
| | | | = 5 Broadside pattern D2=Line count | D2 Not entered=Print continuously = 0 Print 1 line ≠ 0 Print D2 lines | |
| | | | = 6 Selectable pattern/position (Data determined by DATA directive) D2=Number of lines to be printed D3=Number of lines to be printed as a group D4=Number of blank lines between groups | D2 Not entered=Print continuously D2=0 Print 1 line D2≠0 Print D2 lines D3=0 Print continuous lines ≠ 0 No. lines/group 0 ≤ D4 | |
| | | | = 7 Space lines (space orders are issued to each of the 30 possible positions in sequence) | Space Order C0 - CF E0 - EF | |
| | | | = 8 Channel search D2=Channel number D3≠0 Skip channel no. with inhibit upspace | D2 Not entered Skip to all channels in sequence 0 ≤ D2 < 7 | |
| | | | =10 All Utility tests in sequence D2 Line count | D2=0 Print 1 line D2≠0 Print D2 lines | |
| | | | = 9 Paper Slew speed D2 not used | | |

**DIRECTIVES** (Continued)

| Name | Format | Parameter | | | |
|------|--------|-----------|---|---|---|
| | | ID | Definition | Value Range | Standard Value (default) |
| Program Directives – Optional Directives | | | | | |
| Pattern selection (for Utility Test)(TST3.6) | DATA, D1, D2, D3, D4 | D1<br>D2<br>D3<br>D4 | = 4 Variable pattern<br>Starting column<br>Ending column<br>EBCDIC character string<br>(up to 4 EBCDIC characters) | –4<br>1 ~ 132<br>1 ~ 132<br>Any printable codes<br>00 ~ FF<br>(F0F1F2F3) | |
| Limitation of program parameters | LIMT, D1, D2, D3 | D1 | = 1 Limit compare error printouts<br>D2=Maximum number of compare<br>      error printouts | 1, 2<br><br>0 ≤ D2 | |
| | | | = 2 Limit delay time<br>D2=Minimum delay time<br>D3=Maximum delay time | –6<br>0 ≤ D2 ≤ D3 | |

Note:  Parameter of any directive beginning with a D means decimal; with an H means hexadecimal.

## START PROCEDURE

1.  Sense Switch Options, Monitor Directive Options, and Environmental Directives - Refer to DPM section of this manual.
2.  Test Strategy Selection

|  | Comprehensive Test | Functional Test | Random Exerciser Test | Utility Test |
|---|---|---|---|---|
| Recommended Application | Normal Usage | Solid Failure Detection and Specific Problem Analysis | Intermittent Failure Detection | Print Quality Verification |
| Test Directive | TST0 | TST1 | TST2 | TST3 |
| Prerequisite | None | None | TST1 | TST1 |
| Optional Directives | LIMT | LIMT | LIMT | LIMT, DATA |
| Subtests | All functional subtests (1~20) and random exerciser test | 22 subtests (see error messages for the test types) | Prints a predetermined set of test patterns | Prints one or all of predetermined patterns |
| Error Message Format | 1. ERROR NO. DDDD LOC XXXX 2. Self-explanatory | ERROR NO. DDDD LOC XXXX | Self-explanatory | Self-explanatory |

3.  System reset should normally be used in order to insure the resetting of controller test mode logic.

## PROGRAM TEST DESCRIPTION

The following is a description of the tests contained in the Comprehensive Line Printer test program.

### TST0

The directive selects the comprehensive test consisting of the functional test (subtests 1-20) and the random exerciser test.

Parameters:   None

Example:      TST0
1.  The functional test will be run on the printer in sequence (subtest 1 through 20).
2.  The random exerciser will run until six cycles have been completed.  If a failure is encountered, an error message is printed and the exercising continues.

### TST1

The directive selects the entire functional test (no parameters entered) or selects one or more contiguous functional subtests.

Parameters:   D1 – First functional subtest
              D2 – Last functional subtest

              where $0 < D1 \leq D2 \leq 22$

Examples:     Run all functional subtests.

              TST1, 5, 9

              Run functional subtests 5 thru 9.

### TST2

The directive selects the random exerciser test.

Parameters:   D1 – Number of cycles to be executed by random exerciser

Example:      TST2, 3

              The random exerciser will run until three cycles have been completed.

### TST3

The utility test routine allows the user to select a specific utility function and/or print patterns which aid the operator in printer adjustments.

Parameters:   D1 – Utility test selection
              D2 – Defined by the utility test selected
              D3 – Defined by the utility test selected
              D4 – Defined by the utility test selected

D1 = 0 Hammer registration
       D2 = Line count

Generates pattern of broadside character 'E' (same character in all positions) continuously as a reference in checking printer hammer alignment

D1 = 1 Checkerboard pattern
       D2 = Line count

### TST3(Continued)

Generates a worst-case pattern to expose ghost character printing. The pattern consists of alternating character 'E' and blanks.

D1 = 2 Ripple pattern
       D2 = Line count

Generates a pattern consisting of all characters per line, each succeeding line having the characters shifted one position to the left

D1 = 3 Printer speed test
       D2 = Character count (7450 only)

A 36-line pattern of characters is printed to produce maximum print rate. The average time to print and upspace is calculated and the printer speed is determined and reported.

D1 = 4 Printer load test
       D2 = Line count

Generates a pattern of an increasing number of character 'E' each line until 132 positions are printed, then a decreasing number of character 'E' each line

D1 = 5 Broadside pattern
       D2 = Line count

Generates a 64/95 line pattern of all printable characters broadside

D1 = 6 Selectable pattern/position
       D2 = Line count
       D3 = Group/line count
       D4 = Group/space count

Generates a selectable character and position(s) pattern

D1 = 7 Space lines
       D2 = Unused

Space orders are issued to each of the 15 possible positions in sequence.

D1 = 8 Channel search
       D2 = Channel number
       D3 ≠ 0 Skip to channel number with inhibit upspace.

Channel searches are issued to the operator-specified channel.

D1 = 9 Paper Slew speed
       D2 = Not used

Space 15 lines, determine paper slew and report the results.

D1 = 10 Utility test
        D2 = Line count

Run all utility tests in sequence

Examples:     TST3, 7

              Space orders are issued to each of the 15 possible positions in sequence.

              TST3, 8, 4

              Exercise the printer VFU control.  Channel 4 is to be searched.

## ORDER CODES

| | |
|---|---|
| X'01' | Print a line |
| X'41' | Print a line – interrupt at data transmission complete |
| X'03' | Format order (see format codes) |
| X'43' | Format order – interrupt at data transmission complete (see format codes) |
| X'05' | Print with format |
| X'45' | Print with format – interrupt at data transmission complete |

## NORMAL TDV STATUS

| MODEL | BITS | | | | | | | |
|---|---|---|---|---|---|---|---|---|
| | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| 7461, 7462, 7463, 7464, 7465, 7466 | Not Used | Recovery Mode 1 | Recovery Mode 2 | Top of Page | Not Used | Not Used | IO Parity Error | Not Used |

## AIO STATUS                    For Model 7461, 7462, 7463, 7464, 7465, 7466

| BITS | | | | | | | |
|---|---|---|---|---|---|---|---|
| 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| NOT USED | DATA TRANSMISSION COMPLETE INTERRUPT | ←———————— | | NOT USED | | | ————————→ |

## FORMAT CODES FOR FORMAT OPERATIONS

MODEL  7461, 7462, 7463, 7464, 7465, 7466

| | | | |
|---|---|---|---|
| X'60' | Inhibit automatic space after print | X'F0' | Skip to channel 0 (bottom of page) |
| X'C0' | Space 0 lines | X'F1' | Skip to channel 1 (top of page) |
| X'C1' | Space 1 line | X'F2' | Skip to channel 2 |
| X'C2' | Space 2 lines | X'F3' | Skip to channel 3 |
| X'C3' | Space 3 lines | X'F4' | Skip to channel 4 |
| X'C4' | Space 4 lines | X'F5' | Skip to channel 5 |
| X'C5' | Space 5 lines | X'F6' | Skip to channel 6 |
| X'C6' | Space 6 lines | X'F7' | Skip to channel 7 |
| X'C7' | Space 7 lines | X'F8' | Skip to channel 8 |
| X'C8' | Space 8 lines | X'F9' | Skip to channel 9 |
| X'C9' | Space 9 lines | X'FA' | Skip to channel 10 |
| X'CA' | Space 10 lines | X'FB' | Skip to channel 11 |
| X'CB' | Space 11 lines | X'FC' | Skip to channel 8 |
| X'CC' | Space 12 lines | X'FD' | Skip to channel 9 |
| X'CD' | Space 13 lines | X'FE' | Skip to channel 10 |
| X'CE' | Space 14 lines | X'FF' | Skip to channel 11 |
| X'CF' | Space 15 lines | X'D0' | Skip to channel 0 (BOP) and inhibit automatic upspace |
| X'E0' | Space 0 lines and inhibit automatic upspace | X'D1' | Skip to channel 1 (TOP) and inhibit automatic upspace |
| X'E1' | Space 1 line and inhibit automatic upspace | X'D2' | Skip to channel 2 and inhibit automatic upspace |
| X'E2' | Space 2 lines and inhibit automatic upspace | X'D3' | Skip to channel 3 and inhibit automatic upspace |
| X'E3' | Space 3 lines and inhibit automatic upspace | X'D4' | Skip to channel 4 and inhibit automatic upspace |
| X'E4' | Space 4 lines and inhibit automatic upspace | X'D5' | Skip to channel 5 and inhibit automatic upspace |
| X'E5' | Space 5 lines and inhibit automatic upspace | X'D6' | Skip to channel 6 and inhibit automatic upspace |
| X'E6' | Space 6 lines and inhibit automatic upspace | X'D7' | Skip to channel 7 and inhibit automatic upspace |
| X'E7' | Space 7 lines and inhibit automatic upspace | X'D8' | Skip to channel 8 and inhibit automatic upspace |
| X'E8' | Space 8 lines and inhibit automatic upspace | X'D9' | Skip to channel 9 and inhibit automatic upspace |
| X'E9' | Space 9 lines and inhibit automatic upspace | X'DA' | Skip to channel 10 and inhibit automatic upspace |
| X'EA' | Space 10 lines and inhibit automatic upspace | X'DB' | Skip to channel 11 and inhibit automatic upspace |
| X'EB' | Space 11 lines and inhibit automatic upspace | X'DC' | Skip to channel 8 and inhibit automatic upspace |
| X'EC' | Space 12 lines and inhibit automatic upspace | X'DD' | Skip to channel 9 and inhibit automatic upspace |
| X'ED' | Space 13 lines and inhibit automatic upspace | X'DE' | Skip to channel 10 and inhibit automatic upspace |
| X'EE' | Space 14 lines and inhibit automatic upspace | X'DF' | Skip to channel 11 and inhibit automatic upspace |
| X'EF' | Space 15 lines and inhibit automatic upspace | | |

# FUNCTIONAL SUBTESTS AND RELATED ERROR MESSAGES

## FAULT INDEX DESCRIPTION - FUNCTIONAL SUBTESTS

The fault index contains a brief description of each functional subtest and a list of associated error numbers with a brief description of each error. The subtests and error numbers are arranged in ascending sequence. The description of subtest NN is numbered NN00. The first two digits of the error number correspond to the associated subtest; the last two numbers correspond to the individual errors within the subtest.

TST1, 1   HIO, TIO, TDV and AIO instruction recognition. HIO, TIO, TDV and AIO instructions are issued and condition codes status tested.

0101   HIO instruction condition codes or status error.
0102   TIO instruction condition codes or status error.
0103   TDV instruction condition codes or status error.
0104   AIO instruction condition code error. Expect no interrupt recognition.

TST1, 2   SIO invalid order. SIO is issued with all invalid orders and controller tested for unusual end.

0201   SIO instruction condition codes not 00 as expected.
0202   SIO instruction status error.
0203   TIO instruction indicates controller busy 50 usec after SIO. Expect UE.
0204   TIO instruction indicates status error after SIO (invalid order). Expected UE, controller not busy.
0205   TIO instruction terminal byte count not ═ 1 indicating controller accepted one byte for invalid order.

TST1, 03   Format Order - Inhibit Upspace. A format order of a byte count of one, then a byte count of two is issued. Terminal status is verified and that no paper motion has occurred.

0301   SIO status error for format order.
0302   Device, controller busy beyond normal termination time for format order.
0303   Paper motion occurred for a format with inhibit upspace.
0304   Status error for format order.
0305   Byte count did not decrease after format order.

TST1, 05   Interrupt Generation and HIO, AIO Instruction Resetting. The following orders are issued: X'03', X'03', and X'00' in order to test the generation of ICE, IZC and IUE. AIO and HIO instructions are issued to test the interrupt clearing.

0501   TIO instruction indicates IP status not present after X'03' order with ICE flag set.
0502   TIO instruction condition code or status error after X'03' order issued with ICE flag set.
0503   AIO instruction condition code, status or device address error following a X'03' order raising IP.
0504   HIO instruction did not clear IP in controller.
0505   TIO instruction indicates IP not set by X'03' order with IZC flag set.
0506   TIO instruction condition code or status error after X'03' order with IZC flag set.
0507   AIO instruction condition code, status or device address error after X'03' order with IZC flag set.
0508   AIO or HIO instruction did not reset IP status in controller.
0509   TIO indicates X'00' order with IUE flag set did not set IP in controller.
0510   TIO indicates condition code or status error after X'00' order with IUE flag set.
0511   AIO condition code, status or device address error after X'00' order with IUE flag set.
0512   TIO indicates no UE status for X'00' order.
0513   TIO condition code or status error after AIO or HIO issued with IP status present.
0514   AIO did not reset IP status in controller.

TST1, 06   IO Interrupt Generation. A format with ICE flag is issued. Verify that the program is interrupted when the IO interrupt is armed and enabled.

0601   TIO instruction indicates IP not set by SIO, IO interrupt is disarmed.
0602   Program was interrupted while IO interrupt was disarmed.
0603   Program was not interrupted while IO interrupt was armed/enabled.
0604   TIO indicates IP not cleared by an AIO instruction.

TST1, 07   Print with Format - Inhibit Upspace (blank characters). A print with format order is issued to perform a print operation with inhibit upspace format. Terminal status and no paper motion is verified. Bytes of 2 through 134 are transferred.

0701   TDV status error.
0702   Byte count not equal to zero after a print with format order.
0703   IL not set for byte count greater than 132.
0704   IL set for byte count less or equal to 132.
0705   Status error for print with format.
0706   SIO status error for print with format.

TST1, 08   Data Transmission Complete (DTC) Interrupt. Using print with format and interrupt on data transmission complete, verify data transmission complete interrupt is generated.

0801   Data transmission complete interrupt not generated.
0802   TIO indicates condition code or status error for X'45' order. Expected IP status.
0803   AIO condition code, status or device address error after DTC interrupt generated in controller expected AIO status bit 1 set.

TST1, 09   Command Chaining. Using the invalid order, verify the command chaining operation; verify that the UE status terminates the command chaining.

0901   TIO indicates controller busy beyond normal termination time for command chain operation.
0902   TIO indicates status error during command chaining operation.
0903   TIO indicates operational status error following command chain operation.
0904   Byte count not 0 following command chaining operation.
0905   TIO indicates command chaining terminated with first IOCD instead of second IOCD.
0906   Controller busy with invalid order.
0907   TIO indicates UE not generated for invalid order.
0908   TIO status error following invalid order command chained.
0909   Terminal byte count zero following an invalid order command chained.
0910   Command chaining not terminated by UE of invalid order.
0911   SIO status error for invalid order command chained.
0912   SIO status error for command chained.

TST1, 11   Format - Space One Line. A format order is issued to space one line. Verify that paper motion and no print operation occurs.

1101   Status error for format order.

TST1, 13   Print Broadside Pattern. A broadside pattern of all
characters are printed. Terminal status is tested.

1301   Status error for broadside line.


TST1, 14   Print – Sliding One Column Pattern. Print with auto
upspace is issued with incrementing byte counts of a
sliding 1 column pattern. Verify that no print errors
occur.

1401   Status error for a print order.


TST1, 15   Unavailable Character Print Test. This test will
print a line composed of all 8-bit codes between
0 and 127 corresponding to unavailable characters
followed by a similar line composed of all 8-bit
codes between 128 to 255 corresponding to
unavailable characters.

1501   Invalid characters print status error for 8-bit codes 0 to 127.
1502   Invalid characters print status error for 8-bit codes 128-255.


TST1, 17   Space Line Test. This test will issue space lines to
test the correct mapping of the format code.
Operation is to observe if line printer have
spaced the correct space.

1701   Space XX lines IO status error.
1702   Skip to top of page IO status error.


TST1, 18   Skip Channel Test. This test will issue skip to
channel to test the correct mapping of the format
code. Operator to observe the line printer have
skipped to the correct channel.

1801   Skipped to channel XX IO status error.
1802   Print message IO status error.


TST1, 19   Detect Top of Page Test. This test will issue skip to
bottom of page then space one line until top of page
is detected.

1901   Skip to bottom of page IO status error.
1902   Space one line IO status errors.
1903   Top of page not detected.


TST1, 20   Pattern and Format Test. Run a selected set of utility
tests in sequence. Verify that no print error or paper
fault occur.

2001   Status error for hammer registration.
2002   Status error for checkerboard pattern.
2003   Status error for ripple test pattern.
2004   Status error for printer speed test.
2005   Status error for printer load test.
2006   Status error for skip line test.
2007   Status error for channel search test.
2008   Status error for paper slew speed test.


TST1, 22   IOP Halt Test (Sigma 7-9). This test will generate an
IOP halt at the end of a data transmission of 1 through
8 bytes with upspacing inhibited. After the generation
of each IOP halt the entire line will be printed. This
will verify the inhibit upspace and response to an
IOP Halt.

2201   SIO status error with two TIC's.
2202   IO status error with two TIC's.
2203   SIO status error with one TIC.
2204   IO status error with one TIC.

FUNCTIONAL TEST (TST1)  (SS 1 = 0,  SS3 = 1)
INITIALIZING CONDITIONS AND EXPECTED RESULTS

1.  Initializing Conditions:   None
2.  Expected Results:

| SUBTEST | RESULTS |
|---------|---------|
| TST1, 11 | Space 1 line |
| TST1, 13 | Print 64 lines broadside pattern of all printable characters |
| TST1, 14 | Print 132 sliding one column pattern |
| TST1, 15 | Print 2 lines of unavailable characters |
| TST1, 17 | Space many lines |
| TST1, 18 | Skip many lines |
| TST1, 19 | Go to top of page |
| TST1, 20 | Print 32 lines broadside character 'E'<br>Print 32 lines of alternating blank and character 'E'<br>Print 132 lines of ripple test pattern<br>Print 36 printer speed test<br>Print 263 printer load test pattern<br>Space 1 to 15 lines in sequence two times<br>Skip to channel 1 to 12 in sequence two times<br>Space 15 lines paper slew speed test |
| TST1, 22 | Print 8 lines of all XXXX characters |

# Section 14

## SIGMA 5 - 9

### INTERFACE AND
### SWITCH REFERENCE DATA

# Section 14

## CONTENTS

14

SIGMA 8/9 MEMORY - PROCESSOR INTERFACE

| CABLE | PIN PANEL | | Cable 1 | Cable 2 | Cable 3 | Cable 4 | Cable 5 | Cable 6 |
|---|---|---|---|---|---|---|---|---|
| 1/A | D R | 2 6 | M01 | M15 | M29 | L16 | AH | L10 |
| 2/B | D R | 1 4 | M00 | M14 | M28 | L15 | MQ | L11 |
| 3/C | D R | 9 10 | M03 | M17 | M31 | L18 | DR | L12 |
| 4/D | D R | 3 8 | M02 | M16 | M30 | L17 | AR | L13 |
| 5/E | D R | 12 13 | M04 | M18 | L29 | L19 | PE | L14 |
| 6/F | D R | 15 18 | M05 | M19 | L30 | L20 | SRA | L32 |
| 7/G | D R | 19 20 | M06 | M20 | L31 | L21 | M32 | MFI |
| 8/H | D R | 23 22 | M07 | M21 | MW0 | L22 | ABO | DBUSY |
| 9/K | D R | 25 27 | M08 | M22 | MW1 | L23 | POK | MUWS |
| 10/L | D R | 33 34 | M09 | M23 | MW2 | L24 | MR | MUWC |
| 11/M | D R | 35 36 | M10 | M24 | MW3 | L25 | HPQ | SIGMA9 |
| 12/N | D R | 37 38 | M11 | M25 | DG | L26 | ORIL | |
| 13/P | D R | 39 40 | M12 | M26 | EDR | L27 | HOF | |
| 14/R | D R | 45 42 | M13 | M27 | OM | L28 | MFR | |
| SIGMA 8/9 CPU | | | ADD 03L,AG60 | ADD 05L,AG60 | ADD 10K,AG60 | ADD 02K,AG61 | ADD 07L,AG60 | ADD 06K,AG60 |
| MIOP | P: | | 14C,AG60 | 17C,AG60 | 23C,AG60 | 25C,AG60 | 19C,AG60 | 27C,AG60 |
| RIOP | | | 26D,AG70 | 30D,AG70 | 15C,AG60 | 11C,AG60 | 18C,AG60 | 13C,AG60 |
| MEMORY P1: | | | 06C,AG60 | 08C,AG60 | 07B,AG60 | 08A,AG10 | 05B,AG60 | 06A,AG60 |
| | P2: | | 10C,AG60 | 12C,AG60 | 11B,AG60 | 12A,AG10 | 09B,AG60 | 10A,AG60 |
| | P3: | | 23C,AG60 | 21C,AG60 | 22B,AG60 | 21A,AG10 | 24B,AG60 | 23A,AG60 |
| | P4: | | 27C,AG60 | 25C,AG60 | 26B,AG60 | 25A,AG10 | 28B,AG60 | 27A,AG60 |
| SIGMA 5/6/7 5CPU | | | 12M,AT11 | 25P,AT11 | 18R,AT11 | 15R,AT12 | 15S,AT11 | |
| 6/7CPU | | | 21S,AT11 | 19P,AT11 | 27N,AT11 | 15Y,AT11 | 14V,AT11 | |
| MIOP | | | 18A,AT11 | 16A,AT11 | 14A,AT70 | 12A,AT61 | 10A,AT11 | |
| SIOP | | | 20D,AT11 | 18D,AT11 | 15D,AT11 | 11D,AT12 | 13D,AT11 | |
| MEMORY A | | | 02A,AT11 | 02B,AT11 | 04A,AT11 | 04C,AT10 | 06C,AT11 | |
| (OLD) B | | | 06A,AT11 | 06B,AT11 | 04B,AT11 | 02D,AT10 | 04D,AT11 | |
| C | | | 08A,AT11 | 08B,AT11 | 08C,AT11 | 06D,AT10 | 08D,AT11 | |
| MEMLRY 1 | | | 09B,AT60 | 10A,AT60 | 08A,AT60 | 06C,AT60 | 07B,AT60 | |
| (NEW) 2 | | | 14B,AT60 | 15A,AT60 | 13A,AT60 | 11C,AT60 | 12B,AT60 | |
| 3 | | | 19B,AT60 | 18A,AT60 | 20A,AT60 | 22C,AT60 | 21B,AT60 | |
| 4 | | | 24B,AT60 | 23A,AT60 | 25A,AT60 | 27C,AT60 | 26B,AT60 | |
| CFE-3 | | | 32B,AT11 | 30B,AT11 | 28B,AT11 | 24B,AT12 | 26B,AT11 | |

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## MEMORY-PROCESSOR INTERFACE

ABO      Abort Signal - generated by CPU only.
As a result of a write protect violation, overrides a write operation and
prevents changing the contents of memory.

AH      Address Here - generated by addressed port.
Indicates particular address exists.

AR      Address Release - generated by addressed port.
Indicates that memory cycle has started and Processor can drop MQ, L,
MW, OM signals.

DBUSY      Data Bus Busy - generated by addressed port.
Inhibits data transmission from other banks on that port. Only used by
memory units.

DG      Data Gate - generated by addressed port.
During read operations gates data into Processors (MIOP) input register.

DR      Data Release - generated by addressed port.
Indicates during write operation that the data lines may be dropped, during
read operation indicates that next memory cycle can use data bus.

EDR      Early Data Release - generated by addressed port.
During read cycle RIOP uses signal to clear receiving register. Sigma 8/9
CPU delays signal and generates Internal DG.

HOF      Halt on Fault - generated by CPU PCP. (Unused by Sigma 8/9)
Causes address memory to stay busy until PE is cleared.

HPQ      High Priority Request - generated by Processor.
Indicates requesting Processor wants priority changed to higher queue, used
with MQ. (Unused in Sigma 5-7 processors, wired high in Sigma 9 MIOP,
low in CPU but dynamic in Sigma 9 RIOP)

L10-L31      Address Lines - sent by Processor.
Location processor is requesting, signals must remain stable until AR.

L32      Address Parity Line - generated by Processor.
Odd parity bit for L10-L31, MW0-MW3 and OM.

Memory-Processor Interface (Continued)

M00-31          Memory Data Lines - bidirectional lines.
                During read cycle reset at DR time, during write cycle strobed.

M32             Memory Data Parity Line - bidirectional line.
                Odd parity bit for data lines M00-M31.

MFI             Memory Fault Interrupt - generated by port.
                Indicates to Processor a Data Loop Check Error, Parity Error, Overtemp
                or Voltage Irregularities in magnetics.  Reset by MFR or MR.

MFR             Memory Fault Reset - generated by CPU.
                Resets memory fault latch, status latches and the memory fault light signals
                in all ports connected to CPU bus.

MQ              Memory Request - generated by Processor.  (Unused by Sigma 8/9)
                Initiates a request for a memory cycle in the addressed memory.

MR              Memory Reset - generated by CPU.
                Resets memory.

MUWC            Multiple Word Control - generated by Processor.
                N/A, not currently used.

MUWS            Multiple Word Service - generated by Processor.
                N/A, not currently used.

MW0-MW3         Memory Write Byte Lines - generated by Processor.
                Used with OM to determine memory operation.  If OM is false then MW0-
                MW3 indicates which bytes are to be written into memory.  Reset by AR.

OM              Operating Mode - generated by CPU.
                In conjunction with MW0-MW3 determines the type of memory operation.

Memory–Processor Interface (Continued)

| OM | MW0 | MW1 | MW2 | MW3 | Sigma 9 Memory Response |
|----|-----|-----|-----|-----|--------------------------|
| 0 | 0 | 0 | 0 | 0 | Read |
| 0 | X | X | X | X | Any bit set will cause that byte to be written into memory. |
| 1 | 0 | 0 | 0 | 0 | Load and Set |
| 1 | 0 | 0 | 0 | 1 | Read and Inhibit Parity Trap |
| 1 | 0 | 0 | 1 | 0 | Read and Change Parity – force P.E. |
| 1 | 0 | 1 | 1 | 1 | Set Memory Margins |
| 1 | 1 | 0 | 0 | 0 | Read Status Word 0 |
| 1 | 1 | 0 | 0 | 1 | Read Status Word 1 |
| 1 | 1 | 0 | 1 | 0 | Read Status Word 2 |
| 1 | 1 | 1 | 0 | 0 | Read Status Word 0 and clear all status |
| 1 | 1 | 1 | 1 | 0 | Read Status Word 2 and clear all status |
| 1 | 1 | 1 | 1 | 1 | Clear Memory |

ORIL      Override Interleaving – generated by CPU PCP.
Disables interleaving for all banks.

PE      Parity Error – generated by port.
Indicates uncorrectable magnetic data parity error for read or partial write cycles, address or data bus parity at port, or port selection error in driver or matrix. (Different significance for Sigma 7 vs Sigma 9 memory)

POK      Parity OK – generated by port.
No PE conditions (see above).

Memory-Processor Interface (Continued)

SIGMA 9    Generated by Processor.
Indicates all memory interfaces are to be parity checked and also selects
faster interface timing.

SRA    Second Request Allowed - generated by port.
Indicates to CPU, during read operation, that a new memory request can
be initiated.  Not used by Sigma 9 system.

## IOP – DEVICE CONTROLLER INTERFACE

| CABLE PANEL | | | (AT56) Cable 1 | Cable 2 | (AT57) Cable 3 | Cable 4 | Cable 5 | Cable 6 |
|---|---|---|---|---|---|---|---|---|
| 1/A | D | 2 | FR7 | DA7 | RST (15) | HPI (35)(06) | DB0 | DC4 |
|  | R | 6 | | | | | | |
| 2/B | D | 1 | FR6 | DA6 | CL1 (07) | HPS (33)(09) | DB1 | DC5 |
|  | R | 4 | | | | | | |
| 3/C | D | 9 | FR5 | DA5 | ES (17) | FAST (31)(10) | DB2 | DC6 |
|  | R | 10 | | | | | | |
| 4  D | D | 3 | FR4 | DA4 | RSA (18) | AVO (29) AVI (08) | DB3 | DC7 |
|  | R | 8 | | | | | | |
| 5/E | D | 12 | FR3 | DA3 | SIO ($) | | DB4 | BM |
|  | R | 13 | | | | | | |
| 6/F | D | 15 | FR2 | DA2 | HIO ($) | | DB5 | DD0 |
|  | R | 18 | | | | | | |
| 7/G | D | 19 | FR1 | DA1 | TIO (19) | AVIH1 | DB6 | DD1 |
|  | R | 20 | | | | | | |
| 8/H | D | 23 | FR0 | DA0 | TDV (22) | AVIH2 | DB7 | DD2 |
|  | R | 22 | | | | | | |
| 9/K | D | 25 | RS (07) | DAP | AIO (30) | DCOFF (30)(02) | EDX2 | DD3 |
|  | R | 27 | | | | | | |
| 10/L | D | 33 | IOR (47) | ED | ASC (33) | | DC0 | DD4 |
|  | R | 34 | | | | | | |
| 11/M | D | 35 | FSL (50) | PC | FS (36) | | DC1 | DD5 |
|  | R | 36 | | | | | | |
| 12/N | D | 37 | DX2 (45) | DOR | SIC (35) | AT83 | DC2 | DD6 |
|  | R | 38 | | | | | | |
| 13/P | D | 39 | IC (43) | SC | WADR (44) | PANEL | DC3 | DD7 |
|  | R | 40 | | | | | | |
| 14/R | D | 45 | DX4 (39) | AP | IER (45) | | EDX4 | |
|  | R | 42 | | | | | | |
| **SIGMA 8/9** | | | | | | | | |
| MIOP | | | 13H,AG70 | 10G,AG70 | 04G,AG70 | 04H,AG60 | 09F,AG70 | 12E,AG70 |
| MAINT.SUB | | | 10J,AT56 | 13J,AG70 | 17J,AT57 | 04H,AG60 | 15J,AG70 | 27J,AG70 |
| **SIGMA 5/6/7** | | | | | | | | |
| IIOP 5 | | | 10L,AT10 | 08L,AT11 | 09F,AT12 | 09E,AT11 | | |
| MIOP | | | 14B,AT10 | 32A,AT11 | 14C,AT12 | 01D,AT11 | 19C,AT11 | 29A,AT11 |
| SIOP 14 | | | 14E,AT10 | 21E,AT11 | 11E,AT12 | 09E,AT11 | 19E,AT11 | 17E,AT11 |
| MAINT.SUB | | | 31A,AT56 | 29A,AT60 | 27A,AT57 | 25A,AT83 | 19A,AT60 | 17A,AT60 |
| EP RAD 7231 | | | 32C,AT12 | 30C,AT11 | 28C,AT10 | 26C,AT83 | 28B,AT11 | 31B,AT11 |
| HS RAD 7211 | | | 32D,AT12 | 30D,AT11 | 28D,AT10 | 26D,AT83 | 27C,AT11 | 30C,AT11 |
| DISK PAK | | | 32B,AT56 | 30B,AT60 | 28B,AT57 | 26B,AT83 | 29A,AT60 | 31A,AT60 |
| 1 BYTE CONT | | | 32x,AT12 | 30x,AT11 | 28x,AT10 | 26x,AT83 | | |
| PERF SW   X | | | 32B,AT61 | 30B,AT60 | 28B,AT10 | 26B,AT38 | | |
| | | | 24B,AT61 | 22B,AT60 | 20B,AT10 | 18B,AT38 | | |
| | | | 32A,AT10 | 30A,AT11 | 28A,AT12 | 26A,AT11 | | |
| PERF SW (7722) | | | | | | X | 23A,AT60 | 21A,AT60 |
| | | | | | | Y | 15A,AT60 | 13A,AT60 |
| | | | | | | Switched | 19A,AT11 | 17A,AT11 |

## IOP-DEVICE CONTROLLER INTERFACE

AIO
Acknowledge I/O Interrupt – generated by IOP during AIO instruction.
Used with FS and IC to identify type of instruction CPU is requesting interrupting device controller to perform.

ASC
Acknowledge Service Call – generated by IOP.
Used with FS and SC to signal that IOP is free to begin requested service cycle with highest priority device.

AP
Address Parity – generated by Device Controller.
Odd parity bit for FR0-7 during service cycles. Currently only recognized by Sigma 9 MIOP. (DX2 used to request address parity check)

AVI
Available Input – signal received by Device Controller.
Used with FS and function indicators to establish priority for a service cycle.

AVIH1
AVIH2
Available Input – generated by IOP.
High levels used by special terminator to generate AVI into highest priority device controller.

AVO
Available Output – signal generated by Device Controller.
Indicates to next device controller that this D.C. has received FS and was not addressed.

BM
Burst Mode – generated by Device Controller.
Request IOP to continue service connection. Wide interface must be used (EDX4, DX4, NIER). Currently only recognized by Sigma 9 MIOP.

CL1
1.024MH – clock transmitted by IOP.
Crystal controlled signal driven continuously by CPU.

DA0-7
Data Lines – bidirectional.
Exchange of data on DA lines controlled by RS and RSA.

IOP-Device Controller Interface (Continued)

|  | DA LINES | | | | | | | |
|---|---|---|---|---|---|---|---|---|
|  | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| **IOP Uses** |  | | | | | | | |
| TTSH | Device/Device Controller Address | | | | | | | |
| ORDER OUT | Order Byte | | | | | | | |
| DATA OUT | Data Byte | | | | | | | |
| TERMINAL ORDER | INT | CDN | CCH | IOPH | AE | Not Used | | |
| **Device Controller Uses** |  | | | | | | | |
| AIO | Status | | | | | | | |
| DATA IN | Data Byte | | | | | | | |
| ORDER IN | TE | IL | CM | CE | UE | Not Used | | |

DAP
: Data Parity Line – bidirectional.
  Odd parity for data path in use, always generated by IOP, Device Controller may or may not generate (see PC).

DB,DC,DD0-7 Data Lines – bidirectional.
  Optional data lines used during 4-byte data transfer sequences only. Controlled by DX4, EDX4 and IER.

DCOFF
: Device Controller Off – generated by Maintenance Subcontroller.
  Causes all device controllers to Go Off line. Program controllable FF generates signal. Only recognized by AT83, AT87.

DOR
: Data/Order Request – generated by Device Controller.
  Identifies request (RS) during service cycles and condition code 2 during I/O Instruction.

DX2
: Two Byte Request – generated by Device Controller. Also see AP.

## IOP-Device Controller Interface (Continued)

DX4     Four Byte Request - generated by Device Controller.
Device Controller is requesting IOP to use wide interface (DA, DB, DC and DD lines) for data path, requires that Device Controller have wide interface option and that the IOP signal has signalled wide interface option (EDX4).

ED     End Data - bidirectional line.
The IOP or Device Controller may raise ED to indicate no more data is to be transferred in this service sequence. If ED is true and ES is false IOP is signaling device Controller that a terminal order must be requested.

EDX2     Enable Two Byte - generated by IOP.
Indicates IOP has wide interface (DA, DB line) installed, used with DX2, IER. (Not used in Sigma 5-9)

EDX4     Enable Four Byte - generated by IOP.
Indicates IOP has wide interface (DA, DB, DC and DD lines) installed, used with DX4, IER.

ES     End Service - generated by IOP.
The IOP drives ES and RSA to indicate the service sequence is to terminate on the byte being transferred.

FAST     Fast - generated by Device Controller.
No ZBCI during Data chaining.

FR0-FR7     Function Response Lines - generated by addressed Device Controller.
When DC is responding to FS accompanied by a TTSH (TIO, TDV, SIO, HIO), indicator FR0-7 carry D.C. status. During ASC or AIO functions FR0-7 are driven with device address.

FS     Function Strobe - generated by IOP.
Indicates device controllers should look at function indicators when they receive AVI.

During TTSH addressed device controller responds by raising FSL, with status on FR0-7. During AIO or ASC highest priority calling (IC or SC) device controller responds by raising FSL, with DC add on FR0-7. FS and FSL work in a closed-loop manner.

IOP-Device Controller Interface (Continued)

FSL          Function Strobe Acknowledge – generated by device controller.
             Indicates to IOP that a device controller has received AVI and identified
             the operation that the IOP signaled on the function lines. FS and FSL
             work in a closed-loop manner. (See FS)

HIO          Halt I/O Device – generated by IOP.
             Used with FS and DA0-7 to identify type of instruction CPU is requesting
             addressed device controller to perform.

HPI          High Priority Interrupt – generated and used by device controller.
             Used by device controller to put itself into high priority queue for AIO
             function. No standard XDS equipment raises this line.

HPS          High Priority Service – generated and used by device controller.
             Used by device controller to put itself into high priority queue for ASC
             function. No standard XDS equipment raises this line.

IC           Interrupt Call – generated by device controller.
             Signal passed thru IOP to CPU causing interrupt to X'5C'.

IER          Inhibit Extended Request – generated by IOP.
             Denies device controller usage of wide interface because of non word bound
             byte address or insufficient byte count, used to override DX4, EDX4.

IOR          Input/Output Request – generated by device controller.
             Identifies request (RS) during service sequence, High Output, Low Input;
             condition code information during TTSH AIO sequence, H => NCOND1.

PC           Parity Check – generated by IOP and some Device Controllers.
             Request for parity to be checked on DATA (DA0-7).

RS           Request Strobe – generated by service connected Device Controller.
             Signals to the IOP that a data byte is to be exchanged on the DA lines.
             RS and RSA work in closed-loop manner.

RSA          Request Strobe Acknowledge – generated by IOP.
             Signals to the device controller that exchange of data byte is complete, i.e.
             during input operation IOP has accepted byte sent by D.C., during output
             operation IOP is sending requested data byte.

RST          Reset – generated by IOP.
             Reset signal to all device controllers generated by CPU PCP I/O reset, or
             SYST reset switch, or as a result of a RIO instruction. (Sigma 9 only)

IOP–Device Controller Interface (Continued)

SC          Service Call – generated by device controller.
            Device controllers use this line to request an IOP service cycle.  The IOP
            will respond with FS and ASC.

SIC         Special Interrupt Call – generated by IOP.
            Used when FAST is true to indicate ZBCI during Data Chaining, not used.

SIO         Start I/O Device – generated by IOP.
            Used with FS to identify type of instruction CPU is requesting addressed
            device controller to perform.  FS is driven to DC's after SIO indicator
            and DA0–7 (Device Address).

TDV         Test Device – generated by IOP.
            Used with FS to identify type of instruction CPU is requesting addressed
            D.C. to perform.

TIO         Test I/O – generated by IOP.
            Used with FS to identify type of instruction CPU is requesting address
            controller to perform.

WADR        Word Aligned Data Required – generated by IOP.
            Full word being transmitted.  Sigma 3 uses.
            Static line held true by IOP not capable of byte alignment on wide interface.

ZBCI        Zero Byte Count Interrupt – generated by SIOP.
            Used when controller drives FAST, driven by SIOP when IZBC and DC flags
            are true and zero byte count is reached.

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## DIO INTERFACE

| CABLE | BACK PANEL | | Cable 1 | Cable 2 | Cable 3 | Cable 4 |
|---|---|---|---|---|---|---|
| 1/A | D | 2 | DB01 | DB15 | DB29 | A03 |
|     | R | 6 |      |      |      |     |
| 2/B | D | 1 | DB00 | DB14 | DB28 | A02 |
|     | R | 4 |      |      |      |     |
| 3/C | D | 9 | DB03 | DB17 | DB31 |     |
|     | R | 10 |     |      |      |     |
| 4/D | D | 3 | DB02 | DB16 | DB30 | A04 |
|     | R | 8 |      |      |      |     |
| 5/E | D | 12 | DB04 | DB18 | FS | A00 |
|     | R | 13 |     |      |    |     |
| 6/F | D | 15 | DB05 | DB19 | FSA | A01 |
|     | R | 18 |     |      |     |     |
| 7/G | D | 19 | DB06 | DB20 | WD | A08 |
|     | R | 20 |     |      |    |     |
| 8/H | D | 23 | DB07 | DB21 | A05 | A09 |
|     | R | 22 |     |      |     |     |
| 9/K | D | 25 | DB08 | DB22 | A06 | A10 |
|     | R | 27 |     |      |     |     |
| 10/L | D | 33 | DB09 | DB23 | A07 | A11 |
|      | R | 34 |     |      |     |     |
| 11/M | D | 35 | DB10 | DB24 | A12 | CC3 |
|      | R | 36 |     |      |     |     |
| 12/N | D | 37 | DB11 | DB25 | A13 | CC4 |
|      | R | 38 |     |      |     |     |
| 13/P | D | 39 | DB12 | DB26 | A14 | RES |
|      | R | 40 |     |      |     |     |
| 14/R | D | 45 | DB13 | DB27 | A15 | 1MHZ |
|      | R | 42 |     |      |     |      |
| SIGMA 8/9 CPU | | | REG 09K,AG60 | AUX 22E,AG60 | AUX 26E,AG60 | AUX 29E,AG60 |
| MIOP | | | 32B,AG60 | 30B,AG60 | 28B,AG60 | 15B,AG60 |
| RIOP | | | 04B,AG60 | 07B,AG60 | 01A,AG60 | 03A,AG60 |
| EXT.INTER | | | | 22E,AG60 | 26E,AG60 | 29E,AG60 |
| SIGMA 5/6/7 5CPU | | | 09M,AT11 | 22Q,AT11 | 26Q,AT11 | 29Q,AT11 |
| 6/7CPU | | | 23S,AT11 | 27Q,AT11 | 30P,AT11 | 29N,AT11 |
| MAINT.SUB | | | | 11A,AT11 | 13A,AT11 | 15A,AT11 |
| COC 7611 | | | | 13B,AT11 | 15B,AT11 | 17B,AT11 |
| PERF. SW (7720) | | | | | 04A,AT60 | 02A,AT60 |
| DIO ADAP X | | | | 18A,AT60 | 14A,AT60 | 10A,AT60 |
| (7710) Y | | | | 16A,AT60 | 12A,AT60 | 08A,AT60 |
| Switched | | | | 06A,AT11 | 04A,AT11 | 02A,AT11 |
| CFE-3 | | | 23S,AT11 | 27E,AT11 | 25E,AT11 | 30D,AT11 |

## DIO INTERFACE

A00–A15          Address Lines – generated by CPU.
16 least significant bits of the RD/WD instruction.


CC3,CC4          Condition Code Lines – generated by Addressed Device.
Can be used by device during RD/WD to set condition codes in CPU.


CL1              1.024 MHz Clock – generated by CPU.
Crystal controlled signal driven continuously by the CPU.


DB00–DB31        Data Bus – bidirectional data lines.
During WD, CPU puts R data on lines before sending FS; during RD addressed
device puts data on lines before sending FSA.  (Some devices use only
DB16–31).


FS               Function Strobe – generated by CPU.
Signals devices to compare address lines (A00–15) with their assigned address.
FS and FSA work in a closed-loop manner.


FSA              Function Strobe Acknowledge – generated by addressed device.
Response to CPU FS.  FSA signals CPU that device has recognized address and
during WD has accepted data or during RD is transmitting data.  FS and FSA
work in a closed loop manner.


RES              Reset – generated by CPU.
Raised by I/O RESET or SYST RESET switch on PCP or during power on or
power off.


WD               Write Direct – generated by CPU.
Sent with address to indicate operation that device is to perform.  High = >Write
Direct, Low = >Read Direct.

Address of
1xxx = Mode 1 – Interrupt Control
2xxx = Mode 2 – Testers
30xx = Mode 3 – Communications Equipment
9xxx = Mode 9 – Switching Equipment
Axxx = Mode A – System Interface Units
Bxxx = Mode B – Miscellaneous
Cxxx = Mode C – System Interface Units

## CPU - IOP INTERFACE

| CABLE | BACK PANEL | | Sigma 8/9 Cable 1 | Sigma 8/9 Cable 2 | | Sigma 5/6/7 Cable 1 |
|---|---|---|---|---|---|---|
| 1/A | D | 2 | FNC0 | HMSP0 | | FNC0 |
|  | R | 6 | | | | |
| 2/B | D | 1 | FNC1 | HMSP1 | | FNC1 |
|  | R | 4 | | | | |
| 3/C | D | 9 | FNC2 | HMSP2 | | FNC2 |
|  | R | 10 | | | | |
| 4/D | D | 3 | ADRS2 | HMSP3 | | IOPA0 |
|  | R | 8 | | | | |
| 5/E | D | 12 | ADRS3 | HMSP4 | | IOPA1 |
|  | R | 13 | | | | |
| 6/F | D | 15 | ADRS4 | HMSP5 | | IOPA2 |
|  | R | 18 | | | | |
| 7 G | D | 19 | *CNST | ADRS1 | | CNST |
|  | R | 20 | CNST | | | CNST |
| 8 H | D | 23 | *AVL | ADRS0 | | |
|  | R | 22 | *AVL/IN | | | |
| 9/K | D | 25 | NCOND1 | IR1 | | NCOND1 |
|  | R | 27 | | | | |
| 10/L | D | 33 | NCOND2 | IR2 | | NCOND2 |
|  | R | 34 | | | | |
| 11/M | D | 35 | CLIS | IR3 | | CLIS |
|  | R | 36 | | | | |
| 12/N | D | 37 | RIO | PFI | | RIO |
|  | R | 38 | | | | |
| 13/P | D | 39 | IR0 | COND3 | | IR |
|  | R | 40 | | | | |
| 14/R | D | 45 | PR | RQ | | PR |
|  | R | 42 | | | | |

Component SIDE
Etch SIDE

| SIGMA 8/9 | | CONT | CONT | | |
|---|---|---|---|---|---|
| CPU | PBP | 15J,AG13 | 13J,AG60 | | |
|  | PBA | 21J,AG13 | 19J,AG60 | | |
| MIOP | PBP | 09D,AG13 | 03D,AG60 | | |
|  | PBA | 06D,AG13 | 01D,AG60 | | |
| RIOP | PBP | 18A,AG13 | 16A,AG60 | | |
|  | PBA | 13A,AG13 | 11A,AG60 | | |
| SIGMA 5/6/7 | | | | 5CPU | 05F,AT13 |
|  | | | | 6/7CPU | 29L,AT11 |
|  | | | | MIOP | 12C,AT13 |
|  | | | | SIOP | 10F,AT13 |

*These two signals are routed through the circular bus terminator locations, all other signals on cable one are terminated at these locations.

Sigma 8/9       Comp side       Etch side
      PBP       06E,ZT23 & 04E,ZT23 in the AUX Frame
      PBA       10E,ZT23 & 08E,ZT23 in the AUX Frame
PBP is Processor Bus Primary
PBA is Processor Bus Alternate (OPTIONAL)
      Bus selection is by SW1,03J CON CPU
                         SW1,01B    MIOP
                         SW1,09A    RIOP

## CPU – IOP INTERFACE

**ADRS0–ADRS4** Processor Address Lines – generated by CPU only.
If the Instruction is a TIO TDV SIO HIO POLP POLR or RIO, then lines contain Address of Processor that is to execute the indicated Instruction (FNC). If the Instruction is an AIO, then ADRS3 and 4 contain the number of the CPU issuing the AIO.

**AVL, AVL/IN** Bus Available – daisy chained signal used by the CPU's (8/9)
In a multiprocessor system, indicated that the Bus is not in use. Response to a RQ signal, requesting CPU will stop AVL/IN and not pass AVL to next CPU.

**CLIS** 1.024 MHz Clock – generated by CPU.
Crystal controlled signal driven continuously by the CPU.

**CNST** Control Strobe – daisey chained signal, originated by a CPU.
Causes Processors to interogate address lines (ADRS0–4), the processor that recognized address will process instruction (FNC0–2) and respond with PR.

**NCOND1,**
**NCOND2,** Condition Code Lines – driven by addressed processor.
**COND3** Indicates condition code information to the CPU.
COND3 used only by Sigma 8/9.

**FNC0–FNC2** Function Code Lines – generated by the CPU.
Indicates the instruction that the addressed processor is to perform.
000 = SIO                                    100 = RIO (8/9)
001 = TIO                                    101 = POLP (8/9)
010 = TDV                                    110 = AIO
011 = HIO                                    111 = POLR (8/9)

**HMSP0–**
**HMSP5** Homespace Bias – bidirectional lines (8/9)
During TIO TDV SIO or HIO instructions, the CPU sends Homespace so the IOP can access the correctly biased cell 20 and 21. During POLP or POLR instructions, the addressed processor indicates failure to CPU.



|       | 8/9 CPU | 8/9 MIOP | RIOP |
|-------|---------|----------|------|
| HMSP0 | INST. EXCP. TRAP | N/A | N/A |
| HMSP1 | DATA BUS CHECK | DATA BUS CHECK | DATA BUS CHECK |
| HMSP2 | MEMORY PARITY E | CONTROL CHECK | N/A |
| HMSP3 | WATCHDOG TIMER | N/A | N/A |
| HMSP4 | MAP PARITY ERR | N/A | N/A |

## CPU - IOP Interface (Continued)

IRO-IR3      Interrupt Request Lines - generated by IOP's
Triggers CPU interrupt X'5C'.  One line assigned to each CPU in a multi-processor system.

PFI      Processor Fault Interrupt - generated by erring processor (8/9)
Triggers CPU interrupt X'56'.  Enabled by BCF or CCF in IOP's.  Enabled by double PDF in CPU.

PR      Proceed - generated by addressed processor
Indicates addressed processor has completed function (FNC0-2).  CNST and PR work in a closed-loop manner.

RQ      REQUEST - generated by CPU and used only by CPU (8/9)
CPU desiring use of Bus raises this line to request usage of bus then waits for AVL/IN before using Bus.

RIO      Reset I/O - generated by CPU
Raised by I/O RESET or SYST RESET switches on PCP or during power up or power down.

## SIGMA 9 HIGH-SPEED RAD INTERFACE

| CABLE | | BACK PANEL | Cable 1 | Cable 2 | Cable 3 | | Cable 1 | Cable 2 | Cable 3 |
|---|---|---|---|---|---|---|---|---|---|
| 1/A | D R | 2 6 | CMD1 | CMD3 | STAT1 | | WENR | | Pin # for AT27 |
| 2/B | D R | 1 4 | CMD2 | CMD4 | STAT2 | | RENR | | |
| 3/C | D R | 9 10 | DATA06 | CLOCK | STAT3 | | RD3D WD6R | | DV0D(07) |
| 4/D | D R | 3 8 | DATA07 | ID2 | | | DS3D WD7R | | |
| 5/E | D R | 12 13 | DATA05 | CLEAR | ADDST7 | | DS1D WD5R | NMANRST | TRPD(19) |
| 6/F | D R | 15 18 | DATA04 | STAT0 | ADDST6 | | RD1D WD4R | DVTD | AN6D(21) |
| 7/G | D R | 19 20 | DATA03 | DATA15 | ADDST5 | | DS2D WD3R | DS7D | AN5D(20) |
| 8/H | D R | 23 22 | DATA02 | DATA14 | ADDST4 | | RD2D WD2R | RD7D | AD4D(33) |
| 9/K | D R | 25 27 | DATA01 | DATA13 | ADDST3 | | DS0D WD1R | DS5D | AN3D(31) |
| 10/L | D R | 33 34 | DATA00 | DATA12 | ADDST2 | | RD0D WD0R | RD5D | AN2D(34) |
| 11/M | D R | 35 36 | WCL | DATA11 | ADDST1 | | SC2R | DS6D | AN1D(44) |
| 12/N | D R | 37 38 | CMD0 | DATA10 | ADDST0 | | SLNR | RD6D | AN0D(45) |
| 13/P | D R | 39 40 | ID1 | DATA09 | SP | | ID1R | DS4D | SPD(46) |
| 14/R | D R | 45 42 | ID0 | DATA08 | IP | | ID0R | RD4D | IPD(47) |
| SIGMA 9 RIOP UB: | | | 21H,AG70 | 07H,AG70 | 27H,AG70 | | | | |
| 7212 H.S. RAD SELECTION UNIT | | | | | | | 30A,AT11 | 32A,AT11 | 32B,AT27 |
| 7211 H.S. RAD CONTROLLER | | | | | | | 11A,AT11 | 22A,AT11 | 30A,AT11 |

Signal names given at H.S. RAD Selection Unit Interface.

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## 7212 HIGH SPEED RAD INTERFACE

AN0–AN6          Angular Position – sent by Unit Selected
                Indicates the sector that is currently under the Heads.

DS0–DS7         Data Strobe – sent by Unit Selected
                Used to clock associated data channel (RD0–RD7) into the deskew logic
                in the Controller during a read operation.

DVT             Device Test – sent by Addressed Unit
(STAT0)         True if storage unit is being addressed and is operational (Disc up to speed
                and AC/DC power stable).

DVO             Device Operational – sent by Unit Selected
(STAT3)         True if storage unit is selected and is operational (Disc up to speed and
                AC/DC power stable).  Monitored by controller during operation.

ID0–ID1         Identification Lines – sent by Controller
                Specifies one of four storage units during an I/O Instruction.

IP              Index Pulse – sent by Unit Selected
                One pulse per revolution of the disc, identifies sector zero.

NMANRST         Not Reset Signal – sent by Controller
(CLEAR)         Inverted reset signal to all storage units.

RD0–RD7         Read Data – sent by Unit Selected
                Regenerated data from disk.  Clocked to controller during a read operation
                by clock DS0–DS7.

REN             Read Enable – sent by Controller
(CMD2)          Enables data decoders in Unit Selected.

SC2             3 MHz Write Clock – sent by Controller
(WCL)           Used by Unit Selected to encode and format data (WD0–WD7) for writing
                on the disc, enabled by write enable signal (WEN).

SLN             Select Now – sent by Controller
(CMD0)          Selects addressed (ID0 and 1) storage unit and deselects all other units
                during a SIO instruction.

SP              Sector Pulse – sent by Unit Selected
                80 pulses per revolution of disc, identifies beginning of next sector.

### 7212 High Speed RAD Interface (Continued)

TRP

Track Protected – sent by Unit Selected
True when selected band is write protected.

WD0–WD7

Write Data Lines – sent by Controller
During Write operation, Data for tracks 0 thru 7. During Sector Gap, Band
Address on WD2–WD7.

WEN
(CMD1)

Write Enable – sent by Controller
Enables write amplifiers, data encoders and clock doubler.

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## EP AND MS RAD INTERFACE

| CABLE | PANEL | | Cable 1 | Cable 2 |
|---|---|---|---|---|
| 1/A | D | 2 | DAT | IP |
| | R | 6 | | |
| 2/B | D | 1 | NMNRST | PWRMONR |
| | R | 4 | | |
| 3/C | D | 9 | SLN | DS |
| | R | 10 | | |
| 4/D | D | 3 | IDS | SP |
| | R | 8 | | |
| 5/E | D | 12 | DAM | DAI |
| | R | 13 | | |
| 6/F | D | 15 | WEN | TRP |
| | R | 18 | | |
| 7/G | D | 19 | REN | DVT |
| | R | 20 | | |
| 8/H | D | 23 | SC2 | DVO |
| | R | 22 | | |
| 9/K | D | 25 | SC1 | TYP0 |
| | R | 27 | | |
| 10/L | D | 33 | SAI | TYP1 |
| | R | 34 | | |
| 11/M | D | 35 | TRK | AN0 |
| | R | 36 | | |
| 12/N | D | 37 | ID0 | AN1 |
| | R | 38 | | |
| 13/P | D | 39 | ID1 | AN2 |
| | R | 40 | | |
| 14R | D | 45 | ID2 | AN3 |
| | R | 42 | | |
| E.P.RAD | | | | |
| CON. | 7231 | | 28A,AT12 | 26A,AT10 |
| DEV. | 7232 | | 03A,AT10 | 05A,AT12 |
| M.S.RAD | | | | |
| CON. | 7201 | | 32A,AT12 | 30A,AT10 |
| DEV. | 720X | | 18A,AT10 | 28A,AT12 |

SIGMA 9

ACCESS CODE CARD SELECTION (FG25)

| MPB REG ADDRESS | LM Lines 15 16 17 18 19 20 | OUTPUT BITS MPB15-22 |
|---|---|---|
| 00 - 3F | 0  0  C  BYTE | 24A |
| 40 - 7F | 0  1  L | 23A |
| 80 - BF | 1  0  M | 24B |
| C0 - FF | 1  1  N | 23B |
|  |  | AUX FRAME |

ACCESS CODE FINAL BIT SELECTION

| LM Lines | 21 22 |  | OUTPUT | BIT |
|---|---|---|---|---|
|  | 0  0 | Selects | MPB15 | MPD16 |
|  | 0  1 | Selects | MPB17 | MPB18 |
|  | 1  0 | Selects | MPB19 | MPB20 |
|  | 1  1 | Selects | MPB21 | MPB22 |
|  |  |  | MPB0 | MPB1 |

ACCESS CODE WRITE CLOCKS

| MPB REG ADDRESS | Bits 15-22 |
|---|---|
| 00 - 3F | MPBW.CK-13B21 |
| 40 - 7F | MPBW.CK-13B28 |
| 80 - BF | MPBW.CK-13B24 |
| C0 - FF | MPBW.CK-13B43 |
|  | AUXILIARY FRAME |

ACCESS CODE DATA INPUT BITS

| MPB REG ADDRESS | Bits 15-22 |
|---|---|
| 00 - 7F | S24-5 thru S31-5 |
| 80 - FF | S24-6 thru S31-6 |
|  | AUXILIARY FRAME |

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## SIGMA 9

MAP REGISTER CARD SELECTION (FG25)

| MAP REG ADDRESS | LM Lines 15 16 17 18 19 20 21 22 | | | | | | | | MAP REGISTER OUTPUTS MAP10-14 & P | MAP15-22 |
|---|---|---|---|---|---|---|---|---|---|---|
| 00 – 0F | 0 | 0 | 0 | 0 | C | BYTE | | | 32A | 22A |
| 10 – 1F | 0 | 0 | 0 | 1 | O | | | | 31A | 21A |
| 20 – 2F | 0 | 0 | 1 | 0 | L | | | | 30A | 20A |
| 30 – 3F | 0 | 0 | 1 | 1 | U | | | | 29A | 19A |
| 40 – 4F | 0 | 1 | 0 | 0 | M | | | | 32B | 22B |
| 50 – 5F | 0 | 1 | 0 | 1 | N | | | | 31B | 21B |
| 60 – 6F | 0 | 1 | 1 | 0 | | | | | 30B | 20B |
| 70 – 7F | 0 | 1 | 1 | 1 | | | | | 29B | 19B |
| 80 – 8F | 1 | 0 | 0 | 0 | | | | | 28A | 18A |
| 90 – 9F | 1 | 0 | 0 | 1 | | | | | 27A | 17A |
| A0 – AF | 1 | 0 | 1 | 0 | | | | | 26A | 16A |
| B0 – BF | 1 | 0 | 1 | 1 | | | | | 25A | 15A |
| C0 – CF | 1 | 1 | 0 | 0 | | | | | 28B | 18B |
| D0 – DF | 1 | 1 | 0 | 1 | | | | | 27B | 17B |
| E0 – EF | 1 | 1 | 1 | 0 | | | | | 26B | 16B |
| F0 – FF | 1 | 1 | 1 | 1 | | | | | 25B | 15B |
| | | | | | | | | | AUXILIARY FRAME | |

**MAP REGISTER WRITE CLOCKS**

| MAP REG ADDRESS | Bits 10–14 & P | Bits 15–22 |
|---|---|---|
| 00 – 3F 80 – BF | MAPW-1.CK-13B21 | MAPW-3.CK-13B28 |
| 40 – 7F C0 – FF | MAPW-2.CK-13B24 | MAPW-4.CK-13B43 |
| | AUXILIARY FRAME | |

**MAP REGISTER DATA INPUT BITS**

| MAP REG ADDRESS | Bits 10–14 & P | Bits 15–22 |
|---|---|---|
| 00 – 7F | S19-5 thru S23-5 SPARITY/BY23-1 | S24-5 thru S31-5 |
| 80 – FF | S19-6 thru S23-6 SPARITY/BY23-2 | S24-6 thru S31-6 |
| | AUXILIARY FRAME | |

**LB REGISTER TRANSFER TERMS**

| MAP REG ADDRESS | Bits 10–15 | Bits 16–22 |
|---|---|---|
| 00 – 7F | LBXMAP/A-1 | LBXMAP/A-2 |
| 80 – FF | LBXMAP/B-1 | LBXMAP/B-2 |
| | ADDRESS FRAME | |

## WRITE LOCKS CARD SELECTION (FG25)

| LK REG ADDRESS | 15 16 17 18 19 20 | OUTPUT BITS LK15–22 |
|---|---|---|
| 00 – 07<br>20 – 27<br>40 – 47<br>60 – 67<br>80 – 87<br>A0 – A7<br>C0 – C7<br>E0 – E7 | BYTE    0   0   C O L U M N | 21K |
| 08 – 0F<br>28 – 2F<br>48 – 4F<br>68 – 6F<br>88 – 8F<br>A8 – AF<br>C8 – CF<br>E8 – EF | 0   1 | 22K |
| 10 – 17<br>30 – 37<br>50 – 57<br>70 – 77<br>90 – 97<br>B0 – B7<br>D0 – D7<br>F0 – F7 | 1   0 | 23K |
| 18 – 1F<br>38 – 3F<br>58 – 5F<br>78 – 7F<br>98 – 9F<br>B8 – BF<br>D8 – DF<br>F8 – FF | 1   1 | 24K |
|  |  | ADD FRAME |

## WRITE LOCKS DATA INPUT BITS

| LK REG ADDRESS | Bits 15–22 |
|---|---|
| 00 – FF | S24–7 thru S31–7 |
|  | ADDRESS FRAME |

## WRITE LOCK WRITE CLOCKS

| LK REG ADDRESS | Bits 15–22 |
|---|---|
| 00 – FF | LKW.CK–31P22 |
|  | ADDRESS FRAME |

## WRITE LOCK FINAL BIT SELECTION

| LB Lines | 21 22 |  | OUTPUT | BIT |
|---|---|---|---|---|
|  | 0   0 | Selects | LK15 | LK16 |
|  | 0   1 | Selects | LK17 | LK18 |
|  | 1   0 | Selects | LK19 | LK20 |
|  | 1   1 | Selects | LK21 | LK22 |
|  |  |  | LK0 | LK1 |

SIGMA 8/9

GENERAL REGISTER CARD SELECTION

| REG BLOCK ADDRESS | RL Lines 26 27 28 29 30 31 | RR00-07 | OUTPUT BITS | | |
|---|---|---|---|---|---|
| | | | RR08-15 | RR16-23 | RR24-31 |
| 0 | 0 0 C BYTE | 16K | 13K | 14K | 15K |
| 1 | 0 1 L U | 10K | 05K | 06K | 08K |
| 2 | 1 0 M N | 04Q | 01Q | 02Q | 03Q |
| 3 | 1 1 | 26S | 30S | 29S | 27S |
| | | REGISTER FRAME | | | |

REGISTER CLOCKS

| REG BLOCK ADDRESS | RR00-07 | RR08-15 | RR16-23 | RR24-31 |
|---|---|---|---|---|
| 0 - 3 | RWBY0. CK-03P03 | RWBY1. CK-03P06 | RWBY2. CK-03P43 | RWBY3. CK-03P50 |

REGISTER INPUT BITS

| REG BLOCK ADDRESS | RR00-31 |
|---|---|
| 0 - 3 | S00 thru S31 |

SIGMA 6/7

## MAP REGISTER CARD SELECTION (FT25)

| MAP REG ADDRESS | 15 | 16 | 17 | 18 | 19 | 20 | 21 | 22 | OUTPUT BITS MAP15–22 |
|---|---|---|---|---|---|---|---|---|---|
| 00 – 0F | 0 | 0 | 0 | 0 | C | BYTE | | | 17Y |
| 10 – 1F | 0 | 0 | 0 | 1 | O | | | | 18Y |
| 20 – 2F | 0 | 0 | 1 | 0 | L | | | | 19Y |
| 30 – 3F | 0 | 0 | 1 | 1 | U | | | | 20Y |
| 40 – 4F | 0 | 1 | 0 | 0 | M | | | | 21Y |
| 50 – 5F | 0 | 1 | 0 | 1 | N | | | | 22Y |
| 60 – 6F | 0 | 1 | 1 | 0 | | | | | 23Y |
| 70 – 7F | 0 | 1 | 1 | 1 | | | | | 24Y |
| 80 – 8F | 1 | 0 | 0 | 0 | | | | | 25Y |
| 90 – 9F | 1 | 0 | 0 | 1 | | | | | 26Y |
| A0 – AF | 1 | 0 | 1 | 0 | | | | | 27Y |
| B0 – BF | 1 | 0 | 1 | 1 | | | | | 28Y |
| C0 – CF | 1 | 1 | 0 | 0 | | | | | 29Y |
| D0 – DF | 1 | 1 | 0 | 1 | | | | | 30Y |
| E0 – EF | 1 | 1 | 1 | 0 | | | | | 31Y |
| F0 – FF | 1 | 1 | 1 | 1 | | | | | 32Y |

## MAP REGISTER WRITE CLOCKS

| MAP REG ADDRESS | Bits 15–22 |
|---|---|
| 00 – 4F | MAPW.CK24U08 |
| 50 – FF | MAPW-1.CK24U08 |

## LB REGISTER TRANSFER TERMS

| MAP REG ADDRESS | Bits 15–22 |
|---|---|
| 00 – FF | MAP-1 & MAP |

## MAP REGISTER DATA INPUT BITS

| MAP REG ADDRESS | Bits 15–22 |
|---|---|
| 00 – 4F | D24 thru D31 |
| 50 – FF | MAPW15 thru MAPW22 |

## SIGMA 6/7

### LOCK CODE CARD SELECTION (FT25)

| LOCK REG ADDRESS | LB Lines 15 16 17 18 19 20 | OUTPUT BITS LOCK15-22 |
|---|---|---|
| 00 - 3F | 0  0  C    BYTE | 05Y |
| 40 - 7F | 0  1  O L | 06Y |
| 80 - BF | 1  0  U M | 07Y |
| C0 - FF | 1  1  N | 08Y |

### LOCK CODE FINAL BIT SELECTION

| LB Lines | 21 22 | | OUTPUT BITS | |
|---|---|---|---|---|
| | 0  0 | Selects | LOCK15 | LOCK16 |
| | 0  1 | Selects | LOCK17 | LOCK18 |
| | 1  0 | Selects | LOCK19 | LOCK20 |
| | 1  1 | Selects | LOCK21 | LOCK22 |
| | | | LOCK0 | LOCK1 |

### LOCK REGISTERS

| | LOCK REG ADDRESS | Bit 15-22 |
|---|---|---|
| WRITE CLOCK - | 00 - FF | LOCKW.CK-24U04 |
| INPUT BITS - | 00 - FF | NMAP15 thru NMAP22 |

SIGMA 6/7

PROGRAM CONTROL BITS CARD SELECTION (FT25)

| PCB REG ADDRESS | LM Lines 15 16 17 18 19 20 | OUTPUT BITS PCB15-22 |
|---|---|---|
| 00 - 3F | 0  0  C  BYTE | 09Y |
| 40 - 7F | 0  1  L | 10Y |
| 80 - BF | 1  0  M | 11Y |
| C0 - FF | 1  1 | 12Y |

PROGRAM CONTROL BITS FINAL BIT SELECTION

| LM Lines | 21  22 | | OUTPUT BITS | |
|---|---|---|---|---|
| | 0  0 | Selects | PCB15 | PCB16 |
| | 0  1 | Selects | PCB17 | PCB18 |
| | 1  0 | Selects | PCB19 | PCB20 |
| | 1  1 | Selects | PCB21 | PCB22 |
| | | | NPCB0 | NPCB1 |

PROGRAM CONTROL BITS

| | PCB REG ADDRESS | Bits 15-22 |
|---|---|---|
| WRITE CLOCK - | 00 - FF | PCBW.CK24U06 |
| INPUT BITS - | 00 - FF | NMAP15 thru NMAP22 |

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SIGMA 6/7

## GENERAL REGISTER CARD SELECTION (FT25)

| REG BLOCK ADDRESS | 23 24 25 26 27 | RR0-7 | RR8-15 | RR16-23 | RR24-31 |
|---|---|---|---|---|---|
| 0 | 0 0 0 0 0 | 01T | 15T | 01L | 01Q |
| 1 | 0 0 0 0 0 | 02T | 16T | 02L | 02Q |
| 2 | 0 0 0 1 0 | 03T | 17T | 03L | 03Q |
| 3 | 0 0 0 1 1 | 04T | 18T | 04L | 04Q |
| REGISTER SELECTION BITS | | LR28-1<br>LR29-1<br>LR30-1<br>LR31-1 | | LR28-2<br>LR29-2<br>LR30-2<br>LR31-2 | LR28-1<br>LR29-1<br>LR30-1<br>LR31-1 |

## REGISTER CLOCKS

| REG BLOCK ADDRESS | RR0-7 | RR8-15 | RR16-23 | RR24-31 |
|---|---|---|---|---|
| 0 - 3 | RWB0.<br>CK-32P47 | RWB1.<br>CK-32P45 | RWB2.<br>CK-32P42 | RWB3.<br>CK-32P43 |

## REGISTER INPUT BITS

| REG BLOCK ADDRESS | RR0-31 |
|---|---|
| 0 - 3 | RW0-31 |

## SIGMA 5

### GENERAL REGISTER CARD SELECTION (FT25)

| REG BLOCK ADDRESS | RP Lines 24 25 26 27 | OUTPUT BITS | | | |
|---|---|---|---|---|---|
| | | RR0–7 | RR8–15 | RR16–23 | RR24–31 |
| 0 | 0  0  0  0 | 09K | 19K | 05S | 09T |
| 1 | 0  0  0  1 | 10K | 18K | 06S | 10T |
| 2 | 0  0  1  0 | 11K | 17K | 07S | 11T |
| 3 | 0  0  1  1 | 12K | 16K | 08S | 12T |
| REGISTER SELECTION BITS | | NIOFM/1 LR28-1 LR29-1 LR30-1 LR31-1 | | NIOFM-1 LR28-0 LR29-0 LR30-0 LR31-0 | |

### REGISTER CLOCKS

| REG BLOCK ADDRESS | RR0–7 | RR8–15 | RR16–23 | RR24–31 |
|---|---|---|---|---|
| 0 - 3 | RWB0. CK–32P42 | RWB1. CK–32P38 | RWB2. CK–32P45 | RWB3. CK–32P47 |

### REGISTER INPUT BITS

| REG BLOCK ADDRESS | RR0–31 |
|---|---|
| 0 - 3 | RW0 thru RE31 |

SIGMA 8/9 CPU SWITCHES

|  | CONT 03J,SG10 | CONT 02J,SG10 | AUX 03D,SG10 |
|---|---|---|---|
| SW1 | NKPBALT | KCPUN0/D | INTCTRSW1 |
| SW2 | KHMSP12 | KCPUN1/D | INTCTRSW2 |
| SW3 | KHMSP13 | KPBCPUEND | INTCTRSW3 |
| SW4 | KHMSP14 | NKMPCUOP | INTCTRSW4 |
| SW5 | KHMSP15 | – | INTCTRSW5 |
| SW6 | KHMSP16 | – | INTCTRSW6 |
| SW7 | KHMSP17 | – | – |

| INTCTRSW | 1 & 2 = Counter 1 | | |
|---|---|---|---|
| INTCTRSW | 3 & 4 = Counter 2 | | |
| INTCTRSW | 5 & 6 = Counter 3 | | |
|  | 0 | 0 | 500Mhz |
|  | 0 | 1 | PWRFREQ |
|  | 1 | 0 | 2Khz |
|  | 1 | 1 | EXT FREQ |

SIGMA 8/9 MIOP SWITCHES

|  | 01B,SG10 | 07B,LG26 | 09C,LG26 |
|---|---|---|---|
| SW1 | PB/PRIM | DION0 | – |
| SW2 | DIOABLE/SW | DION1 | CPUN0 |
| SW3 | NCLKMGHI | DION2 | CPUN1 |
| SW4 | – | DION3 | CCUN0 |
| SW5 | – | DION4 | CCUN1 |
| SW6 | – | DION5 | CCUN2 |
| SW7 | – | DION6 | CCUN3 |

SIGMA 9 RIOP SWITCHES

|  | 09A,SG10 | 05A,LG26 | 20A,LG26 |
|---|---|---|---|
| SW1 | PRIALT | MI:ADRSW4 | CPUN0 |
| SW2 | MI:DISABLE | MI:ADRSW5 | CPUN1 |
| SW3 | – | MI:ADRSW6 | RIOPN0 |
| SW4 | – | MI:ADRSW7 | RIOPN1 |
| SW5 | – | MI:ADRSW8 | RIOPN2 |
| SW6 | UBABLE | MI:ADRSW9 | RIOPN3 |
| SW7 | TYPE1/1 | MI:ADRSW10 | RIOPN4 |

## SIGMA 8/9 MEMORY SWITCHES

|  | DRIVER A 31B, ST49 | DRIVER A 31C, ST49 | DRIVER A 31A, ST49 |
|---|---|---|---|
| SW1 | SW:UN0 | SW:L12/SA* | CM0 |
| SW2 | SW:UN1 | SW:L13/SA* | CM1 |
| SW3 | SW:UN2 | SW:L14/SA* | CM2 |
| SW4 | SW:UN3 | SW:L15/SA* | CM3 |
| SW5 | – | SW:L16/SA* | CM4 |
| SW6 | SW:L10/SA* | SW:L17/SA* | SW:IL/BBIU* |
| SW7 | SW:L11/SA* | SW:L18/SA* | SW:IL/BTU* |

| DRIVER B 31A, AT49 |  |
|---|---|
| CM0 | Early Write |
| CM1 | Late Write |
| CM2 | Early Strobe |
| CM3 | Late Strobe |
| CM4 | Early DR, PE, POK |
| – |  |
| – |  |

|  | MATRIX 0 02C, SG10 | MATRIX 1 02C, SG10 | MATRIX 2 02C, SG10 |
|---|---|---|---|
| SW1 | INHP1* | INHP5* | INHP9 * |
| SW2 | INHP2* | INPH6* | INHP10* |
| SW3 | INHP3* | INHP7* | INHP11* |
| SW4 | INHP4* | INHP8* | INHP12* |
| SW5 | – | – | – |
| SW6 | – | – | – |
| SW7 | – | – | – |

*These Switches must be in the UP position to enable the Remote Cable to the Memory Configuration Panel (MCP).

## SIGMA 5/7 8265/8465 MEMORY SWITCHES

|  |  | 31C | 29C | PORT 1/5 |
|---|---|---|---|---|
|  |  | 20C | 18C | PORT 2/6 |
|  |  | 15C | 13C | PORT 3/7 |
|  |  | 04C | 02C | PORT 4/8 |
|  | DRIVER A 29B,ST49 | MATRIX ,ST49 | MATRIX ,ST49 |  |
| SW1 | BN0 | L15ASW | L15BSW |  |
| SW2 | BN1 | L16ASW | L16BSW |  |
| SW3 | BN2 | L17ASW | L17BSW |  |
| SW4 | BN3 | L18ASW | L18BSW |  |
| SW5 | AUXENB | ENBASW | ENBBSW |  |
| SW6 | IL4 | BUSPARSW | – |  |
| SW7 | IL2 | CPUBUSSW |  |  |

## SIGMA 5/7 8265/8465 MEMORY CONFIGURATION INFORMATION

| | | | | |
|---|---|---|---|---|
| SW1 | | BN0 | L15ASW | L15BSW |
| SW2 | | BN1 | L16ASW | L16BSW |
| SW3 | | BN2 | L17ASW | L17BSW |
| SW4 | | BN3 | L18ASW | L18BSW |
| SW5 | | AUXENB | ENBASW | ENBBSW |
| SW6 | | IL4 | BUSPARSW | – |
| SW7 | | IL2 | CPUBUSSW | – |
| | | 29B, ST49<br>DRIVER A | ST49<br>MATRIX<br>Port1–31C<br>Port2–20C<br>Port3–15C<br>Port4–04C | ST49<br>MATRIX<br>Port1–29C<br>Port2–18C<br>Port3–13C<br>Port4–02C |
| CABLE PANEL | | CABLE | CABLE | CABLE |
| A | 01 | R:BN3 | RPi:L18A | RPi:L18B |
| B | 07 | R:BN2 | RPi:L17A | RPi:L17B |
| C | – | – | – | – |
| D | 24 | R:IL2 | RPi:CPUBUS | – |
| E | – | – | – | – |
| F | – | – | – | – |
| G | 26 | R:IL4 | RPi:BUSPAR | – |
| H | – | – | – | – |
| K | – | – | – | – |
| L | 10 | | | |
| M | 28 | R:AUXENB | RPi:ENBA | RPi:ENBB |
| N | – | – | – | – |
| P | 30 | R:BN1 | RPi:L16A | RPi:L16B |
| R | 44 | R:BN0 | RPi:L15A | RPi:L15B |

## SIGMA 9 MEMORY REMOTE CONFIGURATION CABLE

| PIN | | CABLE |
| CABLE | PANEL | |
|---|---|---|
| A | 1 | - |
| B | 3 | - |
| C | 7 | - |
| D | 10 | - |
| E | 14 | L/R:IL/BBIU |
| F | 18 | L/R:IL/BTU |
| G | 22 | L/R:L10/SA |
| H | 26 | L/R:L11/SA |
| K | 30 | L/R:L12/SA |
| L | 34 | L/R:L13/SA |
| M | 38 | L/R:L14/SA |
| N | 42 | L/R:L15/SA |
| P | 45 | L/R:L16/SA |
| R | 50 | L/R:L17/SA |
| 1 | 4 | L/R:L18/SA |
| 2 | 6 | - |
| 3 | 8 | L/R:INHP1 |
| 4 | 12 | L/R:INHP2 |
| 5 | 17 | L/R:INHP3 |
| 6 | 19 | L/R:IMHP4 |
| 7 | 21 | L/R:INHP5 |
| 8 | 24 | L/R:INHP6 |
| 9 | 28 | L/R:INHP7 |
| 10 | 33 | L/R:INHP8 |
| 11 | 36 | L/R:INHP9 |
| 12 | 40 | L/R:INHP10 |
| 13 | 43 | L/R:INHP11 |
| 14 | 47 | L/R:INHP12 |
| | | 30D,ZT23 DRIVER A |

## Port Expansion and Maintenance Switches

| Memory Location 20C |
| --- |
| is PORT B expanded? Yes, set S1-1 |
| is PORT A expanded? Yes, set S1-2 |
| For maintenance MQA set S1-3 |
| For maintenance MQB set S1-4 |
| For maintenance MQC set S1-5 |

## Priority Int LT16 Switches

Prior. Int Chas ST14 1J

| If LT16 is in Loc | Set Switches | Int Level LSD |
| --- | --- | --- |
| 7J | None | X0,X1 |
| 8J | S1-1,S1-2 | X2,X3 |
| 9J | S1-3,S1-4 | X4,X5 |
| 10J | S1-5,S1-6 | X6,X7 |
| 14J | S1-7,S1-8 | X8,X9 |
| 15J | S1-9,S1-10 | XA,XB |
| 16J | S1-11,S1-12 | XC,XD |
| 17J | S1-13 | XE,XF |

## Memory Fault-Door Number

| Mem 21C | S1-8 | S1-9 | S1-10 |
| --- | --- | --- | --- |
| Door 0 | 0 | 0 | 0 |
| Door 1 | 0 | 0 | 1 |
| Door 2 | 0 | 1 | 0 |
| Door 3 | 0 | 1 | 1 |
| Door 4 | 1 | 0 | 0 |
| Door 5 | 1 | 0 | 1 |
| Door 6 | 1 | 1 | 0 |
| Door 7 | 1 | 1 | 1 |

## Interleave Block Size

| Mem 21C | S1-3 | S1-4 | S1-5 | S1-6 |
| --- | --- | --- | --- | --- |
| None | 0 | 0 | 0 | 0 |
| 8K | 1 | 0 | 0 | 0 |
| 16K | 0 | 1 | 0 | 0 |
| 32K | 0 | 0 | 1 | 0 |
| 64K | 0 | 0 | 0 | 1 |

## Memory Size

| Mem 21C | S1-1 | S1-2 |
| --- | --- | --- |
| 4K | 0 | 0 |
| 8K | 0 | 1 |
| 12K | 1 | 0 |
| 16K | 1 | 1 |

## Real Time Clock

| CPU Location 24W | | | |
| --- | --- | --- | --- |
| FREQ | CP3 | CP2 | CP1 |
| 8KHZ | S1-5 | S1-10 | S1-15 |
| 2KHZ | S1-4 | S1-9 | S1-14 |
| 500HZ | S1-3 | S1-8 | S1-13 |
| LINE | S1-2 | S1-7 | S1-12 |
| EXT. | above sw's off | above sw's off | above sw's off |

ea. for 8KHZ
CP3 set (1)
S1-5, reset
(0) S1-4,
S1-3, S1-2

| 8411 Opt. | LT16 in 15W? No set S1-1,S1-6 |
| --- | --- |
| Unass. Int. | LT16 in 23W? No set S1-11 |



O ST14

## Memory Starting Address (8451)

Port expanders F and S

| Set starting addr sw's for | | L15 | L16 | L17 | L18 | L19 |
| --- | --- | --- | --- | --- | --- | --- |
| Memory | (20C) Port A | S11 | S12 | S13 | S14 | S15 |
| | (20C) Port B | S6 | S7 | S8 | S9 | S10 |
| | (21C) Port C | S11 | S12 | S13 | S14 | S15 |
| F(24D) S(21E) Port 1 | | S1 | S2 | S3 | S4 | S5 |
| F(24D) S(21E) Port 2 | | S6 | S7 | S8 | S9 | S10 |
| F(25D) S(22E) Port 3 | | S1 | S2 | S8 | S4 | S5 |
| F(25D) S(22E) Port 4 | | S6 | S7 | S8 | S9 | S10 |
| | Bit weight | 64K | 32K | 16K | 8K | 4K |

## Priority Int. Group Addresses

Prior. Int. Chas. LT26 30J

| For Group | S1-1 | S2-1 | S3-1 | S4-1 | Group | S1-1 | S2-1 | S3-1 | S4-1 |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| 2 | 0 | 0 | 1 | 0 | 9 | 1 | 0 | 0 | 1 |
| 3 | 0 | 0 | 1 | 1 | A | 1 | 0 | 1 | 0 |
| 4 | 0 | 1 | 0 | 0 | B | 1 | 0 | 1 | 1 |
| 5 | 0 | 1 | 0 | 1 | C | 1 | 1 | 0 | 0 |
| 6 | 0 | 1 | 1 | 0 | D | 1 | 1 | 0 | 1 |
| 7 | 0 | 1 | 1 | 1 | E | 1 | 1 | 1 | 0 |
| 8 | 1 | 0 | 0 | 0 | F | 1 | 1 | 1 | 1 |



O LT26

## MS DIO Addr

| MS LT26 21A | |
| --- | --- |
| S1-1 | A10 |
| S2-1 | A9 |
| S3-1 | A8 |
| S4-1 | A7 |
| S1-2 | A6 |
| S2-2 | A5 |
| S3-2 | A4 |
| S4-2 | A3 |

| Switches on 23A and 22A must be up | To disable MS, put switch on 23A down |
| --- | --- |

## Sub Controller DVC Number

| DVC Controller Loc 24 LT16 | | | | | | | | |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Addr Bit | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
| Switch | S4-2 | S3-2 | S2-2 | S1-2 | S4-1 | S3-1 | S2-1 | S1-1 |

## REU Address

| REU Chas. LT26 32A | | | |
| --- | --- | --- | --- |
| For BLKs | S3-2 | S3-1 | S2-2 |
| 4-7 | 0 | 0 | 1 |
| 8-11 | 0 | 1 | 0 |
| 12-15 | 0 | 1 | 1 |
| 16-19 | 1 | 0 | 0 |
| 20-23 | 1 | 0 | 1 |
| 24-27 | 1 | 1 | 0 |
| 28-31 | 1 | 1 | 1 |

## SIOP

| SIOP Chas. LT26 8F | |
| --- | --- |
| Switch | Function |
| S1-1 | IOP address bit 0 |
| S1-2 | Set if high priority bus shar. IOP |
| S2-1 | IOP address bit 1 |
| S2-2 | Set if bus shar. opt |
| S3-1 | IOP address bit 2 |
| S4-1 | Set if last IOP |

## MIOP

| MIOP Chas. LT26 13C | |
| --- | --- |
| Switch | Function |
| S1-1 | IOP address bit 0 |
| S1-2 | Set if last IOP |
| S2-1 | IOP address bit 1 |
| S2-2 | Set if 4 byte opt(8473) |
| S3-1 | IOP address bit 2 |
| S3-2 | Set if high prior bus sharing IOP (8473) |

CFE-3

| CFE cont. chosis LT26 3A | |
| --- | --- |
| Switch | Function |
| S1-1,S1-2 | |
| S2-1,S2-2 | for test mode |
| S3-1 | Test mode (1) |
| S3-2 | Test mode clear |
| S4-1 | CFE controller (0 or 1) |
| S4-2 | Test selector 1→test 2 |

# MATRIX SWITCH SETTINGS

| PORT | | | 1 OR 5 | | 2 OR 6 | | 3 OR 7 | | 4 OR 8 | |
|---|---|---|---|---|---|---|---|---|---|---|
| BANK | | | A | B | A | B | A | B | A | B |
| SLOT | | | 31 | 29 | 20 | 18 | 15 | 13 | 04 | 02 |
| STARTING | 64K | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | 32K | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| ADDRESS | | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | 16K | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | 8K | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| PARTITION PORT OUT | YES | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| | | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ | ◯ |
| CHECK INCOMING DATA PARITY | YES | ◯ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ |
| | | ◯ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ |
| CPU BUS | YES | ◯ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ |
| | | ◯ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ | ◯ | ✕ |

CPU BUS — If this switch is in the "yes" position any port encountering a parity error will cause the PE line for this port to be raised.

BLACKEN CIRCLES IN PENCIL TO REPRESENT NORMAL SYSTEM SETTINGS

# DRIVER SWITCH SETTINGS
## SLOT 29B

MSB

BANK NO. =

MEMORY FAULT
INDICATOR–1

LSB

AUXILIARY BUS
PARTITIONED OUT

FOUR WAY INTERLEAVE

TWO WAY INTERLEAVE

**BLACKEN CIRCLES IN PENCIL TO
INDICATE NORMAL SYSTEM
SETTINGS**

TYPICAL RELATIONSHIPS 30 OHM CABLE CARDS

## AT10



| P3 | P1 | P2 |
|----|----|----|
| A | 6 | 1 |
| B | 4 | 2 |
| C | 10 | 3 |
| D | 8 | 4 |
| E | 13 | 5 |
| F | 18 | 6 |
| G | 20 | 7 |
| H | 22 | 8 |
| K | 27 | 9 |
| L | 34 | 10 |
| M | 36 | 11 |
| N | 38 | 12 |
| P | 40 | 13 |
| R | 42 | 14 |

## AT12



| P3 | P1 | P2 |
|----|----|----|
| A | 2 | 1 |
| B | 1 | 2 |
| C | 9 | 3 |
| D | 3 | 4 |
| E | 12 | 5 |
| F | 15 | 6 |
| G | 19 | 7 |
| H | 23 | 8 |
| K | 25 | 9 |
| L | 33 | 10 |
| M | 35 | 11 |
| N | 37 | 12 |
| P | 39 | 13 |
| R | 45 | 14 |

## AT11



| P3 | P1 | P1 | P2 |
|----|----|----|----|
| A | 6 | 2 | 1 |
| B | 4 | 1 | 2 |
| C | 10 | 9 | 3 |
| D | 8 | 3 | 4 |
| E | 13 | 12 | 5 |
| F | 18 | 15 | 6 |
| G | 20 | 19 | 7 |
| H | 22 | 23 | 8 |
| K | 27 | 25 | 9 |
| L | 34 | 33 | 10 |
| M | 36 | 35 | 11 |
| N | 38 | 37 | 12 |
| P | 40 | 39 | 13 |
| R | 42 | 45 | 14 |

## AT13



| P3 | P1 | P1 | P2 |
|----|----|----|----|
| A | 6 | 2 | 1 |
| B | 4 | 1 | 2 |
| C | 10 | 9 | 3 |
| D | 8 | 3 | 4 |
| E | 13 | 12 | 5 |
| F | 18 | 15 | 6 |

| K | 27 | 25 | 9 |
|----|----|----|----|
| L | 34 | 33 | 10 |
| M | 36 | 35 | 11 |
| N | 38 | 37 | 12 |
| P | 40 | 39 | 13 |
| R | 42 | 45 | 14 |



| P3 | P1 |
|----|----|
| G | 20 |
| H | 22 |

| 19 | 7 |
|----|----|
| 23 | 8 |
| P1 | P2 |

AT10  AT12  AT11  AT13

P2  P1  P3

0

Component Side

Etched Side

50

AT

| P3 (Etch) | P2 (Component) |
|-----------|----------------|
| Ground | Ground |
| A | 1 |
| Ground | Ground |
| B | 2 |
| Ground | Ground |
| . | . |
| . | . |
| . | . |
| Ground | Ground |
| P | 13 |
| Ground | Ground |
| R | 14 |
| Ground | Ground |

8457 F 3 to 6 port expander 1 memory assy 130625
8457 S 3 to 6 port expander 2nd memory assy 130626
Module Location Chart – 133621
Installation Drawing Port Exp F  133762
Installation Drawing Port Exp S  133688
Switch Settings – see system switch settings
   ST14S  24D,25E  F expander
           21E,22E  S expander
Cables connecting sources to port expander are connected normal from the bottom, but are attached upside down at the port expander. Cable pin numbers will have to be transposed when using the signal map in the interface section.

Port Ex. Memory Cables, twisted pair ZT38

| | FROM | | TO | |
|---|---|---|---|---|
| Twisted Pair | XF | XS | Port A | Port B |
| Mem Cab #1 | 6C | 8C | 2A | 6A |
| #2 | 11C | 13C | 2B | 6B |
| #3 | 17C | 19C | 4A | 4B |
| #4 | 21C | 23C | 4C | 2D |
| #5 | 25C | 27C | 6C | 4D |

Additional signals provided to the port expander, via the ZT38 modules, on memory interface cables 4 and 5.

| Port XF | | 21C | 25C |
|---|---|---|---|
| Port XS | | 23C | 27C |
| Mem Port A | | 4C | 6C |
| Mem Port B | | 2D | 4D |
| CABLE CONDUCTOR | MOD PINS | MEMORY CABLE 4 | MEMORY CABLE 5 |
| 15 | 7(S) | NR08 | START |
| | 11(L) | | |
| 16 | 17(S) | NR16 | TW500 |
| | 14(L) | | |
| 17 | 21(S) | NR32 | TO |
| | 26(L) | | |
| 18 | 29(S) | NR64 | NPFSRD |
| | 28(L) | | |
| 19 | 31(S) | NS1 | |
| | 30(L) | | |
| 20 | 43(S) | NS0 | |
| | 44(L) | | |
| 21 | 47(S) | (12K) | |
| | 46(L) | | |

(S) Source  e.g.  Memory Source Signal NR08 is provided
(L) Load        at pin 7 of the memory and is received at pin 11 in the Port Expander

SIGMA 7 PORT EXPANDER

14. SIGMA 5–9 INTERFACE AND SWITCH REFERENCE DATA

| PORT 1 | 2B  AT11 | 2D  AT11 | 10B  AT11 | 18D  AT10 | 26B  AT11 |
| PORT 2 | 4B  AT11 | 4D  AT11 | 12B  AT11 | 20B  AT10 | 28B  AT11 |
| PORT 3 | 6B  AT11 | 6D  AT11 | 14B  AT11 | 22B  AT10 | 30B  AT11 |
| PORT 4 | 8B  AT11 | 8D  AT11 | 16B  AT11 | 24B  AT10 | 32B  AT11 |

CABLES CONNECTING SOURCES TO PORT EXPANDER BUS ARE
CONNECTED NORMAL FROM THE BOTTOM, BUT ARE ATTACHED UPSIDE
DOWN AT THE PORT EXPANDER

| CABLE PINS | BACK PANEL PINS | MEMORY CABLE #1 | MEMORY CABLE #2 | MEMORY CABLE #3 | MEMORY CABLE #4 | MEMORY CABLE #5 |
|---|---|---|---|---|---|---|
| 13, P | 39 | M00D | M14D | M28D | L15D | MQD |
|       | 40 | M00R | M14R | M28R |      |     |
| 14, R | 45 | M01D | M15D | M29D | L16D | *   |
|       | 42 | M01R | M15R | M29R |      | AHR |
| 11, M | 35 | M02D | M16D | M30D | L17D | *   |
|       | 36 | M02R | M16R | M30R |      | ARR |
| 12, N | 37 | M03D | M17D | M31D | L18D | *   |
|       | 38 | M03R | M17R | M31R |      | DRR |
| 10, 6 | 33 | M04D | M18D | L29D | L19D | *   |
|       | 34 | M04R | M18R |      |      | PER |
| 9, K  | 25 | M05D | M19D | L30D | L20D | *   |
|       | 27 | M05R | M19R |      |      | SRAR |
| 8, H  | 23 | M06D | M20D | L31D | L21D | *   |
|       | 22 | M06R | M20R |      |      |     |
| 7, G  | 19 | M07D | M21D | MW0D | L22D | AB0D |
|       | 20 | M07R | M21R |      |      |     |
| 6, F  | 15 | M08D | M22D | MW1D | L23D | *   |
|       | 18 | M08R | M22R |      |      | POKR |
| 5, E  | 12 | M09D | M23D | MW2D | L24D | *   |
|       | 13 | M09R | M23R |      |      |     |
| 4, D  | 3  | M00D | M24D | MW3D | L25D | *   |
|       | 8  | M10R | M24R | *    |      |     |
| 3, C  | 9  | M11D | M25D | DGR  | L26D | *   |
|       | 10 | M11R | M25R | *    |      |     |
| 2, B  | 1  | M12D | M26D | EDRR | L27D | *   |
|       | 4  | M12R | M26R |      |      |     |
| 1, A  | 2  | M13D | M27D | *    | L28D | *   |
|       | 6  | M13R | M27R |      |      |     |

Σ7– 8457   MEMORY INTERFACE

ALL SIGNALS DESCRIBED FROM THE POINT OF VIEW OF THE MEMORY PORT EXPANDER.

## CPU EXTERNAL INTERRUPT INTERFACE

| Cable Pins | 8421 CPU Module Pins | 26J AT11 30V AT11 Ex Int/CPU | 12J AT11 Ex Int/EQ | 19J AT11 EX Int/EQ | 32J AT11 Ex Int/EQ |
|---|---|---|---|---|---|
| 1, A | 2 6 | LIN01 DAT17 | ECPURST2 | ECPURST1 | ECPURST |
| 2, B | 1 4 | LIN00 DAT16 | | | |
| 3, C | 9 10 | LIN03 DAT19 | | IS10 | IS4 |
| 4, D | 3 8 | LIN02 DAT18 | | IS11 | IS5 |
| 5, E | 12 13 | LIN04 DAT20 | IS15 | IS9 | IS3 |
| 6, F | 15 18 | LIN05 DAT21 | IS14 | IS8 | IS2 |
| 7, G | 19 20 | LIN06 DAT22 | IS13 | IS7 | IS1 |
| 8, H | 23 22 | LIN07 DAT23 | IS12 | IS6 | IS0 |
| 9, K | 25 27 | LIN08 DAT24 | | | |
| 10, L | 33 34 | LINREQ DAT25 | | ERQ11 ERQ10 | ERQ05 ERQ04 |
| 11, M | 35 36 | DAT26 | ERQ15 | ERQ9 | ERQ03 |
| 12, N | 37 38 | DAT27 | ERQ14 | ERQ8 | ERQ02 |
| 13, P | 39 40 | DAT28 | ERQ13 | ERQ7 | ERQ01 |
| 14, R | 45 42 | DAT29 | ERQ12 | ERQ6 | ERQ00 |

Interface Viewed At------External Interrupt Chassis------

## REU–CPU INTERFACE

| CPU | 5T AT11 | 19T AT11 | 5L AT11 | 5Q AT11 | 28U ZT23 | |
|---|---|---|---|---|---|---|
| REU | 27A AT11 | 15A AT11 | 25A AT11 | 6A AT11 | 30A ZT23 | |
| Cable Pins | Module Pins | Read/Write Byte 0 | Read/Write Byte 1 | Read/Write Byte 2 Address | Read/Write Byte 3 Address | Clock CPU | 1st REU |
| 1,A | 2 6 | | | NLR28-2 | RP24 | CREU1 | CRX2 |
| 2,B | 1 4 | | | LR28-2 | RP23 | CREU2 | CRX2 |
| 3,C | 9 10 | | | LR30-2 | RP26 | CREU3 | CRX3 |
| 4,D | 3 8 | | | LR29-2 | RP25 | CREU4 | CRX4 |
| 5,E | 12 13 | | | LR31-2 | RP27 | CREU5 | CRX5 |
| 6,F | 15 18 | RWB0 | RWB1 | RWB2 | RWB3 | CREU6 | CRX6 |
| 7,G | 19 20 | RR0 S0RRWXS/0 | RR8 S8RRWXS/1 | RR16 S16RRWXS/2 | RR24 S24RRWXS/3 | CREU7 | CRX7 |
| 8,H | 23 22 | RR1 S1RRWXS/0 | RR9 S9RRWXS/1 | RR17 S17RRWXS/2 | RR25 S25RRWXS/3 | | |
| 9,K | 25 27 | RR2 S2RRWXS/0 | RR10 S10RRWXS/1 | RR18 S18RRWXS/2 | RR26 S16RRWXS/3 | | |
| 10,L | 33 34 | RR3 S3RRWXS/0 | RR11 S11RRWXS/1 | RR19 S19RRWXS/2 | RR27 S2RRWXS/3 | | |
| 11,M | 35 36 | RR4 S4RRWXS/0 | RR12 S12RRWXS/1 | RR20 S20RRWXS/2 | RR28 S28RRWXS/3 | Signal presence governed by the installa-tion of the wire changes below. | |
| 12,N | 37 38 | RR5 S5RRWXS/0 | RR13 S13RRWXS/1 | RR21 S21RRWXS/2 | RR29 S29RRWXS/3 | | |
| 13,P | 39 40 | RR6 S6RRWXS/0 | RR14 S14RRWXS/1 | RR22 S22RRWXS/2 | RR30 S30RRWXS/3 | | |
| 14,R | 45 42 | RR7 S7RRWXS/0 | RR15 S15RRWXS/1 | RR23 S23RRWXS/2 | RR31 S31RRWXS/3 | | |

Signals represented from the
point of view of the REU.

| ZT23 Cable=Module Pins = Pins | |
|---|---|
| 1 A | 4 1 |
| 2 B | 6 3 |
| 3 C | 8 7 |
| 4 D | 12 10 |
| 5 E | 17 14 |
| 6 F | 19 18 |
| 7 G | 21 22 |
| 8 H | 24 26 |
| 9 K | 28 30 |
| 10 L | 33 34 |
| 11 M | 36 38 |
| 12 N | 40 42 |
| 13 P | 43 45 |
| 14 R | 47 50 |

Clocking–Clock Cable from the CPU Plugs into Position 30A of
REU No. 1. Coaxial (Part No. 128147-372) and Additional
CPU Wiring for REU's are as follows.

| | Add Wire Sigma 7, CPU | FROM Coax | Shield | TO Coax | Shield |
|---|---|---|---|---|---|
| For REU #1 | | 30A04 REU#1 | 30A02 | 12A13 REU#1 | 12A16 |
| 2 | 28U03-29U17 | 30A06 REU#1 | 30A05 | 12A13 REU#2 | 12A16 |
| 3 | 28U07-29U19 | 30A08 REU#1 | 30A09 | 12A13 REU#3 | 12A16 |
| 4 | 28U10-29U21 | 30A12 REU#1 | 30A13 | 12A13 REU#4 | 12A16 |
| 5 | 28U14-29U23 | 30A17 REU#1 | 30A16 | 12A13 REU#5 | 12A16 |
| 6 | 28U18-29U25 | 30A19 REU#1 | 30A21 | 12A13 REU#6 | 12A16 |
| 7 | 28U22-29U27 | 30A21 REU#1 | 30A23 | 12A13 REU#7 | 12A16 |

## CPU-DEC, CPU-PWR MON-MEM, CPU-IOP INTERFACES

| | | | | |
|---|---|---|---|---|
| | SIOP | | | 10F AT13 |
| | MIOP | | | 12C AT13 |
| | MEM | | 2C AT11 | |
| | DEC | 32C AT11 | | |
| | CPU | 18D AT11 | 30Q AT11 | 29L AT11 |
| | PWR MON | | J5 AT13 | |
| Cable Pins | Module Pins | DEC | PWR MON | IOP |
| 1,A | 2 | DU0 | (MFL1) | |
| | 6 | DU0 | | FNC0 |
| 2,B | 1 | DU1 | (MFL0) | |
| | 4 | DU1 | | FNC1 |
| 3,C | 9 | DU2 | (MFL3) | |
| | 10 | DU2 | | FNC2 |
| 4,D | 3 | DU3 | | |
| | 8 | DU3 | (ST) | IOPA0 |
| 5,E | 12 | DU4 | (MFL4) | |
| | 13 | DU4 | | IOPA1 |
| 6,F | 15 | DU5 | (MFL5) | |
| | 18 | DU5 | | IOPA2 |
| 7,G | 19 | DU6 | | |
| | 20 | DU6 | (RTC) | CNST |
| 8,H | 23 | DU7 | | |
| | 22 | DU7 | (IOEN) | |
| 9,K | 25 | | | NCC1 |
| | 27 | DUCLOCK | (ION) | |
| 10,L | 33 | | | NCC2 |
| | 34 | DUSTART | (IOFF) | |
| 11,M | 35 | DUEND | (MFL2) | |
| | 36 | | | 1MC |
| 12,N | 37 | | | |
| | 38 | DUCLEAR | | RIO |
| 13,P | 39 | DU12 | (MFL6) | IR |
| | 40 | DUMDM | | |
| 14,R | 45 | DU13 | (MFL7) | PR |
| | 42 | | | |
| Interface Viewed At | | DEC | MEMORY | IOP |

SIGMA 8/9 MIOP Single Phase Operation Program

This program will single phase the MIOP thru a complete SIO/IOCD sequence. After each phase step the program will come to a WAIT (location 117). At that time R1 will equal the number of step operations completed and R5 thru RF will contain status information for that phase (the attached sheets provide expected data for each operation). Modifications are provided to allow the program to be addressed to the TTY and/or to do single operation (each step will advance the MIOP thru a SIO, or 00, or DI or 0I operation).

| | | | | |
|---|---|---|---|---|
| 26 | 68000100 | B | X'100' | |

TRAP ROUTINE

| | | | | |
|---|---|---|---|---|
| 46 | 0F000080 | XPSD,0 | X'80' | |
| 80 | 00000000 | DATA | X'00000000' | |
| 81 | 00000000 | DATA | X'00000000' | |
| 82 | 00000084 | DATA | X'00000084' | |
| 83 | 00000000 | DATA | X'00000000' | |
| 84 | 0E100086 | LPSD,1 | X'86' | Clear PDF |
| 85 | 00000000 | | | |
| 86 | 0000010C | DATA | X'0000010C' | |
| 87 | 00000000 | DATA | X'00000000' | |

PROGRAM

| | | | | |
|---|---|---|---|---|
| 100 | 22100001 | LI,1 | X'01' | Initialize counter |
| 101 | 4F004000 | RIO,0 | X'000' | Reset MIOP |
| *102 | 22480000 | LI,4 | X'80000' | Put the M.S.Online and the |
| 103 | 6D40200F | WD,4 | X'200F' | Controllers Offline. |
| 104 | 22403000 | LI,4 | X'3000' | Wait for the AT83's to go Offline. |
| 105 | 64400105 | BDR,4 | X'105' | |
| 106 | 224700FF | LI,4 | X'700FF' | Set M.S. Address = 07 and |
| 107 | 6D40200D | WD,4 | X'200D' | Data byte = FF. |
| # 108 | 22401800 | LI,4 | X'1800' | Put the MIOP (CH A) in Single |
| 109 | 6D402008 | WD,4 | X'2008' | Phase Mode. |
| 10A | 22000090 | LI,0 | X'90' (120) | |
| *10B | 4C200007 | SIO,2 | X'007' | Start Operation |
| 10C | 6C502000 | RD,5 | X'2000' | |
| 10D | 6C602001 | RD,6 | X'2001' | Read CCU Groups |
| 10E | 6C702002 | RD,7 | X'2002' | |
| 10F | 6C802008 | RD,8 | X'2008' | |
| 110 | 6C902009 | RD,9 | X'2009' | |
| 111 | 6CA0200A | RD,A | X'200A' | Read CH A Groups |
| 112 | 6CB0200B | RD,B | X'200B' | |
| 113 | 6CC0200C | RD,C | X'200C' | |
| 114 | 6CD0200D | RD,D | X'200D' | |
| 115 | 6CE0200E | RD,E | X'200E' | Read M.S. Groups |
| 116 | 6DF0200F | RD,F | X'200F' | |
| 117 | 2E000000 | WAIT | | |
| 118 | 20100001 | SI,1 | X'01' | Update counter |
| 119 | 6D402008 | WD,4 | X'2008' | Step MIOP |
| 11A | 22503000 | LI,5 | X'3000' | Wait for MIOP to do Step |
| 11B | 6450011B | BDR,5 | X'11B' | |
| 11C | 6800010C | B | X'10C' | Collect new Status |

I/O COMMAND DOUBLEWORD _ -122

| | | | | |
|---|---|---|---|---|
| 120 | 06000488 | DATA | X'06000488' | IOCD to READ one Byte into |
| 121 | 00000001 | DATA | X'00000001' | location 122 |
| 122 | XX | | | Data input location |

*Changes to use TTY

| | | | | |
|---|---|---|---|---|
| 102 | 68000108 | B | X'108' | Bypass M.S. setup |
| 10B | 4C200001 | SIO,2 | X'001' | Address TTY |

#Changes to do single Operation stepping

| | | | | |
|---|---|---|---|---|
| 108 | 22403000 | LI,4 | X'3000' | Put MIOP in Single Operation |

SIGMA 8/9 MIOP Single Step Operation

M.S. Address = 07

Single
Phase

Single,
Operation

| (R1) | Group 0 | Group 8 | Group 9 | Group C | Group E | Group F | (R1) |
|------|---------|---------|---------|---------|---------|---------|------|
| | SIO INSTRUCTION | | | | | | |
| 1 | | 40040000 | 003D2X00 | 00000000 | 00008400 | 00004800 | |
| 2 | 00000020 | 00240180 | 00212000 | 0000C007 | 00008400 | 00000C80 | |
| 3 | 07800020 | 00150180 | 22212600 | 00000007 | 00002400 | 00000C81 | |
| 4 | 07C00021 | 000C8190 | 04212400 | 00000007 | 00008408 | 00002C80 | |
| 5 | 07C00021 | 80000010 | 04352000 | 00000000 | 00008408 | 00002400 | ← 1 |
| | ORDER OUT | | | | | | |
| 6 | 07C00021 | 40000C30 | 263D2200 | 00000000 | 00001408 | 00002405 | |
| 7 | 07C00021 | 20018000 | 8CB12800 | 00000000 | 00001508 | 00008400 | |
| 8 | 07C00021 | 08008000 | 88B1EC00 | 00000000 | 00001508 | 00008400 | |
| 9 | 00000121 | 040083C0 | 88B1E800 | 00000000 | 00001508 | 00008400 | |
| A | 00000121 | 0201C240 | 88B1E800 | 00000006 | 00000D08 | 00008C00 | |
| B | 00000121 | 01004000 | 88B1C800 | 00000006 | 00000D08 | 00008E00 | |
| C | 00000121 | 80004000 | 84F5C800 | 00000000 | 00008438 | 0000EE00 | ← 2 |
| | DATA IN | | | | | | |
| D | 00000121 | 40004020 | A6FDCA00 | 00000000 | 00001438 | 0000EE05 | |
| E | 00000121 | 20018000 | 0C310800 | 0000FFFF | 00001538 | 00000600 | |
| F* | 04400122 | 01004180 | 88B10C80 | 000000FF | 00000D38 | 00008600 | |
| 10 | 04400122 | 80004000 | 84F50480 | 00000040 | 00008498 | 0000EE00 | ← 3 |
| | ORDER IN | | | | | | |
| 11 | 04400122 | 40004020 | A6FD0C80 | 00000040 | 00001498 | 0000EE05 | |
| 12 | 04400122 | 20018000 | 8CB10C00 | 0000FFFF | 00001598 | 00008600 | |
| 13 | 04400122 | 01004000 | 88B1AC00 | 000000FF | 00000D98 | 00008600 | |
| 14 | 04400122 | 80004000 | 80F5AC00 | 00000000 | 00008480 | 0000CC00 | ← 4 |

| (R1) | Group 0 | Group 8 | Group 9 | Group C | Group E | Group F | (R1) |
|------|---------|---------|---------|---------|---------|---------|------|

*Location 122 now has data byte of FF